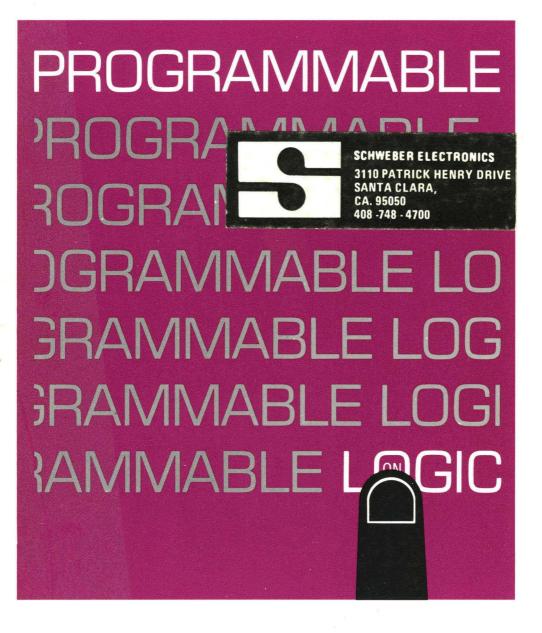
#### Programmable Array Logic

Handbook





## **Advanced Micro Devices**

## Programmable Array Logic Handbook

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# Preface



Programmable Array Logic (PAL) devices are fuse programmable logic building blocks capable of implementing complex, high performance functions which combine the architectural flexibility of a custom design with the instant availability, multiple sourcing and low cost of standard off-the-shelf products.

Early uses of PALs were predominantly as simple SSI and MSI replacement functions where standard TTL catalog items resulted in inefficient multiple package solutions. PALs provided a denser, faster, lower power and lower cost implementation. As designers learned to exploit the freedom of structuring their own components for a specific application, more innovative and efficient uses of fuse programmable logic began to emerge. Today a single PAL package is frequently employed to create functions that would require hundreds of conventional TTL gates.

Advanced Micro Devices is the world's largest merchant supplier of TTL compatible Bipolar LSI Logic and memory products. This has been achieved by implementing innovative, high performance LSI functions with advanced process technologies, such as IMOX<sup>TM</sup> oxide isolation and ultra-reliable platinum-silicide fuse structures, and supporting them with dedicated high volume manufacturing facilities. These same capabilities have now been applied to fuse programmable logic devices. The result is a line of PAL components offering industry leading performance, programming yields, quality guarantees and functional flexibility.

The AmPAL 22V10, introduced in this book, represents a new generation of flexible architecture, fuse programmable logic products. Other, even more advanced, devices are in development based on the greater density and improved performance characteristics of new bipolar technologies. These will insure that programmable logic devices will continue to grow in importance as primary building blocks for advanced high performance systems.

This handbook is intended as an introduction to fuse programmable logic devices as well as a resource manual for experienced designers. If you require additional information on any of the products described in this book or our future plans in this area, please call your local Advanced Micro Devices Sales Office.

> David A. Laws Managing Director Programmable Logic Products

"The VAX-11/730's circuit design is based on the use of PALs, which have helped reduce board area for the CPU by a factor of four and halve component costs, as compared with equivalent performance MSI."

David A. Carlson and Robert P. Morin Digital Equipment Corporation *Electronics*/October 6, 1982

"As time went on, however, it became clear that West had made the right choice; PALs really were the chip of the future."

Tracy Kidder
Referring to the Data General 32-bit
Eclipse MV8000 (Eagle) in
The Soul of a New Machine

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## **Advanced PALs**

## 口

#### **Features of PALs**

- User customizable, high performance logic building blocks
- Custom logic patterns may be generated in minutes with PROM type programmers
- Easy to use software design aids available (PALASM)
- Improves performance and reduces board area and cost of existing TTL SSI/MSI designs
- Aids creation of new system architectures through interactive design techniques
- Security fuse prevents copying of logic by competitors
- Slim 20 and 24-pin DIP packages

#### **Advantages of AMD PALs**

- IMOX oxide isolated technology insures industry's fastest (12ns typ) "A" versions and fastest half-power (24ns typ) "L" versions
- Platinum-silicide fuses and added test words insure programming yields > 98%
- Reliability assured through more than 40 billion fuse hours of life testing with no failures
- Full AC and DC parameter testing at the factory through on-board testing circuitry
- Preload feature permits full logical verification at the device level
- Power-up reset simplifies state machine design
- Industry leading quality guarantees

#### AMD PAL Speed/Power Families

Family	<sup>t</sup> pd ns (Max)	t <sub>S<sup>(1)</sup> ns (Max)</sub>	t <sub>CO<sup>(1)</sup> ns (Max)</sub>	I <sub>CC<sup>(2)</sup> mA (Max)</sub>	I <sub>OL</sub> mA (Min)
High Speed, "A"	25	20	15	155	24
Standard	35	30	25	155	24
Half Power, "L"	35	30	25	80	24

<sup>(1)</sup> Sequential functions.

#### **AMD PAL FUNCTIONS**

Part Number	Array Inputs	Logic	OE	Outputs	Package Pins	
16R8	Eight Dedicated Eight Feedback	Eight 8-Wide AND-OR	Dedicated	Registered Inverting	20	
16R6	Eight Dedicated Six Feedback	Six 8-Wide AND-OR	Dedicated	Registered Inverting	20	
10/10	Two Bidirectional	Two 7-Wide AND-OR-INVERT	Programmable	Bidirectional		
16R4 Eight Dedicated Four Feedback Four Bidirectional		Four 8-Wide AND-OR	Dedicated	Registered Inverting	20	
		Four 7-Wide AND-OR-INVERT	Programmable	Bidirectional		
16L8	Ten Dedicated Six Bidirectional	Eight 7-Wide AND-OR-INVERT	Programmable	Six Bidirectional Two Dedicated	20	
16H8	Ten Dedicated Six Bidirectional	Eight 7-Wide AND-OR	Programmable	Six Bidirectional Two Dedicated	20	
16LD8	Ten Dedicated Six Bidirectional	Eight 8-Wide AND-OR-INVERT	-	Dedicated	20	
16HD8	Ten Dedicated Six Bidirectional	Eight 8-Wide AND-OR	-	Dedicated	20	
22V10	Twelve Dedicated Ten Bidirectional/ Feedback	Ten 12 (Average)-Wide AND-OR/ AND-OR-INVERT	Programmable	Ten Bidirectional/Registered Programmable Polarity	24	

<sup>(2)</sup> Combinatorial functions.



# Introduction to Programmable Array Logic

Features of Programmable Array Logic Advantages of AMD Programmable Array Logic A Comparison Between Programmable Logic and Other Logic Alternatives An Introduction to Programmable Logic Architecture PALs Aid High Performance 32-Bit CPU Design

#### Features of Programmable Array Logic

#### **Flexibility**

#### **Design Optimization**

Programmable logic removes constraints placed on the designer by the available selection of fixed-function TTL SSI/MSI parts. If a desired function does not exist, the designer may need to use a large number of packages to generate it. With PALs, the designer can create a customized part for a specific application.

#### Faster Design Cycle

Programmable logic offers a way to reduce design cycle time. In a typical top down design, rather than determining the specific logic required for a function immediately, the designer can simply specify that a programmable logic device will be used. This allows the architecture and interface between logic blocks to be defined before the specific details of each logic block are specified. The individual logic blocks can then be designed with a minimum number of iterations.

#### Simple Prototyping and Debugging

Programmable logic greatly reduces the costs and time consuming effort associated with system design changes. Any changes because of logic errors or revisions in product specification may be easily implemented by reprogramming the device instead of rewiring or relaying out a board or making a new mask for a gate array.

#### **High Performance**

#### Optimized Design

System performance can be increased through the use of programmable logic. The designer has the freedom to optimize an architecture by tailoring programmable devices to implement it precisely. Thus a design may be implemented in the most efficient manner, frequently increasing performance.

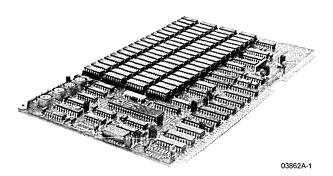
#### **Reduced Delay**

When a logic function is implemented in multiple SSI/MSI packages, the total delay incurred includes the time required for several on and off chip buffers. When the same function is implemented in a single programmable logic element, the delay per logic gate is reduced.

#### **Low Cost**

#### **Reduces Board Space**

PAL devices available today can provide logic complexity equivalent to 300 TTL gates. Implementing a design in programmable logic can therefore significantly reduce the board space or the number of boards necessary to implement a given function. This results in lower system cost, or alternatively, the ability to provide more function in the same enclosure.



PAL Control Logic Fits One Megabyte of RAM onto a Single MULTIBUS Board (Am971024B)

#### **Reduces Inventory Cost**

Programmable logic can be used to replace more than 90% of standard TTL parts. This allows the user to reduce his inventory from hundreds of different TTL devices to just a few programmable logic device types. This simplifies inventory requirements as well as easing purchasing procedures.

#### **Reduced Parts Count**

Compared to standard TTL SSI/MSI, programmable logic reduces the number of packages necessary to implement a given function. In some cases, an entire PC board can be eliminated. This results in increased reliability.

#### **Reduced Interconnections**

The least reliable portions of a digital system are the connections between integrated circuit devices. Reducing the number of packages reduces the number of external connections and therefore improves the reliability.

#### Reliability

#### **Support**

#### PALASM

Programmable logic designs may be executed through an easy to use software design tool called PALASM. The user inputs the desired logic equations and PALASM automatically generates the fuse programming information. The input file, called a PAL DESIGN SPECIFICATION, provides excellent documentation on each design. The output may be downloaded to a wide variety of low cost logic programmers. Logic simulation capabilities are provided in PALASM to help the designer verify the logic design. The output of the simulator can also be used to test a programmed device.

#### **Design Security**

By programming a special "security fuse", the user can disable the fuse verify logic circuitry. This prevents unauthorized duplication of the device, while not interfering with the part's logic functionality. This makes programmable logic ideal for any application where design security is essential.



#### Advantages of AMD Programmable Array Logic

#### **Improved Performance**

#### IMOX

The AMD PAL family is manufactured using Advanced Micro Devices' IMOX advanced oxide isolation process. IMOX, which has been in production for many years on high performance bipolar LSI devices such as the Am2900 family, insures the best speed/power performance PALs available in the industry.

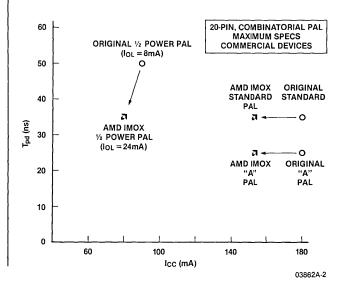
#### Higher Speed—"A" Versions

The use of IMOX technology insures high yields and therefore predictable availability of the high speed "A" versions of PALs. Worst case input to output delay of 25ns is specified with typical performance in the 10ns to 12ns region. New generations of IMOX will provide even faster guarantees.

#### Half Power-"L" Version

A new family of half-power PALs, designated "L" versions, provides standard 35ns maximum delays and full 24mA drive capability at half the standard power. Half power PALs will directly replace standard and early (-2) low power functions while enhancing system reliability and performance.

In addition, AMD standard and high speed "A" combinatorial PALs, are specified at more than 20% lower power dissipation than other manufacturer's devices.



1-5

#### **Flexibility**

#### Enhanced Line (20-pin)

In addition to the popular high volume 20-pin PAL devices, Advanced Micro Devices offers three additional functions.

AmPAL16H8 is an active HIGH version of the AmPAL16L8. These parts together provide the capability of implementing logic with either active HIGH or active LOW outputs. Switching logic equations from one polarity to another can achieve a significant reduction in product term usage. The AmPAL16H8 can functionally replace all other active HIGH 20-pin PALs.

AmPAL16LD8 is an active LOW device implemented with dedicated outputs to increase the number of logical product terms to 8 per output.

AmPAL16HD8 is an active HIGH version of the AmPAL16LD8. These two functions give the capability of creating a wider range of functions in a single PAL.

#### Enhanced Line (24-pin)

The AmPAL22V10 is a 24-pin device which will allow the user to program the architecture. Each of the 10 outputs may be registered or combinatorial, active HIGH or active LOW. Variable product term distribution will permit between 8 and 16 logical product terms per output for a total of 120. This device provides a new standard of flexibility in PAL functions.

#### **Power-up Reset**

The registered devices in the AMD PAL family are designed to reset during system power-up. All registers will be set to zero, setting all the outputs to ones. This feature is especially valuable in simplifying state machine initialization.

#### **Full Test Capability**

#### **Special Test Circuitry**

All AMD PALs include special test circuitry to allow thorough AC and DC testing of unprogrammed units prior to shipment. The test circuitry is used to insure good programming yield and to verify that devices will meet all parametric and switching specifications after programming.

#### **Programmability Testing**

Programming circuitry testing includes tests to assure unique addressing of all fuses. The ability of circuitry in the programming path, to handle the large currents and voltages necessary to blow fuses, is also checked.

Special probing pads, high threshold voltage circuitry and test fuses are employed in programmability testing. This testing coupled with the platinum silicide fuse structure gives industry leading programming yields (>98%) for all AMD PALs.

#### **DC Functional Testing**

Special test circuitry, enabled by means of high voltage signals, checks functionality and DC parameters under conditions that simulate post programming operation. All circuitry and levels that can be involved in operation after programming are checked under worst case conditions.

For example, all input buffers are tested for functionality by switching them through a special path to a single output. All product term AND gates are switched and sensed for uniqueness and functionality.

#### **AC Testing**

Similar special test circuitry permits AC switching delays through worst case paths to be measured. This provides a means to guarantee AC specifications under worst case power supply and loading conditions.

#### **PRELOAD** for Logic Verification

AMD PALs provide the capability of loading the output registers of a PAL to any desired value during testing. PRELOAD is the only way to allow full logical verification of programmed registered PALs and thus guarantee correct logical functionality. Without PRELOAD, many device failures cannot be discovered until the device is tested as a part of the finished system.

#### Reliability

#### **High Programming Yield**

The proven platinum silicide fuse structure used for many years in AMD PROMs is also applied to PALs. This insures that AMD PALs consistently achieve better than 98% programming yields.

#### High Reliability

This same fuse technology has demonstrated an excellent reliability history. Zero fuse failures have been generated in over 40 billion fuse hours of life testing.

#### Design Aid Software

#### **PALASM**

The AMD PAL family is supported by an upgraded version of the PAL Logic Equation Assembler, PALASM. Known as AMPALASM20, this design aid software provides error checking and recovery features and the JEDEC Programmable Logic Data Transfer Format output capability. Advanced Micro Devices provides AMPALASM20 on an 8 inch CP/M floppy disk for the AMD System 8 and 29, and other popular computer systems. Advanced Micro Devices is committed to providing the continuing support necessary for programmable logic as new, faster and more complex devices become available.

## A Comparison Between Programmable Logic and Other Logic Alternatives



Today's logic designer can choose from a wide variety of implementation alternatives. These can be classified into three basic categories: dedicated general purpose devices (hereafter called standard products), fuse programmable logic and custom integrated circuits (Figure 1).

Standard product architectures are defined by the IC manufacturer for a wide market and cannot be altered by the user. Examples of standard products are fixed instruction set

MOS microprocessors, microprogrammable LSI building blocks, and TTL and CMOS SSI/MSI devices. Custom logic on the other hand, is defined by the user for his application. Programmable logic devices fit between standard products and custom logic. The IC manufacturer defines an architecture that a user can program in his facility by blowing appropriate fuses to fit his specific application. PALs, PLAs and PROMs are examples of programmable logic.

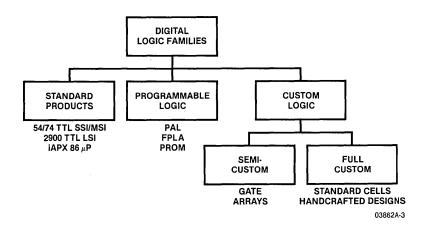


Figure 1. Basic Categories of Digital Logic

Each of these three design alternatives offers distinct advantages and disadvantages in terms of cost, availability and architectural flexibility. Many system designs today, such as the controller board in Figure 2, incorporate all three of the design approaches to some degree. However, in order to evaluate which type is best suited for a particular function, this review will consider each approach on a stand-alone basis.

#### DEDICATED GENERAL PURPOSE DEVICES— STANDARD PRODUCTS

There are five main advantages of standard products. They require little IC engineering expertise by the user, provide lowest cost for an individual device, usually have the best application support, provide the maximum logic density per device and are available off-the-shelf with no development lead time.

Development engineering effort at the IC level is minimal compared to the custom or programmable alternatives. The responsibility for design, test, and debugging is borne by the integrated circuit manufacturer. Because the integrated circuit manufacturer is doing this on a large scale, the process is very efficient. The engineering time and investment saved by the standard product user can be utilized to do design work that is more directly profitable and in his realm of expertise.

Standard products achieve a cost reduction on an individual device basis because they are high volume products. This volume results in lower manufacturing cost and thus lower price per unit. The increased competition encouraged by alternate sourcing products also results in lower cost.

The design support available for standard products is far greater than that for custom or programmable devices. Application software (assemblers, simulators), hardware (emulators) and literature (manuals, books, application notes) make them easier to design with. Since standard products reach a much larger market, the engineering effort necessary to provide this support can be spread over a large number of units, reducing the cost. When a custom or programmable logic device is used, this support must be developed by the engineer doing the design.

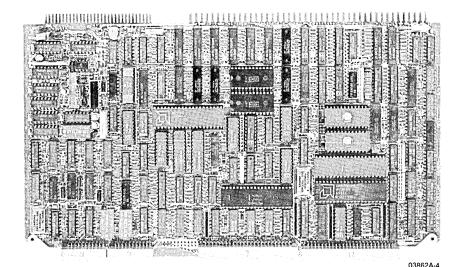


Figure 2. Using PALs for state machines, a gate array for error correction, and standard products including a DMA controller chip, and an 8085 microprocessor, Data Systems Design squeezes hard-disk, floppy-disk, and mag tape controllers onto one board. (7215 Controller Board) Photo Courtesy of Data Systems Design, Inc.

Standard products are optimized for high volume production. The density of logic functions is therefore generally much greater than on custom logic (when implemented with gate arrays) or programmable logic devices. A fixed instruction set microprocessor or microprogrammable building block duplicated with gate arrays or programmable logic devices would take several packages compared to the single dedicated device.

The three potential disadvantages of standard products are non-optimality, higher system cost and lack of unique feature advantages. A standard product, by the very nature of its generality, is not ideal for anyone. It includes too much functionality for some applications and not enough for others. The architecture is seldom ideal for a particular application. Standard products also offer a limited performance selection. IC manufacturers pick a specific performance level aiming at as large a market as possible.

Due to the general purpose nature of standard products, it is difficult to achieve the lowest package count solution. Additional components are required to tailor the function to fit a specific need. Even though individual devices may be lower in price, more of them must be used, raising the cost for the total system when considering the additional PC boards, testing, power supplies, fans, etc.

Another disadvantage of standard products is the lack of competitive features and advantages. Anyone can buy them so it is difficult to differentiate one system supplier's hardware from another.

#### **CUSTOM LOGIC DEVICES—GATE ARRAYS**

Custom logic, predominantly in the form of gate arrays today, offers the system designer important advantages over standard products. Compared to SSI/MSI implementations, reduced package count is of paramount importance. Standard LSI products provide the same benefit but force the designer to use a specific architecture. Custom logic allows the designer to implement his own architecture exactly. This freedom to develop innovative solutions to an applications problem can add a significant competitive advantage to a product.

The four main disadvantages of gate arrays are increased engineering effort, higher cost per individual device, lack of high level support tools and lower density compared to standard LSI products. Engineering effort for a gate array can significantly increase the cost of a system design. Not only must the system be designed, but the custom devices themselves must be designed, debugged and put into production. Both design tasks, chips as well as system, take similar amounts of engineering resources, possibly doubling the design effort and investment. Because of the lack of a competitive market (minimum second sourcing), custom logic devices can end up being substantially more expensive. Only

if the complete system solution can be optimized will the total cost be reduced. Another factor to be considered is the chance of design problems with a custom device. If extra iterations are necessary, or even worse a bug is discovered after a product has been released, correcting the problem can take several months or even years. These potential costs are difficult to estimate and have virtually no limit.

The third disadvantage of custom logic is the lack of high level support. Semiconductor manufacturers cannot provide significant support in the form of software, development systems, application notes, or books for a custom logic design because each device is different. The designer must document the design fully and provide enough support for the system engineer to utilize the device correctly.

Finally, a key disadvantage of gate arrays is the reduced density and therefore higher silicon cost compared to a dedicated general purpose device. They are designed by repeating a common loosely packed structure, leaving wide channels for the metal interconnect. For a given set of design rules a gate array will typically require two to five times the silicon area for the same gate count.

#### PROGRAMMABLE LOGIC DEVICES

Programmable logic combines the advantages of the flexible architecture of a custom design with the off-the-shelf availability and reduced investment—engineering time and device cost—of a standard product.

Programmable logic has the fastest design cycle time of any form of custom logic. Instead of months, or years, as with semicustom or full custom designs, a programmable logic element can be defined by programming the fuses on a blank device. This process takes only seconds. This fast turnaround time allows a revolutionary interactive approach to system design. The engineer can try out a new architectural approach and evaluate it very quickly. If it does not work, a new idea can be defined, programmed and ready to evaluate in hours. The speed with which a new design approach can be explored and evaluated creates a design environment that enhances innovation.

Programmable logic devices share the same economics of high volume production as standard products and other user customizable integrated circuits such as PROMs, EPROMs and EEPROMs. As the manufacturer produces identical blank elements by the millions of units per year, low costs can be achieved. This volume market attracts multiple vendors and encourages price competition, as well as provides alternate parallel construction source security. The cost advantages of a standard product are retained with programmable logic devices, but as parts are customized, system designs may be differentiated from the competition. In fact, truly innovative designs are even patentable, further protecting a design from the competition.

The engineering effort and time needed to design, test, debug and put into production a programmable logic device is larger than the effort necessary for a standard product, but substantially less than for a custom element (Figure 3). Software tools are provided to reduce this overhead considerably. These permit designs to be specified in terms of Boolean equations. The input specification format, for the software, serves as a "data sheet" for the particular application and generates the essential documentation information. Simulation and test vector generation programs also exist to reduce the engineering effort associated with debugging and testing, both in prototyping and production environments.

Programmable logic devices available today and in the near future provide the functional equivalent of up to 250 to 500 gates. While this is an order of magnitude better than typical SSI/MSI designs, it is less than that of advanced gate array products. However when all costs are amortized, programmable logic can still provide the lowest price form of custom logic available to most system manufacturers.

This threshold is increasing rapidly as advanced process technologies improve the effective logic complexity of programmable devices.

#### SUMMARY

Programmable logic combines the strengths of the dedicated general purpose and custom logic design approaches. It provides interactive design via customizability and immediate turn-around time. This revolutionary design approach results in innovative, low cost designs, maximizing the competitive advantage of a product.

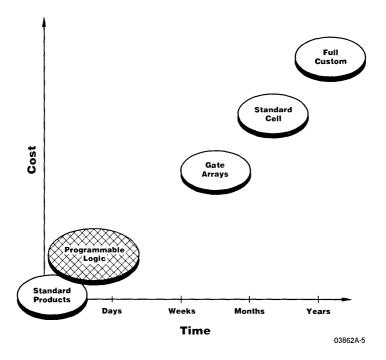


Figure 3. Relative Development Time vs Cost for Alternative Logic Implementations

## An Introduction to Programmable Logic Architecture



Programmable array logic (PAL) devices have many features in common with programmable read-only memory (PROM) and programmable logic array (PLA) devices. All three share the same basic internal AND-OR structure, but vary in allocation of logic features and amount of programmability. Figure 1 shows the basic AND-OR structure of programmable devices. It consists of two levels; the first is the AND array which accepts inputs, performs the desired

AND functions on the inputs and then outputs these functions to the second level, the OR array. The OR array combines various AND functions together producing the desired (AND-OR) outputs. This structure makes programmable devices ideal for implementing logic in Boolean sum-of-products form which is easily generated using logic design techniques such as Karnaugh maps.

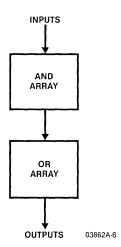
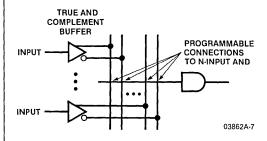


Figure 1. Basic Programmable Logic Array Architecture

Figures 2 and 3 depict the rules for understanding the notation commonly used in logic diagrams to describe programmable logic devices. Figure 2 shows the technique for describing an AND array. All array inputs (true and complement of each device input) are shown connecting to a single input AND-gate. In reality, each array input is an input to the AND-gate. Thus an N-input device will have AND-gates with 2N inputs. For example, the AmPAL16L8 has sixteen inputs and therefore each of its sixty-four AND-gates has thirty-two in-

puts! In a programmable AND array each row and column intersection, as shown in Figure 2, represents a fusible input connection to the AND-gate. Thus, to create an AND function, the fuses associated with undesired inputs must be blown. Figure 3 shows the technique for describing an OR array. All of the rules for the OR array are the same as for the AND, except that an OR function is being implemented instead of an AND.



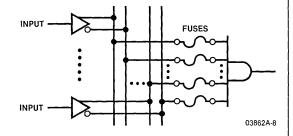
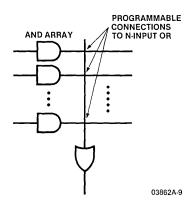


Figure 2a. Programmable AND Array Logic Diagram Notation

Figure 2b. Programmable AND Array Logic Equivalent



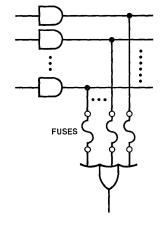


Figure 3a. Programmable OR Array Logic Diagram Notation

Figure 3b. Programmable OR Array Logic Equivalent

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#### PROM ARCHITECTURE DESCRIPTION

Figure 4 shows the basic architecture of a PROM using the notation of Figures 2 and 3. The PROM shown has three inputs, eight memory locations (AND-gates), and four outputs. The important feature of the PROM architecture, as far as programmable logic is concerned, is that the inputs are fully decoded by a fixed AND array which drives a programmable OR array. This means that every combination of inputs is represented by a separate AND-gate. Since there are  $2^{\rm D}$  combinations possible from n inputs, there are  $2^{\rm D}$  AND-gates in a PROM. For example, the PROM of Figure 4 has three inputs and because  $2^{\rm S}$  is eight, there are eight AND-gates in Figure 4.

By programming the OR array for a given output, as desired, the PROM can implement any logic function limited only by the number of inputs available. A separate, independent logic function can be implemented for each device output.

The limitation of PROMs in performing logic functions is their inability to provide the number of inputs and outputs that logic functions need. PROMs have a fixed number of inputs and a fixed number of outputs. For example, a 1K x 8 PROM has ten inputs, to fully decode 1K locations (remember that's 1024 fixed AND-gates!), and eight outputs (some PROMs have only four outputs). Unfortunately, logic functions don't come with fixed numbers of inputs and outputs. This means that a logic function requiring a total number of

inputs and outputs that is less than a device offers may not fit because it requires an allocation of inputs and outputs that doesn't fit the fixed PROM architecture. A function requiring eleven inputs and five outputs would not fit into the previously mentioned 1K  $\times$  8 PROM, despite requiring fewer total inputs and outputs than the device offers.

Typical logic functions can easily have up to sixteen inputs which would require a PROM with 64K locations. Few designs could utilize 64K AND-gates. Typical output functions don't always come in four or eight bits. Data path functions tend to be wider than the path itself because functions such as parity bits, ripple carrys, and serial inputs and outputs are usually required in addition to the data inputs and outputs. Thus four or eight bit data path functions would not be well served by PROMs.

Control path functions, such as state machines, can quickly use up both inputs and outputs. Using a PROM with a register on the outputs as a state machine requires both logical inputs and state feedback inputs, while also requiring state feedback and control outputs (see Figure 5). Note that the feedback inputs and outputs are tied together using up an input and output pin for each bit of state information. Thus, when a large number of states are required, few precious input and output pins are left over.

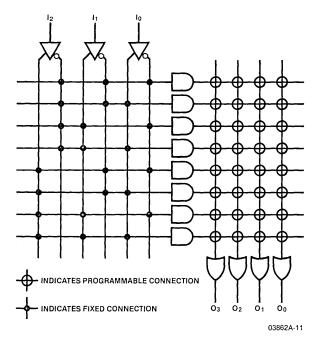


Figure 4. PROM Array Structure

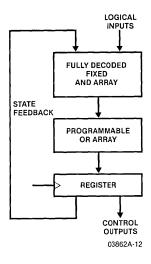


Figure 5. Registered PROM State Machine

#### PAL ARCHITECTURE DESCRIPTION

The array architecture of a PAL is shown in Figure 6. The basic PAL structure is exactly the opposite of a PROM; the AND array is programmable and the OR array is fixed. This immediately removes the restriction that for n inputs there are 2<sup>n</sup> AND-gates. There are six inputs to the PAL array of Figure 6, but only eight AND-gates. Thus one of the key inefficiencies of a PROM is removed, allowing PALs to have as many inputs as needed. The fixed OR array of a PAL dedicates which OR-gate a particular AND-gate will input to. In Figure 6, two AND-gates are dedicated to each OR-gate in the array. This is the only limitation of PAL devices: the number of AND-gates required by an equation may not exceed the number provided.

PAL devices contain many additional architectural features which make them ideal for implementing logic functions. These features include programmable I/O pins, outputs with registers that internally feedback to the AND array, and active HIGH or active LOW outputs. Programmable I/O pins allow the PAL device to be tailored to fit the required allocation of inputs and outputs. Thus PALs effectively remove the limitation of inputs and outputs. This allows PALs to implement far more different and complex logic functions than a PROM (even one with more pins). Registered outputs with internal feedback give PALs the capability to implement state machines efficiently. Device inputs need not be sacrificed as feedback inputs as in the PROM. PALs also provide active HIGH or active LOW capability.

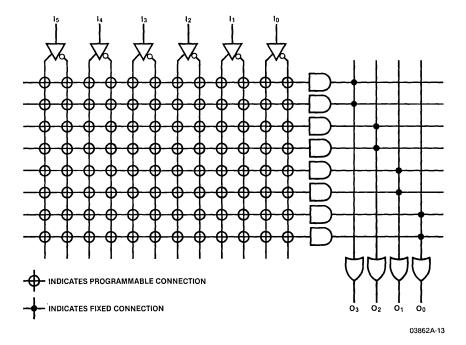


Figure 6. PAL Array Architecture

Logic diagrams for the bidirectional output structures of the PAL devices are shown in Figure 7. One feature of the PAL bidirectional output is the ability to program the output enable as a function of an AND-gate in the array. The output buffer may be programmed in one of three ways: as a dedicated output, a dedicated input, or a dynamically controllable input/output.

When programmed as a dedicated output, the output buffer is always enabled and the logic function is fed-back to the AND array. The feedback path allows more complex logic functions to be implemented by using two or more levels of AND-OR gating.

When programmed as a dedicated input, the AND-OR gate associated with that pin is unused, but an extra input has been created. This ability to trade-off outputs for inputs is one of the big advantages of PALs over other programmable logic devices. The designer isn't limited to a fixed number of input and output pins. The ratio may be programmed to fit the intended application.

Finally, when programmed as a dynamically controllable input/output buffer (i.e., enabled/disabled by a logical combination of one or more inputs) this pin may be utilized as an input, as well as retaining the full logical capability of the

AND-OR gate. This is especially useful in control applications (microprocessor handshaking protocols) and bus oriented data operations (data steering and data storage/manipulation). A serial input/output pin is a common example. When left shifting the pin may be a serial input, but when right shifting the pin would be a serial output. This mode provides maximum utilization of the PAL architectural resources.

A logic diagram for one of the registered outputs of a PAL device is shown in Figure 8. The most important features of this structure are the feedback path and the dedicated output enable. This output enable is common to all registers on the chip. The output register is fed-back into the array internally instead of from the output pin as in the combinatorial part. This configuration is more useful because state information is available at all times instead of only when the output is enabled, simplifying state machine design.

The availability of a common, dedicated output enable makes registered PAL devices ideal for bus oriented systems. The registered PAL can be programmed to provide data storage, operation, or steering functions, the result of which is placed on a data bus by enabling the output buffer. Since all PAL outputs have 24mA current sinking capability, they can drive most on-board buses and many backplane buses.

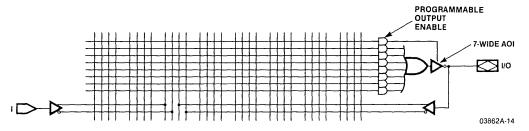


Figure 7a. Active LOW Bidirectional Output

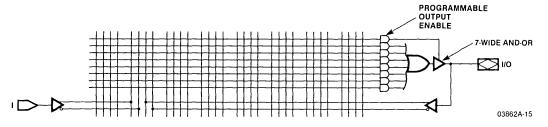


Figure 7b. Active HIGH Bidirectional Output

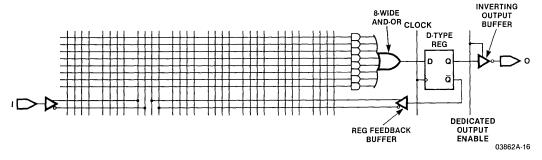


Figure 8. Registered Output

Figure 9 shows the active LOW and active HIGH versions of PAL dedicated outputs. The outputs are always enabled. The AND-gate previously used for this function provides an extra logical AND term in this structure. This brings the total number of AND-gates per output to eight. The feedback path from output to input is still provided, allowing for implementation of multi-level logic. The extra AND-gate makes these outputs ideal for non-bus oriented logic replacement, especially complex control signal generation, encoding and decoding.

#### **AMD 20-PIN PAL ARCHITECTURE**

The AMD 20-pin PAL family is based on an array of over 2000 platinum-silicide fuses. These provide the logical equivalent of sixty-four, 32-input programmable AND-gates. The array outputs feed eight, 8-input fixed OR-gates plus associated I/O and feedback circuitry. Each device type has a unique organization of these I/O components, optimized for specific functional applications.

As any logical function can be expressed in an AND-OR, sumof-products form, these basic elements can be programmed to satisfy a wide variety of complex custom logic requirements. Where a system architecture has been created around this PAL structure, single 20-pin packages have been used to perform functions that would each require over 300 equivalent TTL gates.

A typical member of the AMD 20-pin PAL family, the AmPAL16R4, is shown in Figure 10. This device has 16 available inputs to the fuse programmable array. Eight of these are dedicated inputs (pin numbers 1 through 9), four are feedback paths from the  $\overline{0}$  outputs of the on-board registers and four are via the bidirectional input/output ports (pin numbers 12, 13, 18 and 19). It contains four 8-wide AND-OR structures with inverting registered outputs, each AND-gate having 32 inputs. As half of the inputs are true and the other half complementary, only sixteen of them have effective logical value. A common three-state output enable line serves all four registered outputs. Four more 7-wide AND-OR-INVERT structures have combinatorial outputs with three-state output enables that are programmable through the fuse array.

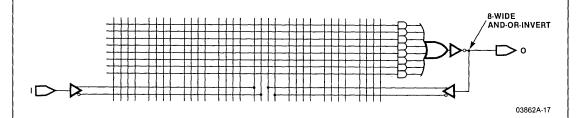


Figure 9a. Active LOW Dedicated Output

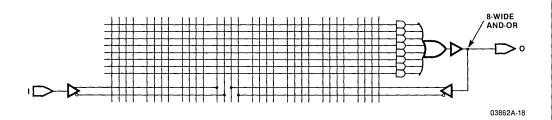
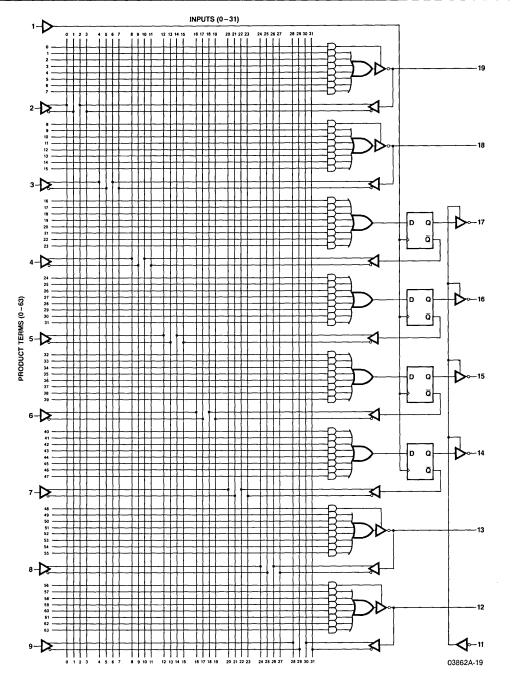


Figure 9b. Active HIGH Dedicated Output



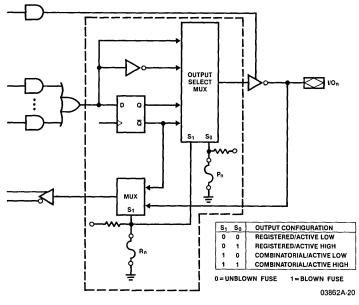
- 16 Array Inputs
  - -8 Dedicated
  - -4 Registered Feedback
  - -4 Bidirectional I/O
- 4 8-Wide AND-OR Structures
  - -Registered, Inverting Outputs with Common, Dedicated Output Enable
- 4 7-Wide AND-OR-INVERT Structures
  - -Combinatorial Outputs with Programmable Output Enables

Figure 10. Logic Diagram of AmPAL16R4

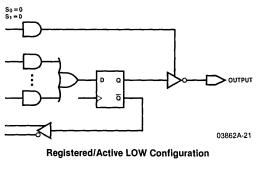
#### AMD 24-PIN PAL PROGRAMMABLE LOGIC STRUCTURE

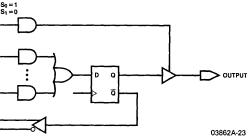
A new 24-pin device, the AmPAL22V10, allows programming of the logical function of each output separately to allow the user to select the preferred output structure. The basic output structure, or "macrocell", is shown in Figure 11 along with diagrams of the different output configurations. The

different configurations are bidirectional/active LOW, bidirectional/active HIGH, registered/active LOW, and registered/active HIGH. Thus the AmPAL22V10 can be architecturally optimized, as well as input and output optimized (as in the 20-pin family), to fit the particular logic function precisely.



AmPAL22V10 Output Logic Macrocell

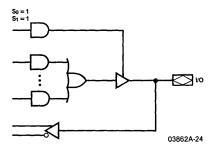




Registered/Active HIGH Configuration

S<sub>0</sub> = 0 S<sub>1</sub> = 1

Combinatorial/Active LOW Configuration



Combinatorial/Active HIGH Configuration

Figure 11

#### PLA ARCHITECTURE DESCRIPTION

The array architecture of a PLA is shown in Figure 12. The PLA allows both the AND array and the OR array to be programmed. This gives the PLA additional logic capability over both PROMs and PALs. PLAs can be designed to incorporate the same advantages over PROMs as do PALs. PLA devices can include the same logic features which reduce limitations of too few inputs, the allocation of inputs vs outputs, registered feedback, or output polarity, although few commercially available devices actually implement them. The programmable OR array allows AND-gates to be tied to ORgates, as desired, by programming. Logic functions are limited by the total number of AND-gates allocated to all outputs instead of by the AND-gates allocated to a particular OR-gate (as in a PAL). Thus if a logic function requires a large number of AND-gates, they may be allocated to the particular OR-gate requiring them. Additionally, AND-gates may be connected (shared) to more than one OR-gate. This allows more efficient utilization of AND-gates in a PLA than in a PAL.

The disadvantages of PLAs are not quite so obvious. PLAs are inherently slower than PALs or PROMs because a given signal must pass through two programmable arrays. This can make a PLA unsuitable for many high performance applications. In practice the user can seldom take advantage of allocating a large number of AND-gates to a particular ORgate. The number of AND-gates required for a particular equation is related to the number of inputs to the equation. PLA devices have a limited number of inputs, thus the number of AND-gates required by an equation is limited. Creation of equations using a large number of AND-gates can become very difficult. Logic design techniques such as Karnaugh maps cannot handle much more than five or six inputs and computer aid for this task is not generally available. Another problem is that commercially available PLAs have fewer AND-gates than comparable PALs because of the added silicon real estate required to provide the programmable OR array. If a designer creates an equation using most of his available AND-gates, only a few may remain for the other OR-gates.

To take advantage of potential AND-gate efficiency with respect to sharing is not easy. For example, in data path applications such as a barrel shifter, individual equations are dependent upon the data line of which they are in the path (i.e., the equation for output  $O_0$  is dependent on  $D_0$  and  $Q_1$  is dependent on  $D_1$ , etc.). This makes sharing of AND-gates impossible. In other words, data path equations are ideally suited to the architecture of PALs. Since the critical path of most systems is the data path, and PALs are faster than PLAs, they are better suited for these applications.

#### CONCLUSION

The three programmable logic architectures are represented by the PROM, PAL, and PLA devices. Although very similar in basic array architecture, they differ significantly in their ability to implement logic functions and in their applications. Each device type implements an AND-OR two-level logic array which allows implementation of logic equations in sumof-products form. The PROM is the most limited of the three device types. While it is able to implement any logic function dependent upon its inputs, it has very few inputs to work with. The PROM also has a fixed number of inputs and outputs and does not provide any architectural features to enhance logic design capability. The PAL, on the other hand, provides significant capability to implement logic functions. The programmable AND array allows equations with many inputs. Architectural features such as programmable I/O, internal registered feedback, and choice of output polarity allow optimization of pin allocation and logic equations. The PLA provides the most flexible architecture of the three for implementation of logic equations by utilizing a programmable AND array and a programmable OR array. However, the added flexibility of the PLA can seldom be effectively utilized. Further, the inherent loss in speed performance when using a PLA is increasingly unacceptable in high performance designs.

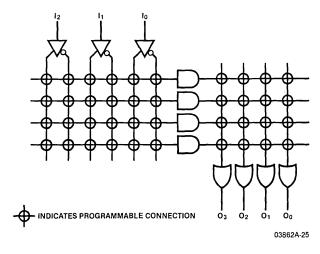


Figure 12. PLA Array Structure



## PALs Aid High Performance 32-Bit CPU Design

Bradford S. Kitson and B. Joshua Rosen\*



The Computervision Analytic Processing Unit (APU) was designed as a very high speed 32-bit super minicomputer intended for engineering applications. PALs were used extensively in the design. Instead of just replacing TTL SSI/MSI, his design utilized PALs as customizable logic building blocks, allowing powerful logic functions to be implemented in a minimum of space. The result is a machine which is twice as fast as competitive designs without an increase in board space. This paper describes several of the APU's "second generation" PAL based applications and illustrates the type of design techniques necessary to rise above the "first generation" TTL SSI/MSI replacement philosophy.

#### APPLICATION OF PALS IN THE COMPUTERVISION APU

The APU processor board set is divided into 4 modules, the Parser/Sequencer, which contains an instruction processor which fetches and decodes instructions in parallel with the execution unit; the Control Processor, which performs address and integer computations; the Floating Point Pipe, which performs both scalar and vector floating point operations; and the Cache/Address Translation Unit, which contains a 256 slot area page table entry cache and a 16K byte memory cache.

Approximately 25% of the chips in the APU board set are PALs. PALs were chosen for three reasons: flexibility, performance, and cost.

The APU is the first implementation of Computervision's new CPU architecture. As such, many aspects of the design were subject to change as the architecture evolved. The use of PALs permitted the designers of the machine to rapidly

modify the hardware to fit the needs of this evolving architecture. In addition, new features and performance enhancements could easily be implemented with minimal impact on the development schedule.

The ability to generate a very large number of essentially custom ICs (there are over 200 different PAL codes used in the APU) resulted in a significant reduction in the processor's size while greatly enhancing its overall performance. The net result is apparent when one considers that although the APU and the Digital Equipment VAX-11/750, a gate array based machine, consume exactly the same amount of board space, the APU is more than twice as fast.

In fact, the Fortran performance of the APU is substantially faster than that of the VAX-11/780, a machine which consumes 5.2 times as much board space as the APU.

#### APU FLOATING POINT PIPE

The APU floating point pipe (FPP) was designed as a very high speed arithmetic extension to the APU execution engine. Unlike other comparable machines, the floating point arithmetic unit of the APU is an integral part of the internal architecture and not an optional add on. As a result, the FPP is used not only to accelerate scalar and vector floating point arithmetic, but also to perform byte, word, double word and quad word string operations. In addition, the FPP is also used to enhance the performance of important non-floating point instructions such as Procedure Call and Return.

The FPP board uses a total of 79 PALs for both control and data path applications. The remainder of this paper focuses on two particular subunits of the APU FPP: the multiplier and the barrel shifter.

<sup>\*</sup>Manager, Processor Development, Computervision Corp., Bedford, MA, at the time this paper was written. This paper reprinted with the permission of Computervision Corp.

#### 3-TO-2 COUNTER

The multiplier section is the heart of the FPP. A block diagram of the multiplier appears in Figure 1. Double precision floating point multiplication requires the calculation of a 56-bit  $\times$  56-bit product. Unfortunately,  $56\times56$  parallel multipliers do not exist on silicon. The best cost/performance solution is to use a number of smaller multipliers to build an intermediate sized parallel multiplier and then produce a large product  $(56\times56)$  in multiple cycles.

The partial product generator logic of the FPP utilizes seven Am25S558  $8 \times 8$  multiplier slices to implement an  $8 \times 56$ -bit

multiplication array. Each multiplier chip produces a 16-bit product. In general, the most significant eight bits of each partial product generator must be added to the least significant eight bits of the next higher slice to generate the full 64-bit partial product. Exceptions are the most significant and least significant eight bits. For a graphic representation see Figure 2.

This technique also requires the ability to accumulate partial products with the partial products from previous cycles. Thus each cycle must be accompanied by two additions; the partial product summation and intermediate product accumulation.

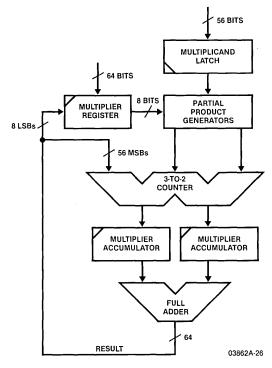


Figure 1. APU Multiplier (U.S. Patent Pending, Computervision Corp.)

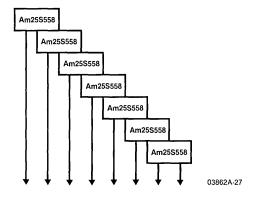


Figure 2. 64-Bit Partial Product Generation

The most straightforward way to accomplish this task is to follow the multipliers with two levels of lookahead adders, usually 74S181s. This technique results in a nanocycle time which is approximately 3 times longer than the partial product generation time of the 8×8 multipliers. This is clearly unacceptable. This scheme can be modified, however, by adding registers between each level of logic (see Figure 3). By pipelining the multiplier in this fashion, the nanocycle time can be reduced to something near the propagation delay time of the multiplier chips plus the clock to output time of the multiplier register plus the set-up time of the intermediate result register. The disadvantages of this scheme are increased pipe latency, caused by the two extra levels of pipelining, and a high part count. Still another technique involves replacing one level of the pipe and one level of

lookahead adders with carry save adders between the partial product generators and the pipeline registers. Carry save adders are used to implement a technique called 3-to-2 counting. As can be seen from Figure 4 any combination of 3 equally weighted bits can be recoded into a 2-bit field.

Thus it is possible to reduce the three operands generated by the multiplication process (the high and low partial products and the 64-bit intermediate product) into only two operands which may then be summed together in a single lookahead ALU. 3-to-2 recoding requires no carry propagate logic and is therefore very fast. Due to the speed of 3-to-2 counters, only one level of pipelining is required, which results in both a reduced parts count and a reduced pipe latency. The technique is ideally suited for implementation in PALs.

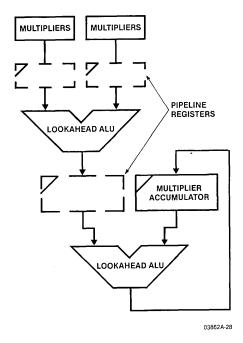


Figure 3. Two-Level Pipelined Multiplier Approach

INPUTS	OUTPUTS	
000	0 0	
0 0 1	0 1	
0 1 0	0 1	
0 1 1	1 0	
100	0 1	
101	1 0	
1 1 0	1 0	
111	1 1	03862A-29

Figure 4. 3-to-2 Counting

In the APU floating point engine, 16 AmPAL16R6s, programmed as triple 3-to-2 counters, are used to reduce the three multiplication operands to two intermediate results (see Figure 5 for a logic diagram). The registered outputs of the PALs are connected to the input buses of the Mantissa ALU, which is also used for floating point addition and subtraction. The Mantissa ALU then calculates the next intermediate product in parallel with the partial products

calculations occurring in the  $8\times 8$  multipliers. This intermediate product and the new partial products are then recoded by the 3-to-2 counter PALs to form the next pair of intermediate results. This process continues until the complete  $56\times 56$  product is generated. Thus without adding pipe latency, the APU is able to accumulate partial products at a rate of  $8\times 56$  bits every 112ns, which happily coincides with the basic nanocycle time of the machine.

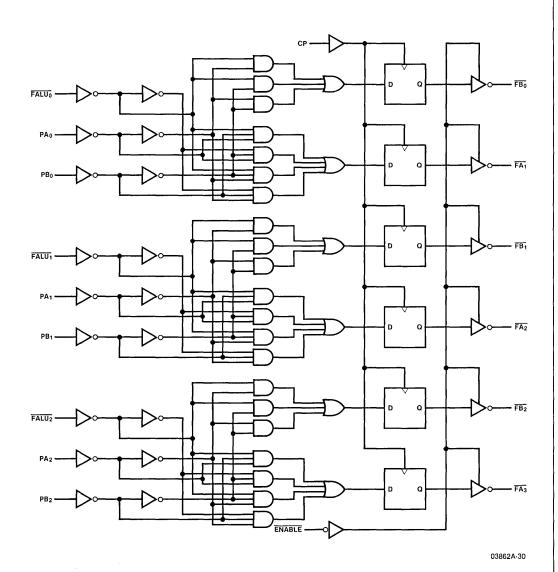


Figure 5. AmPAL16R6 3-to-2 Counter

#### **BARREL SHIFTER**

The APU Barrel Shifter, commonly referred to as the "Rosen Shifter", can perform left shift, right shift and rotate operations of from 0 to 63 bits in a single microcycle. The barrel shifter is used mainly for floating point prescale and normalize operations. A block diagram of the barrel shifter and its associated control logic is shown in Figure 6. The word rotater, nibble rotater and bit shift and mask logic comprise the three stages necessary to implement the barrel shifter. The prescale, leading zero detect and mask control logic comprise the logic required to control it.

The prescale logic converts the signed difference produced by the exponent arithmetic units as a result of the comparison of the two operand exponents, into an absolute shift distance which is then used to right shift (prescale) the Mantissa of the smaller operand of a floating point add or subtract operation. The leading zero detect logic determines the left shift distance required to produce a left justified (normalized) result. The mask control logic is used to convert rotated data to shifted data by masking off the appropriate leading or trailing bits to implement right or left shifts. These three sections are implemented in PALs, but will not be discussed in detail.

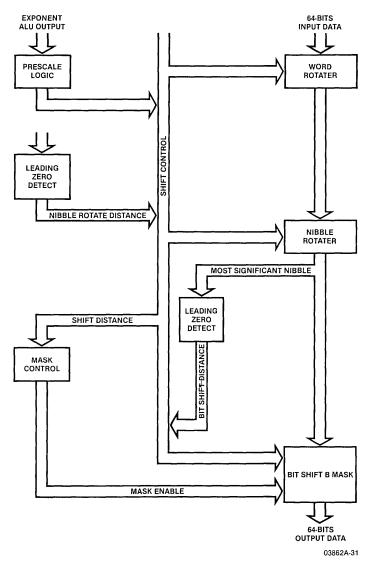


Figure 6. 64-Bit "Rosen Shifter"

To implement the three level 64-bit barrel shifter of Figure 6 in MSI requires the use of Am25S10 4-bit shifters (see Figure 7). The first level is the word rotater which performs a circular rotate of 0, 16, 32 or 48 bits. Although implementation is simple, the MSI solution requires 16 packages. The second level is the nibble rotater which is essentially identical to the word rotater but is wired to rotate 0, 4, 8 or 12 bits. The final stage of the barrel shifter requires not only bit rotate but also leading and trailing bit masking and sticky bit computation (i.e., the logical OR of the masked out bits). An MSI solution would require not only the 16 packages of Am25S10s, used in each of the preceding levels, but also 16 packages of AND gates, for masking, plus still another 16 packages of ANDs for the sticky bit computation. The control logic for performing the mask operation would probably require as much logic as the entire shift path. The more practical solution has usually been to build separate left and right shifters, 48 packages apiece, and not to implement a sticky bit at all.

The PAL implementation of a 64-bit rotater and shifter, with sticky bit computation, requires considerably fewer packages than a unidirectional MSI shifter.

The word rotater consists of 8 identical PALs programmed as two four-bit rotaters per package. The logic diagram of the word rotater is shown in Figure 8. The nibble shifter requires four Am25S10s and 8 PALs programmed as 6-bit wide 4 place shifters. The logic diagram of a nibble shifter is shown in Figure 9. The bit shift and mask logic requires sixteen PALs in the data path and two PALs in the control path. The logic diagram for a shift and mask PAL appears in Figure 10, but some explanation is required to understand the innovative design technique used to implement it.

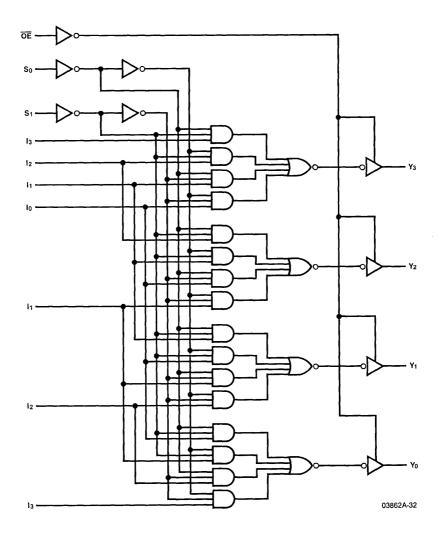
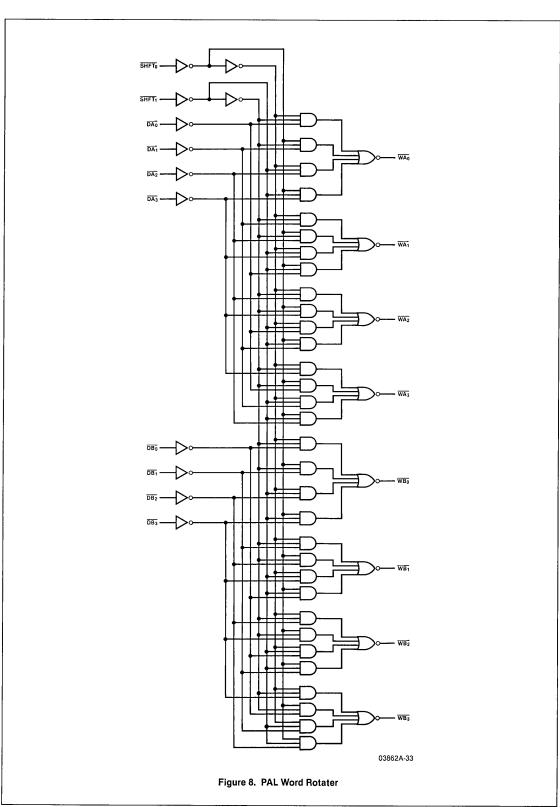
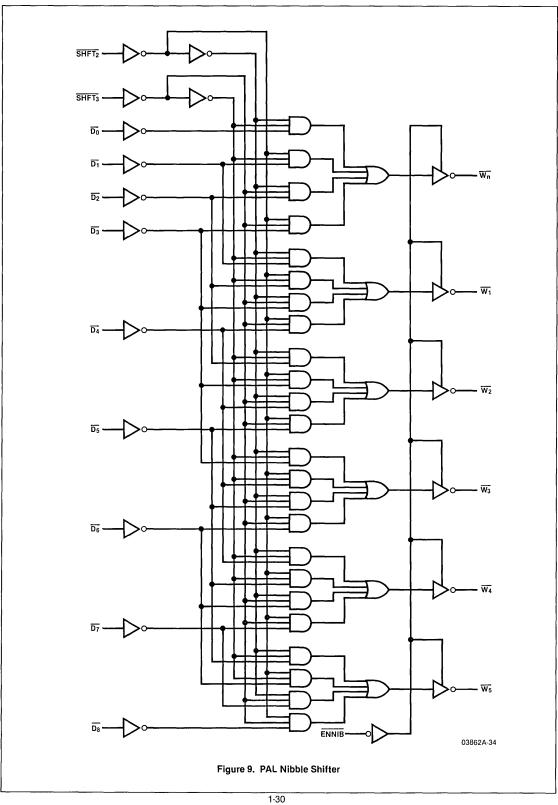
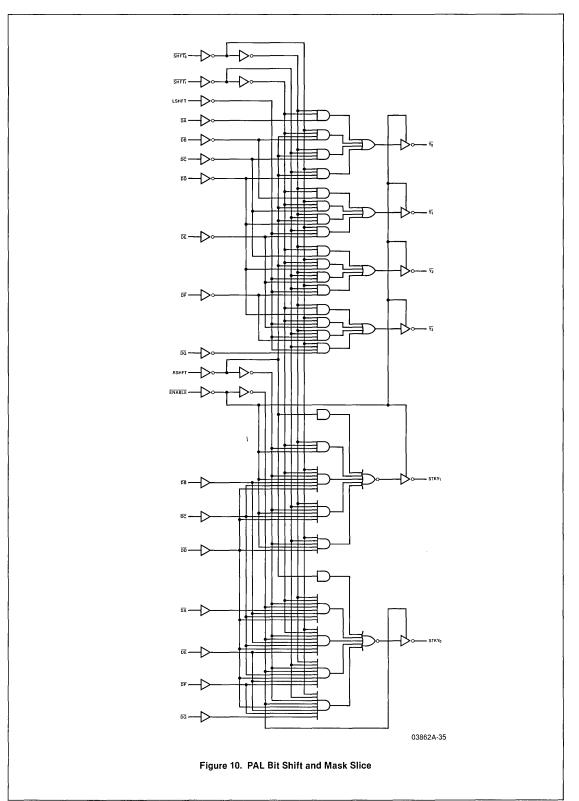


Figure 7. Am25S10 4-Bit Shifter







The technique used to implement the masking function required for shifting is called "nearest neighbor masking", (U.S. patent pending, Computervision Corp.). Each of the shift and mask PALs has an enable input from one of the mask control PALs. In addition, each shift and mask PAL is also connected to the enable inputs from its left and right hand neighbors (see Figure 11). The mask control PAL input determines if all four bits from the slice should be masked off. The enables from the adjacent slice determine if a PAL is at a shift boundary. Should only one of the neighboring slices be disabled then the shift and mask PAL will mask off from 0 to 3 of the bits adjacent to the disabled slice, depending on the bit rotation distance. In this way, the 64-bit masking operation can be implemented with only 16 control lines as opposed to at least 64 for an SSI/MSI solution.

In addition to performing the final shift and mask operation, the bit shifter PALs also compute the logical OR of the masked out bits at each slice position. These outputs are then logically ORed together to generate a sticky bit. The extra hardware required is less than two SSI packages.

The entire PAL Barrel Shifter requires 38 devices to implement 64-bit rotation, left shifting, right shifting and sticky bit accumulation. An MSI based left/right shifter, without sticky bit computation, would require a minimum of 96 parts. In addition, the logic required for implementing the prescale and normalize operations, not discussed, is also significantly reduced through the use of PALs.

#### CONCLUSION

The full potential of PALs has begun to be realized with the availability of high speed devices. PALs now allow the designer to architect the device to fit the application instead of architecting the application to fit the device.

The 3-to-2 counter design example shown illustrated the implementation of a unique architecture in PALs, resulting in significant part count reduction and throughput increase over a comparable TTL solution. The barrel shifter design example shown illustrated the innovative implementation of an application not previously feasible in TTL.

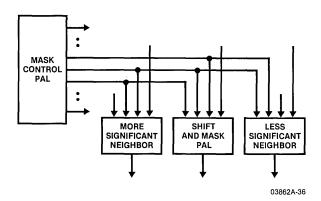


Figure 11. PAL "Nearest Neighbor" Interconnect



# Product Specifications

AMD 20-Pin PAL Family
AMD Half Power PAL Family
AmPAL22V10 Advanced Information
AmPL64S16 Advanced Information
Am27S12A/13A, Am27S12/13 2048-Bit Generic Series Bipolar PROM
Am27S18A/19A, Am27S18/19 256-Bit Generic Series Bipolar PROM
Am27S20A/21A, Am27S20/21 1024-Bit Generic Series Bipolar PROM

## AMD 20-Pin PAL\* Family

20-Pin IMOX<sup>™</sup> Programmable Array Logic Elements Advanced Micro Devices

#### **DISTINCTIVE CHARACTERISTICS**

#### Fast

- High speed "A" versions
- $(t_{pd} = 25ns, t_{s} = 20ns, t_{co} = 15ns, max)$
- Standard speed versions
- $(t_{pd} = 35 \text{ns}, t_{s} = 30 \text{ns}, t_{co} = 25 \text{ns}, \text{max})$

#### Flexible

- User programmability allows customized designs
  - Eases design updates in prototype or product

#### Low Cost

- Reduces board space/chip count
- Reduces design time
- Reduces inventory cost

#### Reliable

- Proven Platinum-Silicide fuse technology
- Fully AC and DC tested
- Preload of output registers allows full logical testing

#### **FUNCTIONAL DESCRIPTION**

AMD PALs are high speed electrically programmable array logic elements. They utilize the familiar sum-of-products (AND-OR) structure allowing users to program custom logic functions to fit most applications precisely.

Initially the AND gates are connected, via fuses, to both the true and complement of every input. By selective programming of fuses the AND gates may be "connected" to only the true input (by blowing the complement fuse), to only the complement input (by blowing the true fuse), or to neither type of input (by blowing both fuses) establishing a logical "don't care." When both the true and complement fuses are left intact a logical false results on the output of the AND gate. An AND gate with all fuses blown will assume the logical true state. The outputs of the AND gates are connected to fixed OR gates. The only limitations imposed are the number of inputs to the AND gates (up to 16) and the number of AND gates per OR (up to 8).

The part types in the AMD PAL family are differentiated by the allocation of registered (with internal feedback) and combinatorial (bi-directional and dedicated) outputs. All combinatorial AMD PALs are available in both active HIGH (AND-OR) and active LOW (AND-OR-INVERT) versions.

#### AMD PAL FAMILY CHARACTERISTICS

All members of the AMD PAL family have common electrical characteristics and programming procedures. All parts in this family are produced with a fusible link at each input to the AND gate array. Connections may be selectively removed by applying appropriate voltages to the circuit.

All parts are fabricated with AMD's fast programming, highly reliable Platinum-Silicide fuse technology. Utilizing an easily implemented programming algorithm, these products can be rapidly programmed to any customized pattern. Extra test words are pre-programmed during manufacturing to insure extremely high field programming yields (>98%), and provide extra test paths to achieve excellent parametric correlation.

Platinum-Silicide was selected as the fuse link material to achieve a well controlled melt rate resulting in large non-conductive gaps that ensure very stable, long term reliability. Extensive operating testing has proven that this low-field, large-gap technology offers the best reliability for fusible link programmable logic.

The AMD PAL family is manufactured using Advanced Micro Devices' selective oxidation process, IMOX. This advanced process permits an increase in density and a decrease in internal capacitance resulting in the fastest possible programmable logic devices.

The AMD PAL family also incorporates the unique capability of preloading the output registers during testing to any desired value. Preload is invaluable when testing the logical functionality of a programmed AMD PAL.

#### AMD PAL FAMILY TABLE

Part	Array					t <sub>pd</sub> t <sub>s</sub> (MAX)					
Number	Inputs	Logic	OE	Outputs	STD	A	STD	Α	STD	Α	
AmPAL16R8	(8) Dedicated (8) Feedback	(8) 8-Wide AND-OR	Dedicated	Registered Inverting	-		30	20	25	15	ns
A . DAI 4000	(8) Dedicated	(6) 8-Wide AND-OR	Dedicated	Registered Inverting	35	٥٥	30	20	25	45	ĺ
AmPAL16R6	(6) Feedback (2) Bidirectional	(2) 7-Wide AND-OR-INVERT	Programmable	Bidirectional	35	25	30	20	25	15	ns
AmPAL16R4	(8) Dedicated	(4) 8-Wide AND-OR	Dedicated	Registered Inverting	35	25	30	20	25	15	
Allii ALIOITA	(4) Feedback (4) Bidirectional	(4) 7-Wide AND-OR-INVERT	Programmable	Bidirectional	35	25	30	20	25		ns
AmPAL16L8	(10) Dedicated (6) Bidirectional	(8) 7-Wide AND-OR-INVERT	Programmable	(6) Bidirectional (2) Dedicated	35	25	-	-	-	-	ns
AmPAL16H8	(10) Dedicated (6) Bidirectional	(8) 7-Wide AND-OR	Programmable	(6) Bidirectional (2) Dedicated	35	25	-	-	-	-	ns
AmPAL16LD8	(10) Dedicated (6) Bidirectional	(8) 8-Wide AND-OR-INVERT	-	Dedicated	35	25	-	-	-	-	ns
AmPAL16HD8	(10) Dedicated (6) Bidirectional	(8) 8-Wide AND-OR	-	Dedicated	35	25		-	-	-	ns

#### MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65 to +150°C
Temperature (Ambient) Under Bias	−55 to +125°C
Supply Voltage to Ground Potential (Pin 20 to Pin 10) Continuous	-0.5 to +7V
DC Voltage Applied to Outputs (Except During Programming)	-0.5V to +V <sub>CC</sub> max
DC Voltage Applied to Outputs During Programming	21V
Output Current Into Outputs During Programming (Max Duration of 1 sec)	200mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	−30 to +5mA

#### **OPERATING RANGE**

		Commercial		Mili	tary	
Parameters	Description	Min	Max	Min	Max	Units
Vcc	Supply Voltage	4.75	5.25	4.50	5.50	٧
T <sub>A</sub>	Operating Free Air Temperature	0	75	-55		°C
тс	Operating Case Temperature				125	°C

#### ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE (Unless Otherwise Noted)

Parameters	Description	Test C	onditions		Min	(Note 1)	Max	Units
,	Output HICH Valence	V <sub>CC</sub> = MIN,	I <sub>OH</sub> = -3.2mA	COM'L	2.4	3.5		Volts
VOH	Output HIGH Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OH</sub> = -2mA	MIL	2.4	3.5		VOILS
V	Output LOW Voltage	V <sub>CC</sub> = MIN,	I <sub>OL</sub> = 24mA	COM'L			0.50	Volts
V <sub>OL</sub>	Output LOVV Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OL</sub> = 12mA	MIL			0.50	voits
V <sub>IH</sub> (Note 2)	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts	
V <sub>IL</sub> (Note 2)	Input LOW Level	Guaranteed input logical LOW voltage for all inputs				0.8	Volts	
կլ	Input LOW Current	$V_{CC} = MAX$ , $V_{IN} = 0.40V$			-20	-250	μΑ	
l <sub>IH</sub>	Input HIGH Current	$V_{CC} = MAX, V_{IN} = 2.7V$				25	μΑ	
11	Input HIGH Current	$V_{CC}$ = MAX, $V_{IN}$ = 5.5V			1.0	mA		
1 <sub>SC</sub>	Output Short Circuit Current	$V_{CC} = MAX$ , $V_{OUT} = 0.5V$ (Not	X, V <sub>OUT</sub> = 0.5V (Note 3)				-90	mA
	D	All include CNID V MAY	16L8, 16H8, 16HD8 16L8A, 16H8A, 16H	•	Ċ	110	155	
ICC Power Supply Current		All inputs = GND, V <sub>CC</sub> = MAX	16R8, 16R6, 16R4 16R8A, 16R6A, 16		120	180	mA	
VI	Input Clamp Voltage	V <sub>CC</sub> = MIN, I <sub>IN</sub> = -18mA				-0.9	-1.2	Volts
lozh	Output Leakage Current	V <sub>CC</sub> = MAX, V <sub>IL</sub> = 0.8V	VO = 2.7V			100		
lozL	(Note 4)	$V_{IH} = 2.0V$ $V_{O} = 0.4V$					-100	μΑ
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0V @f = 1MHz (Note 5	)			6		nE
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0V @f = 1MHz (Note	5)			9		pF

Typ

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ .

- 2. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.
- 3. Not more than one output should be tested at a time. Duration of the short circuit should not be more than one second. V<sub>OUT</sub> = 0.5V has been chosen to avoid test problems caused by tester ground degradation.
- 4. I/O pin leakage is the worst case of  $I_{OZX}$  or  $I_{IX}$  (where X = H or L).
- 5. These parameters are not 100% tested, but are periodically sampled.

## SWITCHING CHARACTERISTICS OVER OPERATING RANGE (Unless otherwise noted)

IIIGII SFEED	•	Test	Тур	CC	M'L	MIL			
Parameters	Description	Conditions	(Note 1)	Min	Max	Min	Max	Units	
t <sub>PD</sub>	Input or Feedback to Non-Registered Output 16L8A, 16R6A, 16R4A, 16LD8A, 16H8A, 16HD8A		12		25		30	ns	
tEA	Input to Output Enable 16L8A, 16R6A, 16R4A, 16H8A	1	12		25		30	ns	
tER	Input to Output Disable 16L8A, 16R6A, 16R4A, 16H8A	COM'L	12		25		30	ns	
tpzx	Pin 11 to Output Enable 16R8A, 16R6A, 16R4A	$R_1 = 200$ $R_2 = 390$	8		20		25	ns	
tpxz	Pin 11 to Output Disable 16R8A, 16R6A, 16R4A	112 - 550	8		20		25	ns	
tco	Clock to Output 16R8A, 16R6A, 16R4A		8		15		20	ns	
ts	Input or Feedback Setup Time 16R8A, 16R6A, 16R4A	MIL	10	20		25		ns	
tH	Hold Time 16R8A, 16R6A, 16R4A	$R_1 = 390$ $R_2 = 750$	-10	0		0		ns	
tp	Clock Period	]		35		45		ns	
tw	Clock Width			15		20		ns	
fMAX	Maximum Frequency				28.5		22	MHz	

Notes: 1. Typical limits are at  $V_{CC}=5.0 V$  and  $T_A=25 ^{\circ} C$ .

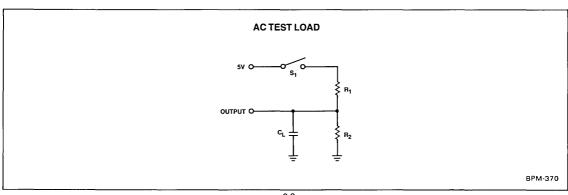
- 2.  $t_{PD}$  is tested with switch  $S_1$  closed and  $C_L = 50pF$ .
- 3. For three-state outputs, output enable times are tested with  $C_L = 50$ pF to the 1.5V level;  $S_1$  is open for high impedance to HIGH tests and closed for high impedance to LOW tests. Output disable times are tested with  $C_L = 5$ pF. HIGH to high impedance tests are made to an output voltage of  $V_{OH} 0.5$ V with  $S_1$  open; LOW to high impedance tests are made to the  $V_{OL} + 0.5$ V level with  $S_1$  closed.

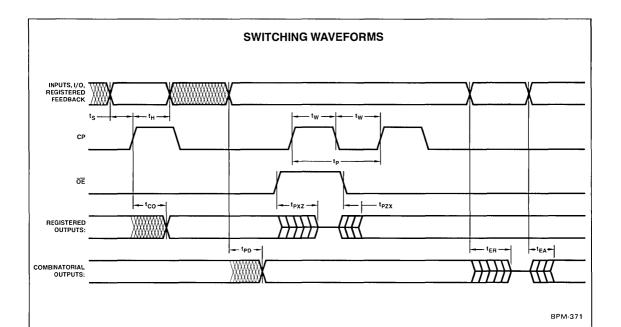
## SWITCHING CHARACTERISTICS OVER OPERATING RANGE (Unless otherwise noted) STANDARD SPEED

		Test	Тур	CO	M'L	N	IIL	
Parameters	Description	Conditions	(Note 1)	Min	Max	Min	Max	Units
t <sub>PD</sub>	Input or Feedback to Non-Registered Output 16L8, 16R6, 16R4, 16LD8, 16H8, 16HD8		17		35		40	ns
tEA	Input to Output Enable 16L8, 16R6, 16R4, 16H8		17		35		40	ns
tER	Input to Output Disable 16L8, 16R6, 16R4, 16H8	COM'L	17		35		40	ns
t <sub>PZX</sub>	Pin 11 to Output Enable 16R8, 16R6, 16R4	$R_1 = 200$ $R_2 = 390$	12		25		25	ns
tpxz	Pin 11 to Output Disable 16R8, 16R6, 16R4	1,2 - 000	12		25		25	ns
tco	Clock to Output 16R8, 16R6, 16R4		12		25		25	ns
ts	Input or Feedback Setup Time 16R8, 16R6, 16R4	MIL	15	30		35		ns
tH	Hold Time 16R8, 16R6, 16R4	$R_1 = 390$ $R_2 = 750$	-10	0		0		ns
tp	Clock Period	1.2 755		55		60		ns
tw	Clock Width			20		25		ns
f <sub>MAX</sub>	Maximum Frequency				18		16.5	MHz

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ .

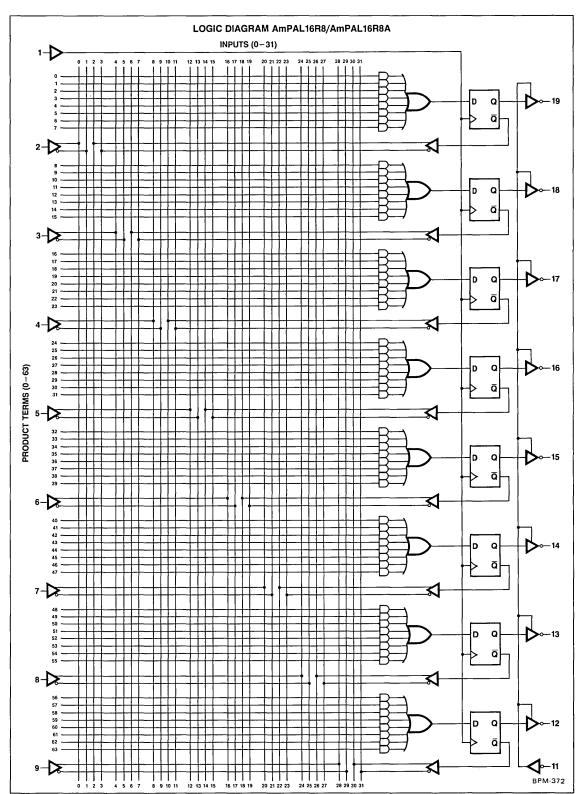
- 2.  $t_{PD}$  is tested with switch  $S_1$  closed and  $C_L = 50 pF$ .
- 3. For three-state outputs, output enable times are tested with  $C_L = 50$ pF to the 1.5V level;  $S_1$  is open for high impedance to HIGH tests and closed for high impedance to LOW tests. Output disable times are tested with  $C_L = 5$ pF. HIGH to high impedance tests are made to an output voltage of  $V_{OH} = 0.5$ V with  $S_1$  open; LOW to high impedance tests are made to the  $V_{OL} + 0.5$ V level with  $S_1$  closed.

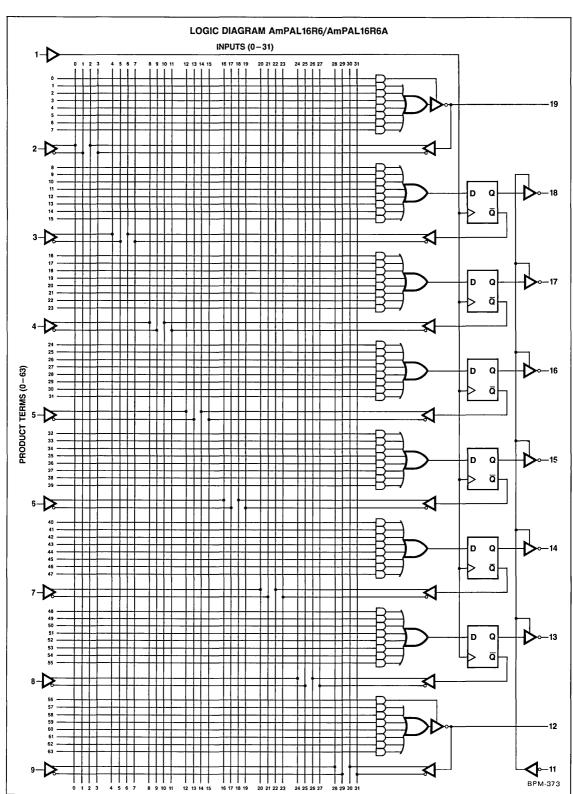


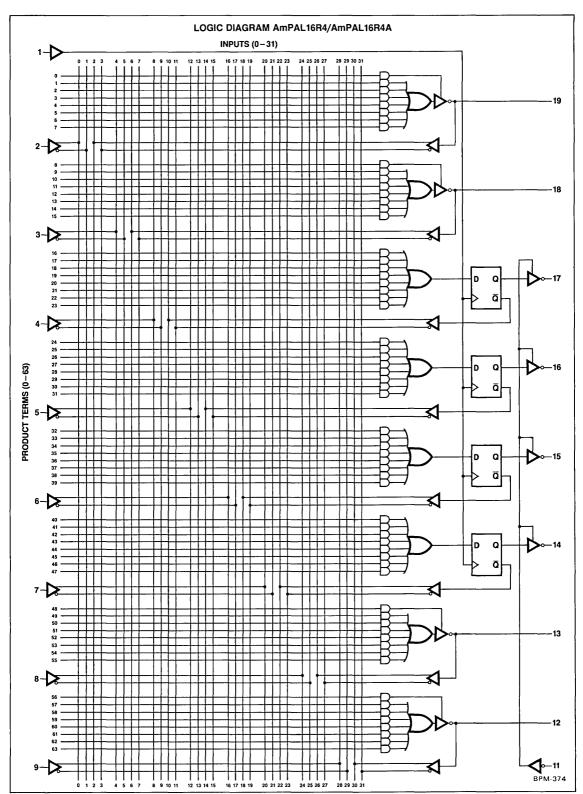


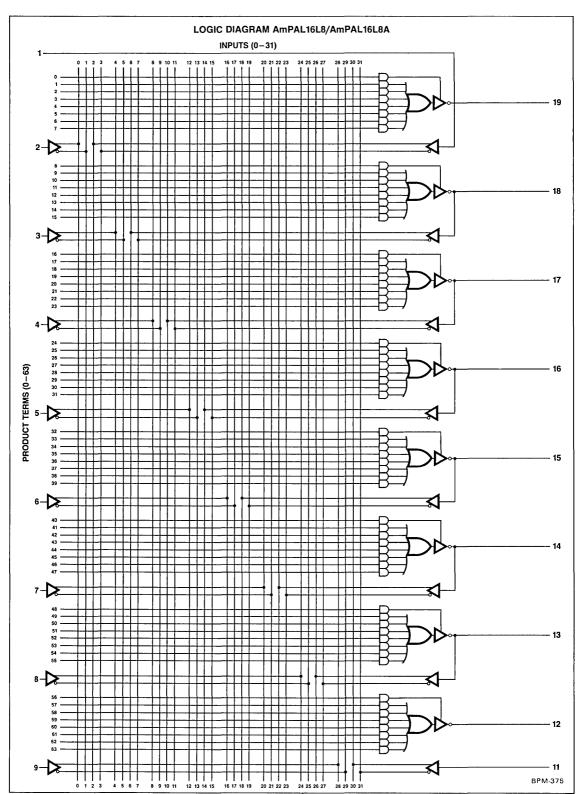
#### **KEY TO TIMING DIAGRAM**

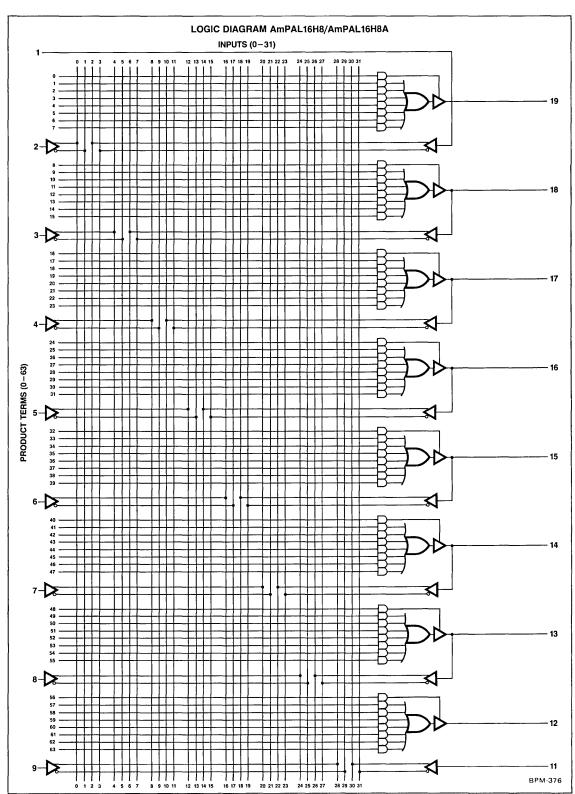
OUTPUTS WAVEFORM INPUTS OUTPUTS WAVEFORM INPUTS DON'T CARE; CHANGING; MUST BE WILL BE ANY CHANGE PERMITTED STATE STEADY STEADY UNKNOWN CENTER DOES NOT LINE IS HIGH IMPEDANCE "OFF" STATE

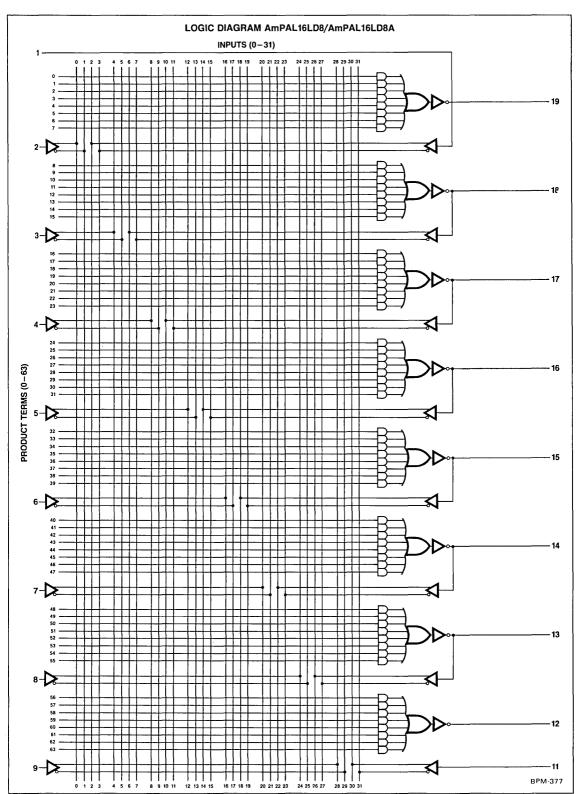


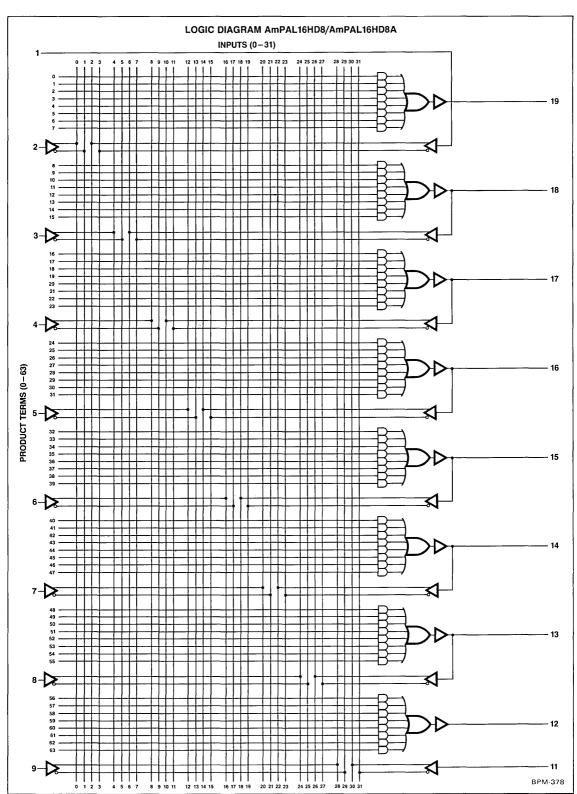












#### **PROGRAMMING**

Each AMD PAL fuse is programmed with a simple sequence of voltages applied to two control pins (1 and 11) and a programming voltage pulse applied to the output under programming. Addressing of the 2048 element fuse array is accomplished with normal TTL levels on eight input pins (five select the input line number and three select the product term number).  $V_{\rm CC}$  is maintained at a normal level throughout the programming and verify cycle — no extra high levels are required.

The necessary sequence levels for programming any fuse is shown in the Programming Waveforms. The address of each fuse in terms of Input Line Number and Product Term Line Number is defined by the Fuse Address Tables 1 and 2. Current, voltage and timing requirements for each pin are specified in the Programming Parameter Table below.

The 16L8, 16R8, 16R6, 16R4, 16H8, 16LD8 and 16HD8 use identical programming conditions and sequences.

After all programming has been completed, the entire array should be reverified at  $V_{CCL}$  and again at  $V_{CCH}$ . Reverification can be accomplished by reading all eight outputs in parallel rather than one at a time. The array fuse verification cycle checks that

the correct array fuses have been blown and can be sensed by the outputs.

AMD PALs have been designed with many internal test features that are used to assure high programming yield and correct logical operation for a correctly programmed part.

An additional fuse is provided on each AMD PAL circuit to prevent unauthorized copying of AMD PAL fuse patterns when design security is desired. Blowing the security fuse blocks entry to the fuse pattern verify mode.

To blow the security fuse:

- 1. Power up part to VCCP
- 2. Raise Pin 5 to V<sub>HH</sub>.
- 3. Pulse Pin 11 from ground to  $V_{OP}$  for a  $50\mu$ sec duration.
- Perform a normal end-of-programming verify cycle at V<sub>CCL</sub> and V<sub>CCH</sub>. All fuse locations should be sensed as blown if the security fuse has been successfully blown.

Note that parts with the security fuse blown may not be returned as programming rejects.

AMD PALs normally have high programming yields (>98%). Programming yield losses are frequently due to poor socket contact, equipment out of calibration or improperly used.

#### PROGRAMMING PARAMETERS $T_{\Delta} = 25^{\circ}C$

Parameters	Des	scription	Min	Тур	Max	Units
V	Control Din Futro High Lovel	Pin 1 @ 10 – 40mA	10	11	12	Volts
V <sub>HH</sub>	Control Pin Extra High Level	Pin 11 @ 10 – 40mA	10	11	12	VOIIS
V <sub>OP</sub>	Program Voltage Pins 12-19@ 1	5-200mA	18	20	22	Volts
V <sub>IHP</sub>	Input High Level During Programn	2.4	5	5.5	Volts	
V <sub>ILP</sub>	Input Low Level During Programm	0.0	0.3	0.5	Volts	
V <sub>CCP</sub>	V <sub>CC</sub> During Programming @ I <sub>CC</sub>	5	5.2	5.5	Volts	
V <sub>CCL</sub>	V <sub>CC</sub> During First Pass Verification	4.1	4.3	4.5	Volts	
V <sub>CCH</sub>	V <sub>CC</sub> During Second Pass Verificat	5.4	5.7	6.0	Volts	
V <sub>Blown</sub>	Successful Blown Fuse	16L8, 16R8, 16R6, 16R4, 16LD8 16L8A, 16R8A, 16R6A, 16R4A, 16LD8A		0.3	0.5	1/-11-
Diomi	Sense Level @ Output	16H8, 16HD8, 16H8A, 16HD8A	2.4	3		Volts
dV <sub>OP</sub> /dt	Rate of Output Voltage Change		20	*****	250	V/µsec
dV <sub>11</sub> /dt	Rate of Fusing Enable Voltage Ch	ange (Pin 11 Rising Edge)	100		1000	V/µsec
	Fusing Time First Attempt		40	50	100	μsec
tр	Subsequent Attempts		4	5	10	msec
t <sub>D</sub>	Delays Between Various Level Ch	Delays Between Various Level Changes			1000	ns
t <sub>V</sub>	Period During which Output is Ser	nsed for V <sub>Blown</sub> Level			500	ns
V <sub>ONP</sub>	Pull-Up Voltage On Outputs Not B	eing Programmed	V <sub>CCP</sub> - 0.3	V <sub>CCP</sub>	V <sub>CCP</sub> + 0.3	Volts
R	Pull-Up Resistor On Outputs Not I	Being Programmed	1.9	2	2.1	KΩ

#### AMD PAL PROGRAMMING EQUIPMENT INFORMATION

Source and Location	Data I/O 10525 Willows Rd., N.E. Redmond, WA 98052	Kontron Electronics, Inc. 630 Price Ave. Redwood City, CA 94063	Stag Microsystems 528-5 Weddel Dr. Sunnyvale, CA 94086	Structured Design, Inc. 1700 Wyatt Dr. #3 Santa Clara, CA 95054	Digilec, Inc. 7335 E. Acoma Dr. Dept-103 Scottsdale, AZ 85260	
Programmer	Model-100, 29,	Model-MPP-80S	Model-PPX	SD1000	ТВА	
Model(s)	19 or 17	or EPP80	Model ZL-30			
AMD PAL Personality	Logicpak 950-1942-001	MOD-33	PPM2200	On Board	-	
Module	000 10 12 001		On Board ZL-30			
Socket	715-1947-003	SA37	Am202S	On Board	-	
Adapter			On Board ZL-30	1		

The machines noted above have been qualified by AMD to insure high programming yields. Check with the factory to determine the current status of vendors noted TBA or other available models.

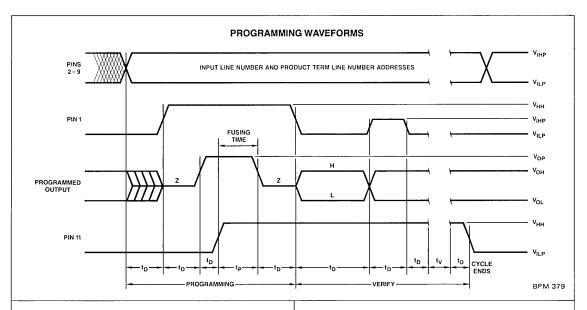


TABLE 1. INPUT ADDRESSING

Input Line		nput l			
Number	9	8	7	6	5
0	L	L	L	L	L
1	L	L	L	L	н
2	L	L	L	н	L
3	L	L	L	Н	н
4	L	L	Н	L	L
5	L	L	н	L	н
6	L	L	Н	Н	L
7	L	L	Н	Н	н
8	L	Н	L	L	L
9	L	Н	L	L	н
10	L	Н	L	н	L
11	L	H	L	н	н
12	L	н	Н	L	L
13	L	Н	Н	L	Н
14	L	Н	Н	н	L
15	L	н	н	Н	Н
16	Н	L	L	L	L
17	Н	L	L	L	H
18	н	L	L	н	L
19	Н	L	L	н	Н
20	н	L	н	L	L
21	Н	L	Н	L	н
22	Н	L	Н	н	L
23	Н	L	Н	Н	Н
24	Н	н	L	L	L
25	Н	н	L	L	н
26	Н	н	L	Н	L
27	Н	н ,	L	Н	н
28	Н	н	Н	L	L
29	н	н	Н	L	Н
30	Н	н	Н	Н	L
31	Н	Н	Н	Н	Н

 $L = V_{ILP}$  $H = V_{IHP}$ 

SIMPLIFIED PROGRAMMING DIAGRAM

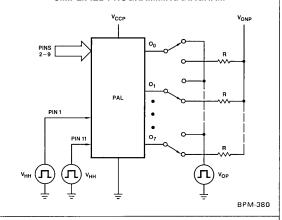


TABLE 2. PRODUCT TERM ADDRESSING

	Pro	duct '		duct T Select dress 3						
0	8	16	24	32	40	48	56	L	L	L
1	9	17	25	33	41	49	57	L	L	н
2	10	18	26	34	42	50	58	L	Н	L
3	11	19	27	35	43	51	59	L	Н	н
4	12	20	28	36	44	52	60	Н	L	L
5	13	21	29	37	45	53	61	Н	L	н
6	14	22	30	38	46	54	62	Н	Н	L
7	15	23	31	39	47	55	63	Н	н	н
Pin	Pin	Pin	Pin	Pin	Pin	Pin	Pin			
19	18	17	16	15	14	13	12			

Programming Access and Verify Pin

 $L = V_{ILP}$ 

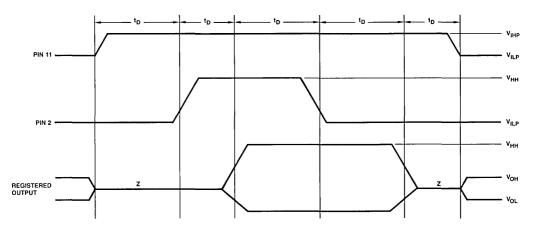
H = VIHP

#### PRELOAD OF REGISTERED OUTPUTS

AMD PAL registered outputs are designed with extra circuitry to allow loading each register asynchronously to either a HIGH or

LOW state. This feature simplifies testing since any initial state for the registers can be set to optimize test sequencing.

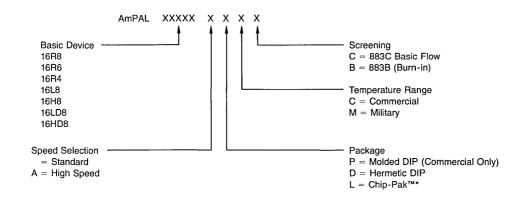
The pin levels and timing necessary to perform the PRELOAD function are detailed below:



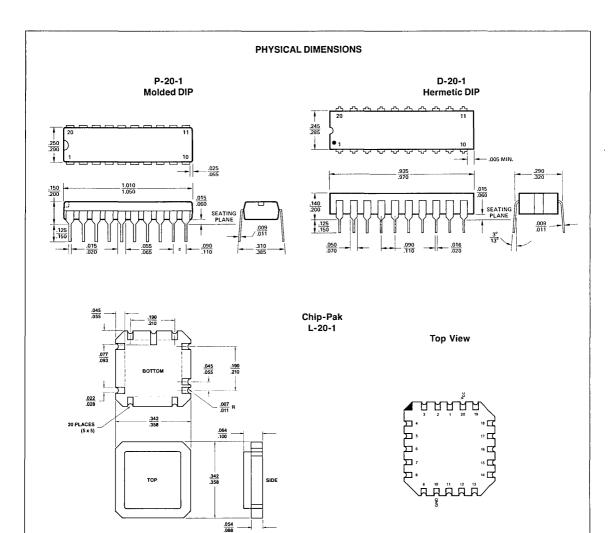
Level forced on registered output pin during PRELOAD cycle	Output state at the output pin after cycle
$V_{HH}$	HIGH
0V to V <sub>CCH</sub> or OPEN	LOW

BPM-381

#### **ORDERING INFORMATION**



\*Chip-Paks are rated at maximum case temperature only.



# AMD Half Power PAL\* Family



#### Half Power 20-Pin IMOX™ Programmable Array Logic Elements **Advanced Micro Devices**

#### DISTINCTIVE CHARACTERISTICS

#### Low Power Dissipation

 1/2 the power of standard PALs (I<sub>CC</sub> = 60mA typ) Reduces power supply requirements and improves system reliability

#### High Performance

Meets all standard power PAL AC specs  $(t_{pd} = 35 \text{ns max}, t_{s} = 30 \text{ns max}, t_{co} = 25 \text{ns max})$ 

#### High Output Drive

- $I_{OL} = 24mA$
- Same as standard power devices
- Drives buses directly (no special driver chips needed)

#### Plug-in Replacement for Standard PALs

Meets ALL standard PAL specs at 1/2 the power

#### • Excellent Programming Yield (typ 98%)

- Platinum Silicide fuses ensure high programming yield, fast programming and unsurpassed reliability

### Improved Testability

Preload feature permits full logical verification

#### Superior Quality

 Full AC and DC testing done at the factory utilizing special designed-in test features

#### GENERAL DESCRIPTION

These low power devices represent a breakthrough in PAL technology by meeting all the specifications of the standard power parts with only half the current requirements. They can directly replace the standard power PALs with no loss of performance, and they, like the standard devices, incorporate the PRELOAD feature essential for full logic verification during testing.

AMD Half Power PALs are high-speed Programmable Array Logic elements which utilize the familiar sum-of-products (AND-OR) logic structure which allows users to program custom logic functions to precisely fit their applications. They are a replacement for Low Power Schottky SSI/MSI logic circuits, reduce the chip count by more than 5 to 1 and greatly simplify prototyping and board layout.

Seven different device types are available, including both registered and combinatorial devices. In addition, the combinatorial devices are offered in both active HIGH (AND-OR) and active LOW (AND-OR-INVERT) versions. The low power dissipation means reduced power supply requirements and improved reliability, while the use of AMD's IMOX process permits extremely high operating speeds.

#### AMD HALF POWER PAL FAMILY TABLE

Part Number	Array Inputs	Logic	OE	Outputs	t <sub>pd</sub> (Max) ns	t <sub>s</sub> (Max) ns	t <sub>co</sub> (Max) ns	I <sub>CC</sub> (Max) mA
AmPAL16R8L	Eight Dedicated Eight Feedback	Eight 8-Wide AND-OR	Dedicated	Registered Inverting	-	30	25	90
Eight Dedicated  AmPAL16R6L Six Feedback		Six 8-Wide AND-OR	Dedicated	Registered Inverting	35	30	25	90
	Two Bidirectional	Two 7-Wide AND-OR-INVERT	Programmable	Bidirectional				
AmPAL16R4L	Eight Dedicated Four Feedback	Four 8-Wide AND-OR	Dedicated	Registered Inverting	35	30	25	90
	Four Bidirectional	Four 7-Wide AND-OR-INVERT	Programmable	Bidirectional				
AmPAL16L8L	Ten Dedicated Six Bidirectional	Eight 7-Wide AND-OR-INVERT	Programmable	Six Bidirectional Two Dedicated	35	_	-	80
AmPAL16H8L	Ten Dedicated Six Bidirectional	Eight 7-Wide AND-OR	Programmable	Six Bidirectional Two Dedicated	35	-	-	80
AmPAL16LD8L	Ten Dedicated Six Bidirectional	Eight 8-Wide AND-OR-INVERT	-	Dedicated	35	-	-	80
AmPAL16HD8L	Ten Dedicated Six Bidirectional	Eight 8-Wide AND-OR	-	Dedicated	35	_	_	80

<sup>\*</sup>PAL is a registered trademark of Monolithic Memories, Inc. IMOX is a trademark of Advanced Micro Devices, Inc.

#### AMD PAL FAMILY CHARACTERISTICS

All members of the AMD PAL family have common electrical characteristics and programming procedures. All parts are produced with a fusible link at each input to the AND gate array, and connections may be selectively removed by applying appropriate voltages to the circuit.

Initially the AND gates are connected, via fuses, to both the true and complement of each input. By selective programming of fuses the AND gates may be "connected" to only the true input (by blowing the complement fuse), to only the complement input (by blowing the true fuse), or to neither type of input (by blowing both fuses) establishing a logical "don't care." When both the true and complement fuses are left intact a logical false results on the output of the AND gate, while all fuses blown results in a logical true state. The outputs of the AND gates are connected to fixed OR gates. The only limitations imposed are the number of inputs to the AND gates (up to 16) and the number of AND gates per OR (up to 8).

All parts are fabricated with AMD's fast programming, highly reliable Platinum-Silicide Fuse technology. Utilizing an easily implemented programming algorithm, these products can be rapidly programmed to any customized pattern. Extra test words are pre-programmed during manufacturing to insure extremely high field programming yields (>98%), and provide extra test paths to achieve excellent parametric correlation.

#### **POWER-UP RESET**

The registered devices in the AMD PAL family have been designed to reset during system power-up. Following power-up, all registers will be initialized to zero, setting all the outputs to a logic 1. This feature provides extra flexibility to the designer and is especially valuable in simplifying state machine initialization.

#### **PRELOAD**

AMD Low Power PALs are designed with unique PRELOAD circuitry that provides an easy method of testing registered

devices for logical functionality. PRELOAD allows any arbitrary state value to be loaded into the PAL's output registers.

A typical functional test sequence would be to verify all possible state transitions for the device being tested. This requires the ability to set the state registers into an arbitrary "present state" value and to set the device inputs to any arbitrary "present input" value. Once this is done, the state machine is clocked into a new state, or "next state." The next state is then checked to validate the transition from the present state. In this way any state transition can be checked.

Without PRELOAD, it is difficult and in some cases impossible to load an arbitrary present state value. This can lead to logic verification sequences that are either incomplete or excessively long. Long test sequences result when the feedback from the state register "interferes" with the inputs, forcing the machine to go through many transitions before it can reach an arbitrary state value. Therefore the test sequence will be mostly state initialization and not actual testing. The test sequence becomes excessively long when a state must be reentered many times to test a wide variety of input combinations.

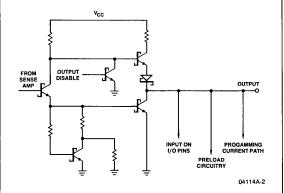
In addition, complete logic verification may become impossible when states that need to be tested can not be entered with normal state transitions. For example, even though necessary, the state entered when machine powers up can not be tested, because it can not be entered from the main sequence. Similarly, "forbidden" or don't care states that are not normaly entered need to be tested to ensure that they return to the main sequence.

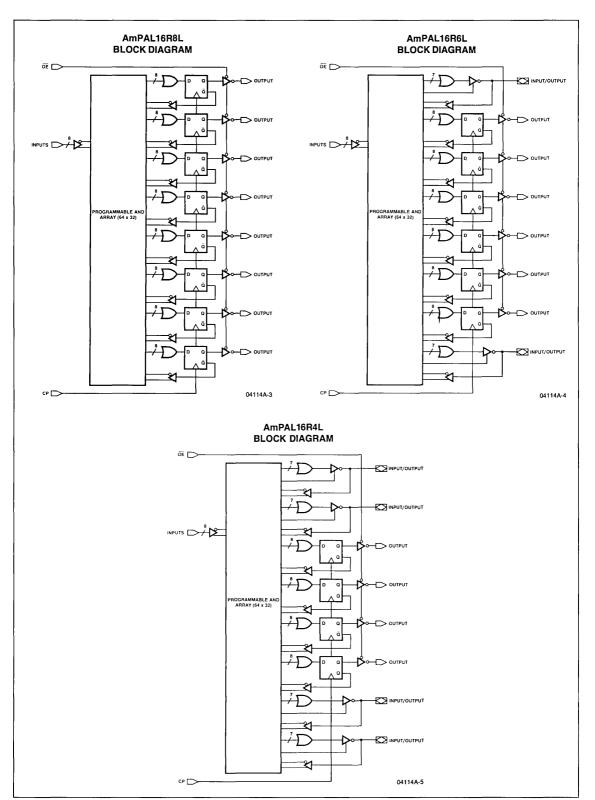
PRELOAD eliminates these problems by providing the capability to go directly to any desired arbitrary state. Thus test sequences may be greatly shortened, and all possible states can be tested, greatly reducing test time and development costs, and guaranteeing proper in-system operation.

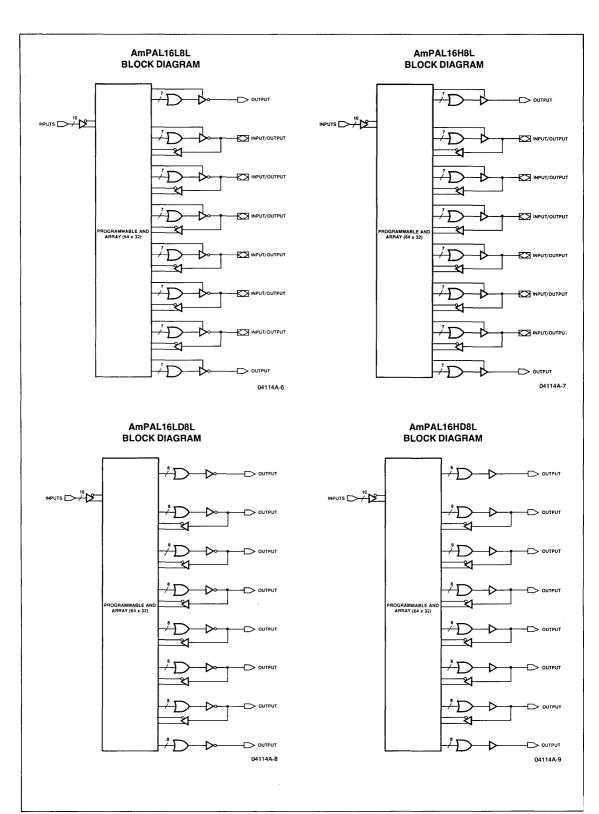
#### INPUT CIRCUITRY

# PROGRAM/VERIFY CIRCUITRY

#### OUTPUT CIRCUITRY







#### MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	−65 to +150°C
Supply Voltage to Ground Potential (Pin 20 to Pin 10) Continuous	-0.5 to +7V
DC Voltage Applied to Outputs (Except During Programming)	-0.5V to +V <sub>CC</sub> max
DC Voltage Applied to Outputs During Programming	21V
Output Current Into Outputs During Programming (Max Duration of 1 sec)	200mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	−30 to +5mA

#### **OPERATING RANGE**

		Commercial		Military		]	
Parameters	Description	Min	Max	Min	Max	Units	
V <sub>CC</sub>	Supply Voltage	4.75	5.25	4.50	5.50	V	
TA	Operating Free Air Temperature	0	75	-55		°C	
T <sub>C</sub>	Operating Case Temperature				125	°C	

#### ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE (Unless Otherwise Noted)

arameters	Description		Test C	onditions		Min	Typ (Note 1)	Max	Units
V		V <sub>CC</sub> = MIN,		I <sub>OH</sub> = -3.2mA	= -3.2mA COM'L		3.5		1/-14-
V <sub>OH</sub> Output HIGH Voltage	$V_{IN} = V_{IH}$ or $V_{IL}$		I <sub>OH</sub> = -2mA	MIL	2.4	3.5		Volts	
V	Output LOW Valtage	V <sub>CC</sub> = MIN,		I <sub>OL</sub> = 24mA	COM'L			0.50	Volts
VOL	Output LOW Voltage	$V_{IN} = V_{IH}$ or $V_{IL}$	_	I <sub>OL</sub> = 12mA	MIL	] _		0.50	VOILS
V <sub>IH</sub> (Note 2)	Input HIGH Level	Guaranteed input logical voltage for all inputs	HIGH			2.0			Volts
V <sub>IL</sub> (Note 2)	Input LOW Level	Guaranteed input logical LOW voltage for all inputs						0.8	Volts
l <sub>IL</sub>	Input LOW Current	$V_{CC} = MAX, V_{IN} = 0.40V$					-20	-250	μΑ
łн .	Input HIGH Current	$V_{CC} = MAX, V_{IN} = 2.7V$						25	μΑ
11	Input HIGH Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 5.5V						1.0	mA
I <sub>SC</sub>	Output Short Circuit Current	$V_{CC} = MAX, V_{OUT} = 0.5$	V (Not	e 3)		-30	-60	-90	mA
Icc	Power Supply Current	All inputs = GND,	16L8I	_, 16H8L, 16HD8 <b>L</b> , 1	6LD8L		55	80	mA
100	топогодругу саполе	V <sub>CC</sub> = MAX	16R8	L, 16R6L, 16R4L			60	90	
VI	Input Clamp Voltage	V <sub>CC</sub> = MIN, I <sub>IN</sub> = -18mA				-0.9	-1.2	Volts	
lozh	Output Leakage Current	$V_{CC} = MAX, V_{II} = 0.8V$ $V_{O} = 2.7V$					100		
lozL	(Note 4)	V <sub>IH</sub> = 2.0V		V <sub>O</sub> = 0.4V				-100	μΑ
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0V @f = 1MHz (Note 5)					6		
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0V @f = 1MH	z (Note	9 5)			9		pF

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ .

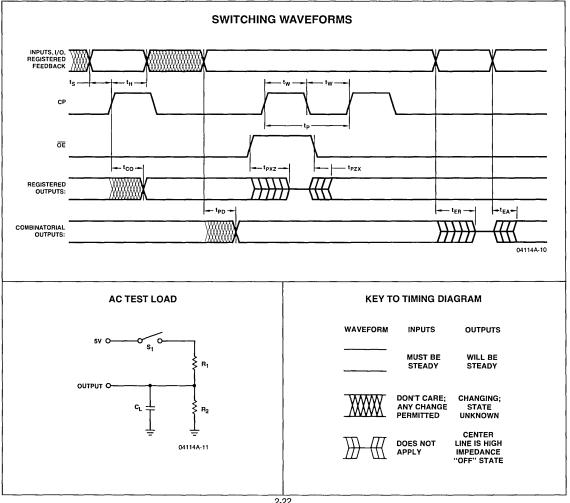
- 2. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.
- 3. Not more than one output should be tested at a time. Duration of the short circuit should not be more than one second. V<sub>OUT</sub> = 0.5V has been chosen to avoid test problems caused by tester ground degradation.
- 4. I/O pin leakage is the worst case of  $I_{OZX}$  or  $I_{IX}$  (where x = H or L).
- 5. These parameters are not 100% tested, but are periodically sampled.

#### SWITCHING CHARACTERISTICS OVER OPERATING RANGE (Unless otherwise noted)

		Test	Typ	COM'L		MIL		
Parameters	Description	Conditions	(Note 1)	Min	Max	Min	Max	Units
t <sub>PD</sub>	Input or Feedback to Non-Registered Output 16L8L, 16R6L, 16R4L, 16LD8L, 16H8L, 16HD8L		-20		35		40	ns
tEA	Input to Output Enable 16L8L, 16R6L, 16R4L, 16H8L	1	-20		35		40	ns
t <sub>ER</sub>	Input to Output Disable 16L8L, 16R6L, 16R4L, 16H8L	COM'L	-20		35		40	ns
t <sub>PZX</sub>	Pin 11 to Output Enable 16R8L, 16R6L, 16R4L	$R_1 = 200$ $R_2 = 390$	-15		25		25	ns
tpxz	Pin 11 to Output Disable 16R8L, 16R6L, 16R4L	112 = 030	-15		25		25	ns
tco	Clock to Output 16R8L, 16R6L, 16R4L	1	-10		25		25	ns
ts	Input or Feedback Setup Time 16R8L, 16R6L, 16R4L	MIL	-20	30		35		ns
tH	Hold Time 16R8L, 16R6L, 16R4L	R <sub>1</sub> = 390	-10	0		0		ns
tp	Clock Period (t <sub>S</sub> + t <sub>CO</sub> )	$R_2 = 750$		55		60		ns
tw	Clock Width	1		25		25		ns
fMAX	Maximum Frequency	}	1		18		16.5	MHz

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ . 2.  $t_{PD}$  is tested with switch  $S_1$  closed and  $C_L = 50pF$ .

- 3. For three-state outputs, output enable times are tested with  $C_L = 50 pF$  to the 1.5V level;  $S_1$  is open for high impedance to HIGH tests and closed for high impedance to LOW tests. Output disable times are tested with  $C_L = 5 pF$ . HIGH to high impedance tests are made to an output voltage of  $V_{OH}^-$  0.5V with  $S_1$  open; low-to-high impedance tests are made to the  $V_{OL}^-$  0.5V level with  $S_1^-$  closed.

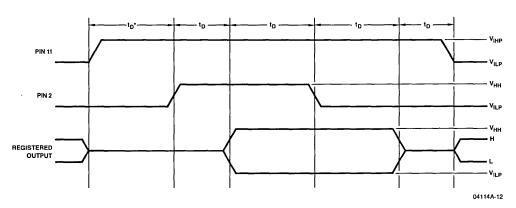


#### PRELOAD OF REGISTERED OUTPUTS

AMD PAL registered outputs are designed with extra circuitry to allow loading each register asynchronously to either a HIGH

or LOW state. This feature simplifies testing since any initial state for the registers can be set to optimize test sequencing.

The pin levels and timing necessary to perform the PRELOAD function are detailed below:



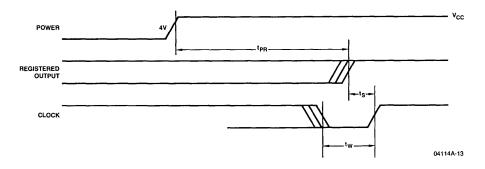
\*t<sub>D</sub> = 200ns typically. See Programming Parameters.

Level forced on registered output pin during PRELOAD cycle	Output state at the output pin after cycle
V <sub>HH</sub>	HIGH
0V to V <sub>CCH</sub> or OPEN	LOW

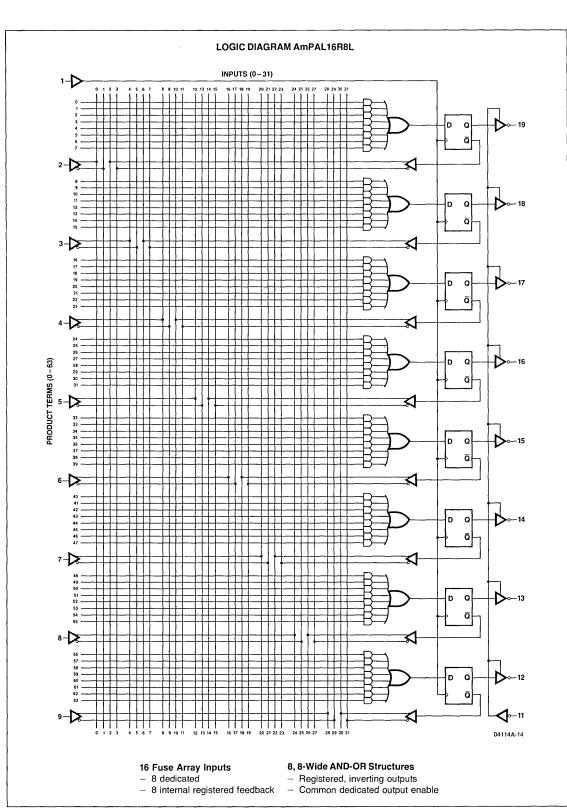
#### POWER-UP RESET

The registered devices in the AMD PAL family have been designed to reset during system power-up. Due to the asynchronous operation of the power-up reset and the wide range of ways  $V_{CC}$  can rise to its steady state, three conditions are required to insure a valid power-up reset. These conditions are:

- 1. The  $V_{CC}$  rise must be monotonic.
- Following reset, the clock input must not be driven from low to high until all applicable input and feedback setup times are met.



Parameters	Description	Min	Тур	Max	Units		
t <sub>pr</sub>	Power-Up Reset Time		600	1000	ns		
t <sub>s</sub>	Input or Feedback Setup Time	See Switching Characteristics					
t <sub>w</sub>	Clock Width						



# LOGIC DIAGRAM AmPAL16R6L INPUTS (0-31) ≴1 Q Q Q PRODUCT TERMS (0-63) D ā Q Q Q ā Q ā 12 04114A-15 6, 8-Wide AND-OR Structures 16 Array Inputs

#### 2-25

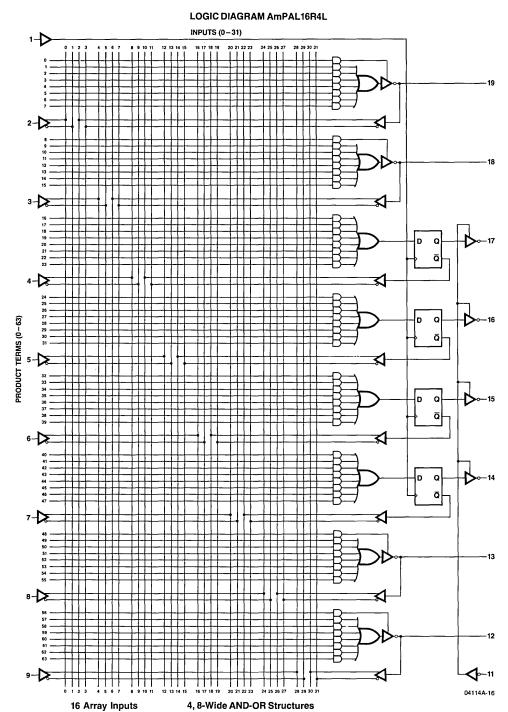
2, 7-Wide AND-OR-INVERT Structures

- Registered, inverting outputs with common dedicated output

- Combinatorial outputs with programmable output enables

- 8 dedicated

6 registered feedback2 bidirectional I/O

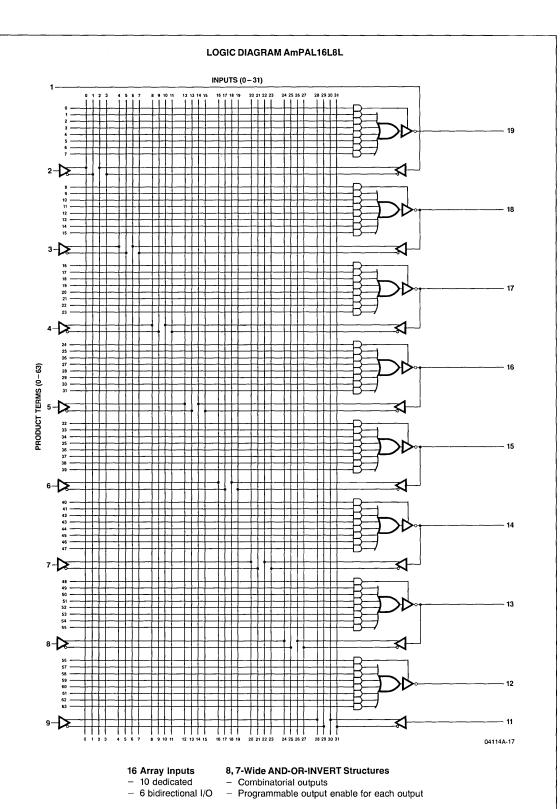


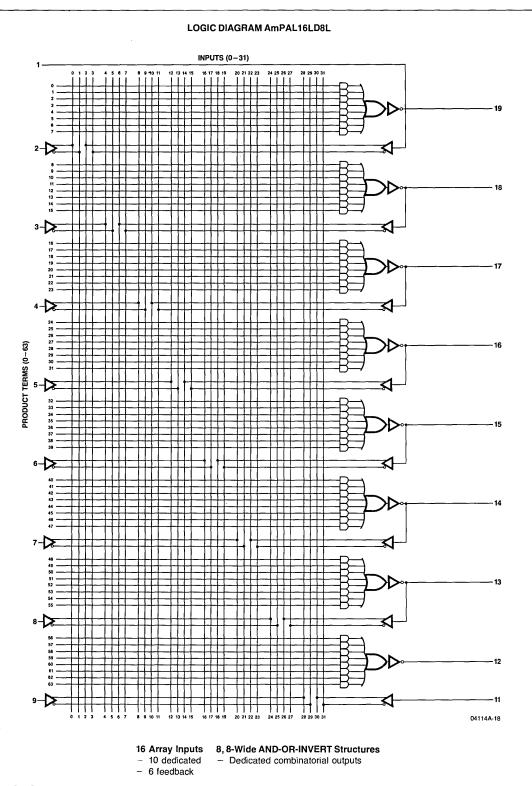
- 8 dedicated
- 4 registered feedback
- 4 bidirectional I/O

Registered, inverting outputs with common, dedicated output enable

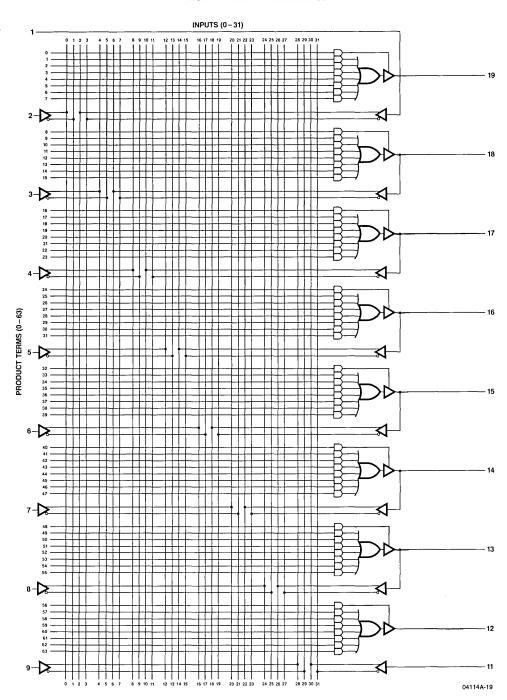
#### 4, 7-Wide AND-OR-INVERT Structures

- Combinatorial outputs with programmable output enables





#### LOGIC DIAGRAM AmPAL16H8L



#### 16 Array Inputs

#### 8, 7-Wide AND-OR Structures

- 10 dedicated
- Combinatorial outputs
- 6 bidirectional I/O Programmable output enable for each output

#### LOGIC DIAGRAM AmPAL16HD8L INPUTS (0-31) 12 13 14 15 0 1 2 3 8 9 10 11 16 17 18 19 20 21 22 23 24 25 26 27 28 29 30 31 ШĨ 19 2-10 11 18 12 -19 -20 -21 -17 22 25 -26 -27 -PRODUCT TERMS (0-63) 16 28 29 30 31 $\mathbb{H}$ $\Box$ 32 33 34 -35 -H 15 $\blacksquare$ 38 39 6-2 Ш ПΠ П -42 -43 -44 -ПТ 45 51 -52 -13 53 54 55 56 57 12 H - 11 8 9 10 11 12 13 14 15 $\overline{H}$ $\Pi\Pi$ 24 25 26 27 20 21 22 23 04114A-20 16 Array Inputs 8, 8-Wide AND-OR Structures

- Dedicated combinatorial outputs

10 dedicated

- 6 feedback

#### PROGRAMMING

Each AMD PAL fuse is programmed with a simple sequence of voltages applied to two control pins (1 and 11) and a programming voltage pulse applied to the selected output, one output at a time. Addressing of the 2048 element fuse array is accomplished with normal TTL levels on eight input pins (five select the input line number and three select the product term number). VCC is maintained at a normal level throughout the programming and verify cycle — no extra high levels are required.

The necessary sequence of levels for programming any fuse is shown in the Programming Waveforms. The address of each each fuse in terms of Input Line Number and Product Term Line Number is defined by the Fuse Address Tables 1 and 2. Current, voltage and timing requirements for each pin are specified in the Programming Parameter Table below.

The 16L8L, 16R8L, 16R6L, 16R4L, 16H8L, 16LD8L and 16HD8L use identical programming conditions and sequences.

After all programming has been completed, the entire array should be reverified at  $V_{CCL}$  and again at  $V_{CCH}$ . Reverification can be accomplished by reading all eight outputs in parallel rather than one at a time. The array fuse verification cycle

checks that the correct array fuses have been blown and can be sensed by the outputs.

AMD PALs have been designed with many internal test features that are used to assure high programming yield and correct logical operation for a correctly programmed part.

An additional fuse is provided on each AMD PAL circuit to prevent unauthorized copying of AMD PAL fuse patterns when design security is desired. Blowing the security fuse blocks entry to the fuse pattern verify mode.

To blow the security fuse:

- Power up part to V<sub>CCP</sub>
- 2. Raise Pin 5 to VHH.
- 3. Pulse Pin 11 from ground to  $V_{OP}$  for a  $50\mu sec$  duration.
- Perform a normal end-of-programming verify cycle at V<sub>CCL</sub> and V<sub>CCH</sub>. All fuse locations should be sensed as blown if the security fuse has been successfully blown.

Note that parts with the security fuse blown may not be returned as programming rejects.

AMD PALs normally have high programming yields (>98%). Programming yield losses are frequently due to poor socket contact, equipment out of calibration or improperly used.

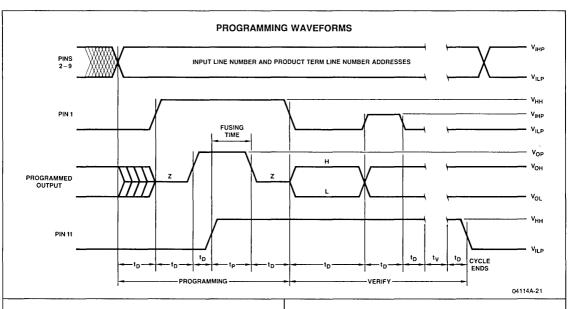
#### PROGRAMMING PARAMETERS (T<sub>A</sub> = 25°C)

Parameters		Description	Min	Тур	Max	Units
	0	Pin 1 @ 10-40mA	10	11	12	Volts
$V_{HH}$	Control Pin Extra High Level	Pin 11 @ 10-40mA	10	11	12	VOITS
V <sub>OP</sub>	Program Voltage Pins 12-19	Program Voltage Pins 12-19 @ 15-200mA			22	Volts
V <sub>IHP</sub>	Input High Level During Prog	ramming and Verify	2.4	5	5.5	Volts
V <sub>ILP</sub>	Input Low Level During Progr	ramming and Verify	0.0	0.3	0.5	Volts
V <sub>CCP</sub>	V <sub>CC</sub> During Programming @	5	5.2	5.5	Volts	
V <sub>CCL</sub>	V <sub>CC</sub> During First Pass Verific	4.1	4.3	4.5	Volts	
V <sub>CCH</sub>	V <sub>CC</sub> During Second Pass Ve	5.4	5.7	6.0	Volts	
V <sub>Blown</sub>	Successful Blown Fuse	16L8L, 16R8L, 16R6L, 16R4L, 16LD8L		0.3	0.5	Volts
DIOWIT	Sense Level @ Output	16H8L, 16HD8L	2.4	3		
dV <sub>OP</sub> /dt	Rate of Output Voltage Chan	ge	20		250	V/μsec
dV <sub>11</sub> /dt	Rate of Fusing Enable Voltage	ge Change (Pin 11 Rising Edge)	100		1000	V/μsec
	Fusing Time First Attempt		40	50	100	μsec
tp	Subsequent Attempts		4	5	10	msec
t <sub>D</sub>	Delays Between Various Lev	Delays Between Various Level Changes		200	1000	ns
t <sub>V</sub>	Period During which Output is Sensed for V <sub>Blown</sub> Level				500	ns
V <sub>ONP</sub>	Pull-Up Voltage On Outputs Not Being Programmed		V <sub>CCP</sub> - 0.3	VCCP	V <sub>CCP</sub> + 0.3	Volts
R	Pull-Up Resistor On Outputs	1.9	2	2.1	ΚΩ	

#### AMD PAL PROGRAMMING EQUIPMENT INFORMATION

Source and Location	Data I/O 10525 Willows Rd., N.E. Redmond, WA 98052	Kontron Electronics, Inc. 630 Price Ave. Redwood City, CA 94063	Stag Microsystems 528-5 Weddel Dr. Sunnyvale, CA 94086	Structured Design, Inc. 1700 Wyatt Dr. #3 Santa Clara, CA 95054	Digilec, Inc. 7335 E. Acoma Dr. Dept-103 Scottsdale, AZ 85260	
Programmer Mode	Model-100, 29, 19 or 17	Model-MPP-80S	Model-PPX	SD1000	ТВА	
Model(s)		or EPP80	Model ZL-30			
AMD PAL Personality			PPM2200	On Board	-	
Module	000 10 12 00 7		On Board ZL-30			
Socket	715-1947-003	SA37	Am202S	On Board	_	
Adapter			On Board ZL-30	7	1	

The machines noted above have been qualified by AMD to insure high programming yields. Check with the factory to determine the current status of vendors noted TBA or other available models.

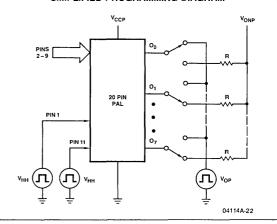


**TABLE 1. INPUT ADDRESSING** 

Input Line			ine N s Pin		
Number	9	8	7	6	5
0	L	L	L	L	L
1	L	L	L	L	н
2	L	L	L	Н	L
3	L	L	L	Н	н
4	L	L	Н	L	L
5	L	L	н	L	н
6	L	L	Н	Н	L
7	L	L	Н	Н	н
8	L	н	L	L	L
9	L.	н	L	L	н
10	L	Н	L	Н	L
11	L	Н	L	Н	н
12	L	Н	Н	L	L
13	L	Н	Н	L	н
14	L	Н	Н	Н	L
15	L	Н	Н	Н	н
16	н	L	L	L	L
17	Н	L	L	L	Н
18	Н	L	L	Н	L
19	Н	L	L	Н	н
20	Н	L	Н	L	L
21	Н	L	Н	L	н
22	Н	L	Н	Н	L
23	Н	L	Н	Н	Н
24	Н	Н	L	L	L
25	Н	Н	L	L	Н
26	Н	Н	L	Н	L
27	Н	Н	L	Н	Н
28	Н	Н	Н	L	L
29	Н	Н	Н.	L	н
30	Н	Н	н	Н	L
31	Н	Н	Н	Н	Н

 $\begin{array}{l} L = V_{ILP} \\ H = V_{IHP} \end{array}$ 

SIMPLIFIED PROGRAMMING DIAGRAM

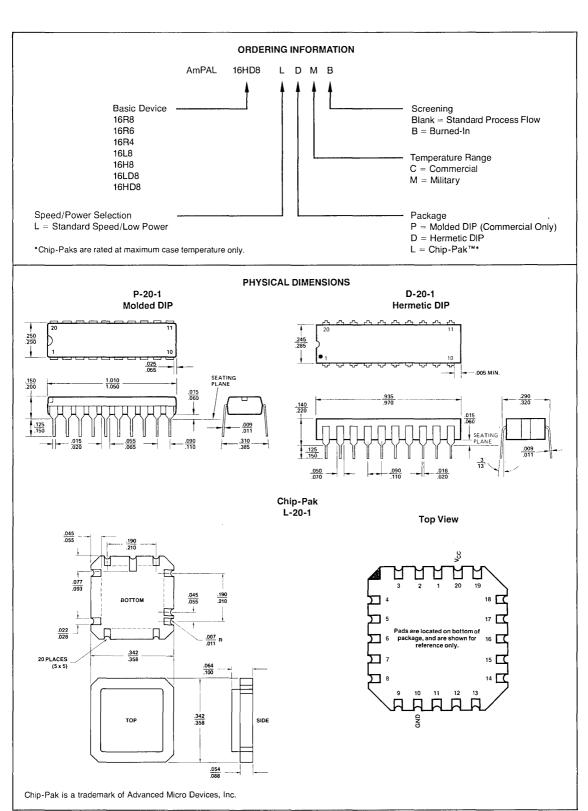


**TABLE 2. PRODUCT TERM ADDRESSING** 

Product Term Line Number								duct To Select dress		
0	8	16	24	32	40	48	56	L	L	L
1	9	17	25	33	41	49	57	L	L	Н
2	10	18	26	34	42	50	58	L	Н	L
3	11	19	27	35	43	51	59	L	Н	Н
4	12	20	28	36	44	52	60	н	L	L
5	13	21	29	37	45	53	61	Н	L	Н
6	14	22	30	38	46	54	62	H '	Н	L
7	15	23	31	39	47	55	63	Н	Н	Н
Pin	Pin	Pin	Pin	Pin	Pin	Pin	Pin			
19	18	17	16	15	14	13	12			

Programming Access and Verify Pin

L = V<sub>ILP</sub> H = V<sub>IHP</sub>



## 24-Pin IMOX™ Programmable Array Logic Advanced Micro Devices

#### DISTINCTIVE CHARACTERISTICS

- · Second generation PAL architecture
- Increased logic power up to 22 inputs and 10 outputs
- Increased product terms average 12 per output
- Variable product term distribution improves ease of use
- Each output USER PROGRAMMABLE for registered or combinatorial operation
- Individually USER PROGRAMMABLE output polarity
- Extra terms provide logical synchronous PRESET and asynchronous RESET capability
- Comes in standard and high speed versions 15ns typical propagation delay
- TTL level PRELOAD for improved testability
- Packaged in SLIMDIP (300 mil) 24 pin package
- Platinum Silicide fuses ensure high programming yield, fast programming and unsurpassed reliability
- Full AC and DC testing done at the factory utilizing special designed-in test features

#### GENERAL DESCRIPTION

The AmPAL22V10 is a second generation Programmable Array Logic device. It utilizes the familiar sum-of-products (AND-OR) logic structure, allowing users to program custom logic functions. The AmPAL22V10 is an extension of the PAL concept. First generation devices were largely limited to TTL replacement applications. The AmPAL22V10 permits the development of custom LSI functions of 300 to 500 equivalent gate complexity.

The AmPAL22V10 contains up to 22 inputs and 10 outputs. It incorporates the unique capability of defining and programming the architecture of each output on an individual basis. Each output is user programmable for either registered or combinatorial operation. This allows the designer to optimize the device design, by having only as many registers as needed. In addition each output has user programmable output polarity, further simplifying design and contributing to precise applications requirements.

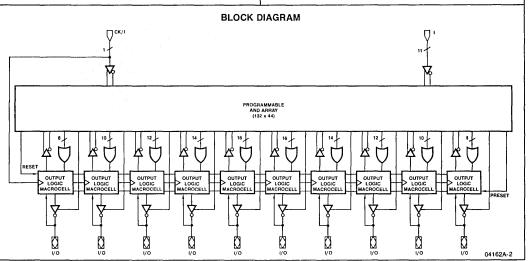
Increased logic power has been built into the AmPAL22V10 by increasing the number of product terms from 8 per output to an average of 12 per output. Further innovation can be seen in the introduction of variable product term distribution. This technique allocates from 8 to 16 logical product terms to each output (please refer to block diagram for distribution details.) This variable allocation of terms allows far more complex functions to be implemented than in previous devices.

System operation has been enhanced by the addition of a synchronous PRESET and an asynchronous RESET product term. These terms are common to all outputs.

The AmPAL22V10 also incorporates power-up reset and the unique capability to PRELOAD the output registers to any desired state during testing. PRELOAD is essential to permit full logical verification during test.

#### CONNECTION DIAGRAM - Top View ск/і 24 🗀 Vcc 10 23 1/0 1 [ 22 | 1/0 □ 1/0 10 \_\_\_ i/o AmPAL22V10 **\_\_\_\_** 1/0 IC 18 🗀 1/0 17 1/0 1 [ 16 ] 1/0 1 E 1.1/0 10 15 1 7/0 11

GND [



IMOX is a trademark of Advanced Micro Devices, Inc. \*PAL is a registered trademark of Monolithic Memories, Inc.

04162A-1

04162A-PLP

This document contains information on a product under development at Advanced Micro Devices, Inc. The information is intended to help you to evaluate this product. AMD reserves the right to change or discontinue work on this proposed product without notice.

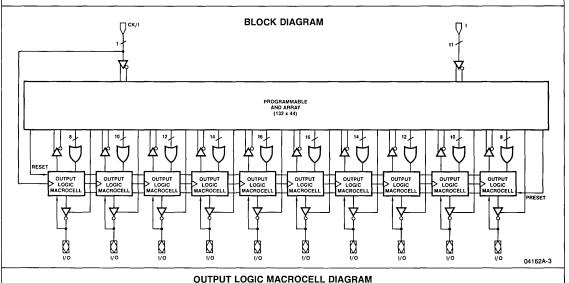
#### **FUNCTIONAL DESCRIPTION**

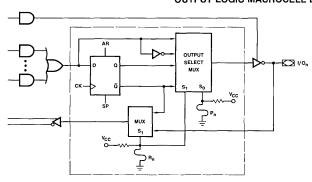
The AmPAL22V10 is a second generation Programmable Array Logic device. It contains a programmable fuse array organized in the familiar sum-of-products (AND-OR) structure.

The block diagram below shows the basic architecture of the AmPAL22V10. There are up to 22 inputs and 10 outputs available. The inputs are connected to a programmable AND array which contains 120 logical product terms. Initially the AND gates are connected, via fuses, to both the true and complement of every input. By selective programming of fuses the AND gates may be "connected" to only the true input (by blowing the complement fuse), to only the complement input (by blowing the true fuse), or to neither type of input (by blowing both fuses) establishing a logical "don't care". When both the true and complement fuses are left intact a logical false results on the output of the AND gate. An AND gate with all fuses blown will assume the logical true state. The outputs of the AND gates are connected to fixed OR gates. There are an average of 12 product terms per OR gate (output) and as the block diagram shows, variable product term distribution has been implemented. This technique allocates different quantities of logical product terms to different outputs, allowing more complex logical functions to be performed than were previously possible. Up to 16 logical terms can be evaluated in one output in a single clock cycle (no feedback necessary).

A dramatic innovation in logic design is the implementation on the AmPAL22V10 of variable output architecture. This allows the user to program on an output by output basis the function of the outputs. As shown in the output logic Macrocell diagram below, each output cell contains two additional fuses (Rn and Pn).  $R_n$  controls whether the output will be registered or combinatorial. Pn controls the output polarity (active HIGH or active LOW). Depending on the states of these 2 fuses, an individual output will operate in one of four modes (see logic diagrams below): Registered active LOW; Registered active HIGH; Combinatorial active LOW; Combinatorial active HIGH. (Note that the feedback path also changes with the output mode.) This innovation gives the designer more flexibility and enables him to optimize the device for precise application requirements. It also allows for better device utilization - you only program as many registers as are needed.

To improve in-system functionality the AmPAL22V10 has additional PRESET and RESET product terms. These terms are connected to all registered outputs. When the synchronous PRESET product term is asserted (HIGH) the output registers will be loaded with a HIGH on the next LOW-to-HIGH clock transition. When the asynchronous RESET product term is asserted (HIGH) the output registers will be immediately loaded with a LOW (independent of the clock). These functions are particularly useful for applications such as system power-on and reset.





S <sub>1</sub>	S <sub>0</sub>	Output Configuration
0	0	Registered/Active Low
0	1	Registered/Active High
1	0	Combinatorial/Active Low
1	1	Combinatorial/Active High

- 0 = Unblown Fuse
- 1 = Blown Fuse

04162A-4

In order to simplify testing problems, the AmPAL22V10 is designed with unique PRELOAD circuitry that provides an easy method of testing registered devices for logical functionality. PRELOAD allows any arbitrary state value to be loaded into the PAL's output registers.

A typical functional test sequence would be to verify all possible state transitions for the device being tested. To verify these transitions requires the ability to set the state registers into an arbitrary "present state" value and to set the device inputs to any arbitrary "present input" value. Once this is done, the state machine is then clocked into a new state, or "next state". The next state is then checked to validate the transition from the present state. In this way any state transition can be checked.

Without PRELOAD, it is difficult and in some cases impossible to load an arbitrary present state value. This can lead to logic verification sequences that are either incomplete or excessively long. Long test sequences result when the feedback from the state register "interferes" with the inputs, forcing the state machine to go through many state transitions before it can reach an arbitrary state value. Therefore the test sequence will be mostly state initialization and not actual testing. The test sequence becomes excessively long when a state must be reentered many times to test a wide variety of input combinations.

In addition, complete logic verification may become impossible when states that need to be tested can not be entered with normal state transitions. For example, the state which the machine powers up into cannot be tested because it cannot be entered from

the main sequence. Similarly, "forbidden" or don't care states that are not normally entered need to be tested to ensure that they return to the main sequence.

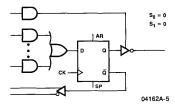
PRELOAD eliminates these problems by providing the capability to go directly to any desired arbitrary state. Thus test sequences may be greatly shortened, and all possible states can be tested, greatly reducing test time and development costs, and guaranteeing proper in-system operation.

The AmPAL22V10 is manufactured using Advanced Micro Devices' IMOX™ oxide isolation process. This advanced process permits an increase in density and a decrease in internal capacitance resulting in the fastest possible programmable logic devices.

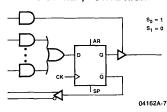
The AmPAL22V10 is fabricated with AMD's fast programming, highly reliable Platinum-Silicide Fuse technology. Utilizing an easily implemented programming algorithm, these products can be rapidly programmed to any customized pattern. Extra test words are preprogrammed during manufacturing to ensure extremely high field programming yields (>98%), and provide extra test paths to achieve excellent parametric correlation.

Platinum-Silicide was selected as the fuse link material to achieve a well controlled melt rate resulting in large nonconductive gaps that ensure very stable, long term reliability. Extensive operating testing has proven that this low-field, largegap technology offers the best reliability for fusible link programmable logic.

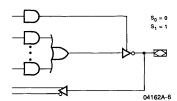
#### REGISTERED/ACTIVE LOW



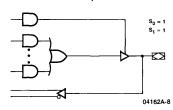
#### REGISTERED/ACTIVE HIGH



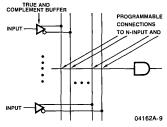
#### COMBINATORIAL/ACTIVE LOW



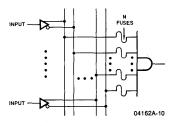
#### COMBINATORIAL/ACTIVE HIGH



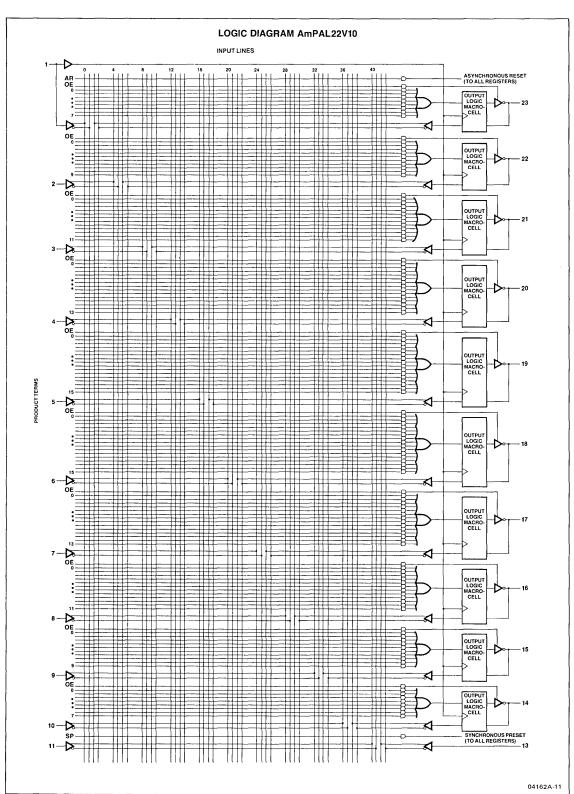
#### **KEY TO LOGIC DIAGRAM**



Programmable AND Array
PAL Logic Diagram Representation



Programmable AND Array Logic Equivalent



#### MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	−65 to +150°C
Supply Voltage to Ground Potential (Pin 24 to Pin 12) Continuous	−0.5 to +7V
DC Voltage Applied to Outputs (Except During Programming)	-0.5V to +V <sub>CC</sub> Max
DC Voltage Applied to Outputs During Programming	21V
Output Current Into Outputs During Programming (Max Duration of 1 sec)	200mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	−30 to +5mA
Ambient Temperature with Power Applied	+125°C

#### **OPERATING RANGE**

		Comn	nercial	Mili		
Parameters	Description	Min	Max	Min	Max	Units
V <sub>CC</sub>	Supply Voltage	4.75	5.25	4.50	5.50	٧
TA	Operating Free Air Temperature	0	75	-55		°C
тс	Operating Case Temperature				125	°C

## **ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE** (Unless Otherwise Noted) **Advanced Information**

Parameters	Description	Те	Test Conditions			Typ (Note 1)	Max	Units
V	Output HIGH Voltage	V <sub>CC</sub> = MIN,	$I_{OH} = -3.2 \text{mA}$	COM'L	2.4	3.5		Volts
V <sub>OH</sub>	Output High voltage	$V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -2mA	MIL	2.4	3.5		VOILS
	Outrat LOW/ Vallage	V <sub>CC</sub> = MIN,	I <sub>OL</sub> = 24mA	COM'L			0.50	Volts
V <sub>OL</sub>	Output LOW Voltage	VIN = VIH or VIL	I <sub>OL</sub> = 12mA	MIL			0.50	VOILS
V <sub>IH</sub> (Note 2)	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs						Volts
V <sub>IL</sub> (Note 2)	Input LOW Level	Guaranteed input logical LOW voltage for all inputs					0.8	Volts
1 <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0.40V				-20	-250	μΑ
l <sub>IH</sub>	Input HIGH Current	$V_{CC} = MAX, V_{IN} = 2.7V$	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 2.7V				25	μΑ
11	Input HIGH Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 5.5V					1.0	mA
Isc	Output Short Circuit Current	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 0.5V	(Note 3)		-30	-60	-90	mA
l <sub>CC</sub>	Power Supply Current	All Inputs = GND, V <sub>CC</sub> = N	1AX		T	120	180	mA
VI	Input Clamp Voltage	V <sub>CC</sub> = MIN, I <sub>IN</sub> = -18mA				-0.9	-1.2	Volts
lozh	Output Leakage Current	$V_{CC} = MAX, V_{IL} = 0.8V$	$V_0 = 2.7V$				100	
lozL	(Note 4)	V <sub>IH</sub> = 2.0V	$V_O = 0.4V$	$V_O = 0.4V$			-100	μΑ
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0V @f = 1MHz (Note 5)				6		pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0V @f = 1MHz	Note 5)			9		PΓ

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ .

- 2. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.
- Not more than one output should be tested at a time. Duration of the short circuit should not be more than one second. V<sub>OUT</sub> = 0.5V has been chosen to avoid test problems caused by tester ground degradation.
- 4. I/O pin leakage is the worst case of IOZX or IIX (where X = H or L).
- 5. These parameters are not 100% tested, but are periodically sampled.

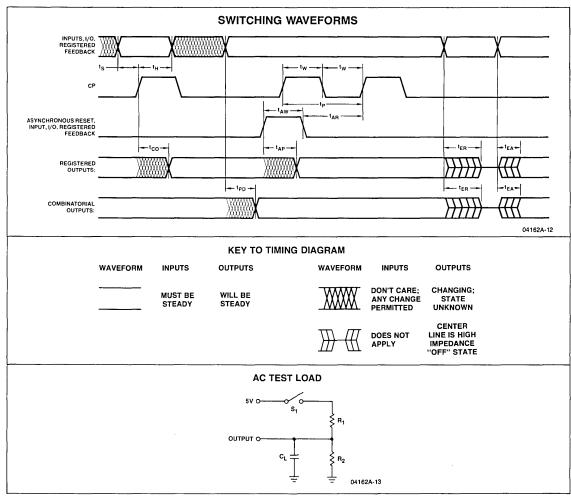
#### SWITCHING CHARACTERISTICS OVER OPERATING RANGE (Unless otherwise noted)

Advanced Information

					COM'L MIL							
		Test	Тур	"A"		"Std"		"A"		"Std"		
Parameters	Description	Conditions	(Note 1)	Min	Max	Min	Max	Min	Max	Min	Max	Units
t <sub>PD</sub>	Input or Feedback to Non-Registered Output		18									ns
tEA	Input to Output Enable	COM'L	18									ns
tER	Input to Output Disable	$R_1 = 200$ $R_2 = 390$	18									ns
tco	Clock to Output	n <sub>2</sub> = 390	10									ns
ts	Input or Feedback Setup Time	1	18									ns
tH	Hold Time	MIL										ns
tp	Clock Period	R <sub>1</sub> = 390										ns
t <sub>W</sub>	Clock Width	R <sub>2</sub> = 750										ns
f <sub>MAX</sub>	Maximum Frequency											MHz

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ . 2.  $t_{PD}$  is tested with switch  $S_1$  closed and  $C_L = 50 pF$ .

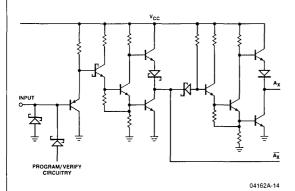
- 3. For three-state outputs, output enable times are tested with  $C_L = 50pF$  to the 1.5V level;  $S_1$  is open for high impedance to HIGH tests and closed for high impedance to LOW tests. Output disable times are tested with C<sub>L</sub> = 5pF. HIGH to high impedance tests are made to an output voltage of  $V_{OH} = 0.5V$  with  $S_1$  open; LOW to high impedance tests are made to the  $V_{OL} = 0.5V$  level with  $S_1$  closed.

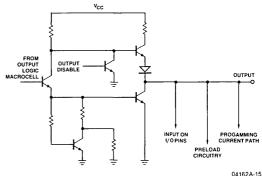


#### INPUT AND OUTPUT CIRCUITRY

#### INPUT CIRCUITRY

#### **OUTPUT CIRCUITRY**



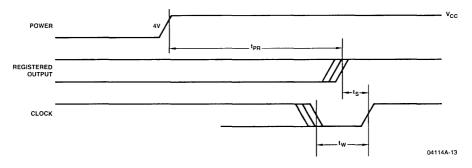


#### **POWER-UP RESET**

The registered devices in the AMD PAL family have been designed with the capability to reset during system power-up. Following power-up, all registers will be zero, setting the outputs to all ones. This feature provides extra flexibility to the designer and is especially valuable in simplifying state machine initialization. A timing diagram and parameter table are shown below. Due to the asynchronous operation of the power-up reset and the wide range of ways V<sub>CC</sub> can rise to its steady state, two conditions are required to insure a valid power-up reset. These conditions are:

- 1. The V<sub>CC</sub> rise must be monotonic.
- Following reset, the clock input must not be driven from low to high until all applicable input and feedback setup times are met.

Following power-up, all registers are set to zero, setting all outputs to one. This provides extra flexibility to the designer and is especially valuable in simplifying state machine initialization. A timing diagram and parameter table are shown below.



Parameters	Description	Min	Тур	Max	Units	
t <sub>pr</sub>	Power-Up Reset Time		600	1000	ns	
t <sub>s</sub>	Input or Feedback Setup Time	See Switching Characteris		ristics		
t <sub>w</sub>	Clock Width					

#### PROGRAMMING AND VERIFICATION

The AmPAL22V10 is programmed and verified using AMD's standard programmable logic programming algorithm. The fuse to be programmed is selected by input line number (array column), product term (array row), and by output (one at a time). The fuse is then programmed and verified by applying a simple sequence of voltages to two control pins (1 and 13).

Input line numbers (0-43) are addressed using a full decode scheme via TTL levels on pins 6-11 where 6 is the LSB and 11 is the MSB. Even numbered input lines represent the true version of a signal and odd numbered lines represent the complement. Input line addressing is shown in Table 1. Note that input lines 44-62 are reserved for further expansion and input line 63 is utilized for selecting the fuses used for programming output polarity and whether the output is registered or combinatorial.

Product terms are addressed using a one-of-24 addressing scheme on pins 2 - 5 where pin 2 is the LSB and 5 is the MSB. Product term addressing is shown in Table 2. Logical product terms (0 - 15) are selected via TTL levels on the four addressing pins. Note that outputs with fewer than 16 product terms will decode blank space for decoding values greater than the number of product terms on that output. Architectural product terms are selected by placing a zener voltage level (V $_{\rm HH}$ ) on the MSB (pin 5) and using pins 2 - 4 for an additional eight decoding states (only 5 are used). The specific decoding of architectural features is best shown in Table 2.

Fuse selection by output must be done one output at a time (following control pin 1 going to  $V_{HH}$ ) as shown in the programming timing diagram (Figure 1).

Once fuses have been selected, the simple programming and verification sequence may be completed as shown in Figure 1. AC and DC requirements for programming are shown in the programming parameter table.

#### **SECURITY FUSE PROGRAMMING**

A single fuse is provided on each AmPAL22V10 part to prevent unauthorized copying of PAL fuse patterns. Once blown, the circuitry enabling fuse verification and registered output preload is permanently disabled.

Programming of the security fuse is the same as shown before. Verification of a blown security fuse is accomplished by verifying the whole fuse array as if every fuse is blown.

#### PROGRAMMING YIELD

AMD PALs have been designed to insure extremely high programming yields (>98%). To help insure that a part was correctly programmed, once programming is completed, the entire fuse array should be reverified at both low and high  $V_{CC}$ . Reverification can be accomplished by reading all ten outputs in parallel rather than one at a time. This verification cycle checks that the array fuses have been blown and can be sensed by the outputs under varying conditions.

AMD PALs contain many internal test features, including circuitry and extra fuses which allow AMD to test the ability of each part to perform programming before shipping, to assure high programming yields and correct logical operation for a correctly programmed part. Programming yield losses are most likely due to poor programming socket contact, programming equipment out of calibration, or improper usage of said equipment.

#### PROGRAMMING PARAMETERS (T<sub>A</sub> = 25°C)

Parameters	De	Description			Max	Units
V	Control Pin Extra High Level	Pin 1 @ 10-40mA	10	11	12	Volts
V <sub>HH</sub>	Control Fill Extra Fight Level	Pin 13 @ 10-40mA	10	11	12	VUILS
V <sub>OP</sub>	Program Voltage Pins 14-23 @	15-200mA	18	20	22	Volts
V <sub>IHP</sub>	Input High Level During Program	Input High Level During Programming and Verify			5.5	Volts
V <sub>ILP</sub>	Input Low Level During Programm	0.0	0.3	0.5	Volts	
V <sub>CCP</sub>	V <sub>CC</sub> During Programming @ I <sub>CC</sub>	5	5.2	5.5	Volts	
V <sub>CCL</sub>	V <sub>CC</sub> During First Pass Verification	4.1	4.3	4.5	Volts	
V <sub>CCH</sub>	V <sub>CC</sub> During Second Pass Verifica	5.4	5.7	6.0	Volts	
V <sub>Blown</sub>	Successful Blown Fuse Sense Le		0.3	0.5	Volts	
dV <sub>OP</sub> /dt	Rate of Output Voltage Change		20		250	V/μsec
dV <sub>13</sub> /dt	Rate of Fusing Enable Voltage C	hange (Pin 13 Rising Edge)	100		1000	V/μsec
•-	Fusing Time First Attempt		40	50	100	μsec
tp	Subsequent Attempts		4	5	10	msec
t <sub>D</sub>	Delays Between Various Level Cl	nanges	100	200	1000	ns
tv	Period During which Output is Se			500	ns	
V <sub>ONP</sub>	Pull-Up Voltage On Outputs Not I	V <sub>CCP</sub> - 0.3	V <sub>CCP</sub>	V <sub>CCP</sub> + 0.3	Volts	
R	Pull-Up Resistor On Outputs Not	1.9	2	2.1	kΩ	

#### Ampal22V10 PROGRAMMING EQUIPMENT INFORMATION

Source and Location	Data I/O 10525 Willows Rd., N.E. Redmond, WA 98052	Kontron Electronics, Inc. 630 Price Ave. Redwood City, CA 94063	Stag Microsystems 528-5 Weddel Dr. Sunnyvale, CA 94086	Structured Design, Inc. 1700 Wyatt Dr. #3 Santa Clara, CA 95054	Digilec, Inc. 7335 E. Acoma Dr. Dept-103 Scottsdale, AZ 85260	
Programmer Model-100, 29,		ТВА	Model-PPX	SD 1000	TBA	
Model(s)	19 or 17		Model ZL-30			
AMD PAL Logicpak Personality 950-1942-001			PPM2200	On Board	-	
Module			On Board ZL-30			
Socket	715-1947-003	TBA	Am203S	On Board		
Adapter			On Board ZL-30			

The machines noted above have been qualified by AMD to insure high programming yields. Check with the factory to determine the current status of vendors noted TBA or other available models.

#### PROGRAMMING WAVEFORMS

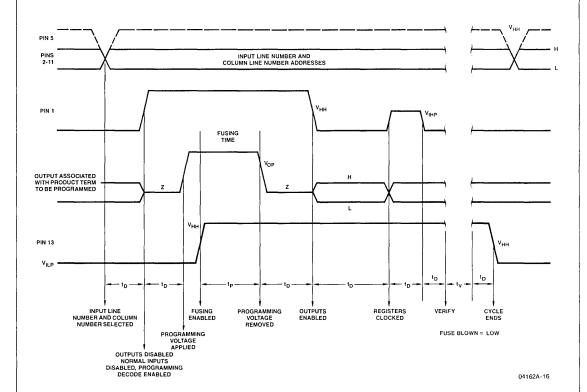


TABLE 1. INPUT ADDRESSING

Input Line	Input Line Number Address Pin States							
Number	11	10	9	8	7	6		
0	L	L	L	L	L	L		
1	L	L	L	L	L	Н		
2	L	L	L	L	н	L		
3	L	L	L	L	н	Н		
4	L	L	L	Н	L	L		
5	L	L	L	Н	L	Н		
6	L	L	L	Н	Н	L		
7	L	L	L	н	н	н		
8	L	L	Н	L	L	L		
9	L	L	Н	L	L	Н		
10	L	L	н	L	н	L		
11	L	L	н	L	Н	Н		
12	L	L	н	Н	L	L		
13	L	L	н	н	L	Н		
14	L	L	н	н	н	L		
15	L	L	н	н	Н	Н		
16	L	н	L	L	L	L		
17	L	Н	L	L	L	Н		
18	L.	н	L	L	н	L		
19	L	н	L	L	Н	н		
20	L	Н	L	н	L	L		
21	L	Н	L	н	L	н		
22	L	н	L	н	Н	L		
23	L	н	L	н	н	Н		
24	L	Н	н	L	L	L		
25	L	Н	н	L	L	Н		
26	L	н	н	L	н	L		
27	L	н	н	L	н	Н		
28	L	н	н	н	L	L		
29	L	н	Н	н	L	Н		
30	L	н	Н	н	Н	L		
31	L	Н	н	н	н	Н		

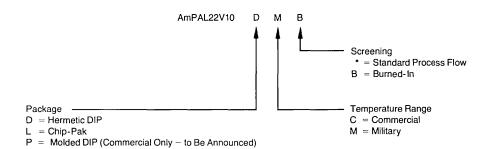
Input Line	Input Line Number Address Pin States							
Number	11	10	9	8	7	6		
32	Н	L	L	L	L	L		
33	н	L	L	L	L	н		
34	н	L	L	L	Н	L		
35	Н	L	L	L	Н	Н		
36	н	Ļ	L	Н	L	L		
37	Н	L	L	Н	L	н		
38	Н	L	L	н	н	L		
39	н	L	L	Н	Н	н		
40	н	L	н	L	L	L		
41	н	L	н	L	L	н		
42	н	L	Н	L	Н	L		
43	н	L	Н	L	Н	н		
			Rese	erved				
63*	н	н	н	н	н	н		

TABLE 2. COLUMN NUMBER ADDRESSING

l													ber Select	
-			,	olumn	Marine					_			in States	
				Joiumn	Numbe	er 				5	4	3	2	
0	0	0	0	0	0	0	0	0	0	L	L	L	L	Logical PT's
1	1	1	1	1	1	1	1	1	1	L	L	L	н	1
2	2	2	2	2	2	2	2	2	2	L	L	н	L	
3	3	3	3	3	3	3	3	3	3	L	L	Н	н	
4	4	4	4	4	4	4	4	4	4	L	н	L	L	
5	5	5	5	5	5	5	5	5	5	L	Н	L	Н	1
6	6	6	6	6	6	6	6	6	6	L	Н	н	L	
7	7	7	7	7	7	7	7	7	7	L	н	Н	Н	
-	8	8	8	8	8	8	8	8		н	L	L	L	
-	9	9	9	9	9	9	9	9	-	Н	L	L	н	1
-	-	10	10	10	10	10	10	-	-	Н	L	н	L	
-	_	11	11	11	11	11	11	-	-	н	L	н	Н	
-	-	-	12	12	12	12	-		-	н	н	L	L	
-	-	-	13	13	13	13	-	-	-	Н	н	L	Н	
-	-	-	-	14	14	-	-	-	i –	н	Н	Н	L	
-	-	-	-	15	15	-	-	-		н	Н	н	н	<b>†</b>
OE	OE	OE	OE	OE	OE	OE	OE	OE	OE	HH	L	L	L —	Output Enable
P	P	P	P	P	P	Р	Р	Р	Р	НН	L	L	н	Output Polarity
R	R	R	R	R	R	R	R	R	R	нн	L	Н	L	Register/Non-Register Output
-	AR*	-	-		-	-	-	SP**	_	HH	L	Н	н	*Asynchronous Reset
-	SF	-	-	-	-	-	-	-	-	НН	Н	L	н ——	
-		-								L=	Vup			Security Fuse (Special
Pin 23	Pin 22	Pin 21	Pin 20	Pin 19	Pin 18	Pin 17	Pin 16	Pin	Pin	H =	VIHP			Verify Required)
23		21	20_	19	18	17	16	15	14	HH =	V <sub>HH</sub>			
		F	rogramn	ning Acc	ess and	Verify P	in							
$\overline{}$										·				

<sup>\*</sup>Architecture row.

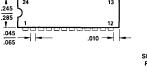
#### ORDERING INFORMATION

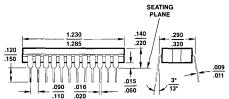


\*A blank in this position of the ordering code indicates the part has been screened to standard process flow.

#### PHYSICAL DIMENSIONS Dual in-Line







P-24-1AA Molded DIP

TO BE ANNOUNCED



## Fuse Microprogrammable Controllers Advanced Micro Devices

#### DISTINCTIVE CHARACTERISTICS

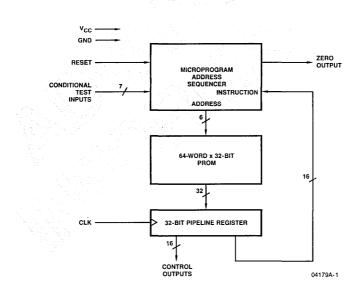
- · Implements complex state machines
- 64 words of 32-bit wide microprogram memory
- 16 control outputs
- 7 conditional test inputs
- · Cascadable to any width
- · High level instruction set
  - conditional
  - conditional looping
  - conditional subroutine call
  - multiway branch
- SSR<sup>™</sup> diagnostics on chip

#### **FUNCTIONAL DESCRIPTION**

The AmPL64S16 is a single-chip Fuse Microprogrammable Controller (FMC) which allows complex control sequences to be implemented by programming the desired series of microinstructions. Because the AmPL64S16 FMC is microprogrammable, designers can easily design complex state machines without the need for Karnaugh Map or Boolean Equation design techniques. State machines may be constructed directly from high-level microinstruction control flow definitions. Jumps, loops and subroutine calls, which can be conditionally executed based on the test inputs, provide the designer with powerful control flow primitives.

A microprogram address sequencer is the heart of the FMC. It provides the microprogram address to an internal 64 word by 32-bit PROM. Instructions such as loop, subroutine call, or branch can be executed conditionally based on the values on the test inputs. The 32-bit microinstruction pipeline register holds the sequencer instruction access time.

#### **BLOCK DIAGRAM**



# Am27S12A • Am27S13A Am27S12 • Am27S13

2048-Bit Generic Series Bipolar PROM (512 x 4 bits with ultra fast access time)

"A" VERSION ADVANCED INFORMATION

#### DISTINCTIVE CHARACTERISTICS

- High Speed 30ns max commercial range access time
- Excellent performance over full MIL and commercial ranges
- Highly reliable, ultra-fast programming Platinum-Silicide fuses
- · High programming yield
- · Low current PNP inputs
- · High current open collector and three-state outputs
- Fast chip select
- Access time tested with N<sup>2</sup> patterns
- Pin for pin replacements for industry standard products
- Common Generic PROM series electrical characteristics and simple programming procedures

#### **GENERIC SERIES CHARACTERISTICS**

The Am27S12A/12 and Am27S13A/13 are members of an Advanced PROM series incorporating common electrical characteristics and programming procedures. All parts in this series are produced with a fusible link at each memory location storing a logic LOW and can be selectively programmed to a logic HIGH by applying appropriate voltages to the circuit.

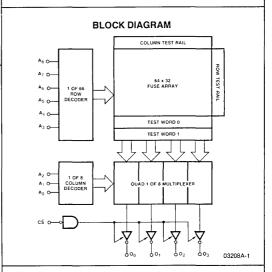
All parts are fabricated with AMD's fast programming highly reliable Platinum-Silicide Fuse technology. Utilizing easily implemented programming (and common programming personality card sets) these products can be rapidly programmed to any customized pattern. Extra test words are pre-programmed during manufacturing to insure extremely high field programming yields, and produce excellent parametric correlation.

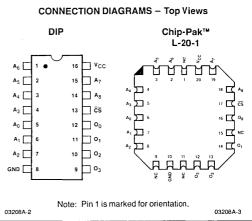
Platinum-Silicide was selected as the fuse link material to achieve a well controlled melt rate resulting in large non-conductive gaps that ensure very stable long term reliability. Extensive operating testing has proven that this low-field, large-gap technology offers the best reliability for fusible link PROMs.

Common design features include active loading of all critical AC paths regulated by a built-in temperature and voltage compensated bias network to provide excellent parametric performance over MIL supply and temperature ranges. Selective feedback techniques have been employed to minimize delays through all critical paths producing the fastest speeds possible from Schottky processed PROMs.

#### **FUNCTIONAL DESCRIPTION**

The Am27S12A/12 and Am27S13A/13 are high speed electrically programmable Schottky read only memories. Organized in the industry standard 512 x 4 configuration, they are available in both open collector Am27S12A/12 and three-state Am27S13A/13 output versions. After programming, stored information is read on outputs  $O_0\text{-}O_3$  by applying unique binary addresses to  $A_0\text{-}A_8$  and holding the chip select input,  $\overline{\text{CS}}$ , at a logic LOW. If the chip select input goes to a logic HIGH,  $O_0\text{-}O_3$  go to the off or high impedance state.





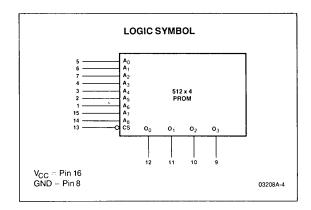
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#### MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65 to +150°C
Temperature (Ambient) Under Bias	−55 to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 to +7.0V
DC Voltage Applied to Outputs (Except During Programming)	-0.5V to +V <sub>CC</sub> max
DC Voltage Applied to Outputs During Programming	21V
Output Current into Outputs During Programming (Max Duration of 1 sec)	250mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	-30 to +5mA

#### **OPERATING RANGE**

Range	Vcc	Temperature
COM'L	4.75 to 5.25V	T <sub>A</sub> = 0 to +75°C
MIL	4.5 to 5,5V	T <sub>C</sub> = -55 to +125°C



#### **ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE (Unless Otherwise Noted)**

Parameters	Description	т	est Condition	าร	Min	Typ (Note 1)	Max	Units
V <sub>OH</sub> (Note 2)	Output HIGH Voltage	$V_{CC} = MIN, I_{C}$ $V_{IN} = V_{IH} \text{ or } V$			2.4			Volts
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = MIN, I <sub>C</sub> V <sub>IN</sub> = V <sub>IH</sub> or V					0.45	Volts
V <sub>IH</sub>	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 3)			2.0			Volts
V <sub>IL</sub>	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 3)					0.8	Volts
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = MAX, \	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0.45V			-0.010	-0.250	mA
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 2.7V					25	μΑ
I <sub>SC</sub> (Note 2)	Output Short Circuit Current	V <sub>CC</sub> = MAX, \	$V_{OUT} = 0.0V$ (No	ote 4)	-20	-40	-90	mA
Icc	Power Supply Current	All inputs = GI V <sub>CC</sub> = MAX	ND			100	130	mA
V <sub>I</sub>	Input Clamp Voltage	V <sub>CC</sub> = MIN, I <sub>II</sub>	<sub>N</sub> = -18mA	·			-1.2	Volts
				V <sub>O</sub> = 4.5V	·		40	
I <sub>CEX</sub>	Output Leakage Current	$V_{CC} = MAX$ $V_{\overline{CS}} = 2.4V$		V <sub>O</sub> = 2.4V			40	$\muA$
		1.03 2.44	(Note 2)	$V_0 = 0.4V$			-40	
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0V @ f = 1MHz (Note 5)				4		
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0V	@ f = 1MHz (No	te 5)		8		pF

Notes: 1. Typical limits are at  $V_{CC}=5.0V$  and  $T_A=25^{\circ}C$ .

- 2. This applies to three-state devices only.
- 3. These are absolute voltages with respect to device ground pin and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.
- 4. Not more than one output should be shorted at a time. Duration of the short circuit should not be more than one second.
- 5. These parameters are not 100% tested, but are periodically sampled.

# Am27S18A • Am27S19A Am27S18 • Am27S19

256-Bit Generic Series Bipolar PROM (32 x 8 bits with ultra fast access time)

"A" VERSION ADVANCED INFORMATION

#### **DISTINCTIVE CHARACTERISTICS**

- High Speed 25ns max commercial range access time
- Excellent performance over full MIL and commercial ranges
- Highly reliable, ultra-fast programming Platinum-Silicide fuses
- High programming yield
- Low current PNP inputs
- High current open collector and three-state outputs
- · Fast chip select
- Access time tested with N<sup>2</sup> patterns
- Pin for pin replacements for industry standard products
- Common Generic PROM series electrical characteristics and simple programming procedures

#### **FUNCTIONAL DESCRIPTION**

The Am27S18A/18 and Am27S19A/19 are high speed electrically programmable Schottky read only memories. Organized in the industry standard 32 x 8 configuration, they are available in both open collector Am27S18A/18 and three-state Am27S19A/19 output versions. After programming, stored information is read on outputs  $O_0\!-\!O_7$  by applying unique binary addresses to  $A_0\!-\!A_4$  and holding the chip select input,  $\overline{CS}$ , at a logic LOW. If the chip select input goes to a logic HIGH,  $O_0\!-\!O_7$  go to the off or high impedance state.

#### **GENERIC SERIES CHARACTERISTICS**

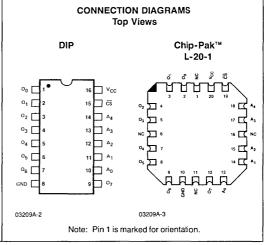
This Am27S18A/18 and Am27S19A/19 are members of an Advanced PROM series incorporating common electrical characteristics and programming procedures. All parts in this series are produced with a fusible link at each memory location storing a logic LOW and can be selectively programmed to a logic HIGH by applying appropriate voltages to the circuit.

All parts are fabricated with AMD's fast programming highly reliable Platinum-Silicide Fuse technology. Utilizing easily implemented programming (and common programming personality card sets) these products can be rapidly programmed to any customized pattern. Extra test words are pre-programmed during manufacturing to insure extremely high field programming yields, and produce excellent parametric correlation.

Platinum-Silicide was selected as the fuse link material to achieve a well controlled melt rate resulting in large non-conductive gaps that ensure very stable long-term reliability. Extensive operating testing has proven that this low-field, large-gap technology offers the best reliability for fusible link PROMs.

Common design features include active loading of all critical AC paths regulated by a built-in temperature and voltage compensated bias network to provide excellent parametric performance over MIL supply and temperature ranges. Selective feedback techniques have been employed to minimize delays through all critical paths producing the fastest speeds possible from Schottky processed PROMs.

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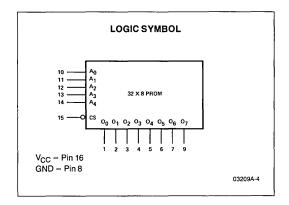
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#### MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65 to +150°C
Temperature (Ambient) Under Bias	−55 to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 to +7.0V
DC Voltage Applied to Outputs (Except During Programming)	−0.5V to +V <sub>CC</sub> max
DC Voltage Applied to Outputs During Programming	21V
Output Current into Outputs During Programming (Max Duration of 1 sec)	250mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	-30 to +5mA

#### **OPERATING RANGE**

напде	vcc _	remperature
COM'L	4.75 to 5.25V	$T_A = 0 \text{ to } +75^{\circ}C$
MIL	4.5 to 5.5V	$T_{C} = -55 \text{ to } + 125^{\circ}\text{C}$



#### **ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE** (Unless Otherwise Noted)

						Тур		
Parameters	Description	Те	st Conditio	ns	Min	(Note 1)	Max	Units
V <sub>OH</sub> (Note 2)	Output HIGH Voltage	$V_{CC} = MIN, I_{OH}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$			2.4			Volts
V <sub>OL</sub>	Output LOW Voltage	$V_{CC} = MIN, I_{OL}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$					0.45	Volts
V <sub>IH</sub>	Input HIGH Level	Guaranteed inp voltage for all in		4	2.0			Volts
V <sub>IL</sub>	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 3)					0.8	Volts
կլ	Input LOW Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0.45V				-0.010	-0.250	mA
I <sub>I</sub> H	Input HIGH Current	V <sub>CC</sub> = MAX, V <sub>I</sub>	<sub>V</sub> = 2.7V				25	μΑ
I <sub>SC</sub> (Note 2)	Output Short Circuit Current	V <sub>CC</sub> = MAX, V <sub>C</sub>	<sub>NUT</sub> = 0.0V (N	ote 4)	-20	-40	-90	mA
lcc	Power Supply Current	All inputs = GN	D, V <sub>CC</sub> = MAX	<		90	115	mA
VI	Input Clamp Voltage	V <sub>CC</sub> = MIN, I <sub>IN</sub>	= -18mA				-1.2	Volts
		V <sub>CC</sub> = MAX		V <sub>O</sub> = 4.5V			40	
ICEX	Output Leakage Current	V <sub>CS</sub> = 2.4V	(Note 2)	V <sub>O</sub> = 2.4V			40	$\mu$ A
			(Note 2)	V <sub>O</sub> = 0.4V			-40	
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0V @ f = 1MHz (Note 5)				4		pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0V @	f = 1MHz (No	ote 5)		8		F.

Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ .

- 2. This applies to three-state devices only.
- These are absolute voltages with respect to device ground pin and include all overshoots due to system and/or tester noise.Do not attempt to test these values without suitable equipment.
- 4. Not more than one output should be shorted at a time. Duration of the short circuit should not be more than one second.
- 5. These parameters are not 100% tested, but are periodically sampled.

# Am27S20A • Am27S21A Am27S20 • Am27S21

1024-Bit Generic Series Bipolar PROM (256 x 4 bits with ultra fast access time)

"A" VERSION ADVANCED INFORMATION

#### DISTINCTIVE CHARACTERISTICS

- High Speed 30ns max commercial range access time
- Excellent performance over full MIL and commercial ranges
- Highly reliable, ultra-fast programming Platinum-Silicide fuses
- · High programming yield
- · Low current PNP inputs
- · High current open collector and three-state outputs
- Fast chip select
- Access time tested with N<sup>2</sup> patterns
- Pin for pin replacements for industry standard products
- Common Generic PROM series electrical characteristics and simple programming procedures

#### **GENERIC SERIES CHARACTERISTICS**

The Am27S20A/20 and Am27S21A/21 are members of an Advanced PROM series incorporating common electrical characteristics and programming procedures. All parts in this series are produced with a fusible link at each memory location storing a logic LOW and can be selectively programmed to a logic HIGH by applying appropriate voltages to the circuit.

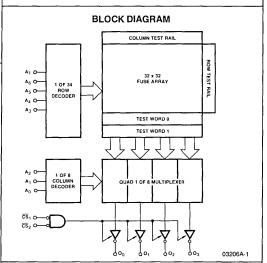
All parts are fabricated with AMD's fast programming highly reliable Platinum-Silicide Fuse technology. Utilizing easily implemented programming (and common programming personality card sets) these products can be rapidly programmed to any customized pattern. Extra test words are pre-programmed during manufacturing to insure extremely high field programming yields, and produce excellent parametric correlation.

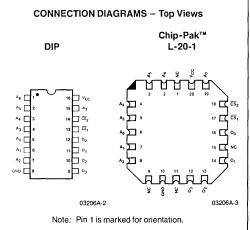
Platinum-Silicide was selected as the fuse link material to achieve a well controlled melt rate resulting in large non-conductive gaps that ensure very stable long term reliability. Extensive operating testing has proven that this low-field, large-gap technology offers the best reliability for fusible link PROMs.

Common design features include active loading of all critical AC paths regulated by a built-in temperature and voltage compensated bias network to provide excellent parametric performance over MIL supply and temperature ranges. Selective feedback techniques have been employed to minimize delays through all critical paths producing the fastest speeds possible from Schottky processed PROMs.

#### **FUNCTIONAL DESCRIPTION**

The Am27S20A/20 and Am27S21A/21 are high speed electrically programmable Schottky read only memories. Organized in the industry standard 256 x 4 configuration, they are available in both open collector Am27S20A/20 and three-state Am27S21A/21 output versions. After programming, stored information is read on outputs  $O_0$ -O3 by applying unique binary addresses to  $A_0$ -A7 and holding chip select inputs,  $\overline{OS}_1$  and  $\overline{CS}_2$ , at a logic LOW. If either chip select input goes to a logic HIGH,  $O_0$ -O3 go to the OFF or high impedance state.





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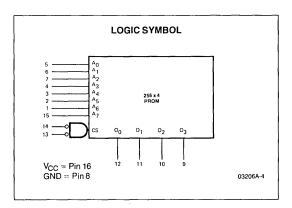
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#### MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	−65 to +150°C
Temperature (Ambient) Under Bias	−55 to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 to +7.0V
DC Voltage Applied to Outputs (Except During Programming)	-0.5V to +V <sub>CC</sub> max
DC Voltage Applied to Outputs During Programming	21V
Output Current into Outputs During Programming (Max Duration of 1 sec)	250mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	-30 to +5mA

#### **OPERATING RANGE**

	Range	v <sub>cc</sub>	Temperature
ſ	COM.F	4.75 to 5.25V	$T_A = 0 \text{ to } +75^{\circ}\text{C}$
Γ	MIL	4.5 to 5.5V	$T_C = -55 \text{ to } + 125^{\circ}\text{C}$



#### **ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE** (Unless Otherwise Noted)

					тур			
Parameters	neters Description Test Conditions		ns	Min	(Note 1)	Max	Units	
V <sub>OH</sub> (Note 2)	Output HIGH Voltage	$V_{CC} = MIN$ , $I_{OH} = -2.0mA$ $V_{IN} = V_{IH}$ or $V_{IL}$			2.4			Volts
V <sub>OL</sub>	Output LOW Voltage	$V_{CC} = MIN, I_{OL} = 16mA$ $V_{IN} = V_{IH} \text{ or } V_{IL}$				0.45	Volts	
V <sub>IH</sub>	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 3)		2.0			Volts	
V <sub>IL</sub>	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 3)				0.8	Volts	
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0.45V			-0.010	-0.250	mA	
·IH	Input HIGH Current	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 2.7V				25	μΑ	
I <sub>SC</sub> (Note 2)	Output Short Circuit Current	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 0.0V (Note 4)		-20	-40	-90	mA	
lcc	Power Supply Current	All inputs = GND V <sub>CC</sub> = MAX			100	130	mA	
VI	Input Clamp Voltage	V <sub>CC</sub> = MIN, I <sub>IN</sub> = -18mA				-1.2	Volts	
	Output Leakage Current	$V_{CC} = MAX$ $V_{\overline{CS}_1} = 2.4V$		$V_0 = 4.5V$			40	μΑ
I <sub>CEX</sub>			(Note 2)	V <sub>O</sub> = 2.4V			40	
				$V_O = 0.4V$			-40	
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0V @ f = 1MHz (Note 5)			4			
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0V @ f = 1MHz (Note 5)			8		pF	

- Notes: 1. Typical limits are at  $V_{CC} = 5.0V$  and  $T_A = 25^{\circ}C$ .
  - 2. This applies to three-state devices only.
  - These are absolute voltages with respect to device ground pin and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.
  - 4. Not more than one output should be shorted at a time. Duration of the short circuit should not be more than one second.
  - 5. These parameters are not 100% tested, but are periodically sampled.

## Section 3

# How to Design with PALs



Introduction to Fuse Maps and Design Examples Exclusive-OR
The Multiplexer
Decoding/Chip Select
Shift Registers
The Counter

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# How to Design with PALs

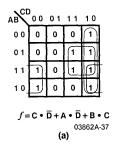


Since any Boolean function can be expressed in the sum-of-products form, any logic function can be implemented in a PAL as long as the number of inputs, outputs and product terms required to perform the function do not exceed what is available in the device. There are many ways of deriving this sum-of-products form, one common way is by the use of Karnaugh maps (K-Maps). When implementing functions in PALs with active HIGH outputs (AND-OR), the usual method of grouping the "1"s will produce the desired equations (see Figure 1a). However, when using PALs with active LOW outputs (AND-OR-INVERT), the sum-of-products equations are obtained by grouping the "0"s (Figure 1b). Grouping the "0"s instead of the "1"s has the effect of inverting the equations. This is a convenient technique for generating inverted logic for use with active LOW PALs.

When using PALs, the term "product term" is often used. This is simply another way of describing an AND function. Referring again to Figure 1a, since there are 3 logical AND terms in

the function equation, we would say that it would require 3 product terms to perform that function. The phrase "product term" is often abbreviated as "PT".

A demonstration of an early methodology used to relate logic equations to the internal structure of PALs is shown in the design example. This is a technique which relies on the hand generation of fuse maps. As you might imagine, it is slow and extremely cumbersome, but is included for the interested reader. Instead, to aid in the development of PAL designs, a software tool called PALASM has been developed. This tool greatly speeds the development of PAL designs. AMD offers a version of this called AMPALASM20, which supports all AMD 20-pin PALs, and offers improved ease of use and error detection. AMPALASM20 has been used in most of the examples in this section. Its use is described more fully in Section 4 of this handbook.



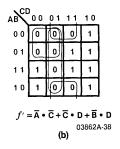


Figure 1. Using K-Maps for Obtaining the Sum-of-Products Form of PAL Logic

### INTRODUCTION TO FUSE MAPS AND DESIGN EXAMPLES

Prior to the availability of PALASM as a tool to aid in the development of PAL designs, all designs were generated by hand using a technique which depended upon fuse maps. With this technique the designer was required to actually identify the individual fuses which needed to be blown to implement the desired function. While this technique is no longer used, it is still useful, as an understanding of it provides a firm foundation in physical reality of how a PAL implements a function.

As a demonstration of this methodology, we will use the arbitrary circuit shown in Figure 2 as an example for selecting and coding a PAL. This example shows the technique of using a PAL once the logic diagram has been developed. Again, this technique is no longer used, as it is much easier to simply generate the equations directly as input to PALASM.

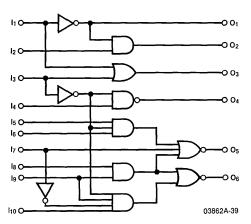


Figure 2. Design Example, Logic Diagram

The first step is to generate the Boolean equations for this function. These are derived directly from the logic diagram. (It should be noted that good design practice is to use meaningful pin names rather than  $I_1$  or  $O_6$ . This will help in providing good design documentation.)

The following symbols will be used for all logic equations:

$$* = AND + = OR / = NOT (invert)$$

Boolean equations for Figure 2 are:

$$01 = /I1$$

$$02 = /I1*I2$$

$$03 = I1 + I3$$

$$04 = /(/I3*I4)$$

$$05 = /(/13*15*16 + 17 + 18*19)$$

$$06 = /(18*19 + /13*/17*19*110)$$

The next step is to select the particular PAL we want to use for this function. Since no registers are required, we should select from the combinatorial devices (AmPAL16L8, AmPAL16HB, AmPAL16HD8). Since 3 outputs have AND-OR functions and 3 outputs have AND-OR-INVERT functions, we could still select from either active HIGH or active LOW (H or L) parts, but since the more complex functions are AND-OR-INVERT, the active LOW (L) series is most likely. Finally, we see that no output enable is required, thus we could use either the AmPAL16L8 or the AmPAL16LD8. For the purposes of this example we will select the AmPAL16L8.

Now, since we have selected an AmPAL16L8 (which has inverting outputs) we need to apply DeMorgan's theorem to convert these equations from the active HIGH to the active LOW output. DeMorgan's theorem can be used to convert any logic equation in any form into the AND-OR structure used in PALs. Applying DeMorgan's theorem gives the active LOW form of the equation:

$$/01 = I1$$

$$/02 = I1 + /I2$$

$$/03 = /I1*/I3$$

$$/04 = /I3*I4$$

$$/05 = /13*15*16 + 17 + 18*19$$

$$/06 = 18*19 + /13*/17*19*110$$

We can now determine which fuses need to be programmed for the PAL to perform this function. Figure 3 shows the conventions which are used when coding fuse maps.

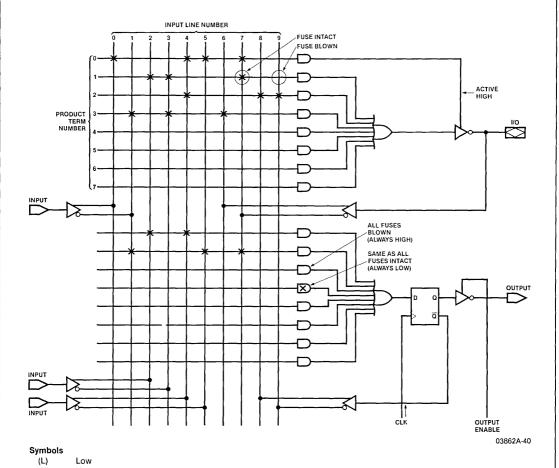
Figure 4 shows the logic diagram of the AmPAL16L8. We will assign outputs  $O_1$ – $O_6$  to pins 14–19, and inputs  $I_1$ – $I_{10}$  to pins 2–9, 11 and 13.

 $O_1$  is assigned to pin 19. To make this output the inverse of  $I_1$ , leave input line 0 connected (not blown) to product term 1 and blow all the remaining fuses on that product term. This is indicated by the X at the intersection of input line 0 and product term 1 in Figure 4.

Since the other inputs to the OR gate are unused, they are forced to zero by leaving all the fuses intact on product terms

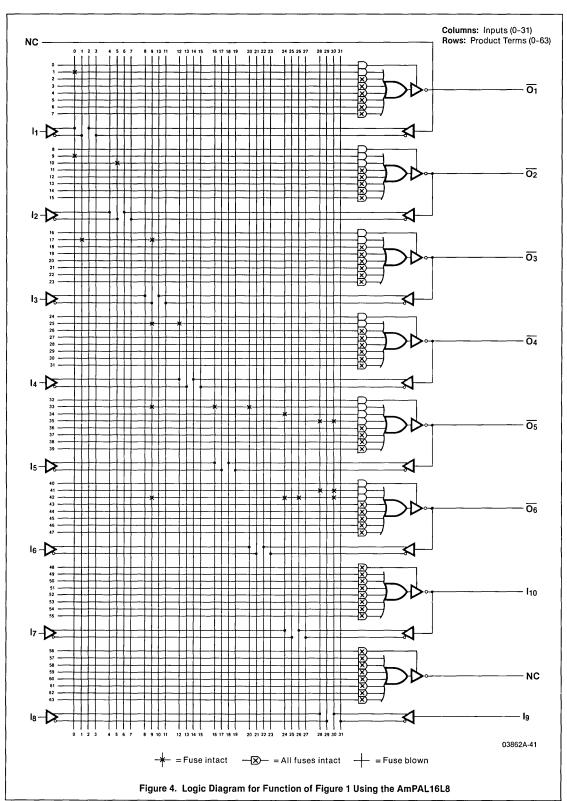
2–7. As shown in Figure 3, unused product terms (those with all fuses intact) are indicated by Xs in the small AND gates at the NOR gate inputs.

The final consideration for  ${\rm O_1}$  is the output enable. By referring back to either the logic diagram for the circuit (Figure 2) or the Boolean equation, we see that there is no output enable function for  ${\rm O_1}$ . In other words,  ${\rm O_1}$  should be enabled all the time. Referring to Figure 4, we see that product term 0 controls the output enable function for  ${\rm O_1}$ . To have the output always enabled, we blow all the fuses in product term (PT)0. A product term with all fuses blown is always HIGH, so this will leave the three-state gate always on, and the output will always be enabled.



(H) High
(N) Negative
(P) Positive
(0) Zero
(1) One
Fuse intact
Fuse blown

Figure 3. Coding Conventions



The next output,  $O_2$ , is the AND function of  $I_1$  and  $I_2$ . Again, since we are using an "L" device, we must apply DeMorgan's theorem and use the inverted form. Since we want to have  $O_2 = I_1 + \overline{I_2}$ , we first leave input line 0 ( $I_1$ ) connected to PT 9 and blow the rest of the fuses on that product term. Then since we have an OR (+) function, we go to the next product term, and leave input line 5 ( $\overline{I_2}$ ) connected to PT 10.

Since PT 11–15 will be unused, we indicate this as we did in  $O_1$ , by putting a X in the AND gate at the input to the NOR gate. Also, since we want  $O_2$  to be always enabled, we leave PT 8 blank, indicating that all of the fuses in that product term should be programmed.

Output  $O_3$  is the AND of  $\overline{I_1}$  and  $\overline{I_3}$ . To implement this, we leave input line 1 connected to PT 17. Since we want an AND function, we also leave input line 9 ( $\overline{I_3}$ ) connected to PT 17. These connections are indicated by Xs. We then blow the rest of the fuses in PT 17. Since the rest of the product terms are unused, we place an X in the AND gates for PT 18–23. Again, we leave PT 16 blank, which will leave  $O_3$  always enabled.

Output  $O_4$  is very similar to  $O_3$ . In order to generate this AND function, we leave input line 9 ( $\overline{l_3}$ ) and input line 12 ( $l_4$ ) connected to PT 25, and program the remainder of the fuses in PT

25. We again indicate that the rest of the product terms are unused, and the output is always enabled.

Output O $_5$  is generated by ANDing  $\overline{l}_3$ ,  $l_5$ , and  $l_6$  on PT 33, connecting  $l_7$  to PT 34, ANDing  $l_8$  and  $l_9$  on PT 35, and leaving PT 36–39 unused.

Output  $O_6$  is generated by ANDing I $_8$  and I $_9$  on PT 41 and ANDing  $\overline{I_3}$ ,  $\overline{I_7}$ , I $_9$  and I $_{10}$  on PT 42. Product terms 43–47 are left unused.

Since pins 12 and 13 are not being used as outputs, Xs are put in the AND gates for all of those product terms.

The completed fuse map is shown in Figure 4.

As you can see, any function can be put into the sum-of-products form and then used to generate a fuse map. However, it can be very time consuming to generate these maps by hand. Therefore, AMD has developed a software tool called AMPALASM20 which will automatically generate the fuse map from the Boolean equations. This software tool is described in Section 4, but for comparison purposes, Figures 5 and 6 show abbreviated input and output data for AMPALASM20.

03862A-42

```
PAL16L8
                                  PAL DESIGN SPECIFICATION
PATO01
                                  MITCH RICHMAN 4/7/83
DESIGN EXAMPLE
ADVANCED MICRO DEVICES
   Ι1
       I2 I3
               I4 I5
                        I6
                           17
                               18
                                   GND
               05 04 03
                           02
                               01
                                   VCC
   NC
      I10 06
/O1 = I1
/02 = I1
      II2
/03 = /I1*/I3
/04 = /I3*I4
/05 = /I3*I5*I6
      17
      18*19
/06 = 18*19
      /I3*/I7*I9*I10
```

Figure 5. Abbreviated AMPALASM20 Input

```
DESIGN EXAMPLE
    11 1111 1111 2222 2222 2233
 0123 4567 8901 2345 6789 0123 4567 8901
5 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
9 X--- --- 11
10 ---- -X- ---- /I2
11 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
16 ---- ---- ----
17 -X-- --- -X-- --- /I1*/I3
19 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
23 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
25 ---- -X-- X--- ---- /I3*I4
32 --- --- /13*15*16
33 --- -- X-- X-- X-- --- /13*15*16
34 --- -- X-- 17
35 --- X-X 18*19
41 ---- X- I8*I9
42 ---- -X- -X- -X- I8*I9
43 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
55 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
59 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
LEGEND: X : FUSE NOT BLOWN (L,N,O) - : FUSE BLOWN (H,P,1)
NIMBER OF FUSES BLOWN = 493
                 03862A-43
```

Figure 6. AMPALASM20 Output Fuse Map

#### **Complex Functions**

Most complex functions can be built up from smaller functional building blocks that are easy to understand and design. This section will show some techniques for designing several common functional blocks that can be tailored for specific applications and used to build up the desired PAL designs. Each block includes a PAL DESIGN SPECIFICATION, a compiled AMPALASM20 output, and a fuse map of the desired function.

#### **Control Functions**

An important feature of PALs with registers is the availability of registered outputs as inputs to the programmable array. This feedback is often used to configure PALs into state sequencers. Feedback also gives an easy way to create a device with a "clock enable". The purpose of disabling the clock is to prevent the contents of the output registers from changing (retain the same state). This result is easily obtained by feeding back the contents of the registers and having these values be clocked back in. In this way, the clock is not actually disabled, but the desired effect is achieved.

Another feature of PALs is programmable I/O pins. One product term controls a three-state driver whose output is fedback as an array input as well as connected to a pin. Thus, if the three-state driver is disabled (high impedance state), the pin can be used as an input. This makes these pins perfect for use as bidirectional lines for such purposes as shifting data serially.

Several common "special" functions, such as clearing and setting, can be incorporated into PALs with ease. The clear function is performed by disabling all of the AND-gates, causing the output of the register to go LOW. On the other hand, the set function is performed by forcing one product term HIGH, causing the output of the register to go HIGH. Loading the registers with data is another common function and, for each bit, can be accomplished by selecting one AND-gate to pass the input data to the registers while disabling the remaining AND-gates. In general, a control or logic function is performed by selecting the necessary AND-gates and deselecting all others unused by the function.

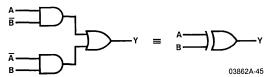
#### **EXCLUSIVE-OR**

An Exclusive-OR (XOR) is often used as a selective inverter or digital comparator. The XOR (2-input) performs the following function: if either of the inputs is HIGH, but not both, then the output is HIGH. The function table and logic equation of the 2-input XOR appearing in Figure 7 shows this graphically. The logic equation can be derived through the use of a Karnaugh map if desired. The logic diagram and logic symbol for the 2-input XOR appear in Figure 8.

XORs of more than two inputs are often used for Modulo-2 arithmetic and odd parity generation. Intuitively, the multiple input XOR is HIGH when an odd number of inputs are HIGH. Figure 9 shows the Karnaugh map for a 4-input XOR. Notice that due to the diagonal pattern of one's in the map, there is no way to combine terms. Also note that exactly half of the squares in the map are ones. Since an n-input function results in 2<sup>n</sup> squares in a Karnaugh map, an n-input XOR will require 2<sup>(n-1)</sup> product terms. For example, the 4-input XOR of Figure 7 requires eight product terms (see Figure 10).

INPUTS	OUTPUT	
A B	Y	
0 0	0	Y=A•B+Ā•B
0 1	1	1-4-514-5
1 0	1	
1 1	_ 0	03862A-44

Figure 7. XOR Function Table and Logic Equation



(a) XOR Logic and (b) Symbolic Representation

Figure 8. XOR Logic Diagram and Logic Symbol

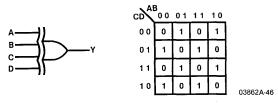
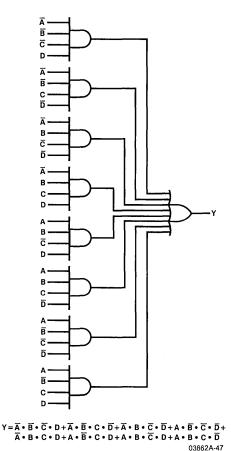


Figure 9. Karnaugh Map and Logic Symbol for a 4-Input XOR



		INP	OUTPUT			
S <sub>1</sub>	S <sub>0</sub>	$D_3$	$D_2$		D <sub>0</sub>	Y
0	0	X	Х	Х	0	0
0	0	Х	Х	Х	1	1
0	1	Х	Х	0	Х	0
0	1	Х	Х	1	X	1
1	0	Х	0	Х	Х	0
1	0	Х	1	Х	Х	1
1	1	0	Х	Х	Χ	0
1	1	1	X	Х	Х	1
			-			03862A

Figure 11. Function Table for 1-of-4 Multiplexer

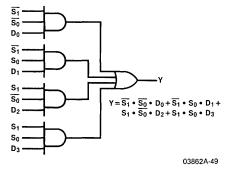


Figure 10. 4-Input XOR Logic

Figure 12. Multiplexer Logic

#### THE MULTIPLEXER

The multiplexer (also called a data selector) is used to selectively route data from several inputs to one output. A simple 4-to-1 multiplexer has four data input lines and two control lines that select which one of the four data inputs is to be passed to the output. The function table for this device is shown in Figure 11. The logic equation can be derived directly from the function table (see Figure 12).

Each AND-gate has a data input and a two-input combination of select inputs. Given one of four possible combinations of

select bits, only the AND-gate corresponding to this combination is enabled, allowing the desired input data to pass to the output. This can be easily expanded to accommodate more data simply by adding more select lines and data inputs. For every n select lines there can be 2<sup>n</sup> data inputs, each of which requires one product term.

The Design Specification and Logic Diagram for this Exclusive-OR and multiplexer based on an AmPAL16H8 are shown in Tables 1(a) and 1(b).

#### Table 1(a). Design Specification for XOR and MUX Function

> S1\*/S0\*D2 S1\* S0\*D3

PAL DESIGN SPECIFICATION JENNY YEE 10/22/82

#### FUNCTION TABLE

PAL16H8

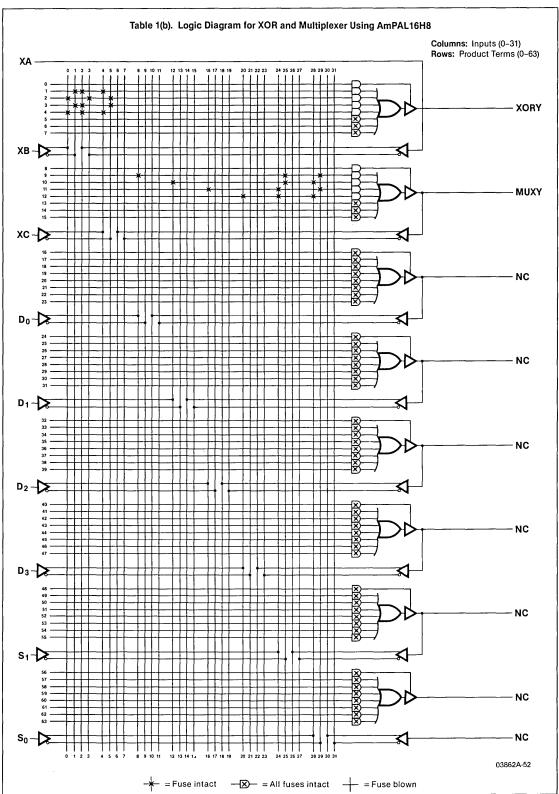
S1	S0	XA	XB	ХC	D3	D2	D1	DO	XORY MUXY
; A	CTIV	ATE	XOR	OUTI	PUT				
;									
X	X	L	L	L	X	X	X	X	L X
X	X	L	L	Η	X	X	X	X	H X
X	X	L	H		X	X	X	X	H X
X	X	L	Н	Н	X	X	χ.	X	L X
X	X	Η	L	L	X	X	X	X	H X
X	X	Н	L	Н	X	X	X	X	L X
X	X	H	H	Н	X	X	Х	X	H X
;									
; A	CTIV	ATE	MUX	OUTF	PUT				
;									
L	L	X	X	X	X	X	X	L	X L
L	L	Х	X	X	X	X	X	Н	X H
L	H	X	X	X	X	X	L	X	X L
L	Н	Х	X	X	X	X	Н	X	Х Н
Н	L	X	X	X	X	L	X	X	X L
Н	L	X	X	X	X	Н	X	Y	х н
Н	Н	X	X			X	X	X	X L
Н	Н	X	Х		Н	X	X	X	Х Н

DESCRIPTION: THIS IS A SIMPLE EXAMPLE EXECUTING THE FUNCTIONS OF THE EXCLUSIVE-OR AND THE MULTIPLEXER 03862A-50

Note: See Section 4 for description of the PAL DESIGN SPECIFICATION format.

#### Table 1(a). Design Specification for XOR and MUX Function (Continued)

```
PAL16H8
                      PAL DESIGN SPECIFICATION
PAT020
                      JENNY YEE 10/22/82
XOR AND MUX FUNCTION
ADVANCED MICRO DEVICES
*D9725
*F0*
LO288 1111 1111 0111 1111 1111 1111 1011 1011 *
LO320 1111 1111 1111 0111 1111 1111 1011 0111 *
L0352 1111 1111 1111 1111 0111 1111 0111 *
C26D2*
VOOO1 OOOXXXXXXXXXXXXXXXL1 *
VOOO4 O11XXXXXXXXXXXXXXXXL1 *
V0006 101XXXXXXXXXXXXXXXL1 *
VOOO8 XXXOXXXOOOXXXXXXXLX1 *
V0009 XXX1XXX000XXXXXXXXXXXXX
VOO10 XXXXOXXO10XXXXXXXLX1
VOO11 XXXX1XXO1OXXXXXXXXXXXX
VOO12 XXXXXOX100XXXXXXXLX1 *
VOO14 XXXXXXO110XXXXXXXLX1 *
0221
                               03862A-51
```

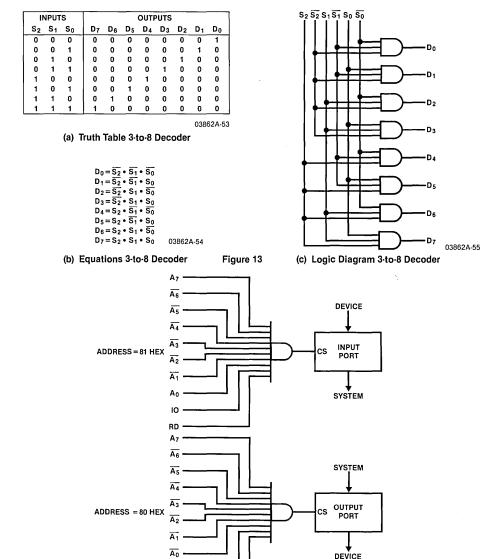


#### **DECODING/CHIP SELECT**

Decoding is one of the most common logic functions to be performed in a design. Essentially all random logic control signals are generated by decoding. Two examples are output enabling and chip selection. The decoding function can be described as being true when the desired set of inputs is true. This, of course, is simply the AND function. In its most general form, an n-input decoder can have 2<sup>n</sup> decoded outputs implemented by 2<sup>n</sup> AND-gates. Each AND-gate has a different combination of inputs allowing only one output to be true at any given time. If Karnaugh maps were used to describe an n-input decoder, there would be 2<sup>n</sup> maps with only a single one in each one. Figure 13 shows the truth table, logic equations and logic diagram for a 3-to-8 decoder imple-

mented with an AmPAL16H8. The design specification and logic diagram for this decoder are shown in Tables 2(a) and 2(b).

In most applications, three inputs (such as in a 3-to-8 decoder), are insufficient to perform the entire decode. For example, decoding the address and control for an I/O device requires anywhere from 8 to 16 address control and timing inputs. Besides the address lines, the control and timing signals which are commonly used as inputs for decoding are: READ/WRITE (R/W), MEMORY/IO (M/IO), BYTE/WORD (B/W) and ADDRESS STROBE (AS). Figure 14 shows typical input and output ports with required decoders.



03862A-56

10

WR -

#### Table 2(a). Design Specification for 3-to-8 Decoder

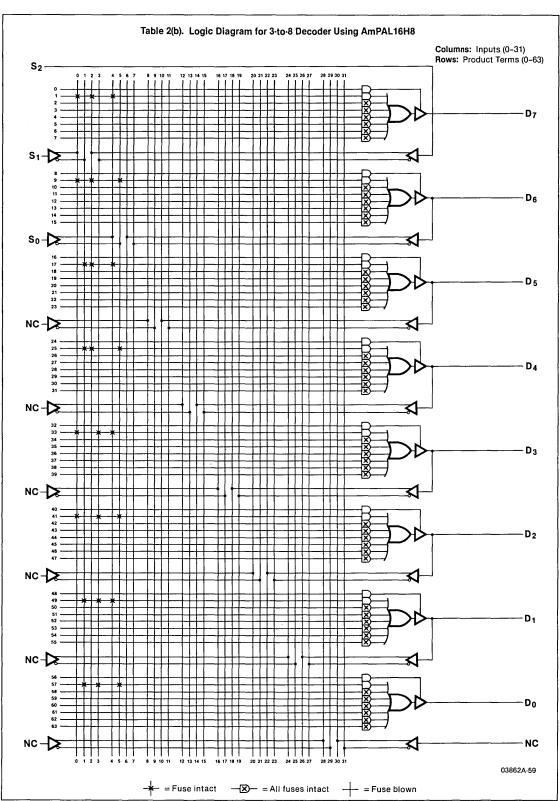
```
PAL DESIGN SPECIFICATION
PAL16H8
                                     JENNY YEE 10/22/82
PATO22
3 TO 8 DECODER
ADVANCED MICRO DEVICES
S2 S1 SO NC NC NC NC NC NC GND
NC DO D1 D2 D3 D4 D5 D6 D7 VCC
DECODER OUTPUT SIGNALS
        = /S2*/S1*/S0
DO
D1
        = /S2*/S1* S0
D2
        = /S2* S1*/S0
D3
        = /S2* S1* S0
D4
        = S2*/S1*/S0
D5
        = S2*/S1* S0
        = S2* S1*/S0
D6
D7
        = S2* S1* S0
FUNCTION TABLE
                 D7 D6 D5 D4 D3 D2 D1 D0
S2 S1 S0
                            L
L
   L
                     L
                               L
                                   L
                                     L
                                          Η
      L
                 L
                        L
                               L
                                      Н
                                          L
L
   L
      Η
                  L
                     L
                        L
                            L
                                   L
                            L
                                   Н
                                          L
L
   Н
      L
                  L
                     L
                        L
                               L
                                      L
                       L
                              Н
                    L
                                     L
L
  н н
                  L
                            L
                                   L
                                          L
                       L
                              L
                                     L
                           Н
                                  L
                                          L
Н
  L L
                  L L
                                  L L
                                          L
Н
  L H
                  L L
                        Н
                           L
                              L
                                          L
Η
   H L
                  L H L
                            L
                                   L L
Н
   H H
                  H L L
                            L
                              L
                                   L L
```

#### DESCRIPTION

THIS DEVICE IMPLEMENTS A 3 TO 8 DECODER. THE SAMPLE SHOWS THE DESIGN OF THE DECODER USING PAL. 03862A-57

#### Table 2(a). Design Specification for 3-to-8 Decoder (Continued)

```
PAL DESIGN SPECIFICATION
PAL16H8
PAT022
                   JENNY YEE
                         10/22/82
3 TO 8 DECODER
ADVANCED MICRO DEVICES
*D9725
*F0*
LO256 1111 1111 1111 1111 1111 1111 1111 *
L0768 1111 1111 1111 1111 1111 1111 1111 *
L1568 1010 0111 1111 1111 1111 1111 1111 *
C3EC4*
VOOO1 OOOXXXXXXXXXHLLLLLL1 *
VOOO2 OO1XXXXXXXXXXLHLLLLLL1 *
VOOO3 O1OXXXXXXXXXLLHLLLLL1 *
VOOO4 011XXXXXXXXXXLLLHLLLL1 *
VOOO5 100XXXXXXXXXXLLLLHLLL1 *
VOOO6 101XXXXXXXXXXLLLLLHLL1 *
VOOO7 110XXXXXXXXXLLLLLLLLL1 *
VOOO8 111XXXXXXXXXXLLLLLLLH1 *
FC30
                           03862A-58
```



#### SHIFT REGISTERS

Shift registers are useful for multiplication, division and serial communications.

An easy way to construct a shift register is to think of it as being composed of a set of multiplexers with registered outputs. A typical shift register can load data, shift data to the right, shift data to the left, and "hold" (leave unchanged) the data. There would be two select lines that control the multiplexers and choose the desired function. If data is to be loaded into the shift register, this path is enabled and the data is passed through and clocked into the registers (see Figure 15a). Figures 15b and 15c illustrate how the shift functions are performed. When shifting right, bit i will clock in bit i+1. This is accomplished by feeding back the output of register i+1 to the multiplexer of bit i and selecting this path. Similarly, shifting left is done by clocking bit i-1 into bit i,

using similar feedback techniques. "Holding" data is easily done by feeding back register i to itself and selecting the path, as shown in Figure 15d. Thus keeping data unchanged is accomplished by feedback, **not** by gating the clock (which is a poor design practice).

This information is now used to design a 4-bit shift register using an AmPAL16H8. The function has four data inputs, four outputs, and two select lines, a left serial input, a right serial input, an output enable, and a clock input. The serial inputs are bidirectional and are used to input new data while shifting. The function table for the shift register is shown in Figure 16 and the logic diagram in Figure 17. The Design Specification and Logic Diagram for these shifters are shown in Tables 3(a) and 3(b).

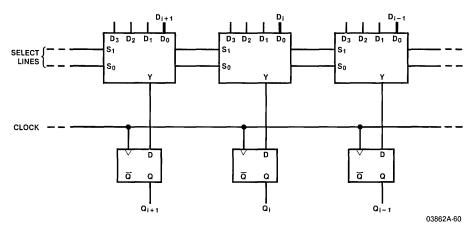


Figure 15a. Loading the Shifter

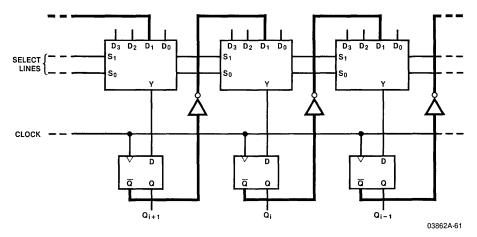


Figure 15b. Shifting Right

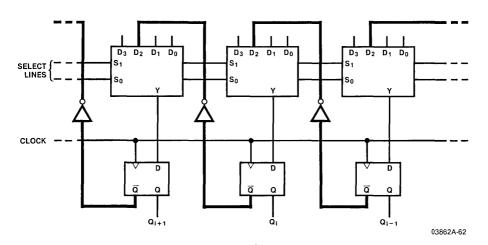


Figure 15c. Shifting Left

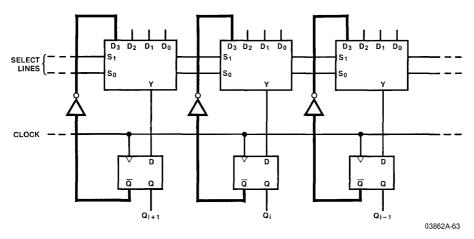


Figure 15d. "Holding" Data

		INPUTS			OUTPUTS					
S <sub>1</sub>	S <sub>0</sub>		RIAL RIGHT	Q <sub>3</sub>	Q <sub>2</sub>	Q <sub>1</sub>	Qo	SEI RIGHT	RIAL LEFT	
0	0	X	Х	D <sub>3</sub>	D <sub>2</sub>	D <sub>1</sub>	Do	Z	Z	
0	1	X	0	0	Q3 <sub>0</sub>	Q2 <sub>0</sub>	Q1 <sub>0</sub>	$Q0_0$	Z	
0	1	Х	1	1	$Q3_0$	Q2 <sub>0</sub>	Q1 <sub>0</sub>	Q0 <sub>0</sub>	Z	
1	0	0	Х	Q2 <sub>0</sub>	Q1 <sub>0</sub>	$Q0_0$	0	Z	$Q3_0$	
1	0	1	X	Q20	Q1 <sub>0</sub>	$Q0_0$	1	Z	Q3 <sub>0</sub>	
1	1	Х	Х	Q3 <sub>0</sub>	Q2 <sub>0</sub>	Q1 <sub>0</sub>	$Q0_0$	Z	Z	

03862A-64

Figure 16. Shift Register Function Table

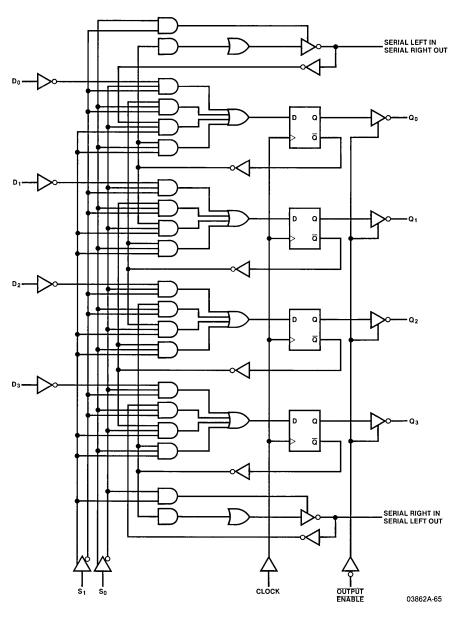


Figure 17. 4-Bit Bidirectional Shift Register

#### Table 3(a). Design Specification for Shift Register

```
PAL16R6
                                            PAL DESIGN SPECIFICATION
                                           JENNY YEE
                                                         10/22/82
PAT023
SHIFT REGISTER
ADVANCED MICRO DEVICES
    S1 S0 D3 D2
                       D1
                           DO
                                NC NC GND
OE SRISLO NC Q3 Q2 Q1 Q0 NC SLISRO VCC
;SHIFT REGISTER OUTPUT SIGNALS
;
/Q3
      := /S1*/S0*/D3
         /S1* SO*/SRISLO
          S1*/S0*/Q2
          S1* S0*/Q3
      := /S1*/S0*/D2
/Q2
         /S1* S0*/Q3
          S1*/S0*/Q1
          S1* S0*/Q2
/Q1
      := /S1*/S0*/D1
         /S1* S0*/Q2
          S1*/S0*/Q0
          S1* S0*/Q1
/Q0
      := /S1*/S0*/D0
         /S1* S0*/Q1
          S1*/SLISRO*/SO
          S1* S0*/Q0
IF(/S1*S0) / SLISRO = /Q0
IF(S1*/S0) / SRISLO = /Q3
                                                           03862A-66
```

Table 3(a). Design Specification for Shift Register (Continued)

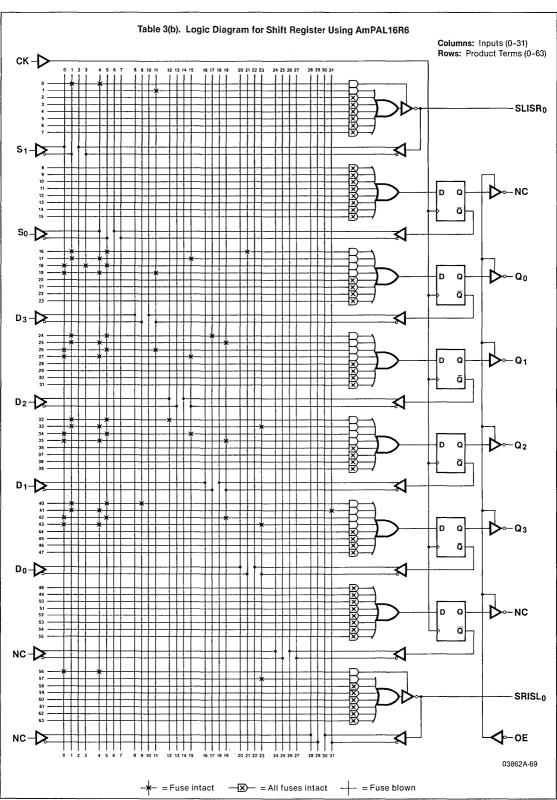
	NCTI												
CK	S1	S0	D3	D2	D1	DO	OE	SRISLO	SLISRO	Q3	Q2	Q1	QO
;							_						
	LOAD			HIF".	Γ_R	IGH'	Γ_	_	_	_	_	_	_
С	L	_	L	L	L	L	L	Z	Z			L	L
С	Η	Н	X	X		X	L	Z	Z	L	L	L	L
С	L	Н	X	Х	X	X	L	H	L	H	L	L	L
С	L	H	X	X	X	Χ	L	L	L	L	H	L	L
С	L	Н	X	X	X	X	L	L	L	L	L	Н	L
С	L	Н	X	X	Χ	X	L	L	Н	L	L	L	H
С	L	Н	X	Х	X	X	L	L	L	L	L	L	L
;													
;	LOAD	AN	D S	HIF	ΤL	EFT							
C	L	L	Η	Н	Η	Н	L	Z	Z	Н	Н	H	H
С	Н	Η	X	X	Χ	X	L	Z	Z	Н	Н	H	Н
С	Н	L	X	X	X	X	L	Н	L	Н	Н	H	L
С	Н	L	X	X	X	X	L	Н	Н	H	H	L	Н
С	Н	L	X	X	X	X	L	Н	H	Н	L	Н	H
С	Н	L		X	X	X	L	L	Н	L	Н	H	H
Ċ		L	X	X	X		L	Н	H	Н	Н	H	H
;													
	HOLD												
Ċ	Н	Н	Х	X	X	Х	L	Z	Z	Н	Н	Н	Н
~													

DESCRIPTION

THIS DEVICE IMPLEMENTS A SHIFT REGISTER. THE LAYOUT PROVIDED IS A DEMONSTRATION OF HOW THE SHIFT REGISTER MAY BE DESIGNED USING A PAL. 03862A-67

#### Table 3(a). Design Specification for Shift Register (Continued)

```
PAL DESIGN SPECIFICATION
PAL16R6
                       JENNY YEE
                              10/22/82
PATO23
SHIFT REGISTER
ADVANCED MICRO DEVICES
*D9724
*FO*
L0512 1011 1011 1111 1111 1111 1011 1111 1111 *
L1056 1011 0111 1111 1111 1111 1110 1111 1111.*
L1376 0111 0111 1111 1111 1111 1110 1111 1111 *
L1792 0111 1011 1111 1111 1111 1111 1111 *
L1824 1111 1111 1111 1111 1111 1110 1111 1111 *
C49E9*
VOOO1 COOOOOOXXOOZXLLLLXZ1 *
VOOO2 C11XXXXXXXOOZXLLLLXZ1 *
VOOO3 CO1XXXXXXXOO1XHLLLXL1 *
VOOO4 CO1XXXXXXOOOXLHLLXL1
VOOO5 CO1XXXXXXOOOXLLHLXL1 *
VOOO6 CO1XXXXXXXOOOXLLLHXH1
VOOO7 CO1XXXXXXOOOXLLLLXL1 *
VOO08 COO1111XXOOZXHHHHXZ1
VOOO9 C11XXXXXXOOZXHHHHXZ1 *
VOO10 C10XXXXXXOOHXHHHLXO1 *
VOO11 C10XXXXXXOOHXHHLHX11 *
VOO12 C10XXXXXXOOHXHLHHX11 *
VOO13 C10XXXXXXOOLXLHHHX11 *
VOO14 C10XXXXXXOOHXHHHHX11 *
VOO15 C11XXXXXXOOZXHHHHXZ1 *
5060
                                03862A-68
```



#### THE COUNTER

Counters are used for such purposes as state sequencing, delay timing, and event counting. The key to designing a counter is knowing when a bit should be toggled. For an upcounter, a bit is toggled whenever every bit of lesser significance is HIGH (see the counting sequence of Figure 18).

Conversely, for a down-counter, a bit is toggled whenever every bit of lesser significance is LOW. In both cases, the LSB is always toggled. By ANDing all bits of lesser significance along with the complement of the current data in the register, the problem of when this bit is to be toggled has been solved. However, this is not sufficient. In order to complete the design, it must be ensured that the bit remains unchanged under all other conditions. This can be accomplished by ORing the complements of the lesser significant bits together and then ANDing the result with the current data in the register (see Figure 19). The equation in Figure 19 can be changed into the sum-of-products form (Figure 20) for direct implementation in a PAL. Thus if a bit is to be toggled, the complement of the current data will be clocked in; if not, the data remains unchanged by clocking in the current data.

A 4-bit up-counter example illustrates this approach. Typical counter functions are loading data, counting, and "holding" data (COUNTING). The function table is shown in Figure 21 and the logic diagram in Figure 22.

Expanding the number of bits in the counter is done by expanding the function table to incorporate the additional bits. Karnaugh maps, although not essential, can be used to find the required equations in sum-of-products form for PAL implementation. In general, besides any fixed overhead for control functions (CLEAR, LOAD, and HOLD in this example) bit n will require n additional product terms. Therefore, if this example 4-bit counter is to be expanded to five bits, the fifth bit will require five product terms plus three additional product terms for clearing, loading, and counting (see Figure 23). Notice that the original 4-bit block is unaffected by the addition of the fifth bit. This basic counter is easily expandable to perform more complex functions. The Design Specification and Logic Diagram for this counter, using an AmPAL16R8 device, are shown in Tables 4(a) and 4(b).

CURRENT	NEXT	
STATE	STATE	
0000	0001	
0001	0010	
0010	0011	
0011	0100	
0100	0101	
0101	0110	
0110	0111	
0111	1000	
1000	1001	
1001	1010	
1010	1011	
1011	1100	
1100	1101	
1101	1110	
1110	1111	
1111	0000	03862A-70

Figure 18. Counting Sequence

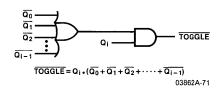
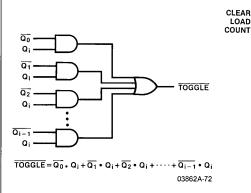


Figure 19. Logic for not Toggling Bit i



	INP	UTS				OUT	PUTS			
	S <sub>1</sub>	So	Q3 <sub>0</sub>	Q2 <sub>0</sub>	Q1 <sub>0</sub>	$Q0_0$	$Q_3$	$Q_2$	Q <sub>1</sub>	$Q_0$
CLEAR	0	0	Х	Х	Х	Х	0	0	0	0
LOAD	0	1	x	X	Х	Х	$D_3$	$D_2$	D <sub>1</sub>	$D_0$
COUNT	1	0	0	0	0	0	0	0	0	1
	1	0	0	0	0	1	0	0	1	0
	1	0	0	0	1	0	0	0	1	1
	1	0	0	0	1	1	0	1	0	0
	1	0	0	1	0	0	0	1	0	1
	1	0	0	1	0	1	0	1	1	0
	1	0	0	1	1	0	0	1	1	1
	1	0	0	1	1	1	1	0	0	0
	1	0	1	0	0	0	1	0	0	1
	1	0	1	0	0	1	1	0	1	0
	1	0	1	0	1	0	1	0	1	1
	1	0	1	0	1	1	1	1	0	0
	1	0	1	1	0	0	1	1	0	1
	1	0	1	1	0	1	1	1	1	0
	1	0	1	1	1	0	1	1	1	1
	1	0	1	1	1	1	0	0	0	0
HOLD	1	1	X	X	Х	Х	$Q3_0$	$Q2_0$	Q1 <sub>0</sub>	$Q0_0$

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Figure 20. Equivalent Form of Figure 16

Figure 21. Function Table for 4-Bit Up Counter

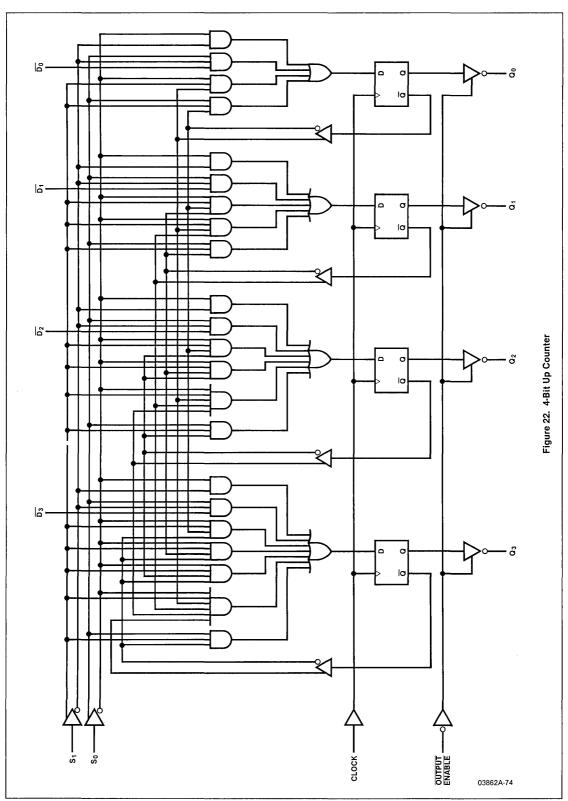


Figure 23. 5-Bit Up Counter

#### Table 4(a). Design Specification for 4-Bit Counter

```
PAL16R8
                                           PAL DESIGN SPECIFICATION
PATO21
                                           JENNY YEE 10/22/82
4-BIT COUNTER
ADVANCED MICRO DEVICES
CK S1 SO D4 D3 D2 D1 DO NC GND
OE NC NC NC QO Q1 Q2 Q3 NC VCC
; COUNTER OUTPUT SIGNALS
/Q0
         := /S1*/S0
                                     +
            /S1* S0*/D0
             S1*/S0* Q0
             S1* S0*/Q0
/01
         := /S1*/S0
            /S1* S0*/D1
             S1*/S0*/Q1*/Q0
             S1*/S0* Q1* Q0
             S1* S0*/01
/Q2
         := /S1*/S0
            /S1* S0*/D2
             S1*/S0*/Q2*/Q0
             S1*/S0*/Q2*/Q1
             S1*/S0* Q2* Q1* Q0
             S1* S0*/Q2
/Q3
       :=
            /S1*/S0
            /S1* S0*/D3
             S1*/S0*/Q3*/Q0
             S1*/S0*/Q3*/Q1
             S1*/S0*/Q3*/Q2
             S1*/S0* Q3* Q2* Q1* Q0 +
             S1* S0*/03
                                                            03862A-76
```

Table 4(a). Design Specification for 4-Bit Counter (Continued)

#### FUNCTION TABLE

CK S1	. S0	OE	DO	D1	D2		Q3 Q2 Q1 Q0
; CLEAF	- <b></b> -						
; C I	L	L	X	X	X	X	L L L
; LOAD							
C I	. H		H L	H L	H L	H L	H H H H L L L L
COUNT							
C H C H C H C H C H C C C H C C C H C C C H C C C H C C C H C C C H C C C C H C C C C H C C C C H C C C C C H C C	I L I L I L I L I L I L I L I L I L I L	L L L L L L L L	X X X X X X X X X X X X X X X X X X X	X X X X X X X X X X X X X X X X X X X		X X X X X X X X X X X X X X X X X X X	L L L H L L H L L L H H L L L L H H L H L L H L H L H L L H H L L L H L L H L L H L L H L H H L L L H L H H L L L H L H H L L L H L L H L L H L L H L L H L L H L L H L L H L L H L L H L L H L L H L L H L L H L L H L L L L
; HOLD ; C I	н н	L	Х	Х	X	Х	LLLL

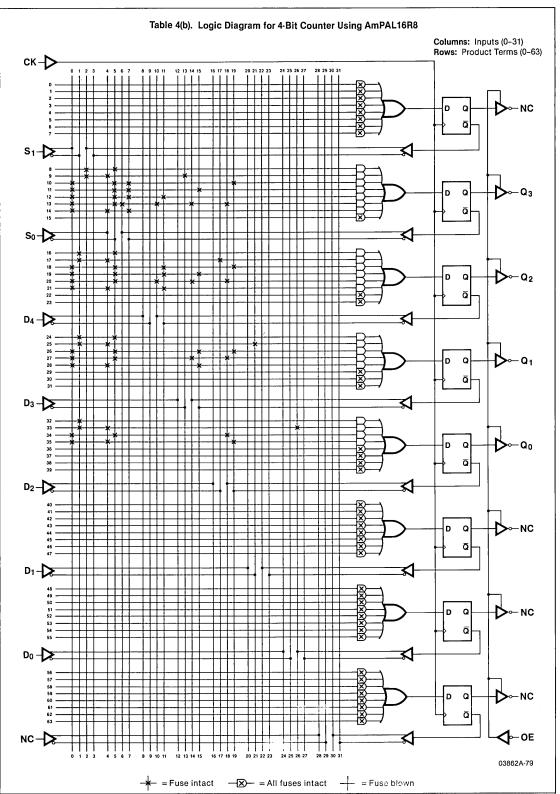
DESCRIPTION

THIS DEVICE IS AN UP-COUNTER. THE SAMPLE LAYOUT SHOWS THE FORMAT OF DESIGNING THE COUNTER USING A PAL.

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#### Table 4(a). Design Specification for 4-Bit Counter (Continued)

```
PAL16R8
                       PAL DESIGN SPECIFICATION
                       JENNY YEE 10/22/82
PATO21
4-BIT COUNTER
ADVANCED MICRO DEVICES
*D9724
*FO*
L0256 1011 1011 1111 1111 1111 1111 1111 *
L0384 0111 1010 1110 1111 1111 1111 1111 *
LO512 1011 1011 1111 1111 1111 1111 1111 *
L0800 1011 0111 1111 1111 1111 1011 1111 1111 *
L1056 1011 0111 1111 1111 1111 1111 1011 1111 *
C4FAE*
VOOO1 COOXXXXXXOOXXXLLLLX1 *
VOOO2 CO1X11111XOOXXXHHHHX1 *
V0003 C01X0000X00XXXLLLLX1 *
VOOO4 C10XXXXXXOOXXXHLLLX1 *
VOOO5 C10XXXXXXXOOXXXLHLLX1 *
VOOO6 C10XXXXXXOOXXXHHLLX1 *
VOOO7 C10XXXXXXOOXXXLLHLX1 *
VOOO8 C10XXXXXXOOXXXHLHLX1 *
VOOO9 C10XXXXXXOOXXXLHHLX1 *
VOO10 C10XXXXXXOOXXXHHHLX1 *
VOO11 C10XXXXXXOOXXXLLLHX1 *
VOO12 C10XXXXXXOOXXXHLLHX1 *
VOO13 C10XXXXXXOOXXXLHLHX1 *
VOO14 C10XXXXXXOOXXXHHLHX1 *
VOO15 C10XXXXXXOOXXXLLHHX1 *
VOO16 C10XXXXXXOOXXXHLHHX1 *
VOO17 C10XXXXXXOOXXXLHHHX1 *
VOO18 C10XXXXXXOOXXXHHHHX1 *
VOO19 C10XXXXXXOOXXXLLLLX1 *
VOO20 C11XXXXXXOOXXXLLLLX1 *
887C
                               03862A-78
```



## **Software Support** for AMD PALs



Design Aid Software for Programmable Logic PAL DESIGN SPECIFICATION

### Design Aid Software for Programmable Logic



#### INTRODUCTION

The main function of programmable logic design aid software is to translate a custom logic design specification into a format which can be accepted by a programmer.

Programmable logic software is also an excellent tool for design simulation and documentation. Simulation aids in debugging an initial design and helps to assure that a device will operate as intended the first time instead of requiring multiple design iterations. Documentation capability is essential for someone other than the original designer to understand a custom programmable logic specification.

#### THIRD PARTY SOFTWARE

Many different programmable logic design aid software programs and software programs resident on programmable logic programmers are available or under development. Table 1 lists some current suppliers of these design tools. Contact

the indicated companies for the status of their particular product.

#### **PALASM**

One particular software program, specifically for PALs, is PALASM (short for PAL ASSEMBLER).

PALASM is a computer aided design tool which has the capability of accepting an input file of Boolean equations and assembling the file into an output (fuse map) in a format compatible with PAL programmers. PALASM also allows the designer to input, in a tabular format, test vectors to perform simulation and debug of the Boolean equation input. The PAL design input file, called PAL DESIGN SPECIFICATION, when used in conjunction with PALASM documentation outputs, can provide as much documentation as is required to understand custom PAL design.

Table 1. Third Party Design Aid Software Tools

CUPL (Software) IBM PC

PALASM (Programmer Resident)

PALASM (Programmer Resident)

PALASM (Programmer Resident)

PALASM (Programmer Resident)

Assisted Technology, Inc. Suite 150 2381 Zanker Road San Jose, CA 95131 (408) 942-8787

Data I/O Corporation 10525 Willows Road N.E./C-46 Redmond, WA 98052

Digilec, Inc. 7335 East Acoma Drive STE. 103

(206) 881-6444

Scottsdale, AZ 85260 (602) 991-7268

Stag Microsystems, Inc. 528-5 Weddell Drive Sunnyvale, CA 94086 (408) 745-1991

Structured Design 1700 Wyatt Drive Suite 3 Santa Clara, CA 9

Santa Clara, CA 95054 (408) 988-0725

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#### AMPALASM20

Advanced Micro Devices offers a powerful, enhanced version of PALASM, called AMPALASM20 to support the AMD 20-pin PAL family. It is based on the original version of PALASM but adds extensive error checking features and the industry standard JEDEC output format PLDTF (Programmable Logic Data Transfer Format).

The new error checking functions insure that creation of a correct PAL DESIGN SPECIFICATION is an easily understood and straightforward process. Most important, AMPALASM20 does not allow the designer to create incorrect fuse patterns or try to program a device with inadequate logical capacity for the desired function. The JEDEC PLDTF output is designed to transfer data in a format which can program PALs from all manufacturers. This eliminates the need for the user to modify code to accommodate different supplier's devices.

AMPALASM20 is currently available on 8 inch floppy disk media in IBM 3740 format for the CP/M operating system. It is offered in both Fortran source code and object code versions. Advanced Micro Devices only supports object code written for 8080 based systems. Source code is provided for customers who wish to port AMPALASM20 to their particular system, but no support is furnished and no responsibility can be accepted for any use of source code information.

To use this version of AMPALASM20 the designer should have access to:

- —A microcomputer with a CP/M operating system
- -An 8 inch floppy disk drive (IBM 3740 format)
- -A CRT terminal with keyboard
- -System software which includes an editor
- A means of downloading the fuse programming data to a programmer

To perform automatic downloading of AMPALASM20 output to a PAL programmer, a link between the computer and the programmer is required. Most programmers accept input via an RS232 interface. This usually requires only an RS232 port, and RS232 cable from the computer and a software driver for the port, which are resident on most computers. Please refer to the programmer manufacturer's reference materials for details. The CP/M version of AMPALASM20 provides the necessary software driver.

Versions of AMPALASM20 for the IBM CMS operating system and VAX VMS operating system are under development. Check with your local Advanced Micro Devices sales office for price and availability.

A complete specification of the CP/M version AMPALASM20 and the PAL DESIGN SPECIFICATION input file appears later in Section 4.

# PAL DESIGN SPECIFICATION



The input to AMPALASM20 is called the PAL DESIGN SPECIFICATION. Since AMPALASM20 is a batch-oriented program, the PAL DESIGN SPECIFICATION is intended to be an input file created using the editing facility of the machine on which AMPALASM20 is executing. The PAL DESIGN SPECIFICATION is divided into five main sections: the heading, pin list, logic equations, function table, and description.

#### **HEADING**

The heading comprises the first four lines of the PAL DESIGN SPECIFICATION. Line one requires the left justified PAL part number starting in column one. Valid PAL part numbers supported by the present version of AMPALASM20 are the following:

AMPAL16L8 AMPAL16R8 AMPAL16R6 AMPAL16H8 AMPAL16LD8 AMPAL16HD8

An invalid part number will generate a fatal (nonrecoverable) error. The rest of the heading is optional, the following recommendations are standard.

The recommended heading "PAL DESIGN SPECIFICATION" should be included after the part number (separated by at least one space).

Lines two through four are reserved for design documentation. The recommended format for these lines is:

Line 2: User internal part number, date

Line 3: Device application name

Line 4: Company name, address

An example heading is given below:

AMPAL16R4 PAL DESIGN SPECIFICATION
PATTERN NUMBER K2/044-C WARREN MILLER 4/1/82
DUAL BUS 4-BIT COUNTER WITH BIT SWAPPABLE OUTPUTS
ADVANCED MICRO DEVICES 901 THOMPSON PLACE SUNNYVALE CA 94086

#### PIN LIST

The pin list must begin on line five. It is a sequence of symbolic names given to device pins 1 through 20 in order. Each pin name must be separated by one or more spaces. The following rules should be followed when specifying the pin list:

- (1) The pin list must contain exactly 20 names or a fatal error will be reported.
- (2) Pin names should not exceed 8 characters. If they do, only the last 8 characters will be used.
- (3) Any printable characters may be used in a pin name except "=: \* + ( );". A slash may be used as the first character in a pin name to indicate an active LOW input signal.
- (4) Duplicated pin names are allowed (for example, NC for No Connection), but only if they are not used in any equations.
- (5) GND and VCC may be usd on pins 10 and 20 respectively, but should not be used in any equations.

An example pin list is given below:

CLK CARRYIN ADATAO ADATA1 ADATA2 ADATA3 SO S1 RESET GND /OE BDATAO BDATA1 QO Q1 Q2 Q3 BDATA2 BDATA3 VCC

#### LOGIC EQUATIONS

Logic equations may begin on the first line after the pin list. These equations are the heart of the PAL DESIGN SPECIFICATION. They specify the logical operations of a device in a sum-of-products (AND-OR) Boolean format.

The terms used when writing logic equations are:

OPERATOR SYMBOLS (in hierarchy of evaluation):

- \* AND (product)
- + OR (sum)

EXPRESSION is a sequence of PIN NAMES (or their complements) separated by operators, where the PIN NAME is the symbolic input or output name taken from the pin list.

PRODUCT is a sequence of PIN NAMES (or their complements) separated by the AND operator, "\*", where the PIN NAME is the symbolic input or output name taken from the pin list.

#### ADDITIONAL SYMBOLS:

- ; The remainder of the present line is a comment
- / Complement, prefix to a pin name
- Combinatorial equality
- := Sequential equality

Three forms of logic equations are possible:

#### PIN NAME = EXPRESSION

Combinatorial equality. The output specified by the PIN NAME is logically equal to the expression. If the device has an inverting output, the complement of the PIN NAME must be specified.

#### IF (PRODUCT) PIN NAME = EXPRESSION

Conditional combinatorial equality. When the product is logically true, the output specified by PIN NAME is equivalent to the expression. When the product is logically false, the output is placed in the high impedance (high-Z) state. If the device has an inverting output, the complement of the PIN NAME must be specified.

#### PIN NAME : = EXPRESSION

Sequential equality. On the low to high transition of the clock, the registered output specified by the PIN NAME is loaded with the logical value defined by the equation. If the device has an inverting output, the complement of the PIN NAME must be specified.

It is important to notice that AMPALASM20 equations are written with respect to the AND inputs of the internal AND-OR structure. The only way to enable (output = HIGH) an AND-gate is with all HIGHs on the inputs. Therefore to enable an AND-gate when active LOW inputs (pin names with preceding slashes) are specified, the complement of the inputs (active HIGH or true version, without the slash) are necessary. Also, notice that to enable an AND-gate with active HIGH inputs the active HIGH version of the inputs is necessary (no slash). Thus the polarity of the input signals is written the same independent of the polarities of the pin names. It is, then merely a question of AMPALASM20 automatically selecting the inverting (active LOW) on non-inverting (active HIGH) path of the input buffer to the AND-gate.

It is also important to notice that the AMPALASM20 equations are written with respect to the output of the ORstructure in the combinatorial (16L8, 16H8, 16LD8, 16HD8) devices and at the Q outputs of the registers for the registered (16R8, 16R6, 16R4) devices. On the active LOW parts (16L8, 16LD8, 16R8, 16R6, 16R4) the output signals on the output pins are inverted versions of the internal, AMPALASM20 specified, OR-structure outputs. A warning is generated by AMPALASM20 if this inversion between pin list pin names and AMPALASM20 output pin names is not observed.

An example with a pin list and output equations is given below. Note the inversion between pin names and left hand sides of the equations, the use of sequential equality on registered outputs, and combinatorial equality on the non-registered outputs. Furthermore, note that an input such as RESET could be made active LOW by just adding a preceding slash "/" to the pin name (this tells PALASM 20 to select the inverting path of the input buffer).

```
RESET
CLK CARRYIN ADATAO ADATA1 ADATA2 ADATA3 SO S1
                                                           GND
/OE BDATAO BDATA1 QO
                           01
                                  Q2
                                          Q3 BDATA2 BDATA3 VCC
     /Q0 :=
                RESET
               /S1*/SO*/ADATAO
                                                :LOAD A
               /S1* SO*/BDATAO
                                                ; LOAD B
                S1* QO* CARRYIN
                                                ;COUNT
                S1*/Q0*/CARRYIN
     /Q1 :=
                RESET
               /S1*/S0*/ADATA1
                                                ;LOAD A
               /S1* SO*/BDATA1
                                                ;LOAD B
                                             +
                S1* Q1* QO* CARRYIN
                                                ;COUNT
                S1*/Q1*/Q0
                S1*/Q1*/CARRYIN
     /Q2 :=
                RESET
               /S1*/S0*/ADATA2
                                                ;LOAD A
               /S1* SO*/BDATA2
                                                :LOAD B
                S1* Q2* Q1* QO* CARRYIN
                                                ; COUNT
                S1*/02*/01
                S1*/Q2*/Q0
                S1*/O2*/CARRYIN
      /Q3 :=
                RESET
               /S1*/S0*/ADATA3
                                             +
                                                ; LOAD A
               /S1* SO*/BDATA3
                                             +
                                                ; LOAD B
                S1* Q3* Q2* Q1* Q0* CARRYIN +
                                                ;COUNT
                S1*/Q3*/Q2
                S1*/Q3*/Q1
                S1*/03*/00
                                             +
                S1*/Q3*/CARRYIN
IF( S1 ) /BDATAO = /SO*/QO
                                       ;ENABLE NORMAL
                     S0*/Q3
                                         ; ENABLE SWAPPED
                    /S0*/Q1
IF(S1)/BDATA1 =
                                      + ; ENABLE NORMAL
                     S0*/Q2
                                         ; ENABLE SWAPPED
IF(S1)/BDATA2 =
                    /S0*/Q2
                                      + ; ENABLE NORMAL
                     S0*/Q1
                                         ; ENABLE SWAPPED
                    /S0*/03
IF(S1)/BDATA3 =
                                      + ; ENABLE NORMAL
                     S0*/00
                                         ;ENABLE SWAPPED
```

#### **FUNCTION TABLE**

The function table portion of the PAL DESIGN SPECIFICA-TION is similar to the familiar truth table found in most TTL data books. It defines, in a tabular format, how the device is to function. Additionally, the function table is used by the SIMULATE function to check a PAL DESIGN for correctness. BULLATE will take the vector specified in the function table and "plug it into" the equation portion of the PAL DESIGN SPECIFICATION.

Any discrepancy between the computed values and the function table values will be flagged by the output of SIMULATE. Besides catching the most common errors (signal inversions and typing errors), it also provides a check on the more subtle logic errors. The more detailed the function table, the higher the confidence level that the device will function as desired.

For combinatorial PALs, by using the input values specified in a function table line, the outputs may be computed against the output values listed in the same line of the table. For registered PALs, the present state (before clock) of the registers may also be necessary to compute and check the next state (after clock) outputs. The function table defines the present state outputs to be the registered outputs of the previous vector (i.e., line) and next state outputs to be in the current vector (line) with the present inputs. Note that the first vector in a function table has no present state and therefore cannot be dependent upon one. Also note that the combinatorial outputs of registered PALs are defined as a function of the present inputs and next state outputs.

The function table format is given below:

FUNCTION	TABLE:	(pin list)
		d
••••		d

The beginning of the function table is defined by the text "FUNCTION TABLE:". This identifier must begin in column 1. Following the function table, on the next line, is a pin list which defines the order of function table entries. This pin list must use the same signal names as the pin list at the beginning of the equation section of AMPALASM20. However, either the true or complement of the signal may be specified. Additionally, the order of entries need not be the same between the two pin lists.

Following the pin list is a dashed line of any length, which specifies the beginning of the body of the function table. Each entry in the function table indicates the forced state (in the case of inputs) or the checked state (in the case of outputs). A full line in the function table represents a test vector. A state (e.g., L, H, C, X, Z) must be specified for each pin name, with separating spaces optional. Optional comments may follow the vector. An entire line may be commented if the first

character of the line is a semi-colon ";". The definitions for inputs and outputs in the function table are:

#### For inputs:

- L indicates drive input to a logical LOW
- H indicates drive input to a logical HIGH
- C indicates drive input to a logical LOW, then to a logical HIGH (clock)
- X indicates an irrelevant input (treated as drive to a logical LOW)

#### For outputs:

- L indicates test output for a logical LOW
- H indicates test output for a logical HIGH
- Z indicates test output for a logical HIGH impedance
- X indicates don't test

A function table for the sample device in the equations section is shown on the following page. The sample device equations implement a 4-bit loadable up counter. The counter is loadable from both the ADATA and BDATA ports. The counter outputs are available on both the three-state Q output and the BDATA port. When enabled onto the BDATA port either the normal output ( $Q_3$ ,  $Q_2$ ,  $Q_1$ ,  $Q_0$ ) or a swapped output ( $Q_0$ ,  $Q_1$ ,  $Q_2$ ,  $Q_3$ ) is available.

Note that the function table pin list does not maintain the same order as the device pinout. This allows the table to be laid out in a logical manner and be easily read and understood. Also note that the pin list is defined with the same polarity as the device pinout. This makes the table more like a "black box" definition of how the device will work. In general, the complement version of the device pinout is more desirable in the list only when internal state variables or multilevel logic is defined in the device. This is because these functions are intermediate and have nothing to do with the "black box" definition, and also because the true version of internal points of a PAL is usually the complement of the pinout (it's easier to read).

The first test vector of the function table checks the output disable function. This is done by driving the OE signal HIGH (H) and checking the Q outputs for the disabled state (Z). The second vector tests the reset function. The RESET signal is driven LOW (L), OE is LOW (L) and the clock input is clocked (C). The resulting Q outputs should be LOW (L).

The next two function table entries load the A and B ports respectively. This is done by selecting the load operations (LL and LH select codes) and checking that the correct value is clocked into the register.

The next 16 function table entries check the increment and B outputs functions. The first 7 vectors check the normal B output, the last 9 check the swapped B output. It is important to realize that the next state value of registered outputs can depend on both the inputs and the previous state (from the previous line) of the register. For example, the first entry in the increment section uses the previous value of the register (LLLL) as an input. This is incremented to the new value (LLLH). The next vector then uses that register state (LLLH) for the starting value of the test.

```
CLK ADATA3 ADATA2 ADATA1 ADATAO BDATA3 BDATA2 BDATA1 BDATAO
/RESET S1 SO CARRYIN /OE Q3 Q2 Q1 Q0
                        C
   AAAA BBBB
                        Α
                        R
   DDDD
          DDDD
                 R
                        R
   AAAA
          AAAA
                  Ε
   Τ
    Т
      ТТ
          TTTT
                  S
                        Y
          AAAA
                  Ε
                    SS
                        Ι
                           0
                             QQQQ
   AAAA
          3 2 1 0
                 Τ
                    1 0
                        N
                           Ε
                             3 2 1 0
                                        COMMENTS
X
  X X X X X X X X X X
                   ХХ
                       х н
                           Z Z Z Z ;OUTPUT DISABLE
Ċ
  HHHHHHHLLLL L LLLL; RESET
  HHHHLLLL H LL L L HHHH ; LOAD A
  HHHH LLLL H LH L L LLLL
                                   ;LOAD B
                         L L L L H ; INCREMENT WITH
  X X X X
         LLLH H
                   ΗL
                       Η
  X X X X
         LLHL
                         LLLHL
                                   B NORMAL
                 Η
                   H L
                       Η
```

H L

H L

H L

HH H L HHHH

X X X X L L L H H L L L L L L L ; DISABLE INCREMENT

H L LLLL

H L H L

н н

н н

HH H L

ΗL

LLHH

LHLL

LHLH

LHHL

I. H H H

HLLL

HLLH

HLHL

H L H H

HHLL

HHLH

HHHL

; INCREMENT WITH

;B SWAPPED

### PAL DESCRIPTION

FUNCTION TABLE:

 $X \quad X \quad X \quad X$ 

X X X X

 $X \quad X \quad X \quad X$ 

X X X X

X X X X

X X X X

 $X \quad X \quad X \quad X$ 

X X X X

X X X X

X X X X

 $X \quad X \quad X \quad X$ 

X X X X

X X X X

C

С

С

C

LLHH

LHLL

LHHL

LHHH

LLLH

HLLH

LHLH

HHLH

LLHH

HLHH

XXXX LLLL H

LHHH H

нини н

LHLH H

HHLHL

HHL

HHLHL

HHLHL

HHHHL

HHHHL

H H H H L

H H H H I.

Η

Η

The description section of the PAL DESIGN SPECIFICATION is an important documentation tool. In this section the designer can describe the operation of the device and its intended application. If this section is done correctly the PAL DESIGN SPECIFICATION becomes a data sheet for the newly created device, completely documenting the design. The format for the description section is simply the keyword DESCRIPTION: followed by the text describing the design. An example description is given below:

DESCRIPTION: THIS PAL IMPLEMENTS A 4-BIT COUNTER FOR A MULTIPLE BUS CPU. THE COUNTER CAN BE LOADED FROM EITHER THE ADATA INPUT BUS OR THE BDATA INPUT-OUTPUT BUS. THE CONTENTS OF THE COUNTER CAN BE OUTPUT TO THE THREE STATE Q BUS OR THE BDATA INPUT-OUTPUT BUS. ADDITIONALLY WHEN THE BDATA BUS IS USED TO OUTPUT THE COUNTER CONTENTS EITHER A BIT-NORMAL OR A BIT-REVERSED VERSION CAN BE SELECTED.

MODE DEFINITIONS ARE GIVEN BELOW.

				:	S1	SO	CARRY-IN
LOAD A					0	0	X
LOAD B					0	1	X
HOLD,	OUTPUT	В	NORMAL		1	0	0
COUNT,	OUTPUT	В	NORMAL		1	0	1
HOLD,	OUTPUT	В	SWAPPED		1	1	0
COUNT,	OUTPUT	В	SWAPPED		1	1	1

#### **EXAMPLE**

The following pages contain the complete PAL DESIGN SPECIFICATION for the example used in the previous sections.

```
AMPAL16R4
                                        PAL DESIGN SPECIFICATION
PATTERN NUMBER K2/044-C
                                           WARREN MILLER 4/1/82
DUAL BUS 4-BIT COUNTER WITH BIT SWAPPABLE OUTPUTS
ADVANCED MICRO DEVICES 901 THOMPSON PLACE SUNNYVALE CA 94086
CLK CARRYIN ADATAO ADATA1 ADATA2 ADATA3 SO S1
                                                RESET GND
OE BDATAO BDATA1 QO Q1 Q2 Q3 BDATA2 BDATA3 VCC
     /Q0 :=
               RESET
              /S1*/SO*/ADATAO
                                            ;LOAD A
                                          + ;LOAD B
              /S1* SO*/BDATAO
               S1* OO* CARRYIN
                                            ;COUNT
               S1*/QO*/CARRYIN
     /01 :=
               RESET
              /S1*/S0*/ADATA1
                                             ; LOAD A
              /S1* SO*/BDATA1
                                          + ; LOAD B
               S1* Q1* QO* CARRYIN
                                          + ;COUNT
               S1*/Q1*/Q0
               S1*/Q1*/CARRYIN
     /Q2 :=
               RESET
                                           + ;LOAD A
               /S1*/SO*/ADATA2
               /S1* SO*/BDATA2
                                           + ;LOAD B
               S1* Q2* Q1* QO* CARRYIN
                                          + ; COUNT
               S1*/Q2*/Q1
               S1*/Q2*/Q0
               S1*/O2*/CARRYIN
      /03 :=
               RESET
               /S1*/SO*/ADATA3
                                              ; LOAD A
               /S1* SO*/BDATA3
                                             ;LOAD B
               S1* Q3* Q2* Q1* Q0* CARRYIN +
                                             ; COUNT
               S1*/Q3*/Q2
               S1*/Q3*/Q1
               S1*/03*/00
               S1*/Q3*/CARRYIN
IF(S1)/BDATAO = /SO*/QO
                                   + ; ENABLE NORMAL
                    S0*/Q3
                                       ; ENABLE SWAPPED
IF(S1)/BDATA1 = /S0*/Q1
                                    + ; ENABLE NORMAL
                    S0*/Q2
                                       :ENABLE SWAPPED
IF(S1)/BDATA2 = /SO*/Q2
                                    + :ENABLE NORMAL
                    S0*/Q1
                                       ; ENABLE SWAPPED
IF(S1)/BDATA3 = \sqrt{S0*/Q3}
                                  + :ENABLE NORMAL
                    S0*/Q0
                                       ; ENABLE SWAPPED
```

FUNCTION TABLE:
CLK ADATA3 ADATA2 ADATA1 ADATAO BDATA3 BDATA2 BDATA1 BDATAO
/RESET S1 SO CARRYIN /OE Q3 Q2 Q1 Q0

```
AAAA BBBB /
                      Α
  D D D D D D D D R
                      R
  AAAA
         A A A A
                Ε
                      R
;C
  тттт
         тттт
                S
                      Y
                  SSI
 AAAA AAAA E
                        0 QQQQ
  3 2 1 0 3 2 1 0 T 1 0 N E 3 2 1 0
                                    COMMENTS
X X X X X X X X X X X X X X H Z Z Z Z ;OUTPUT DISABLE
 HHHHHHHLLLL LLLL ; RESET
 HHHH LLLL H LL L L HHHH ; LOAD A
  HHHH LLLL H LH L L LLLL ; LOAD B
  XXXX LLLH H H L L L L L H ; INCREMENT WITH
  XXXX LLHL H HL H L LLHL ; B NORMAL
  X X X X
        LLHH H
                  H L H
                       LLLHH
        LHLL H HL H L LHLL
  X X X X
C
  X \quad X \quad X \quad X
        LHLH H HL H L LHLH
  XXXX LHHL H HL
                     H L LHHL
  XXXX LHHH H H L
                      H L LHHH
C
  XXXX LLLH
               н н н
                      Н
                       L H L L L ; INCREMENT WITH
                       L H L L H ; B SWAPPED
C
  X \quad X \quad X \quad X
        HLLH
               н н н
                      Н
                       LHLHL
  X X X X
         LHLH
               H
                  н н
                      Η
  X \quad X \quad X \quad X
        HHLH
               Н
                  Н Н
                     Н
                       LHLHH
C
  X X X X
        LLHH
               н н н
                     H L HHLL
C
  XXXX HLHH H HH H L HHLH
  XXXX LHHH H HH
                     H L HHHL
  XXXX H H H H H H H L H H H H
 XXXX LLLL H HL H L LLLL
 XXXX LLLL H H L L L L L L ; DISABLE INCREMENT
```

DESCRIPTION: THIS PAL IMPLEMENTS A 4-BIT COUNTER FOR A MULTIPLE BUS CPU. THE COUNTER CAN BE LOADED FROM EITHER THE ADATA INPUT BUS OR THE BDATA INPUT-OUTPUT BUS. THE CONTENTS OF THE COUNTER CAN BE OUTPUT TO THE THREE STATE Q BUS OR THE BDATA INPUT-OUTPUT BUS. ADDITIONALLY WHEN THE BDATA BUS IS USED TO OUTPUT THE COUNTER CONTENTS EITHER A BIT-NORMAL OR A BIT-REVERSED VERSION CAN BE SELECTED.

#### MODE DEFINITIONS ARE GIVEN BELOW.

				SI	SU	CARRY-IN
LOAD A				0	0	X
LOAD B				0	1	X
HOLD,	OUTPUT	В	NORMAL	1	0	0
COUNT,	OUTPUT	В	NORMAL	1	0	1
HOLD,	OUTPUT	В	SWAPPED	1	1	0
COUNT,	OUTPUT	В	SWAPPED	1	1	1

#### AMPALASM20 COMMANDS (CP/M Version)

AMPALASM20 contains several different commands which simplify the design process. These commands not only translate the PAL DESIGN SPECIFICATION into a format useable by a programmable logic device programmer, but also help in checking designs for correctness and assist in design documentation. The list of AMPALASM20 commands appears below. A detailed description of each command follows the list.

JEDEC:

Creates a fuse map in the JEDEC standard PLDTF from the PAL DESIGN SPECIFICA-

TION and stores it on disk.

SIMULATE: Simulates the Boolean equation input by comparing it with a user created table of test vectors in the PAL DESIGN SPECIFICATION, called the FUNCTION TABLE. Following simulation, a JEDEC standard PLDTF output with fuse map and test vectors is created.

ECHO:

Prints a copy of the PAL DESIGN

SPECIFICATION.

PLOT:

Prints a graphic representation of the programmed PAL fuse map.

NEXT:

Loads a new file from the disk to be assembled. This allows multiple files to be assembled in a single session.

CHANGE: Changes the output destination to either the

CRT, disk or programmer.

QUIT:

Quit AMPALASM20 and return to native operating system.

#### JEDEC STANDARD PROGRAMMABLE LOGIC DATA TRANSFER FORMAT "J"

The Joint Electron Devices Engineering Council (JEDEC) programmable logic data transfer format (PLDTF) is a universal transfer format for fuse and test information between hosts and intelligent device programmers. This format is an industry standard used by many commercial programmer manufacturers. It gives each fuse a unique decimal address (specified in a logic diagram schematic) and indicates the state of each fuse for the programmed part. The format consists of four main sections: the design specification identifier, fuse link information, structured functional test information, and the sumcheck. The output of this command is a fuse map ready to be downloaded to a PAL programmer.

Details of the various sections of the PLDTF are available in Appendix A for the interested user.

An example of the JEDEC transfer format is shown on the next page. All fields except the structured test vectors are shown. The structured vectors are only created from AMPALASM20 following the SIMULATE command (explained

#### ENTER PAL2O OPTION: J

```
AMPAL16R4
                              PAL DESIGN SPECIFICATION
PATTERN NUMBER K2/044-C
                                 WARREN MILLER 4/1/82
DUAL BUS 4-BIT COUNTER WITH BIT SWAPPABLE OUTPUTS
ADVANCED MICRO DEVICES 901 THOMPSON PLACE SUNNNYVALE CA 94086
*D9724
*F0*
L0000 1111 1111 1111 1111 1111 1111 0111 1111 *
L0064 1111 1111 1111 1111 1111 0110 1111 1111 *
LO256 1111 1111 1111 1111 1111 1111 0111 1111 *
LO288 1111 1111 1111 1110 1111 1011 1111 1111 *
L0576 1110 1111 1111 1111 1111 0111 1011 1111 *
L0608 0111 1111 1101 1101 1101 1101 0111 1111 *
L0640 1111 1111 1110 1110 1111 1111 0111 1111 *
L0672 1111 1111 1110 1111 1110 1111 0111 1111 *
L0704 1111 1111 1110 1111 1111 1110 0111 1111 *
LO736 1011 1111 1110 1111 1111 1111 0111 1111 *
LO768 1111 1111 1111 1111 1111 1111 1111 0111 *
L0832 1111 1110 1111 1111 1111 0111 1011 1111 *
L0864 0111 1111 1111 1101 1101 1101 0111 1111 *
L0896 1111 1111 1111 1110 1110 1111 0111 1111 *
L0928 1111 1111 1111 1110 1111 1110 0111 1111 *
L0960 1011 1111 1111 1110 1111 1111 0111 1111 *
L1088 1111 1111 1111 1111 1111 0111 1010 1111 *
L1120 0111 1111 1111 1111 1101 1101 0111 1111 *
L1152 1111 1111 1111 1111 1110 1110 0111 1111 *
L1184 1011 1111 1111 1111 1110 1111 0111 1111 *
L1344 1111 1111 1111 1111 1111 0111 1011 1110 *
L1376 0111 1111 1111 1111 1101 0111 1111 *
L1408 1011 1111 1111 1111 1111 1110 0111 1111 *
L1536 1111 1111 1111 1111 1111 1111 0111 1111 *
L1600 1111 1111 1111 1110 1111 0111 1111 1111 *
L1792 1111 1111 1111 1111 1111 1111 0111 1111 *
L1824 1111 1111 1111 1111 1111 1010 1111 1111 *
C8C36*
89A3
```

#### SIMULATE "S"

The SIMULATE command uses the function table entries and the logic equations to emulate the operation of the specified device. Any difference between the expected value (computed value) and the actual value (function table value) is flagged as a fatal error. The output format follows the JEDEC Programmable Logic Data Transfer Format as described previously under the JEDEC output format command. This output may be used by intelligent device programmers to program and test programmable logic devices, verifying logical functionality. An example output of the SIMULATE command is given below:

ENTER PAL20 OPTION: S

```
AMPAL16R4
                                 PAL DESIGN SPECIFICATION
PATTERN NUMBER K2/044-C
                                    WARREN MILLER 4/1/82
DUAL BUS 4-BIT COUNTER WITH BIT SWAPPABLE OUTPUTS
ADVANCED MICRO DEVICES
                    901 THOMPSON PLACE SUNNNYVALE CA 94086
*D9724
*F0*
L0000 1111 1111 1111 1111 1111 1111 0111 1111 *
L0064 1111 1111 1111 1111 1111 0110 1111 1111
LO256 1111 1111 1111 1111 1111 1111 0111 1111 *
L0288 1111 1111 1111 1110 1111
                         1011 1111
L0576 1110 1111 1111 1111 1111 0111 1011 1111
L0608 0111 1111 1101 1101 1101 1101 0111 1111 *
L0640 1111 1111 1110 1110 1111 1111 0111 1111
L0672 1111 1111 1110 1111 1110 1111 0111 1111 *
L0704 1111 1111 1110 1111 1111 1110 0111 1111 *
L0736 1011 1111 1110 1111 1111 1111 0111 1111
L0768 1111 1111 1111 1111 1111 1111 1111 0111
L0832 1111 1110 1111 1111 1111 0111 1011 1111
L0864 0111 1111 1111 1101 1101 1101 0111 1111
L0896 1111 1111 1111 1110 1110 1111 0111 1111
L0928 1111 1111 1111 1110 1111 1110 0111 1111
L0960 1011 1111 1111 1110 1111 1111 0111 1111
L1088 1111 1111 1111 1111 1111 0111 1010 1111
L1120 0111 1111 1111 1111 1101 1101 0111 1111
L1152 1111 1111 1111 1111 1110 1110 0111 1111
L1184 1011 1111 1111 1111 1110 1111 0111 1111 *
L1344 1111 1111 1111 1111 1111 0111 1011 1110 *
L1376 0111 1111 1111 1111 1111 1101 0111 1111 *
L1408 1011 1111 1111 1111 1111 1110 0111 1111 *
L1536 1111 1111 1111 1111 1111 1111 0111 1111 *
L1600 1111 1111 1111 1110 1111 0111 1111 1111 *
L1792 1111 1111 1111 1111 1111 0111 1111 *
L1824 1111 1111 1111 1111 1111 1010 1111 1111 *
C8C36*
VOOO1 XXXXXXXXXXO1XXZZZXXX1 *
V0002 C011110010011LLLL1111 *
V0003 C0111100000000HHHH001 *
V0004 C011111000000LLLL001 *
VOOO5 C1XXXXO1000HLHLLLLL1 *
VOOO6 C1XXXXO1000LHLHLLLL1 *
VOOO7 C1XXXXO1OOOHHHHLLLL1 *
VOOO8 C1XXXXO1000LLLHLHL1 *
V0009 C1XXXX01000HLHLHLHL1 *
V0010 C1XXXX01000LHLHHLHL1 *
VOO11 C1XXXXO1OOOHHHHHLHL1 *
VOO12 C1XXXX11000HLLLLHLL1 *
V0013 C1XXXX11000HLHLLHLH1 *
V0014 C1XXXX11000HLLHLHHL1 *
V0015 C1XXXX11000HLHHLHHH1 *
V0016 C1XXXX11000HHLLHHLL1 *
VOO17 C1XXXX11000HHHLHHLH1 *
V0018 C1XXXX11000HHLHHHHL1 *
VOO19 C1XXXX11000HHHHHHHH1 *
V0020 C1XXXX01000LLLLLLLL *
VOO21 COXXXX01000LLLLLLLL1 *
1B05
```

#### ECHO "E"

The ECHO command displays the PAL DESIGN SPECIFICATION input file on the console. This mode allows the file to be reviewed for correctness or spooled to a listing device as a hard copy. An example of the ECHO command is given below:

#### ENTER PAL2O OPTION: E

```
AMPAL16R4
                                       PAL DESIGN SPECIFICATION
PATTERN NUMBER K2/044-C
                                           WARREN MILLER 4/1/82
DUAL BUS 4-BIT COUNTER WITH BIT SWAPPABLE OUTPUTS
ADVANCED MICRO DEVICES 901 THOMPSON PLACE SUNNYVALE CA 94086
CLK CARRYIN ADATAO ADATA1 ADATA2 ADATA3 SO S1
                                                RESET GND
                                       Q3 BDATA2 BDATA3 VCC
OE BDATAO BDATA1 QO Q1 Q2
     /00 :=
               RESET
               /S1*/SO*/ADATAO
                                          + ;LOAD A
               /S1* SO*/BDATAO
                                          + ;LOAD B
               S1* QO* CARRYIN
                                          + ; COUNT
               S1*/QO*/CARRYIN
     /Q1 :=
               RESET
               /S1*/S0*/ADATA1
                                           + :LOAD A
               /S1* S0*/BDATA1
                                           + ;LOAD B
               S1* Q1* QO* CARRYIN
                                         + ;COUNT
                S1*/Q1*/Q0
                S1*/Q1*/CARRYIN
     /Q2 :=
               RESET
               /S1*/SO*/ADATA2
                                            ;LOAD A
                                            ;LOAD B
               /S1* SO*/BDATA2
                S1* Q2* Q1* QO* CARRYIN
                                           +
                                              ;COUNT
                S1*/Q2*/Q1
                S1*/Q2*/Q0
                S1*/O2*/CARRYIN
      /Q3 :=
               RESET
               /S1*/S0*/ADATA3
                                             :LOAD A
               /S1* SO*/BDATA3
                                            ;LOAD B
                S1* Q3* Q2* Q1* Q0* CARRYIN + ;COUNT
                S1*/03*/02
                                           +
                S1*/Q3*/Q1
                                           +
                S1*/03*/00
                S1*/Q3*/CARRYIN
IF(S1)/BDATAO = /SO*/OO
                                   + ;ENABLE NORMAL
                    S0*/Q3
                                       ; ENABLE SWAPPED
IF(S1)/BDATA1 = /S0*/Q1
                                   + ;ENABLE NORMAL
                    S0*/Q2
                                      ;ENABLE SWAPPED
IF(S1) /BDATA2 = /SO*/Q2
                                   + ;ENABLE NORMAL
                    S0*/01
                                       ; ENABLE SWAPPED
IF( S1 ) /BDATA3 = /SO*/Q3 + ;ENABLE NORMAL SO*/Q0 ;ENABLE SWAPPER
                                       ; ENABLE SWAPPED
```

FUNCTION TABLE:
CLK ADATA3 ADATA2 ADATA1 ADATAO BDATA3 BDATA2 BDATA1 BDATAO
/RESET S1 SO CARRYIN /OE Q3 Q2 Q1 Q0

```
AAAA BBBB
                       Α
   D D D D D D D
                R
                       R
   A A A A
         AAAA
                Ε
                       R
  TTTT
         TTTT
                S
                       Y
  A A A A
         A A A A
                Ε
                  SS
                      Ι
                         0
                           QQQQ
  3 2 1 0 3 2 1 0 T
                         F.
                           3 2 1 0
                  10 N
                                     COMMENTS
X X X X X X X X X X X X X X H Z Z Z Z :OUTPUT DISABLE
C H H H H H H H H L L L L L L L L : RESET
 HHHH LLLL H LL L HHHH :LOAD A
 HHHH LLLL H LH L L LLLL ;LOAD B
C
  X X X X L L L H H H L H L L L L H ; INCREMENT WITH
                                 ;B NORMAL
  XXXX LLHL H HL H L LLHL
  XXXX LLHH
               Η
                  ΗL
                      H L L L H H
  X X X X
         LHLL
                Н
                  H L
                      Η
                        L
                          LHLL
  XXXX
         LHLH
               Н
                  H L
                      Н
                        L
                          L H L H
С
  X X X X
        LHHL
               H H L
                      H L LHHL
С
  XXXX LHHH H HL
                      H L L H H H
                                 ; INCREMENT WITH
  XXXX LLLH H H H H
                      H L HLLL
 XXXX H L L H H H H H L H L L H ; B SWAPPED
С
  X X X X
         L H L H
                      H L H L H L
               Н
                  ΗН
  X X X X
C
        HHLH
               Н
                  нн
                      H L
                          HLHH
С
  X X X X
        LLHH
               н нн
                     H L H H L L
С
  X X X X
        ніннн
                  н н
                     H L H H L H
  XXXX LHHH H
                  ΗН
                      H L H H H L
  XXXX H H H H H H H L H H H H
  XXXX LLLL H HL
                      H L LLLL
 XXXX LLLL H H L L L L L L :DISABLE INCREMENT
```

DESCRIPTION: THIS PAL IMPLEMENTS A 4-BIT COUNTER FOR A MULTIPLE BUS CPU. THE COUNTER CAN BE LOADED FROM EITHER THE ADATA INPUT BUS OR THE BDATA INPUT-OUTPUT BUS. THE CONTENTS OF THE COUNTER CAN BE OUTPUT TO THE THREE STATE Q BUS OR THE BDATA INPUT-OUTPUT BUS. ADDITIONALLY WHEN THE BDATA BUS IS USED TO OUTPUT THE COUNTER CONTENTS EITHER A BIT-NORMAL OR A BIT-REVERSED VERSION CAN BE SELECTED.

#### MODE DEFINITIONS ARE GIVEN BELOW.

				S1	S0	CARRY-IN
LOAD A				0	0	X
LOAD B			,	0	1	X
HOLD,	OUTPUT	B	NORMAL	1	0	0
COUNT,	OUTPUT	В	NORMAL	1	0	1
HOLD,	OUTPUT	В	SWAPPED	1	1	0
COUNT,	OUTPUT	В	SWAPPED	1	1	1

#### PLOT "P"

The PLOT command displays a graphical representation of the location of blown and intact fuses defined in the PAL DESIGN SPECIFICATION. It is oriented similarly to the fuse map in the PAL logic diagram; inputs from top to bottom, product terms from left to right. Additionally, the equation is displayed to the right of each product term. A cross "X" indicates an intact link and a dash " — " indicates a blown link for the appropriate input line. An example plot is given below:

ENTER PAL2O OPTION: P

```
DUAL BUS 4-BIT COUNTER WITH BIT SWAPPABLE OUTPUTS
        11 1111 1111 2222 2222 2233
 0123 4567 8901 2345 6789 0123 4567 8901
1 ---- --- /S0*/Q3
2 ---- --- S0*/Q0
7 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
9 ---- --- /S0*/Q2
10 ---- --- S0*/Q1
15 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
              --- X--- RESET
17 ---- --- /S1*/S0*/ADATA3
18 ---x ---- /S1*S0*/BDATA3
19 X--- --- -X- -X- -X- X--- S1*Q3*Q2*Q1*Q0*CARRYIN
20 ---- X--- S1*/Q3*/Q2
21 ---- S1*/Q3*/Q1
22 ---- S1*/Q3*/Q0
23 -X-- --- X --- --- X --- S1*/Q3*/CARRYIN
24 --- X-- RESET
25 --- -X- -X- -X- -X- -X- /S1*/S0*/ADATA2
26 --- -X --- -X --- -X- -X- -X- /S1*S0*/BDATA2
27 X--- --- S1*Q2*Q1*Q0*CARRYIN
28 --- --- --- X --- X --- X --- X --- S1*/Q2*/Q1
29 --- --- X --- X X --- S1*/Q2*/Q0
30 -X --- --- S1*/Q2*/CARRYIN
--- --- X--- RESET
33 ---- -X-- -X-- -X-- -X-- -X-- /S1*/S0*/ADATA1
34 ---- -X-- -X-- X--- /S1*S0*/BDATA1
35 X--- --- S1*Q1*Q0*CARRYIN
36 ---- S1*/Q1*/Q0
37 -X-- --- S1*/Q1*/CARRYIN
40 --- X-- RESET
41 --- X- --- --- X-- X-- KS1*/S0*/ADATAO
42 --- X-- X-- X-- X/S1*S0*/BDATAO
43 X--- --- S1*Q0*CARRYIN
44 -X-- --- S1*/Q0*/CARRYIN
49 ---- /S0*/Q1
50 ---- x -x --- x ---- /S0*/Q1
54 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
57 ---- ---- /S0*/Q0
58 ---- --- S0*/03
59 XXXX XXXX XXXX XXXX XXXX XXXX XXXX
LEGEND: X : FUSE NOT BLOWN (L,N,O) - : FUSE BLOWN (H,P,1)
NUMBER OF FUSES BLOWN = 1120
```

#### NEXT "N"

The NEXT command loads a new file from the disk to be assembled. This allows multiple files to be assembled in a single session.

Enter PALASM20 Option: N

Enter PAL DESIGN SPEC Input Filename: DMC.PAL

**Output Destination:** 

D = DISK

C = CRT

P = PROGRAMMER (PUN)

Enter Destination: C

ASSEMBLY SUCCESSFUL!

#### **CHANGE "C"**

The CHANGE command reassigns the output destination to either the CRT, disk or programmer.

Enter PALASM20 Option: C

Output Destination:

D = DISK

C = CRT

P = PROGRAMMER (PUN)

Enter Destination: C

#### QUIT "Q"

The QUIT command transfers control back to the native operating system.

Enter PALASM20 Option: Q

#### **ERROR MESSAGES**

#### Introduction

AMPALASM20 may produce error messages when improper PAL description files are processed. Three types of error messages are possible: warnings, errors, or fatal errors. Examples of typical error messages are given below. Details of others are provided on AMPALASM20 HELP file.

#### Warning Messages

Warnings are used to notify the user that an oversight may have been made when the PAL description file was created. A warning will not prohibit creation of an output file, but the user should check the warnings before programming a device to insure that the output matches the intended device definition.

#### DESCRIPTION:

You do not have to use VCC or GND in the equation. Try to delete it.

777777777777777777777777777777777777777	79999999999999999999999999999999999	777777
%		%
% ****WARNING****	THE FUNCTION TABLE IS OMITTED	%
%	PREVENTING SIMULATION!	%
%		%
777777777777777777777777777777777777777	799999999999999999999999999999999999999	7%%%%%%

#### **Error Messages**

Errors are used to notify the user that an illegal operation has been requested during execution of AMPALASM20. For example if an illegal file is requested as input to or output from AMPALASM20, an error message will be displayed.

#### **DESCRIPTION:**

Physical read error.

#### DESCRIPTION:

The program cannot find the input file specified; you have to reenter an existing input file name.

#### Fatal Error Messages

Fatal errors are used to notify the user that a nonrecoverable error exists in a PAL description file. These errors prohibit output file creation and must be corrected by the user prior to re-running AMPALASM20.

#### DESCRIPTION:

This occurs because AMPALASM20 cannot recognize the PAL part you specify in the first line, note that the first line must begin with PAL, AMPAL, AmPAL, otherwise will activate this fatal error. Check your input file!

#### DESCRIPTION:

A pin name is missed between the specified pin name and following operator.

#### Symbol Definition

- @ is a place holder for the part number or pin name associated with the indicated error. In the displayed error message the actual number or name will be shown.
- is a place holder for the line of text associated with the indicated error. In the displayed error message the actual text will be shown.

#### APPENDIX A

## JEDEC Standard Programmable Logic Data Transfer Format "J"

The Joint Electron Devices Engineering Council (JEDEC) programmable logic data transfer format (PLDTF) is a universal transfer format for fuse and test information between hosts and intelligent device programmers. This format is an industry standard used by many commercial programmer manufacturers. It gives each fuse a unique decimal address (specified in a logic diagram schematic) and indicates the state of each fuse for the programmed part. The format consists of four main sections: the design specification identifier, fuse link information, structured functional test information, and the sumcheck. The output of this command is a fuse map ready to be downloaded to a PAL programmer.

#### **Design Specification Identifier**

The DESIGN SPECIFICATION identifier is a heading used by the designer to document the device to be programmed. The user is free to specify any documenting text desired. The AMD recommended format is identical to the first four lines of the PAL DESIGN SPECIFICATION. The heading is begun with an ASCII "STX" (02 HEX) and is terminated with an ASCII asterisk "\*" (2A HEX). Notice that this requires the PAL DESIGN SPECIFICATION heading to be asterisk free.

An optional device code can be specified, indicating to the device programmer the type of part to be programmed. This code is a variable length decimal number, preceded by an ASCII "D" (44 HEX) and terminated by an ASCII "\*" (2A HEX).

#### **Fuse Link Information**

This section of the format defines the state of each fuse, and consists of three fields: fuse default state, link information, and checksum. The first field is optional and is used to indicate the fuse default state. If a fuse state isn't otherwise specified, the default state will be used. The default state is specified by an ASCII "F" (46 HEX) followed by an ASCII "0" (32 HEX) for a low resistance link or an ASCII "1" (33 HEX) for a high resistance link. The field is terminated with an ASCII "\*" (2A HEX).

The second field, link information, identifies the state of each fuse individually. The field begins with an ASCII "L" (4C HEX) followed by an ASCII decimal fuse address of variable length, terminated by an ASCII "\*" (2A HEX). This indicates the fuse address of the first fuse state. The individual fuses are specified by an ASCII "0" (32 HEX) or an ASCII "1" (33 HEX) indicating low resistance and high resistance respectively. The fuse address is incremented for each additional fuse state. Thus fuse states can be specified sequentially. Any number of fuse addresses may be specified by inserting additional "L" fields. If a link is specified 2 or more times, the last state replaces the preceding entries.

The third field is an optional checksum for the link information. This checksum is computed by performing a 16-bit addition of the 8-bit words constructed from the specified state of each fuse link in the device. The 8-bit words are constructed sequentially from the single bit fuse state definitions. The method of constructing these words is shown below.

		MSB						I	LSB
		****	****	****	·***	****	****	****	***
Word	0	*	* *	*	*	*	*	*	*
		****	****	****	****	<b>**</b> **	****	****	***
Link	No.	7	6	5	4	3	2	1	0
		****	****	****	****	****	÷***	****	****
Word	1	*	* *	*	*	*	*	*	*
		***	****	****	****	****	***	****	****
Link	No.	15	14	13	12	11	10	9	8
		****	****	****	****	****	÷***	****	****
Word	2	*	* *	*	*	*	*	*	*
or a	_	****	****	****	****	****	***	***	****
Link	No.	23	22	21	20	19	18	17	16
					*				
					76				
					*				
					*				
			**	****	****	****	×***	****	****
Word	137		**	*	3	<b>!</b> -	*	*	*
			**	****	****	****	****	****	****
Link	No.		1	100	1099	1098	3 10	97 1	096
			1	ast					
			1	ink					

The word encompassing the last link is constructed by setting zeros for all bit locations more significant than the last link. The 16-bit sum is expressed as 4 ASCII Hex characters. On ASCII "C" precedes the four Hex characters. The last character is followed by an ASCII "\*".

#### Structured Functional Test Information

The structured functional test information is an optional field which can define test vectors to be used by intelligent programmable logic device programmers to test the logical functionality of a programmed device. These vectors specify the driven state for inputs and the checked value for outputs.

The field is specified with an ASCII "V" followed by a variable length decimal test vector address. The address is terminated by an ASCII "W". Following the test vector address is a series of 20 characters specifying the driven or tested state for each pin.

The format for each character in the test vector output is given below:

- H Test output for a logical HIGH
- L Test output for a logical LOW

- 1 Drive input to a logical HIGH
- 0 Drive input to a logical LOW
- X Irrelevant. If an output do not test. If an input drive to a logical LOW as a default.
- C Drive input from logical LOW to logical HIGH. (clock pulse).
- Z Test output for high impedance.

The test vector is terminated with an ASCII asterisk "\*". Multiple test vectors are specified by incrementing the decimal vector address by 1 for each additional test vector.

#### Sumcheck

The sumcheck field provides redundancy to help in detecting errors in data transmission. This field is constructed by performing a binary addition of each character between the STX and ETX in the transmitted file. The resulting least significant 16 bits are the sumcheck. This number is represented as four Hex characters preceded by an ASCII asterisk "\*" in the final printout.

Examples of the JEDEC transfer format are shown previously in descriptions of the JEDEC and SIMULATE commands.

## Section 5

## **Applications**



Four-Bit Slice Registered Barrel Shifter
Dynamic Memory Control State Sequencer
GCR (4B-5B) Encoder/Decoder
Interfacing the 8086 (8088) to the Z-BUS
An AMD PAL MULTIBUS Arbiter
Am8500 to MC68000 PAL Interface
The Berkeley-1 Plus—A High Performance CPU Utilizing PALs



# Four-Bit Slice Registered Barrel Shifter

### by Warren Miller Advanced Micro Devices

In most data processing systems, some form of data shifting or rotation is necessary. This elementary function is used in such diverse applications as floating point arithmetic and string manipulation. In the typical computer, the shifter is located on the output of the ALU. This architecture allows single cycle add and shift, and mask and shift operations (see Figure 1 for a typical computer ALU architecture).

#### **DESIGN REQUIREMENTS**

A barrel shifter takes data input and cyclically rotates it by an arbitrary number of bit positions. This cyclic rotation means

that data rotated off the most significant end of the shifter is brought back on the least significant end. The name barrel shifter is used because of the circular nature of the shift operation.

The storage register on the output of the shifter is used in this architecture to pipeline the data operation, increasing throughput. The three-state buffer on the register output is necessary to interface the ALU to the output data bus.

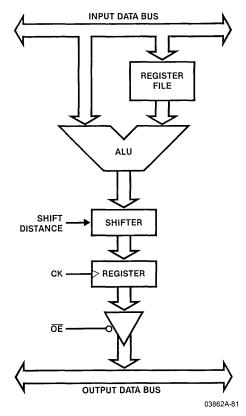


Figure 1. Typical ALU Architecture

#### DESIGN APPROACH

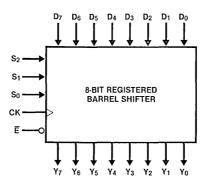
An 8-bit registered barrel shifter would take at least 8 data inputs, 8 registered data outputs, and 3 control lines to implement (see Figure 2). The AmPAL16R8 has 8 registered data outputs but only 8 inputs, not enough to implement the 8-bit registered barrel shifter in a single device. In cases like this, where the function to be implemented can't fit into a single PAL because of pin limitations, the problem is best approached by dividing it into smaller functions. These smaller functions should be chosen in such a way that each function requires a reduced number of pins, hence, easing the pin limitation problem. One possible approach would be to "slice" the 8-bit function into two 4-bit functions. Figure 3 shows the approach used to divide the part into two sections, each containing a smaller number of pins.

Notice that every data and control input participates in each output function. Thus the 4-bit partition must include all data

and control inputs, giving a total of 11 array inputs and 4 outputs per device. If both devices are programmed identically, the 8-bit function can be implemented as shown in Figure 4. The data inputs are "offset" by 4 places to differentiate between the upper and lower nibbles.

A 4-bit slice of the 8-bit barrel shifter can be implemented in a AmPAL16R4. This part allows up to 12 inputs (one more than necessary) and 4 registered outputs. The extra input is used for a set function, loading the output register with all ones. The logic diagram and PALASM listing for the registered barrel shifter slice are shown following.

The PAL solution requires only two 20-pin packages. An MSI version of the 8-bit barrel shifter would require 4 Am25S10 four-bit shifters and an Am25S374 octal three state register. The savings in cost, board space and power are considerable, and the PAL solution is also faster.



#### **FUNCTION DEFINITION**

CONT	ROL IN	IPUTS		1	NPUT 1	το ουτ	PUT M.	APPING	3	
S <sub>2</sub>	S <sub>1</sub>	S <sub>0</sub>	Y <sub>7</sub>	Y <sub>6</sub>	Y <sub>5</sub>	Y4	Y3	Y <sub>2</sub>	Y <sub>1</sub>	$Y_0$
0	0	0	D <sub>7</sub>	D <sub>6</sub>	D <sub>5</sub>	D <sub>4</sub>	D <sub>3</sub>	D <sub>2</sub>	D <sub>1</sub>	D <sub>0</sub>
0	0	1	D <sub>6</sub>	$D_5$	$D_4$	$D_3$	$D_2$	$D_1$	$D_0$	$D_7$
0	1	0	D <sub>5</sub>	$D_4$	$D_3$	$D_2$	$D_1$	$D_0$	D <sub>7</sub>	$D_6$
0	1	1	D <sub>4</sub>	$D_3$	$D_2$	$D_1$	$\mathbf{D}_{0}$	$D_7$	$D_6$	$D_5$
1	0	0	D <sub>3</sub>	$D_2$	$D_1$	$D_0$	$D_7$	$D_6$	$D_5$	$D_4$
1	0	1	D <sub>2</sub>	$D_1$	$D_0$	$D_7$	$D_6$	$D_5$	$D_4$	$D_3$
1	1	0	D <sub>1</sub>	$D_0$	D <sub>7</sub>	$D_6$	$D_5$	$D_4$	$D_3$	$D_2$
1	1	1	D <sub>0</sub>	$D_7$	$D_6$	$D_5$	$D_4$	$D_3$	$D_2$	$D_1$

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Figure 2. 8-Bit Registered Barrel Shifter

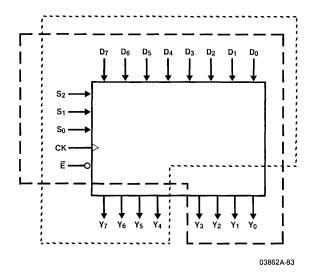


Figure 3. 4-Bit Slice Approach

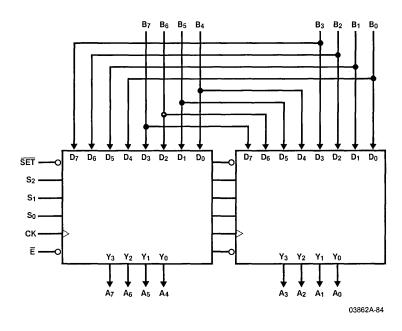


Figure 4. 8-Bit Barrel Shifter Implementation with Two 4-Bit Slices

```
PAL DESIGN SPECIFICATION KEVIN M. OW-WING 6/22/82
```

```
PAL16R4
PATO01
4-BIT SLICE FOR AN 8-BIT BARREL SHIFTER
ADVANCED MICRO DEVICES
       D6 D5 D4 D3 D2 D1 D0 GND
/E /SET SO QO Q1 Q2 Q3 S1 S2 VCC
/Q3 := /SET*/S2*/S1*/S0*/D3 +
       /SET*/S2*/S1* S0*/D2 +
       /SET*/S2* S1*/S0*/D1 +
       /SET*/S2* S1* S0*/D0 +
       /SET* S2*/S1*/S0*/D7 +
       /SET* S2*/S1* S0*/D6 +
       /SET* S2* S1*/S0*/D5 +
       /SET* S2* S1* S0*/D4
/02 := /SET*/S2*/S1*/S0*/D2 +
       /SET*/S2*/S1* S0*/D1 +
       /SET*/S2* S1*/S0*/D0 +
       /SET*/S2* S1* S0*/D7 +
       /SET* S2*/S1*/S0*/D6 +
       /SET* S2*/S1* S0*/D5 +
       /SET* S2* S1*/S0*/D4 +
       /SET* S2* S1* S0*/D3
/Q1 := /SET*/S2*/S1*/S0*/D1 +
       /SET*/S2*/S1* S0*/D0 +
       /SET*/S2* S1*/S0*/D7 +
       /SET*/S2* S1* S0*/D6 +
       /SET* S2*/S1*/S0*/D5 +
       /SET* S2*/S1* S0*/D4 +
       /SET* S2* S1*/S0*/D3 +
       /SET* S2* S1* S0*/D2
/Q0 := /SET*/S2*/S1*/S0*/D0 +
       /SET*/S2*/S1* S0*/D7 +
       /SET*/S2* S1*/S0*/D6 +
        /SET*/S2* S1* S0*/D5 +
       /SET* S2*/S1*/S0*/D4 +
       /SET* S2*/S1* S0*/D3 +
       /SET* S2* S1*/S0*/D2 +
       /SET* S2* S1* S0*/D1
```

#### FUNCTION TABLE

#### CK /E /SET S2 S1 S0 D7 D6 D5 D4 D3 D2 D1 D0 Q3 Q2 Q1 Q0

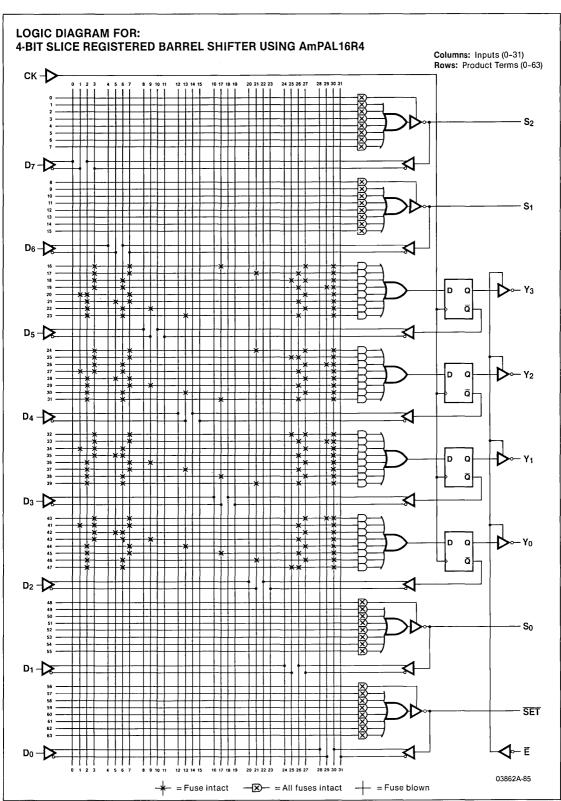
; ; X	HIG H	H Z X	TEST X	Х	х	X	Х	х	Х	X	X	х	Х	Z	Z	Z	Z
;	SET	י חווי	TPUTS	TI	7CT												
ċ	L	L	X	X	X	X	X	X	X	X	Х	X	X	H	Н	H	H
;	DCE	חחוד	RAND	ОΜ	מאם	זיזם	CUT	ניחים	יים כו	TP C TP	cro	OHE	MOD				
,	1 31		MAND	Ort	DAK	KEL	SUT	LIL	K I	CO1	OE	QUE	NCE				
С	L	Н	L	L	L	L	L	L	L	L	L	L	H	L	L	L	Η
С	L	H	L	L	H	L	L	L	L	L	L	Н	Ţ,	L	Н	L	L
Ċ	L	Н	L	H	L	H	L	L	L	Ĺ	Ĺ	Ť	ī	Ĺ	Ĺ	H	Ĺ
č	Ĺ	Ĥ	Ĺ	H	H	L	Ĺ	Ħ	Ĺ	Ĺ	Ĺ	Ĺ	Ĺ	ī	ī.	L	H
-			_	••	11		_	n	_	7.	11	11	r.	ᆢ		_	71
С	L	Η	Н	L	L	L	H	L	L	L	L	L	L	ᅩ	H	L	L
С	L	Η	H	L	Н	L	L	L	Н	L	L	L	L	L	L	Η	L
С	L	Н	Н	H	T.	T.	T.	H	T.	Ţ,	Ι.	ī.	L	H	L	L	L
Č	Ĺ	H	H	H	H	ī	ī	ī	ī.	ī.	ī	H	ī.	1	Ť	ī.	Н
-			- 11				Ţ.	1.		_	11	11		T.	-	_	
С	L	H	L	L	H	ь	ь	L	L	L	Н	L	ь	H	L	L	L
С	L	H	Н	Η	H	$_{\rm L}$	L	L	L	H	$\mathbf{L}$	L	L	$\mathbf{L}$	H	L	$\mathbf{L}$

DESCRIPTION: THIS PART IS A 4-BIT SLICE OF AN 8-BIT REGISTERED BARREL SHIFTER. IT TAKES 8 DATA INPUTS AND CYCLICALLY ROTATES THE DATA FROM 0 TO 7 PLACES UNDER CONTROL OF THE SELECT ( S ) INPUTS. A SET INPUT CAN BE USED TO INITIALIZE THE OUTPUTS TO THE ALL ONES STATE.

```
KEVIN M. OW-WING 6/22/82
PAT001
4-BIT SLICE FOR AN 8-BIT BARREL SHIFTER
ADVANCED MICRO DEVICES
*D9724
*F0*
L0512 1110 1110 1111 1111 1011 1111 1110 1101 *
L0544 1110 1110 1111 1111 1111 1011 1101 *
L0576 1110 1101 1111 1111 1111 1111 1010 1101 *
L0608 1110 1101 1111 1111 1111 1111 1101 1001 *
L0640 1001 1110 1111 1111 1111 1111 1110 1101 *
L0672 1101 1010 1111 1111 1111 1111 1101 1101 *
L0704 1101 1101 1011 1111 1111 1111 1110 1101 *
L0736 1101 1101 1111 1011 1111 1111 1101 1101 *
L0768 1110 1110 1111 1111 1111 1011 1110 1101 *
L0800 1110 1110 1111 1111 1111 1111 1001 1101 *
L0832 1110 1101 1111 1111 1111 1111 1110 1001 *
L0864 1010 1101 1111 1111 1111 1111 1101 1101 *
L0896 1101 1010 1111 1111 1111 1111 1110 1101 *
L0928 1101 1110 1011 1111 1111 1111 1101 1101 *
L0960 1101 1101 1111 1011 1111 1111 1110 1101 *
L0992 1101 1101 1111 1111 1011 1111 1101 1101 *
L1024 1110 1110 1111 1111 1111 1111 1010 1101 *
L1056 1110 1110 1111 1111 1111 1111 1101 1001 *
L1088 1010 1101 1111 1111 1111 1111 1110 1101 *
L1120 1110 1001 1111 1111 1111 1111 1101 1101 *
L1152 1101 1110 1011 1111 1111 1111 1110 1101 *
L1184 1101 1110 1111 1011 1111 1111 1101 1101 *
L1216 1101 1101 1111 1111 1011 1111 1110 1101 *
L1248 1101 1101 1111 1111 1111 1011 1101 1101 *
L1280 1110 1110 1111 1111 1111 1111 1110 1001 *
L1312 1010 1110 1111 1111 1111 1111 1101 1101 *
L1344 1110 1001 1111 1111 1111 1111 1110 1101 *
L1376 1110 1101 1011 1111 1111 1111 1101 1101 *
L1408 1101 1110 1111 1011 1111 1111 1110 1101 *
L1440 1101 1110 1111 1111 1011 1111 1101 1101 *
L1472 1101 1101 1111 1111 1111 1011 1110 1101 *
L1504 1101 1101 1111 1111 1111 1111 1001 1101 *
C67E0*
V0001 XXXXXXXXXX01XXZZZZXX1 *
VOOO2 CXXXXXXXXOOOXHHHHXX1 *
V0003 C000000010010HLLL001 *
V0004 C000000100011LLHL001 *
V0005 C100000000010LHLL101 *
V0006 C001000000011HLLL101 *
V0007 C010000000010LLHL011 *
V0008 C000100000011LHLL011 *
V0009 C001000000010LLLH111 *
V0010 C000000100011HLLL1111 *
V0011 C000001000011LLLH001 *
V0012 C000010000011LLHL111 *
994E
```

PAL DESIGN SPECIFICATION

PAL16R4



# Dynamic Memory Control State Sequencer

#### by Brad Kitson Advanced Micro Devices



An example of a control path application for an AMD PAL is in a memory system. Most large memory systems use MOS dynamic RAMs. Their high density allows packing a large memory size into a small board area. Dynamic RAM prices also make them very cost effective.

Dynamic RAMs require external logic for address multiplexing, timing generation and refresh control. This application note shows the use of an AmPAL16R8A and an Am2964B to provide the necessary external logic for a typical dynamic memory system. The PAL is used as a state sequencer for timing generation and the Am2964B provides specialized control circuitry and reduces timing skew between control signals. This implementation replaces about 20 SSI/MSI packages.

#### **DESIGN REQUIREMENTS**

A system block diagram is shown in Figure 1. The control bus provides most of the inputs to the PAL state sequencer. These include: Memory Request (MREQ), READ/WRITE (RW), RESET (RST), Refresh Clock (RFCK), and Read-Modify-Write (RMW). Two upper address lines of the address bus serve as board selects (BS<sub>1</sub>, BS<sub>0</sub>), and one local signal, SLOW/FAST Memory (FAST), allows use of either slow or fast memory. A READ/WRITE sequence is initialized by MREQ ANDed with the proper board select conditions and a refresh sequence is initialized by RFCK. If both sequences are requested at the same time, a refresh sequence is performed. RW when HIGH selects a READ operation and when LOW selects a WRITE operation. RMW when HIGH selects a Read-Modify-Write cycle.

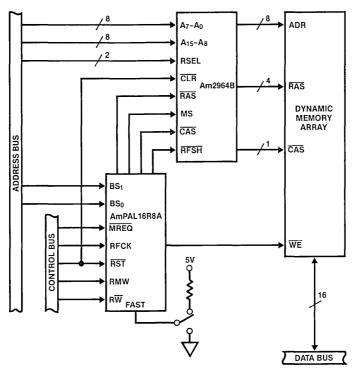


Figure 1. Dynamic Memory Controller

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The outputs of the PAL provide the timing and control inputs to the Am2964B. These are: Row Address Strobe (RAS), Address Multiplexer Select (MS), Column Address Strobe (CAS), and Refresh (RFSH). In addition, the PAL provides the Write Enable (WE) to the Memory Array. Figure 2 shows the timing for fast READ/WRITE cycles. The memory cycle is initiated by  $\overline{\text{MREQ}}$  going LOW. The PAL responds by bringing  $\overline{\text{RAS}}$  LOW at  $t_0$ , followed by MS going LOW at  $t_1$ , and finally bringing  $\overline{\text{CAS}}$  LOW at  $t_2$ . If RW is LOW,  $\overline{\text{WE}}$  is also brought LOW at

 $t_2$ .  $\overline{\text{WE}}$  is held LOW until  $t_4$ .  $\overline{\text{RAS}}$ , MS and  $\overline{\text{CAS}}$  are brought HIGH at  $t_5$ . The rising edge of any of these 3 signals may be used to latch output data during a Read operation. The state sequencer is then disabled for 3 states to allow for memory precharge.

By holding the FAST input LOW, an extended memory cycle is available to accommodate slower RAMs. The timing appears in Figure 3.

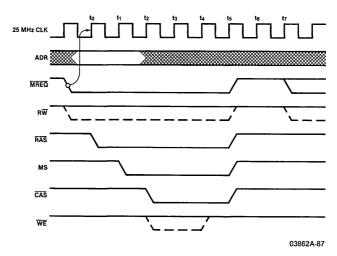


Figure 2. Fast READ/WRITE Cycle

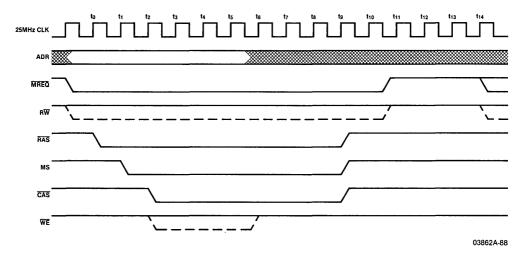


Figure 3. Extended Memory Cycle

 $\overline{\text{RAS}}$ -Only refresh cycle timing is shown in Figure 4. The refresh cycle is initiated when RFCK goes HIGH. The  $\overline{\text{RFSH}}$  output goes LOW at  $t_0$ , followed by  $\overline{\text{RAS}}$  at  $t_1$ . The Am2964B supplies the necessary refresh address.  $\overline{\text{RAS}}$  is brought back HIGH at  $t_5$  and precharge is then timed out. An extended refresh cycle for slower memory is available also. Burst refresh can be accomplished by leaving RFCK HIGH for as many refresh cycles as desired.

Read-Modify-Write cycle timing is activated by setting RMW HIGH. This is especially valuable in systems with Error Detection/Correction (EDC) capability. Data can be read, modified by the EDC circuitry (Am2960), and if necessary, written back to memory in a single memory cycle. Read-Modify-Write cycle timing is shown in Figure 5. Note that WE goes LOW at the end of the cycle.

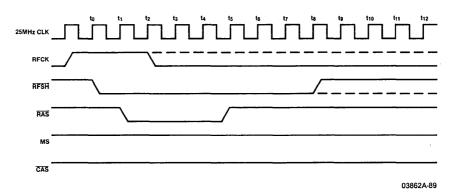


Figure 4. RAS-Only Refresh Cycle

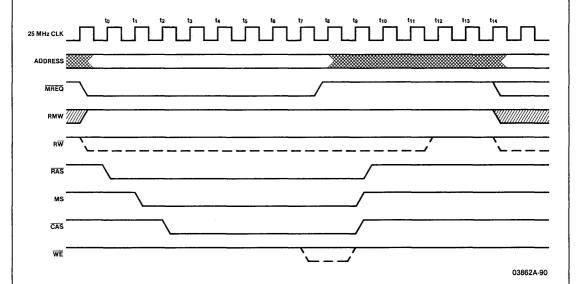


Figure 5. Read-Modify-Write Cycle

#### **DESIGN APPROACH**

The first step in the state sequencer design process is to define the timing waveforms for all of the functions desired. Figures 2, 3, 4 and 5 are the result. Next, characteristics of the resulting waveforms are examined. Initially, the sequencer is waiting on the  $\overline{\text{MREQ}}$  or RFCK input. If  $\overline{\text{MREQ}}$  goes LOW, the  $\overline{\text{RAS}}$  to MS to  $\overline{\text{CAS}}$  sequence is initiated. If RFCK goes HIGH, the  $\overline{\text{RFSH}}$  to  $\overline{\text{RAS}}$  sequence is initiated. Both sequences are equivalent to a simple "shift" function. Once the shift sequence is completed and the signals are asserted, they must stay asserted for a specific time depending on the selected function. To time the length that signals must stay asserted

requires a "counting" function. The precharge sequence at the end of all cycles also requires "counting". This partitions most of the design into two smaller functional blocks; a shifter and a counter. The remaining function select and control logic is partitioned into a "multiplexer-like" functional block. Figure 6 shows the PAL partitioned into functional blocks. By dividing the design into blocks, its implementation becomes simple.

The following pages show the easy to read PAL DESIGN SPECIFICATION and a logic diagram for the AmPAL16R8A dynamic memory state sequencer.

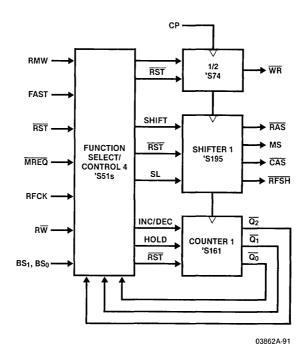


Figure 6. Partitioned Design/PAL Equivalent

```
PAL16R8
                                         PAL DESIGN SPECIFICATION
                                                          2/10/82
                                         BRAD S. KITSON
PATO02
DYNAMIC MEMORY CONTROL STATE SEQUENCER
ADVANCED MICRO DEVICES
CK RFCK /RST RW /MREQ RMW FAST BS1 BS0 GND
/E /QO /Q1 /Q2 /RFSH /WE /CAS MS /RAS VCC
00 := /RST* /MS*/00
        /RST* RFSH*RAS*/QO
        /RST*/FAST*/QO*Q2
        /RST*/FAST*/QO*Q1
        /RST*/FAST* Q1*Q2
        /RST* FAST*/RMW*QO*/Q1 +
        /RST* FAST*/RMW*QO*/Q2
Q1 := /RST* RAS*/Q0* Q1
        /RST* RAS* 00*/01
        /RST*/RAS* QO* Q1
        /RST*/RAS*/QO* Q2
Q2 := /RST*RAS*Q2
        /RST* Q0*Q2
        /RST*RAS*QO*Q1
RFSH := /RST*RFCK*/Q2*/Q1*/Q0*/RAS +
        /RST*RFSH*RAS
        /RST*RFSH*/FAST* Q1
        /RST*RFSH* Q2
WE := /RST*/RW*/MS*/RFSH*/RMW*/QO*/Q2
        /RST*/RW*/MS*/RFSH*/RMW*/Q1*/Q2
        /RST*/RW*/MS*/RFSH* RMW*/QO* Q1*Q2 +
        /RST*/RW*/MS*/RFSH* RMW* QO*/Q1*Q2
       /RST*/RFSH*/MS*/00
CAS :=
        /RST*/RFSH*/MS*/Q1
        /RST*/RFSH*/MS*/Q2
/MS :=
       /RST*/RFSH*RAS*/QO
        /RST*/RFSH*RAS*/Q1
        /RST*/RFSH*RAS*/Q2
RAS :=
        /RST*/RFCK*/QO*/Q1*/Q2*MREQ*/BS1*/BSO +
        /RST*/RFSH*/QO*/Q1*/Q2*MREQ*/BS1*/BSO +
        /RST* RFSH*/Q0*/Q1*/Q2 +
        /RST*RAS*/QO
        /RST*RAS*/Q1
        /RST*RAS*/Q2
```

FUNCTION TABLE

CK /E /RST /MREQ BS1 BS0 RFCK RW RMW FAST RAS /MS CAS WE RFSH Q2 Q1 Q0

; ;Il	TIV	'IAL	IZE														
Ċ	L	L	Х	X	X	X	Х	X	X	L	L	L	L	L	L	L	L
;																	
•	AST			RATI													
С	L	Η	L	L	L	L	X	Х	X	H	L	L	L	L	L	L	L
С	L	Н	Х	X	X	X	X	X	X	H	Н	L	L	L	L	L	L
С	L	H	Х	X	Х	X	L	L	H	H	Η	H	Н	L	L	L	Н
C	L	Н	X	X	Х	Х	L	L	Н	H	H	Η	H	L	L	Н	Н
С	L	Н	Х	X	Х	X	L	L	H	H	H	Н	L	L	Н	L	H
C	Ţ	H	X	X	X	X	Ļ	Ţ	H	H	H	H	L	Ĺ	H	H	H
	L	H	X	X	X	X	L	L	H	Ļ	L	L	L	L	H	L H	L L
C C	L L	H H	X X	X X	X X	X X	L L	L L	H	L L	L	L L	L L	L L	L L	н L	L
	ъ	п	Λ	Λ	Λ	Λ	Ъ	ь	H	Ъ	L	L	L	ь	Ъ	Tı	Ъ
; ;R/	٩S	ONL	Y REFRE	SH C	YCLE												
Ċ	Ĺ	Н	Н	X	X	Н	X	X	X	L	L	L	L	Н	L	L	L
C	L	Н	X	X	X	H	X	X	X	H	Ĺ	Ĺ	Ĺ	H	Ĺ	L	Ĺ
С	L	Н	X	X	X	X	X	X	H	H	L	L	L	Н	L	L	H
С	L	H	X	X	Х	X	X	X	H	Н	L	L	L	Н	L	H	H
С	L	Η	X	X	X	X	Х	X	H	H	L	L	L	Н	Н	L	H
С	L	Н	X	X	X	X	X	X	H	H	L	L	L	Н	Н	Η	H
С	L	H	X	X	Х	X	X	X	H	L	L	L	$_{ m L}$	Н	H	L	L
C	L	H	X	X	X	X	X	X	H	L	$\mathbf{L}$	L	L	H	L	Н	L
С	L	Н	X	X	X	Х	X	Х	H	L	L	L	L	L	L	L	L
;																	
			DIFY-WR			TION					_	_	_	_	_	_	_
C	L	H	L	L	L	L	Х	Х	Х	H	L	Ĺ	Ţ	Ţ	Ţ	ŗ	Ļ
C	L	H	X	X	X	X	X	X	X	H	Н	L	L	L	L	Ļ	L
C	L	Н	X	X	X	X	L	H	L	H	H	Н	L	L	L	L H	H L
C C	L L	H H	X X	X X	X X	X X	L	Н	L	H	H	H	L L	L	L	н	H
C	L	H	X	X		X	L	H	L	H	H H	H	L	$_{ m L}$	L H	L	ь Г
C	L	Н	X	X	X X	X	L L	H H	L L	H H	н	H H	L	L	H	L	Н
c	L	Н	X	X	X	X	L	л Н	L	n H	н	п Н	Н	L	п Н	Н	L
Č	L	Н	X	X	X	X	L	Н	Ĺ	H	Н	Н	Н	L	Н	Н	Н
C	L	Н	X	X	X	X	L	H	L	L	L	L	L	L	H	L	H
Č	L	Н	X	X	X	X	L	Н	L	L	L	L	L	L	Н	L	L
Č	Ĺ	Н	X	X	X	X	L	Н	L	Ĺ	Ĺ	L	L	L	L	H	Н

#### DESCRIPTION

DYNAMIC MEMORY CONTROL STATE SEQUENCER FOR USE WITH THE AM2964B MEMORY CONTROLLER. THE SEQUENCER PROVIDES /RAS,MS,/CAS, & REFRESH TIMING GENERATION TO THE AM2964B AND /WE TO THE DRAMS. IT SUPPORTS BOTH FAST (150NS) AND SLOW (300NS) READ/WRITE CYCLES, /RAS ONLY REFRESH, BURST REFRESH, AND READ-MODIFY-WRITE FOR MEMORY BOARDS OF UP TO 256K.

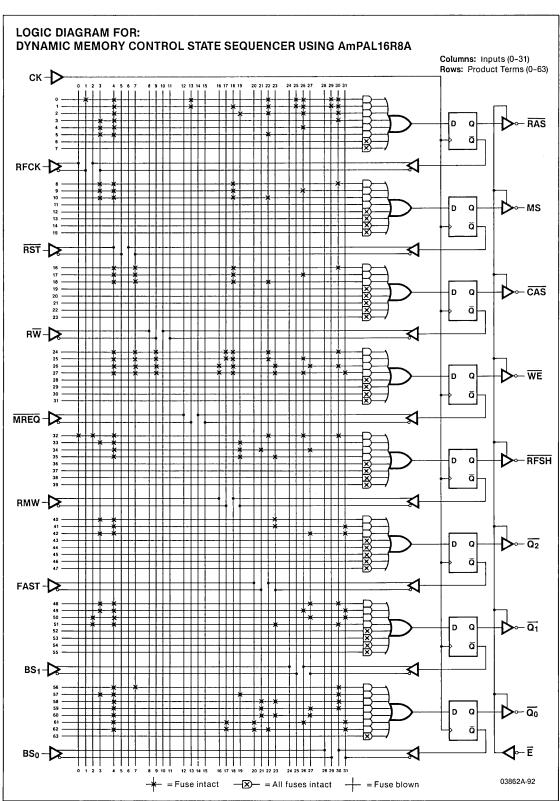
PAL DESIGN SPECIFICATION

2/10/82

PAL16R8

```
VOO15 CX1XXX1XXOOLHLLHHHL1 *
VOO16 CX1XXX1XXOOLLLLHHHL1 *
VOO17 CX1XXX1XXOOHHLLHHHH1 *
VOO18 CX1XXX1XXOOHLHLHHHH1 *
VOO19 CX1XXX1XXOOHHHHHHHHH *
VOO20 CO1XOXXOOOOHHHHHHHL1 *
VOO21 CX1XXXXXXOOHHHHHHLL1 *
VOO22 CX10X10XXOOLHHHHLLL1 *
VOO23 CX10X10XXOOHLHHHLLL1 *
VOO24 CX10X10XXOOLLHHHLLL1 *
VOO25 CX10X10XXOOHHLHHLLL1 *
VOO26 CX10X10XXOOLHLHHLLL1 *
VOO27 CX10X10XX00HLLHLLLL1 *
VOO28 CX10X10XX00LLLHLLLL1 *
VOO29 CX10X10XXOOLHLHHHHHH1 *
VOO30 CX10X10XXOOHHLHHHHHH *
VOO31 CX10X10XXOOLLHHHHHHH1 *
```

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•			<u> 1</u>

# GCR (4B-5B) Encoder/Decoder

by Warren Miller Advanced Micro Devices



One of the more common logic functions performed on serial data is the data encode/decode function. Usually it is desirable to map (encode) the logical bit stream to a physical bit stream, adjusting for the peculiarities of the particular transmission or storage media.

Noise, bandwidth, and reliability considerations may mean that a different data format would be desirable when data is sent along to or stored on a given media. For example, groupcoded recording (GCR) formats take a given number of data bits and encode them with a larger number of bits. A 4B-5B GCR code would take 4 data bits and encode them into 16 states with 5 new bits. A particular 4B-5B code is shown in Table 1.

This mapping allows at most two zeros to occur in succession. Also note that data combinations with more than one zero at the beginning and end of the word are excluded. This is necessary to insure that when data words are serialized, no more than two zeros occur in succession at any point in the bit stream. Finally, the data combination 11111 is reserved as a synchronization mark. In tape systems, this results in increased bit density and eases clock synchronization.

Table 1. 4B-5B Code

			4B-	DB C	oa	е			
4-E	3it	Da	ata		5	Bi	t C	at	а
0	0	0	0		1	1	0	0	1
0	0	0	1		1	1	0	1	1
0	0	1	0		1	0	0	1	0
0	0	1	1		1	0	0	1	1
0	1	0	0		1	1	1	0	1
0	1	0	1		1	0	1	0	1
0	1	1	0		1	0	1	1	0
0	1	1	1		1	0	1	1	1
1	0	0	0		1	1	0	1	0
1	0	0	1		0	1	0	0	1
1	0	1	0		0	1	0	1	0
1	0	1	1		0	1	0	1	1
1	1	0	0		1	1	1	1	0
1	1	0	1		0	1	1	0	1
1	1	1	0		0	1	1	1	0
1	1	1	1		0	1	1	1	1

03862A-93

#### **DESIGN REQUIREMENTS**

The system diagram in Figure 1 shows how the GCR Encoder/Decoder (GCR E/D) interfaces to a tape drive and tape controller. Parallel input data is given to the GCR E/D, converted to the 5-bit format, serialized, and written to the tape. On a read, the serial data from the tape is parallelized, converted back to the 4-bit format and output to the tape controller. Additionally, during a read, two status signals are developed. The first signal,  $\overline{\text{INV}}$ , indicates the presence of an invalid input, ie., too many zeros in succession. The second status signal,  $\overline{\text{H}}$ , indicates the detection of the synchronization mark (11111).

The operation modes for the GCR E/D are shown in the Data-Flow Diagrams of Figure 2. The control signal definition and operation functions are indicated for each operation mode. In particular, the data flow between each bit of the output register is indicated schematically.

The first mode of operation of the GCR E/D is the HOLD mode. When ENABLE is HIGH, all data operations on the output register are disabled, independent of the two mode controls,  $M_1$  and  $M_0$ . The output data is simply fed-back to the register inputs. Thus the register content is retained after the clock transition.

When the  $\overline{\text{ENABLE}}$  input is LOW, the operations indicated by the M<sub>1</sub> and M<sub>0</sub> mode bits are executed on the clock transition. When M<sub>1</sub> and M<sub>0</sub> are both LOW, the SERIAL SHIFT IN mode is selected. In this mode the output register is configured as a serial shift register. The serial input is consecutively shifted into the register until all 5 bits from the tape have been stored, MSB at Y<sub>3</sub> and LSB at SERIAL OUT.

The CONVERT SERIAL INPUT AND LOAD operation is selected when  $\overline{\text{ENABLE}}$  is LOW,  $M_1$  is HIGH and  $M_0$  is LOW. After the 5 bits of data have been serialized by the SERIAL SHIFT IN instruction, the 5B code must be converted to a 4B code. This is accomplished by taking the outputs of the 5 register bits and converting them to 4 bits with combinatorial logic. On the clock transition, the result is loaded into the Y register. On the same clock transition that loads the converted data into the Y register, the serial input is loaded into the serial output register. Because the serial data is being read continuously, one data bit per clock transition, the conversion must be done without missing a serial data bit.

The CONVERT PARALLEL INPUT AND LOAD operation is selected when ENABLE is LOW,  $M_1$  is HIGH and  $M_0$  is HIGH. This mode takes the 4 input data bits and converts them to the 5 bit representation. The result is loaded into the output register on the clock transition. The LSB of the 5B representation is loaded into the  $Y_3$  bit of the output register and the MSB is loaded into the serial output bit. This configuration, in conjunction with the next instruction, allows the serial data to be written to the tape drive one bit per clock transition.

The final operation, SERIAL SHIFT OUT, is selected when ENABLE is LOW,  $M_1$  is LOW and  $M_0$  is HIGH. After the CONVERT PARALLEL INPUT AND LOAD operation is executed, the SERIAL SHIFT OUT operation outputs the converted data to the tape drive. A series of one convert operation followed by 4 shift operations will transfer a sequence of 5-bits to the tape drive, one bit per clock cycle.

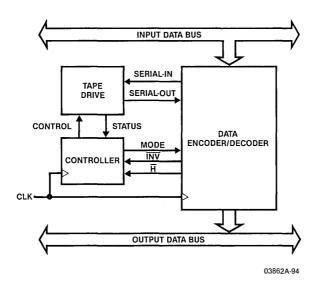
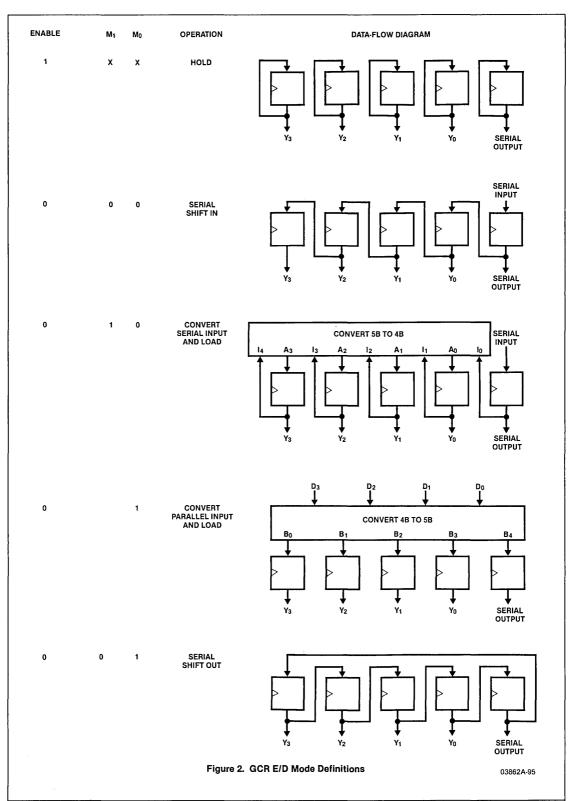


Figure 1. Typical Tape Storage System



#### **DESIGN APPROACH**

The PAL implementation of the GCR Encoder/Decoder takes advantage of the multiplexer-like structure of the AND-OR array. Each valid combination of ENABLE, M1 and M0 selects a different set of AND terms. In some cases, only one term is selected (in data steering operations for example). In other cases, multiple AND terms are selected to implement a combinatorial logic function (the 5B to 4B conversion for example). This concept, using the control inputs to enable one or more AND terms, allows the direct implementation of the PAL design from the mode Data-Flow Diagrams (with a little Karnaugh map help). The K-Maps for the 5B to 4B conversion logic and the 4B to 5B conversion logic for the Y<sub>3</sub> output are shown in Figures 3 and 4. Given these maps and the flow diagrams in Figure 2, the Boolean equations can be constructed for the Y<sub>3</sub> output. The resulting equation, in PALASM format, is shown in Figure 5.

It is important to note that the equation in Figure 5 is written for the inverse of the  $Y_3$  output  $(\overline{Y_3})$ . This is necessary if true data is desired on the output pin because of the inverting nature of the output buffer on the PAL. The inverted form of the equation is easily implemented by selecting the negative version of the data  $(\overline{Y_3}$  in the hold operation for example) or by grouping zeros in a combinatorial logic function (see Figures 3 and 4). Notice that the multiplexer strategy works equally well for active LOW or active HIGH logic functions.

Once the transformation of the Data-Flow Diagrams and K-Maps to Boolean equations is understood, the interested reader should be able to construct K-Maps for the other Y outputs and, in conjunction with the Data-Flow Diagrams of Figure 2, write the PALASM equations for the resulting logic functions. This exercise will help the reader to fully appreciate the advantages of the Data-Flow Diagram/Multiplexer method of PAL design. Consult the full PALASM listing (Figure 9) for the complete solutions.

Once the data portion of the Encoder/Decoder is completed, only the two status outputs,  $\overline{H}$  and  $\overline{INV}$ , need to be implemented.  $\overline{H}$  indicates the synchronization mark (11111) has been detected and is simply an AND of  $Y_3$  through  $S_{OUT}$ .  $\overline{INV}$  indicates an invalid serial input was received.

The  $\overline{\text{INV}}$  signal is registered and held until the clear  $\overline{\text{INV}}$  flag input (CIF) is brought LOW, deactivating the flag. Only during a 5B-4B conversion operation (M<sub>1</sub> = HIGH, M<sub>0</sub> = LOW) is the  $\overline{\text{INV}}$  flag activated. Figures 6 and 7 show the  $\overline{\text{INV}}$  flag mode definitions and the intermediate INVALID logic equation respectively.

In this case, an active LOW output is desired so the active HIGH form of the  $\overline{\text{INV}}$  signals is developed internally. Ones are grouped in the intermediate combinatorial logic function (INVALID) and the true version of the data is selected. The complete PALASM equation for  $\overline{\text{INV}}$  is given in Figure 8.

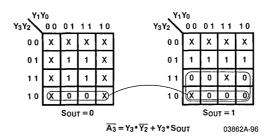


Figure 3. 5B to 4B Conversion K-Map for Y<sub>3</sub> Output

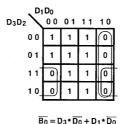


Figure 4. 4B to 5B Conversion K-Map for Y<sub>3</sub> Output

Figure 5. PALASM Equation for  $\overline{Y_3}$ 

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038624-97

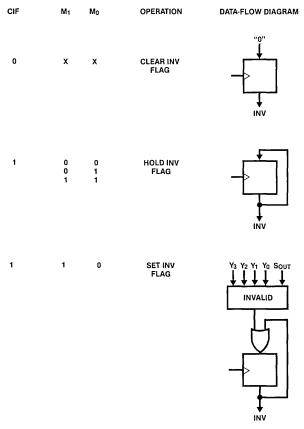


Figure 6. INV Flag Mode Definitions

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03862A-101

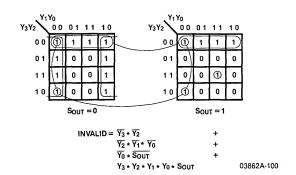


Figure 7. PALASM Equation for INVALID

Figure 8. PALASM Equation for INV

5-23

```
PAT003
                                        WARREN K. MILLER 2/15/82
4B-5B ENCODER/DECODER
ADVANCED MICRO DEVICES
        MO D3 D2 D1 DO /EN /CIF GND
/E SIN /INV YO Y1 Y2 Y3 SOUT /H
                                    VCC
/SOUT := EN*/SOUT
                                       ; HOLD
                                       ;SERIAL SHIFT IN ;SERIAL SHIFT OUT
        /EN*/M1*/MO*/SIN
                                  +
        /EN*/M1* MO*/YO
                                  +
        /EN* M1*/MO*/SIN
                                       ;CONVERT SERIAL INPUT AND LOAD
                                  +
        /EN* M1* MO* D3* D1
                                       :CONVERT PARALLEL INPUT AND LOAD
        /EN* M1* MO* D3* DO
/Y0
      := EN*/YO
        /EN*/M1*/MO*/SOUT
        /EN*/M1* MO*/Y1
        /EN* M1*/MO*/SOUT
        /EN* M1*/MO* Y3* Y2*/YO
        /EN* M1* MO*/D3* D1
        /EN* M1* MO*/D3* D2* D0
/Y1
      := EN*/Y1
        /EN*/M1*/MO*/YO
        /EN*/M1* MO*/Y2
        /EN* M1*/MO*/YO
        /EN* M1*/MO* Y3* Y2
        /EN* M1* MO*/D2
/Y2
      := EN*/Y2
        /EN*/M1*/MO*/Y1
        /EN*/M1* MO*/Y3
        /EN* M1*/MO*/Y1
        /EN* M1* MO*/D3*/D1*/DO
                                 +
        /EN* M1* MO*/D3* D2*/D1
        /EN* M1* MO* D3*/D1* DO
/Y3
      := EN*/Y3
        /EN*/M1*/MO*/Y2
        /EN*/M1* MO*/SOUT
        /EN* M1*/MO* Y3* SOUT
        /EN* M1*/MO* Y3*/Y2
        /EN* M1* MO* D3*/D0
        /EN* M1* MO* D1*/DO
 INV := /CIF* INV
                                        :HOLD INV FLAG
        /CIF* M1*/MO*/Y3*/Y2
                                        SET INV FLAG IF INVALID TRUE
        /CIF* M1*/M0*/Y2*/Y1*/Y0 +
        /CIF* M1*/MO*/YO*/SOUT
        /CIF* M1*/MO* Y3* Y2* Y1* YO* SOUT
     = Y3* Y2* Y1* Y0* SOUT
Η
```

PAL DESIGN SPECIFICATION

PAL16R6

#### FUNCTION TABLE

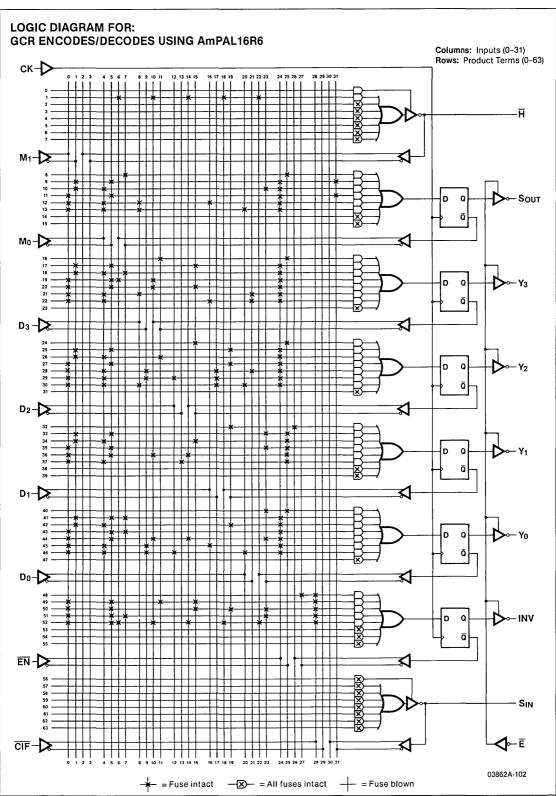
; INITIALIZE /INV C L X X X X X X X X L X X X X H ; SERIAL SHIFT IN TEST	X X H H H H H
X H X X X X X X X X X X Z Z Z Z Z Z Z Z	X H H H H
; INITIALIZE /INV C L X X X X X X X X L X X X X H ; SERIAL SHIFT IN TEST	X H H H H
C L X X X X X X X X L X X X X H ; ; SERIAL SHIFT IN TEST	H H H H
; SERIAL SHIFT IN TEST	H H H H
; SERIAL SHIFT IN TEST	H H H H
·	H H H H
C L H H H H H H X H H H H L H	H H H H
	H H
C L H L L X X X X H H H H L H H H	H
;	
; SYNCHRONIZATION MARK DETECT TEST	
	H
; 4B TO 5B CONVERSION FOLLOWED BY 5B TO 4B RECONVERSION	
	H
	H
	H H
_	Н
	H
	H
	H H
	Н
	Н
	H
	H H
	Н
	Н
	H
	H H
	H
	Н
	H
	H
	H H
	H
	H
C L H H H H H L X H L H H L L H C L H H L X X X X L H H H H L L H	H H
C	п
C L H H L X X X X L H H H L L L H	H

;																	
;	SE	RIA	LS	HIF	ΤΙ	ΝI	EST	'									
С	L	H	H	H	Н	Н	Н	H	X	H	H	Н	H	Н	L	H	H
С	L	H	L	H	Х	Х	Х	Х	Х	Н	L	Н	Н	Н	H	H	H
С	$\mathbf{L}$	Н	L	Н	X	Х	Х	Х	Х	H	H	L	Н	H	H	H	H
С	L	Н	L	Н	Х	Х	X	X	X	H	H	H	L	H	H	H	H
С	L	Н	L	Н	X	Х	Х	Х	Х	H	Н	H	Н	L	Н	H	Н
С	ī.	Н	L	Н	X	X	X	Х	Х	H	Н	Н	Н	Н	L	H	H
Č	Ī.	H						X		H	ī.	Н	Н	Н	H	Н	Н
-										••				••	••	21	•••

## DESCRIPTION

THIS PART IMPLEMENTS A 4B 5B ENCODER/DECODER FOR TAPE DRIVES. ON A WRITE IT ENCODES THE 4B INPUT DATA TO THE 5B FORMAT AND SERIALIZES THE DATA. ON A READ THE 5B DATA IS SHIFTED IN, RECONVERTED TO THE 4B FORMAT, AND OUTPUT TO THE DATA BUS.

```
V0009 C1100001100XHHLLHHH1 *
V0010 C10XXXX11000HHLLLH1 *
V0011 C1100011100XHHLHHHH1 *
VOO12 C10XXXX11000HHLLLLH1
V0013 C1100101100XHLLHLHH1
VOO14 C10XXXX11000HHLLHLH1
V0015 C1100111100XHLLHHHH1 *
V0016 C10XXXX11000HLLLLLH1 *
V0017 C1101001100XHHHLHHH1 *
VOO18 C10XXXX11000HHHHLLH1 *
V0019 C1101011100XHLHLHHH1 *
V0020 C10XXXX11000HHLHLLH1 *
V0021 C1101101100XHLHHLHH1 *
VOO22 C10XXXX11000HHLHHLH1
V0023 C1101111100XHLHHHHH1
VOO24 C10XXXX11000HLLHLLH1
V0025 C1110001100XHHLHLHH1 *
VOO26 C10XXXX11000HHHLHLH1
V0027 C1110011100XHHLLHLH1
V0028 C10XXXX11000HLHLLLH1
V0029 C1110101100XHHLHLLH1
VOO30 C10XXXX11000HLHLHLH1
V0031 C1110111100XHHLHHLH1 *
V0032 C10XXXX11000HLLLHLH1 *
V0033 C1111001100XHHHHLHH1
V0034 C10XXXX11000HHHHHLH1 *
V0035 C1111011100XHHHLHLH1 *
V0036 C10XXXX11000HLHHLLH1 *
V0037 C1111101100XHHHHLLH1 *
V0038 C10XXXX11000HLHHHLH1 *
V0039 C1111111100XHHHHHLH1 *
VOO40 C10XXXX11000HLLHHLH1
V0041 C11111111100XHHHHHLH1 *
VOO42 CO1XXXX1100XHHHHLHH1
VOO43 CO1XXXX1100XHHHLHHH1 *
VOO44 CO1XXXX1100XHHLHHHH1 *
V0045 C01XXXX1100XHLHHHHH1 *
V0046 C01XXXX1100XHHHHHLH1 *
V0047 C01XXXX1100XHHHHLHH1 *
CA76
```





# Interfacing the 8086 (8088) to the Z-BUS

## by Nick Zwick Advanced Micro Devices

This application note describes how replacing two 8086 support chips with a Z8000 support chip and an AmPAL16R8A allows the 8086 CPU to interface directly to the Z-BUS. Since the timing of the signals used is the same for the 8088 CPU, this circuit will work equally well in those applications.

Interfacing the 8086 CPU to the Z-BUS allows 8086 users to take advantage of the very powerful Z8000 peripheral and memory support circuits that are available. The Z8000 peripheral circuits in particular offer the user higher throughput rates, simpler control software and less system overhead requirements than any previous generation peripheral family for any CPU.

#### **DESIGN REQUIREMENTS**

The 8086 CPU can operate in two different modes. In minimum mode, it generates all the bus control and timing signals for the 8086 (8085, 8088) buses directly on-chip. In maximum mode, the CPU puts out status information early in each bus cycle and relies on an external bus controller chip, the 8288, to generate timing and control signals. This implementation uses the CPU in maximum mode and replaces the 8288 with a programmable array logic element

(AmPAL16R8A) that generates the Z-BUS timing and control signals from the status signals provided by the CPU. It also makes use of the AmZ8127 clock generator to allow precise timing resolution by providing an oscillator signal at 3 times the CPU clock frequency. The AmZ8127 provides all the clock generation functions of an 8284A as well as several additional functions. Either clock chip will work in this system.

The bus controller provides the following functions:

- —Generates AS, DS, INTACK and R/W with proper timing relative to address and data.
- —Provides simultaneous assertion of  $\overline{\text{AS}}$  and  $\overline{\text{DS}}$  during reset.
- —Automatic insertion of 1 wait state for all I/O cycles.
- —Synthesizes a single Z-BUS interrupt acknowledge cycle from the 8086 IACK cycles.

Figure 1 shows the circuit interconnection diagram. The system uses a high speed AmPAL16R8A to generate  $\overline{AS}$ ,  $\overline{DS}$ , R/W and  $\overline{INTACK}$  of the Z-BUS, RDY for wait state generation, and three internal state variables. The registers are clocked with the 15MHz OSC signal from the 8127. The five input signals to the PAL are 5MHz CPU Clock Signal (CLK), System Reset (RESET), and the three CPU Status States  $(\overline{S_0}, \overline{S_1}, \overline{S_2})$ .

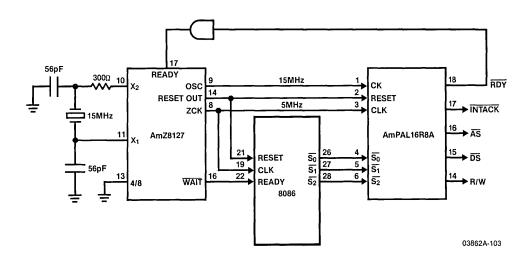


Figure 1. Circuit Interconnection Diagram

The CPU indicates the start of a bus cycle by bringing at least one of the status lines low from the idle high state (see Figure 2). This starts an internal timing sequence within the PAL which corresponds closely to the various T states of a bus cycle.  $\overline{AS}$  is asserted during the time CLK is LOW during  $T_1.$   $\overline{DS}$  is asserted at the start of  $T_3.$  If it is an I/O cycle, then RDY would be disabled for one CLK period straddling  $T_2$  and  $T_3$  causing the 8127 to request 1 wait state after  $T_3.$  In either case,  $\overline{DS}$  remains asserted until after the first 1/3 of  $T_4$ , which is identified by the status lines returning to the idle state during the previous cycle. R/W is generated by sampling  $\overline{S_0}$  and  $\overline{S_1}$  during  $\overline{AS}.$ 

It is in the realm of interrupts where the Z8000 peripherals shine over other periperhals. Each peripheral can identify many different exception conditions during its operation. The occurrence of one or more of these conditions causes activation of a single interrupt request line. The peripheral wants the CPU to respond with a single interrupt acknowledge cycle, during which the peripheral resolves priority and provides the CPU with enough status and vector information to allow it to respond to the exception without any further interrogation of the peripheral. This allows interrupt driven systems to achieve very high data throughput rates.

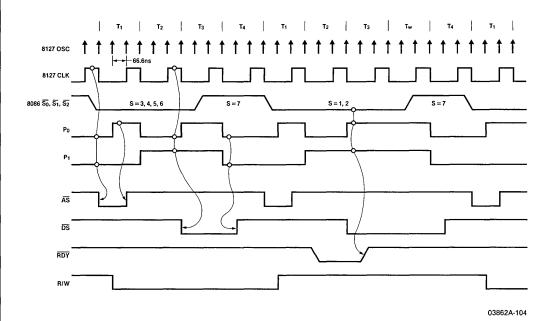


Figure 2. Memory and I/O Timing Diagram

The 8086 CPU responds to an interrupt request with a sequence of two interrupt acknowledge cycles, and only in the second is any data read off the bus. As stated before, the Z-BUS peripherals require only one acknowledge cycle. The timing of this has to be such that there is enough delay between  $\overline{\rm AS}$  going HIGH and  $\overline{\rm DS}$  going LOW to allow any prioritizing daisy chains to settle, and  $\overline{\rm DS}$  has to be wide enough to allow the peripheral time to place vector or status information on the bus. Figure 3 shows how these two requirements are accomplished by turning the two acknowledge cycles into one. The first cycle allows only  $\overline{\rm AS}$  and the second asserts only  $\overline{\rm DS}$  and does so for the complete cycle. This appears to the peripheral as one very long bus cycle which is identified as an interrupt acknowledge cycle by the assertion of  $\overline{\rm INTACK}$ .

#### **DESIGN APPROACH**

To implement this design in a AmPAL16R8A requires recognizing the Z-BUS timing characteristics in Figures 2 and 3. The major characteristic to consider is counting the phases of a bus cycle. Internal state variables  $P_0$  and  $P_1$  are the result (see Figure 4a). An additional internal state variable  $(I_2)$  is necessary to count the second bus cycle of an interrupt acknowledge sequence. As shown in Figure 4b,  $I_2$  in conjunction with  $\overline{INTACK}$  allows  $\overline{AS}$  to be asserted only in the first interrupt acknowledge cycle and  $\overline{DS}$  only in the second. The RESET input is used to initialize the internal variables and assert  $\overline{AS}$  and  $\overline{DS}$ . Note also that  $\overline{S_0}$  and  $\overline{S_1}$  are included in the  $\overline{DS}$  equation to prevent  $\overline{DS}$  from being asserted during a halt cycle.

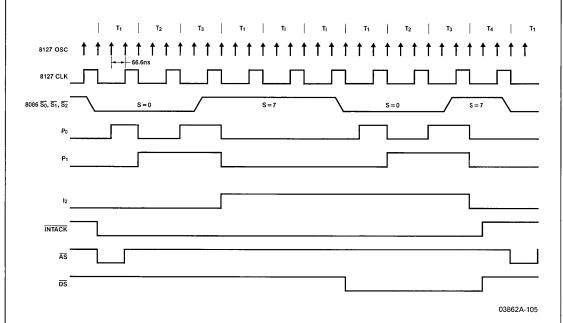


Figure 3. Interrupt Acknowledge Timing Diagram

The fact that AMD PALs are user programmable allows a great deal of flexibility for the designer. Minor timing changes are easily implemented by simply adding or changing a term in the logic equations and reprogramming the device. In this system, we have timing resolution to 67ns. This same configuration can be used with a 24MHz crystal for 8MHz CPU chips. The logic equations would change because the OSC period would be 42ns. The only hardware change would be the crystal.

An additional PAL could also perform chip select decoding based on both address and status signals.

### CONCLUSION

We have seen how a properly programmed PAL can be used to replace a specialized bus controller chip and allow an 8086 CPU to interface directly to Z-BUS peripheral(s) and/or memory systems. This brings all the advantages of the superior Z8000 peripheral family in terms of both throughput and ease of use to 8086 users with no increase in chip count while still allowing a wide range of design flexibility. The logic diagram and PALASM equations for the AmPAL16R8A 8086 to Z-BUS interface chip are also shown.

P <sub>1</sub>	P <sub>0</sub>	PHASE	CPU T STATES
0	0	IDLE	T4, T1
0	1	AS TIME	T <sub>1</sub>
1	0	AS TO DS DELAY	T <sub>2</sub>
1	1	DS TIME	T <sub>3</sub> , T <sub>W</sub>

03862A-106

Figure 4a

l <sub>2</sub>	INTACK	ĀS	<del>DS</del>
NO	NO	YES	YES
NO	YES	YES	NO
YES	YES	NO	YES

03862A-107

Figure 4b

```
PAL16R8
                                     PAL DESIGN SPECIFICATION
                                                      6/21/82
                                     NICK ZWICK
PATO04
8086 TO Z-BUS INTERFACE CHIP
ADVANCED MICRO DEVICES
CK RESET CLK /SO /S1 /S2 NC
                                 NC NC GND
/E /PO /P1 /RW /DS /AS /INTACK RDY /I2 VCC
;INTERNAL STATE VARIABLES
        := /RESET* SO*/PO*/P1*/CLK +
P0
           /RESET* S1*/PO*/P1*/CLK +
           /RESET* S2*/P0*/P1*/CLK +
           /RESET*PO*/CLK
           /RESET*P1*CLK* SO
           /RESET*P1*CLK* S1
           /RESET*P1*CLK* S2
P1
        := /RESET*PO*/P1*CLK
           /RESET*P1*/CLK
           /RESET*P1*CLK* SO
           /RESET*P1*CLK* S1
           /RESET*P1*CLK* S2
        := /RESET*INTACK*/I2*CLK*PO*P1 +
12
           /RESET*I2*/P1
           /RESET*I2*/PO
           /RESET*I2*PO*P1*/CLK
;Z-BUS OUTPUT SIGNALS
AS
        := RESET
           /PO*/P1*CLK*/I2
           AS*/PO*/I2*/DS
DS
        := RESET
           /INTACK*/PO*P1*CLK*SO
                                   +
           /INTACK*/PO*P1*CLK*S1
           I2* S0* S1* S2
           DS*PO*P1
RW
        := AS*SO*/S1
           RW*/AS
INTACK := /RESET* SO* S1* S2
           /RESET*INTACK*/I2*P1
           /RESET*I2
/RDY
        := /RESET*SO*/S1* S2*/PO*P1 + ;DISABLE READY ON I/O OP
           /RESET*/SO*S1* S2*/PO*P1
```

FUNCTION TABLE CK RESET CLK /S2 /S1 /SO PO P1 I2 /AS /DS /RW /INTACK RDY

	NITIAI								_				
C ;	H	X	X	X	X	L	L	L	L	L	Х	Н	Н
	EMORY	WRIT			'ION								
С	L	L	H	H	Н	L	L	L	H	H	H	H	H
C C	L	Н	H	H	L	L	L	L	L	Н	H	Н	H
C	L L	L L	H H	H H	L L	H H	L L	L L	L H	H H	L L	H H	H H
Č	L	H	H	H	L	L	Н	L	H	Н	L	Н	H
C	L	L	H	H	Ĺ	Ĺ	H	Ĺ	H	H	Ĺ	Ĥ	Ĥ
С	L	L	H	Н	L	L	H	L	H	H	L	H	Н
C	L	H	H	H	L	Н	H	Ļ	H	L	L	Н	H
C C	L L	L L	H H	H H	L H	H H	H H	L L	H H	L L	$_{ m L}$	H H	H H
C	L	Н	п Н	н	л Н	L	n L	L	п Н	L	L	H	Н
Č	Ĺ	Ĺ	H	H	H	Ĺ	Ĺ	L	H	H	Ĺ	H	H
С	L	L	Н	Н	H	L	L	L	Н	Н	L	H	H
; • T	/O REA	AD OF	PERAT	מחדי									
Ċ	L	Н	L	L	Н	L	L	L	L	Н	L	Н	Н
С	L	L	L	L	Н	H	L	L	L	Н	H	Н	H
С	L	L	L	L	Н	Н	L	L	Н	Н	H	H	H
C	L	H	L	L	H	L	Н	L	Н	H	Н	H	Н
C	L	L	L	L	H	L	H	L	H	H	H	H	Ļ
C	L L	L H	L L	L L	H	L	Н	L	Н	H	Н	H	L L
C	L	п L	L	L	H H	H H	H H	L L	H H	L L	H H	H H	H
č	Ĺ	Ĺ	Ĺ	Ĺ	H	H	Н	Ĺ	H	Ĺ	H	H	H
С	L	H	L	L	H	Н	Н	L	H	Ĺ	H	H	H
C	L	L	L	L	H	H	H	L	H	L	Н	H	H
C	L	ŗ	H	H	H	H	H	L	Н	L	H	H	H
C C	L L	H L	H H	H H	H H	L L	L L	L L	H H	L H	H H	H H	H H
;	Ь	ы	п	п	п	ь	П	יד	п	n	п	п	n
	WO CYO	CLE I	NTE	RUPT	SEQ	UENC	E						
С	L	Н	L	L	L	L	L	L	L	H	H	L	H
C	L	L	L	Ĺ	L	H	Ļ	L	L	H	H	L	H
C	L L	L H	L	L	L L	H	L	L	Н	H	H	L	H
C	L	n L	L L	L L	L	L L	H H	L L	H H	H H	H H	L L	H H
Č	L	L	Ĺ	L	L	Ĺ	Н	L	п Н	Н	п Н	L	n H
С	Ĺ	H	Ĺ	Ĺ	Ĺ	H	Н	Ĺ	Н	H	H	Ĺ	H
C	L	L	L	L	L	H	Н	L	Н	H	Н	L	H
Č	L	L	H	Н	H	Н	H	L	H	H	H	L	Н
C	L	H	H	H	H	L	L	Н	H	H	Н	L	Н
C	L	L	H	H	Н	L	L	H	H	H	H	L	H
C	L L	L H	H L	H L	H L	L L	$_{ m L}$	H H	H H	H L	H H	L L	H H
C	L	n L	L	L	L	H	L	н	н	L	H	L	л Н
Č	L	L	Ĺ	Ĺ	L	Н	L	Н	Н	Ĺ	Н	Ĺ	Н
C	L	H	L	Ĺ	Ĺ	L	H	Н	Н	Ĺ	H	Ĺ	H

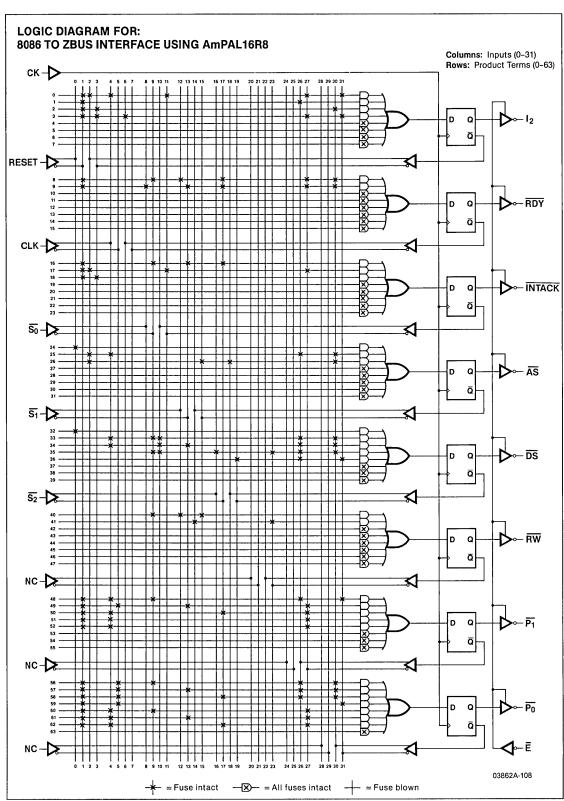
С	L	L	L	L	L	L	Н	Н	Н	L	Н	L	H
С	L	L	L	L	L	L	Н	Н	H	L	H	L	H
					L								H
С	L	L	L	L	L	H	Н	Н	H	L	H	L	Н
					H								H
С	L	Н	H	H	H	L	L	L	H	L	H	L	H
С	L	L	H	H	H	Ļ	L	L	Н	Н	H	H	H

#### DESCRIPTION

THIS DEVICE IS USED FOR INTERFACING THE 8086 CPU DIRECTLY TO THE Z-BUS ALLOWING INTEGRATION OF THE VERY POWERFUL Z8000 PERIPHERAL AND MEMORY SUPPORT CIRCUITS INTO 8086 SYSTEMS. THE DEVICE IS DESIGNED TO WORK IN CONJUNCTION WITH THE Z8127 CLOCK GENERATOR FOR PRECISE TIMING RESOLUTION.

```
PAL16R8
                              PAL DESIGN SPECIFICATION
PATO04
                              NICK ZWICK
                                            6/21/82
8086 TO Z-BUS INTERFACE CHIP
ADVANCED MICRO DEVICES
*D9724
*F0*
L0032 1010 1111 1111 1111 1111 1111 1101 1111 *
L0096 1010 1011 1111 1111 1111 1111 1110 1110 *
L0256 1011 1111 1011 0111 1011 1111 1110 1101 *
LO288 1011 1111 0111 1011 1011 1111 1110 1101 *
L0544 1001 1111 1110 1111 1111 1111 1110 1111 *
L0576 1010 1111 1111 1111 1111 1111 1111 *
L0768 0111 1111 1111 1111 1111 1111 1111 *
L0800 1101 0111 1111 1111 1111 1111 1101 1101 *
L1056 1111 0111 1001 1111 1111 1111 1110 1101 *
L1088 1111 0111 1101 1011 1111 1111 1110 1101 *
L1152 1111 1111 1111 1111 1110 1111 1110 **
L1312 1111 1111 1111 1101 1111 1110 1111 1111 *
L1536 1011 0111 1111 1111 1111 1111 1101 1110 *
L1568 1011 1011 1111 1111 1111 1111 1110 1111 *
L1600 1011 0111 1011 1111 1111 1111 1110 1111 *
L1632 1011 0111 1111 1011 1111 1111 1110 1111 *
L1664 1011 0111 1111 1111 1011 1111 1110 1111 *
L1792 1011 1011 1011 1111 1111 1111 1101 1101 *
L1824 1011 1011 1111 1011 1111 1111 1101 1101 *
L1856 1011 1011 1111 1111 1011 1111 1101 1101 *
L1920 1011 0111 1011 1111 1111 1111 1110 1111 *
L1952 1011 0111 1111 1011 1111 1111 1110 1111 *
L1984 1011 0111 1111 1111 1011 1111 1110 1111 *
C711D*
VOOO1 C1XXXXXXXXXXXXHXLLHHH1 *
V0002 C00111XXX0XHHHHHHHHH *
V0003 C01011XXX0XHHHHLHHH1 *
VOOO4 COOO11XXXOXLHLHLHHH1 *
V0005 C00011XXX0XLHLHHHHHH *
VOOO6 CO1011XXXOXHLLHHHHHH1 *
V0007 C00011XXX0XHLLHHHHH1 *
VOOO8 COOO11XXXOXHLLHHHHHH1 *
VOOO9 CO1011XXXOXLLLLHHHHH1 *
VOO10 COOO11XXXOXLLLLHHHH1 *
VOO11 COO111XXXOXLLLLHHHHH1 *
VOO12 CO1111XXXOXHHLLHHHH1 *
V0013 C00111XXXOXHHLHHHHH1 *
VOO14 COO111XXXOXHHLHHHHHH *
VOO15 CO1100XXXOXHHLHLHHH1 *
VOO16 COO100XXXOXLHHHLHHH1 *
VOO17 COO100XXXOXLHHHHHHHHH *
```

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VOO18 CO1100XXXOXHLHHHHHHH *
VOO19 COO100XXXOXHLHHHHLH1 *
VOO20 COO1OOXXXOXHLHHHHLH1
VOO21 CO1100XXXOXLLHLHHLH1 *
VOO22 COO1OOXXXOXLLHLHHHHH1 *
VOO23 COO1OOXXXOXLLHLHHHHH1 *
VOO24 CO1100XXXOXLLHLHHHHH1 *
VOO25 COO100XXXOXLLHLHHHHH1 *
VOO26 COO111XXXOXLLHLHHHH1
VOO27 CO1111XXXOXHHHLHHHH1 *
V0028 C00111XXX0XHHHHHHHHH *
VOO29 CO1000XXXOXHHHHLLHH1 *
VOO30 COOOOOXXXOXLHHHLLHH1 *
V0031 C00000XXX0XLHHHHLHH1 *
VOO32 CO1000XXXOXHLHHHLHH1 *
VOO33 COOOOOXXXOXHLHHHLHH1 *
VOO34 COOOOOXXXOXHLHHHLHH1 *
V0035 C01000XXX0XLLHHHLHH1 *
VOO36 COOOOOXXXOXLLHHHLHH1 *
VOO37 COO111XXXOXLLHHHLHH1 *
V0038 C01111XXX0XHHHHHLHL1 *
V0039 C00111XXX0XHHHHHLHL1 *
VOO40 COO111XXXOXHHHHHLHL1
VOO41 CO1000XXXOXHHHLHLHL1
VOO42 COOOOOXXXOXLHHLHLHL1
VOO43 COOOOOXXXOXLHHLHLHL1
VOO44 CO1000XXXOXHLHLHLHL1
VOO45 COOOOOXXXOXHLHLHLHL1 *
VOO46 COOOOOXXXOXHLHLHLHL1 *
VOO47 CO1000XXXOXLLHLHLHL1 *
VOO48 COOOOOXXXOXLLHLHLHL1 *
VOO49 COO111XXXOXLLHLHLHL1 *
VOO50 CO1111XXXOXHHHLHLHH1 *
V0051 C00111XXX0XHHHHHHHH1 *
A334
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# An AMD PAL MULTIBUS Arbiter

by Mark S. Young Advanced Micro Devices



The popularity of bus oriented systems can be traced to their low cost, flexibility, and expandability. Expansion is easy because a well defined standard enforces compatibility and simplifies interfacing. The MULTIBUS is a good example of a popular and easily used bus standard. However, all of these bus systems require some way of interacting with the other devices on the bus. This interaction is generally controlled by an arbitration unit. This application note will describe how a PAL can be used to construct a custom MULTIBUS arbiter which is higher performance and more economical than the LSI alternatives.

#### **DESIGN REQUIREMENTS**

Since the MULTIBUS can have more than one master trying to use the bus at the same time, an arbitration scheme is required to ensure correct operation of the system. Prioritization is accomplished by assigning different access priorities to the different bus masters. The two implementations available to assign priority are serial and parallel. The serial method involves a daisy chain of bus grant ins (BPRN) and bus grant outs (BPRO) with higher priority devices occupying the positions closer to the beginning of the chain (Figure 1a). The parallel method prioritizes the bus requests (BREQ) of all the masters and generates a bus grant in (BPRN) to the master of highest priority (Figure 1b). The priority decoder of Figure 1b is easily implemented in a single AmPAL16L8 (Figure 1c).

The timing requirements for the MULTIBUS are very easy to implement and are designed to handle the usual timing problems that appear in many systems. Control signals are all active LOW so that unconnected signals don't interfere with the

normal operation of the bus. All bus arbitration is synchronous and all data transfers are asynchronous (see Figures 2a and 2b). The only requirement is that an address be valid 50ns before any control signals (read or write) become active. This prevents subtle timing problems caused by slow buffer/driver turn-on times.

The arbitration and grant timing (illustrated in Figure 2c) is also straightforward. Transfer requests are sent to the arbiters which then decide who gets the bus. If a master device is currently using the bus and is ordered off, it is allowed to complete its current bus transfer cycle (i.e., the current word or byte only). If the master, which was overruled, still needs the bus, it must wait until its priority is high enough to regain the bus.

A typical sequence is initiated when an external request is received (SREQ) from a master device. This signal is synchronized to insure a valid bus request, minimizing the possibility of a metastable state occurring. After synchronization, the bus priority out (BPRO) line is disabled to signal lower priority masters in the chain that a higher priority master wants the bus (serial method). In the parallel method, bus request and common bus request (BREQ and CBREQ) are asserted to let the other MULTIBUS arbiters know a master wants the bus. Now, if the bus is not busy (BUSY is inactive), then the arbiter grants the requesting master access to the bus and asserts BUSY. The address buffers are enabled at this time, one cycle ahead of the read and write signals. When the master receives a bus acknowledge (XACK) from the slave device, a single transfer cycle has occurred. The bus master then releases the bus and if it needs to do more transfers, another arbitration/grant cycle must take place.

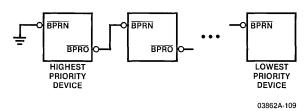


Figure 1a. Serial Priority Resolution

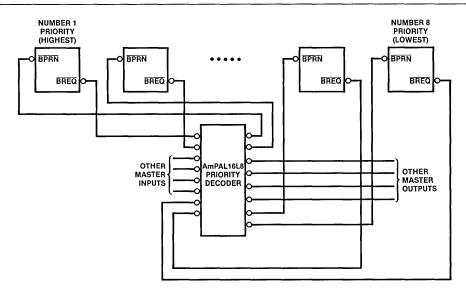


Figure 1b. Parallel Priority Technique

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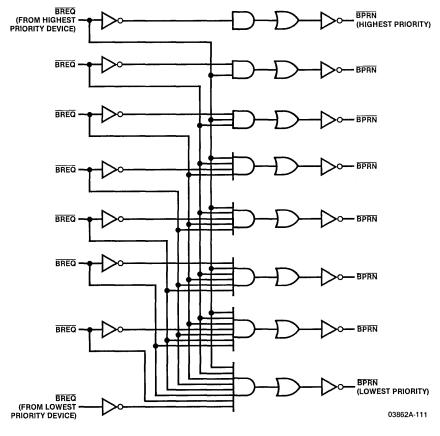
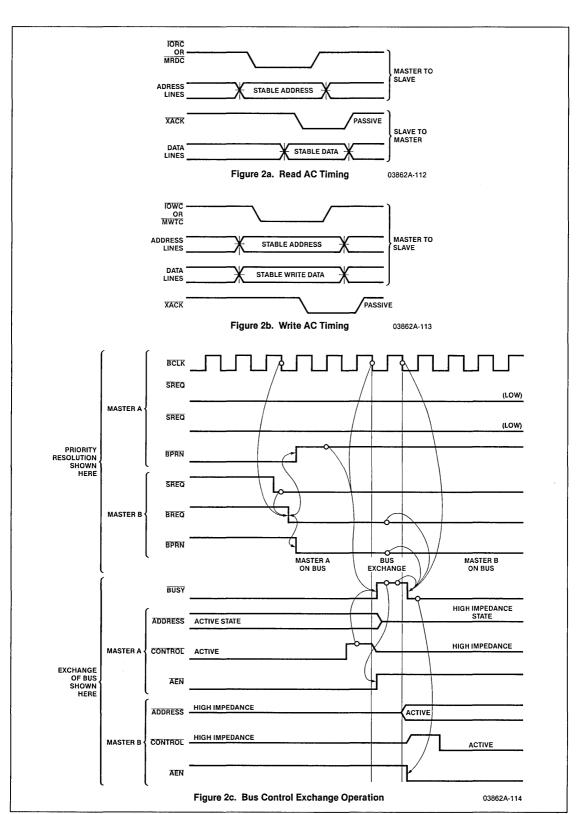


Figure 1c. PAL Implementation of Parallel Priority Resolution for MULTIBUS



#### **DESIGN APPROACH**

The first step in actually designing the arbiter was to convert the arbitration/grant and control signal sequence into a simple state transition diagram (see Figure 3). The state diagram was then partitioned into its three basic components:

- -request/synchronization
- -grant/access logic
- -control signals

The bus request logic decides when to issue a bus request using SREQ along with a qualifying read or write request (RD or  $\overline{WR}$ ). This signal is then fed through a double synchronizer (states 1 and 2). This creates an internally stable bus request signal for the arbiter state machine (see Figure 4a). Next, this

request is fed into a bus grant flip-flop through some intervening logic. The intervening logic uses current bus status lines to determine whether to acquire the bus, give it up after the current transfer cycle is complete, or hold the bus (see grant/access logic in Figure 4b). The final major function is the bus control logic. After successful acquisition of the bus, the appropriate control signals (MRDC, MWTC, IORC, IOWC) and address buffer enables must be asserted. In this case, the address buffer enable/grant (AEN) line is run through a flip-flop to become a delayed read/write control signal enable (OEN). This gives the drivers enough turn-on and set-up time (100ns minimum) for the address to stabilize on the MULTIBUS. The bus transfer control signal logic is illustrated in Figure 4c.

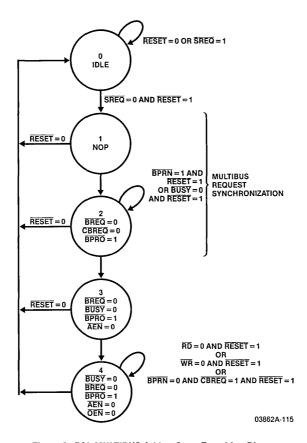


Figure 3. PAL MULTIBUS Arbiter State Transition Diagram

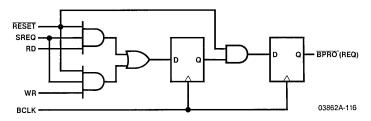


Figure 4a. Request Synchronizer

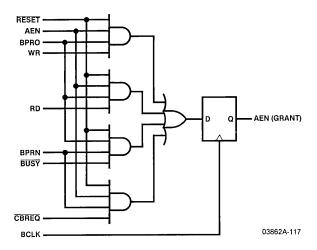


Figure 4b. Grant/Access Logic

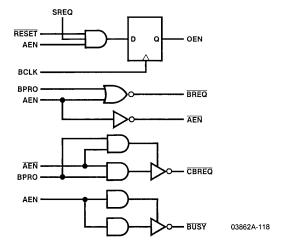


Figure 4c. Bus Transfer Control

The RESET line is run to all the registers to provide a synchronous reset for arbiter initialization. The full MULTIBUS standard requires a control signal drive capability of 32mA for all of its control lines. The PAL 24mA drive specification can drive up to 7 cards on the bus, which is more than adequate for almost all applications.

A couple of interesting features are available which show the flexibility and functionality of PALs in a custom logic design such as this. The available MULTIBUS arbiters, like most LSI devices, have been optimized for one processor family. Any microprocessor (from the Z80 to the 8086, Z8000 or 68000) can be interfaced to the MULTIBUS by tailoring the request logic of the PAL arbiter. This can result in a significant parts count reduction. The MULTIBUS uses open collector drivers for several signal lines (BUSY and CBREQ). While PALs don't have open collector drivers, that condition can easily be

simulated by enabling the output drivers only when the output is active. In addition, most MULTIBUS arbiters force each master to re-arbitrate for access to the bus at the end of each data transfer. However, in the PAL arbiter design, if a master is executing multiple data transfers and if no master of higher priority is requesting the bus then the current master can retain the bus and execute more transfers. This reduces bus arbitration overhead and increases bus bandwidth. Finally, at the completion of all transfers, the current bus master normally releases the bus. In this design, if no one wants the bus, the last master to use it holds onto the bus on the assumption that it is going to be the next user. If it is, arbitration time is saved. If not, no time is lost.

Figure 5 shows a block diagram of the arbiter and bus control logic (which fits into 1/2 of a AmPAL16L8). A complete logic diagram and PALASM equations of the AmPAL16R4 are shown on the following pages.

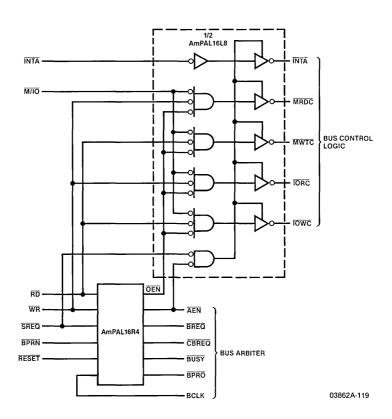


Figure 5. PAL MULTIBUS Arbiter with Bus Control Logic

PAL16R4

PAL DESIGN SPECIFICATION MARK S. YOUNG 6/22/82

PATO05

MULTIBUS ARBITER

ADVANCED MICRO DEVICES

BCLK /RD /WR /SREQ /RESET /BPRN NC NC NC GND

/E /CBREQ /BUSY /SYNC /BPRO /AEN /OEN /BREQ NC VCC

SYNC := /RESET\*SREQ\*RD

/RESET\*SREQ\*WR

BPRO := /RESET\*SYNC

AEN := /RESET\* AEN\*BPRO\*WR

/RESET\* AEN\*BPRO\*RD +

/RESET\*BPRO\*BPRN\*/BUSY +

/RESET\* AEN\*BPRN\*/CBREQ

OEN := /RESET\*SREQ\*AEN

IF(BPRO\*/AEN) CBREQ = BPRO\*/AEN

IF(AEN) BUSY = AEN

BREQ = BPRO AEN

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#### FUNCTION TABLE

BCLK /E /RESET /RD /WR /SREQ /BPRN SYNC BPRO AEN OEN CBREQ BUSY BREQ

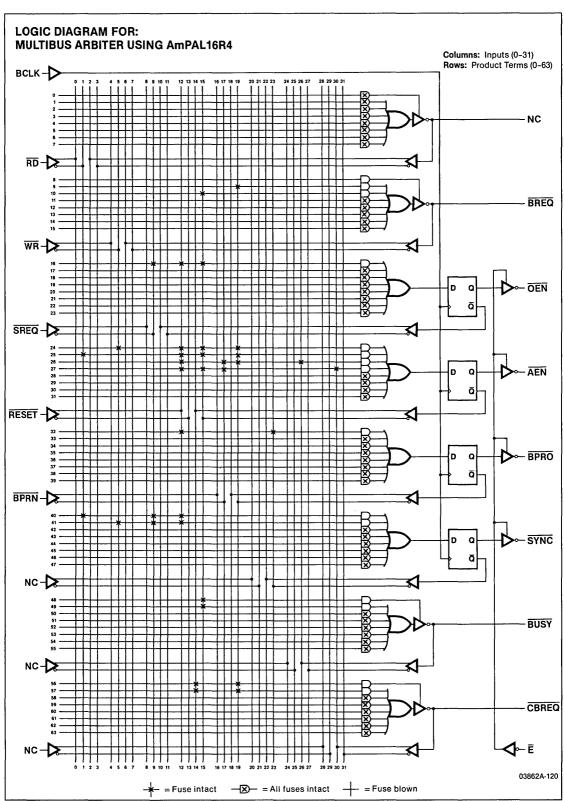
;													
;IN	ITIA	LIZE											
Ċ	L	L	Х	X	X	X	L	L	L	L	L	L	L
;													
;WR	ITE	OPER	ATION										
С	$\mathbf{L}$	H	H	Н	L	L	$\Gamma$	$\mathbf L$	L	L	L	L	L
С	L	Н	H	L	$\mathbf{L}$	L	H	$\mathbf{L}$	L	L	L	L	L
С	L	H	H	L	L	L	H	Н	L	L	Н	L	H
С	L	Н	H	L	L	L	H	H	Н	L	L	X	H
С	L	H	H	L	L	L	H	H	Н	Н	L	Н	H
C C	$\mathbf{L}$	H	H	L	L	L	H	H	H	H	L	H	H
С	$\mathbf{L}$	H	H	L	L	L	H	H	H	H	L	H	H
С	L	H	H	H	L	L	L	H	H	H	L	H	H
C	$\mathbf{L}$	Η	H	H	H	L	L	$\mathbf{L}$	H	L	L	Н	H
;													
;RE	MOVE	THE	ARBITI	ER F	ROM T	HE BUS							
C	Ĺ	H	H	H	H	H	L	L	L	L	L	L	L
;													
; RE	AD O	PERA	TION (V	HTIN	BUS	CONTENT:	ION)						
С	L	H	H.	H	L	L	Ĺ	L	L	L	L	H	L
С	L	H	L	H	Ĺ	L	Н	L	L	L	L	Н	L
С	L	H	L	Н	L	L	H	H	L	L	Н	Н	Н
Ċ	L	Н	L	H	L	L	H	Н	L	L	Н	Н	Н
С	L	Н	L	H	L	Ĺ	H	H	L	Ĺ	H	H	H
Č	L	H	Ĺ	H	Ĺ	Ĺ	H	H	H	L	L	X	Н
C	L	Н	L	H	L	Ĺ	H	H	H	H	Ĺ	H	H
Č	Ĺ	H	Ĺ	Ĥ	Ĺ	Ĺ	H	H	H	H	Ĺ	H	H
C	L	H	L	H	Ĺ	Ĺ	H	H	H	H	Ĺ	H	Ĥ
Č	Ĺ	H	Ĺ	H	Ĺ	Ĺ	H	H	H	Ĥ	Ĺ	H	H
C	L	H	H	H	Ĺ	Ĺ	Ĺ	H	H	H	Ĺ	H	H
Č	Ĺ	H	Ĥ	H	H	Ĺ	Ĺ	Ĺ	H	Ĺ	Ĺ	H	H

### DESCRIPTION

THIS DEVICE IS A MULTIBUS ARBITER. IT SUPPORTS BOTH SERIAL AND PARALLEL BUS ARBITRATION SCHEMES. INTERNAL SYNCHRONIZATION LOGIC MINIMIZES THE POSSIBILITY OF METASTABLE CONDITIONS. THE GRANT/ACCESS LOGIC HAS BEEN DESIGNED TO MINIMIZE BUS ARBITRATION OVERHEAD. THE TRANSFER CONTROL LOGIC HAS BEEN DESIGNED TO ALLOW INTERFACING A WIDE VARIETY OF PROCESSORS TO THE MULTIBUS.

5484

6/22/82



# Am8500 to MC68000 PAL Interface

by Mark S. Young Advanced Micro Devices



Modern 16-bit microprocessors, such as the 8086, Z8000, and 68000, are being used to form the nucleus of powerful personal/business computers and engineering workstations. However, support peripheral chips are virtually non-existent for the most recently introduced 16-bit CPUs such as the Motorola 68000. Since the modern microprocessor system depends as much on the peripheral controllers as it does on the CPU, it is important for a system designer to have a large variety of peripheral chips available. The 8500 family of peripheral chips from AMD, provides users of non-multiplexed bus microprocessors, such as the 68000, a variety of powerful peripheral chips that can be interfaced easily with a single programmable array logic (AMD PAL) device.

#### THE Am8500 FAMILY

The Am8500 family is a group of programmable peripheral chips which offload a variety of system functions from the main CPU. They support a variety of operating modes which are specified by writing to their control registers. The current members of the family include the Am8536 Counter/Timer and Parallel I/O Unit (CIO), the Am8038 FIFO Input/Output Interface Unit (FIO), and the Am8530 Serial Communications Controller (SCC). While the object of this article is not to discuss the capabilities of the Am8500 family, a brief overview is necessary to fully understand its interface requirements.

The Am8536 is a counter/timer chip which has available three 16-bit counters. These timer/counters have features such as duty cycle control (pulsed, one-shot, or square waved), retriggering options, and external access control lines. The CIO also provides up to 20 lines of programmable I/O ports. The Am8038 FIO is an asynchronous 128 byte buffer specially designed to be used by two CPUs or a CPU and a peripheral device as a communication or data buffer. It supports a variety of handshake interfaces on both I/O ports. Finally, the Am8530 SCC is a dual channel, multi-protocol data communications peripheral. The SCC functions as a serial to parallel, parallel to serial converter/controller. It supports a wide variety of serial communications protocols and includes extensive on-board hardware such as baud rate generators, digital phase-locked-loops, and crystal oscillators to reduce the need for external logic.

The Control and frequently used Data registers are accessed in a different manner. These registers are accessed using a single cycle or write. This scheme allows the CPU to interact efficiently with the 8500 peripherals during normal use. The slower, clumsier initialization procedure is used much less frequently and protects the user from altering the operation mode accidentally.

All the members of the Am8500 family are controlled and configured by software. The host CPU initializes the Am8500 operating modes by writing to the internal mode/options registers. The internal mode registers are not directly addressable by the CPU like the Control and some data registers. Instead, a two cycle process is needed to write to them. First, the address of the mode/options register being modified is written to the Control register; next, the data is written to the mode/options register via the Control register. The Am8500 peripheral has an internal state machine to keep track of whether address or data is being written to the Control register. Reading the value of the mode/options register is accomplished by first, writing an address to the Control register, and second, reading the mode/options data from the Control register.

#### **DESIGN REQUIREMENTS**

There are several problems associated with interfacing a general purpose peripheral device to a CPU. One major problem involves the various control signals each chip uses. Unless the two families are designed to be pin for pin compatible (e.g., the AMD/Intel 8086/8087/8089) there generally is going to be minor variations between them; the same problem exists when interfacing the 8500 peripherals to the 68000. Part of the pin incompatibility involves genuine signal differences while other pins only require name changes.

The data pins (D<sub>0</sub>–D<sub>7</sub>) on the 8500 parts are connected directly to the lower 8 data lines on the 68000 bus. The register select pins (A<sub>0</sub>, A<sub>1</sub>, A/ $\overline{B}$ , D/ $\overline{C}$ )\* can be directly connected to A<sub>1</sub> and A<sub>2</sub> of the 68000 address bus. The  $\overline{RD}$  and  $\overline{WR}$  lines have to be generated from the 68000's R/ $\overline{W}$  and  $\overline{AS}/\overline{UDS}/\overline{LDS}$  signals. The 8500 clock (PCLK) is generated by dividing down the 68000 clock.

<sup>\*</sup>Note: The register select/control pins have different names on each of the 8500 peripherals.

The Interrupt Request line (INT) can be wire-ORed together and connected to one of the IPL0-IPL2 inputs on the 68000, giving all the peripherals a common interrupt priority level. An alternate method might be to give each of the peripherals a separate priority level (which would require priority encoding). The interrupt acknowledge line must be generated from the CPU status lines (FC0-FC2) by the PAL. Whenever an interrupt acknowledge cycle is started, FC0-FC2 equal all ones. The Interrupt daisy chain control pins (IEI and IEO on each 8500 device) are tied together in a standard priority daisy chain arrangement (see Figure 1). When implementing the daisy chain, arbitration delay down the chain must be accounted for in the PAL signal generation logic. The chip enable pins for each of the 8500 devices must come from the system memory mapping logic. The system designer must also provide an 8500 PAL enable line to select the PAL controller whenever any one of the 8500 devices has been selected. The DTACK signal back to the CPU will be generated by the PAL logic using an internally implemented state counter to generate the correct timing. The output is implemented as a simulated open collector output so that other non-Am8500 peripherals in the system can use the DTACK line

Another problem with interfacing general purpose peripherals to the 68000 is timing. Most peripherals run at speeds considerably slower than the 8, 10, 12, and 16MHz CPUs being produced today. This means using either a slower clock or dividing down the CPU clock. In the case of the 8500 family this generally means dividing the CPU clock in half and using a CPU operating at less than or equal to 12MHz. Aside from just speed problems, system integrators frequently have to

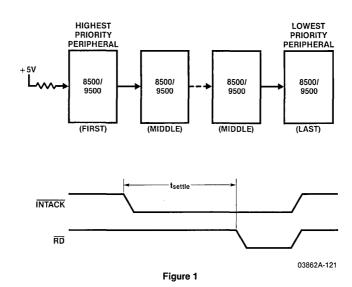


Table 1. Interrupt Daisy Chain/Propagation Delay

Chain Position (ns)											
Perip	heral	First	Middle	Last							
8536	CIO	350	150	100							
8038	FIO	350	150	100							
8530	scc	250	120	120							

Note: First position timing is INTACK to IEO.

Middle position timing is IEI to IEO.

Last position timing is IEI to data strobe set-up.

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tackle subtle timing differences between signals or from devised signal equivalents, e.g., deriving the Am8500 RD, WR, and DTACK from the 68000's LDS and R/W; or guaranteeing data set-up and hold times.

The 68000 has two ways of interfacing to peripherals such as the 8500 family. The first uses the special VPA (Valid Peripheral Address) input pin on the 68000. The VPA pin can be activated by the Am8500 device select logic at the start of a cycle to tell the 68000 that a peripheral is being accessed. This interface was designed to allow the slow, synchronous bus 6800 peripherals to talk to the 68000's asynchronous bus until the new 68000 peripherals could be produced. Also, the VPA interface has a slow access rate (a minimum peripheral access time of over 1000ns not including recovery time) which would slow down the CPU considerably. And, since all the 68000 peripherals are being designed to use the asynchronous method, this interface will not be discussed.

When writing data, the 68000 puts address and data onto their respective buses and uses the  $\overline{\text{DTACK}}$  line as a "got data successfully" handshake from the selected device. When the  $\overline{\text{DTACK}}$  line is recognized, the 68000 removes address and data one CPU clock later. This method allows the user to take advantage of the asynchronous bus of the 68000. The major difference between the 8500 family and the 68000  $\overline{\text{DTACK}}$  timing is the way data is strobed in and out of the 8500 chips. The 8500 devices sample the data on the falling edge of  $\overline{\text{WR}}$ . The 68000 asserts an address (when reading) onto the bus and then uses the  $\overline{\text{DTACK}}$  signal from the selected peripheral (memory included) to indicate valid data and then

samples on the next falling edge of the CPU clock. The other method of interfacing the Am8500 family to the 68000 uses the Data Transfer Acknowledge (DTACK) cycle.

#### **DESIGN APPROACH**

Two different methods of interfacing 8500 devices to the 68000 bus will be presented. One method allows the user to obtain fast access to all the 8500 devices. However, some minimum software requirements are imposed. The other interface slows down the access rate by the CPU but guarantees all 8500 minimum timing specifications and imposes no software overhead.

There are several timing requirements imposed by the 8500 family. The first involves read/write access to the parts. The 8500 (4MHz) peripherals have a read/write/interrupt acknowledge timing as shown in Figure 2. The minimum read/write access time is 400ns. This means the PAL interface must guarantee a valid access cycle of greater than 400ns (by forcing the 68000 to execute several wait states).

The basic read or write cycle generated by the PAL interface looks like Figure 3. The 68000 R/W and LDS lines have been converted into 8500  $\overline{\text{RD}}$  and  $\overline{\text{WR}}$  control signals and with a state timing generator, produce the 68000 data valid signal  $\overline{\text{DTACK}}$ . While the 8500 peripherals latch the data internally on the falling edge of  $\overline{\text{WR}}$ , all 9500 (Intel-type) peripherals use the rising edge of  $\overline{\text{WR}}$  to strobe in data. So, the timing used is designed to guarantee proper set-up and hold time for both Am8500 and Am9500 devices.

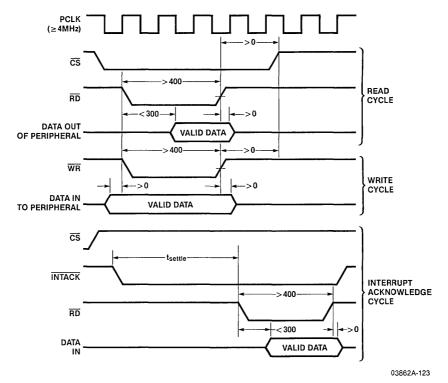


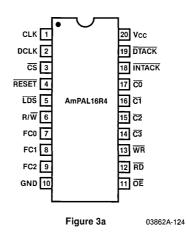
Figure 2. Am8500 Interface Timing (4MHz)

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The  $\overline{DTACK}$  control logic is the only control line which employs any sort of special timing in both of the PAL interfaces. In order to guarantee proper set-up and hold time for write operations to the 9500 parts, it was necessary to start the  $\overline{DTACK}$  cycle in the middle of a PCLK cycle. Hence, it was necessary to use the CPU clock to condition the assertion of  $\overline{DTACK}$ . Using the C<sub>0</sub> (PCLK) and the C<sub>1</sub>-C<sub>3</sub> inputs only, would have allowed a potential set-up time violation during a write operation under worst case conditions for an 8MHz 68000.

The interrupt acknowledge cycle is very similar to the read/write cycle; only two differences exist. First, the interrupt acknowledge cycle involves only a read operation (see

interrupt acknowledge timing in Figure 3). Secondly, the read cycle needs to be stretched out to allow time for the interrupt daisy chain to resolve priority. If a parallel priority resolution scheme is used, then only the priority decode time delay and peripheral response time is added on to the interrupt cycle. The interrupt time delay varies, based on the number of 8500 devices in the daisy chain. The time delay is based on the 8500's position in the chain: first, somewhere in the middle, and the last device in the daisy chain (see Table 1). Both of the current PAL interfaces assume there are three 8500 peripherals in the interrupt daisy chain.



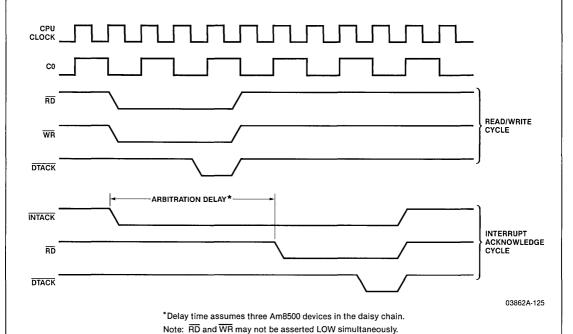


Figure 3b. PAL Generated Interface Signals

The PAL interfaces offered are designed to give the system designer maximum flexibility in integrating Am8500 peripherals with 68000 based systems. The first version is designed to allow maximum access to the 8500 devices (see Figure 4a). It does this by delegating the read/write recovery time into software. All 8500 peripherals have a minimum post access recovery time, i.e., they can't be accessed for a minimum period of time after being read or written (see Table 2). Generally, this restriction manifests itself only if the CPU has to make repeated accesses to the same peripheral part rapidly. While the instruction fetch time of the CPU allows for some recovery time, it doesn't quarantee enough time (since the average recovery time is approximately 1000ns and a 68000 instruction fetch requires a minimum of 500ns@8MHz). Hence, the first design requires the user to implement minimum software recovery time.

The software recovery routines in this case generally take the form of executing 1-2 instructions (depending on execution and fetch time) in between accessing the *same* 8500 device. For most systems, these instruction executions can be used to process the data just received. Another method of insuring the minimum peripheral recovery time is to juggle the accessing of the 8500 devices in the system so the recovery time requirement is not violated.

The second design (see slow PAL timing in Figure 4b) relieves the user of all software considerations when using the Am8500 parts. The recovery time is built into the PAL design. This is done by delaying access on the read/write and then taking advantage of the 68000 next instruction fetch to guarantee that the minimum recovery time is given. Also, a minor change was required in the interrupt acknowledge timing, i.e., stretching out the INTACK timing slightly to avoid a potential glitch on the RD line after an interrupt acknowledge cycle.

The advantage of software-independent hardware is offset by longer read/write cycles to the peripherals, even for single accesses. Also, the user is denied access to another 8500 peripheral until the minimum recovery time has been met for the previous one. However, having software-independent hardware is sometimes an important feature in a system; and slowing down the peripheral access rate slightly is a small price to pay for it. Note, the interrupt acknowledge cycles for both designs are virtually the same. This occurred because the normal interrupt processing by the 68000 guarantees that another access to the 8500 parts cannot occur in time to violate their access recovery times. Hence no software delay is needed for the fast access interface.

The interrupt acknowledge delay (for the daisy chained priority resolution scheme) in this example has been chosen by using an assumption of three 8500 peripherals in the chain. Larger or smaller numbers of parts in the daisy chain would increase or decrease this result with minor changes to the PAL logic equations. The design is flexible enough to support the addition of at least 3 more peripherals in the daisy chain.

The PAL equations and logic diagram for both designs are given at the end of the article. The equations were derived directly from their respective timing diagrams (Figures 4a and 4b). Some obvious logic simplification was done on the initial equations to reduce the number of terms. The integration of the Am8500 peripherals and the PAL timing generator are shown in a sample configuration in Figure 5.

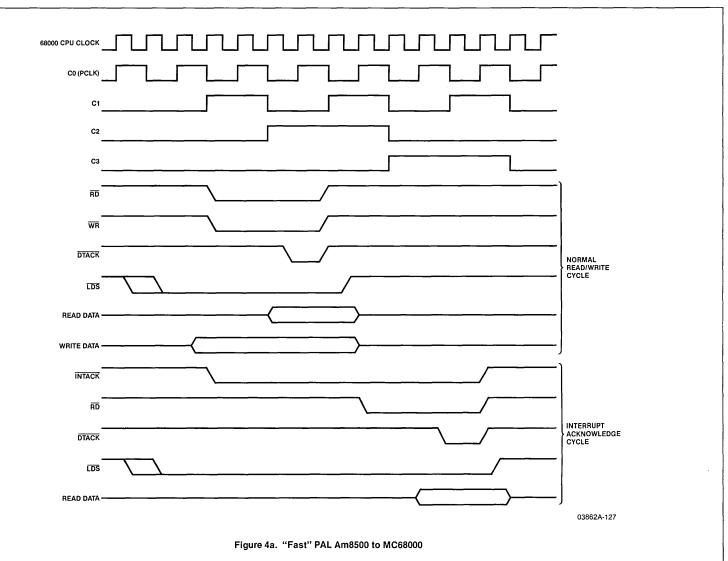
Finally, the design presented was optimized for an 8MHz 68000 system and 4MHz 8500 parts. The timing/state counter ( $C_0$ – $C_4$ ) only counts as far as it is needed. Higher performance CPUs, up to 12MHz, can be used with this interface, but 6MHz 8500 parts will have to be used.

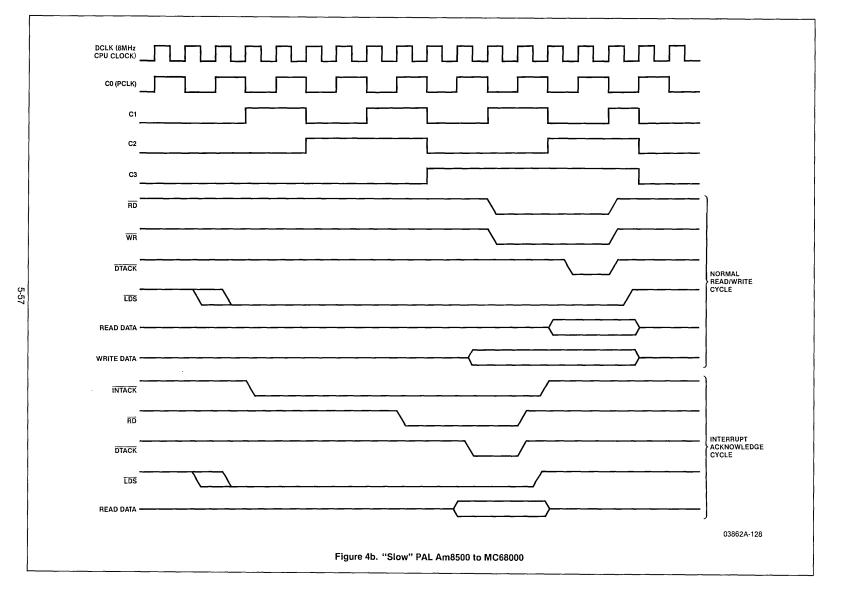
Table 2. Peripheral Access Recovery Time

Periph (4MH		Recovery Time
8530	scc	Greater than 6 PCLK cycles + 200ns
8536	CIO	Greater than 3 PCLK cycles or 1000ns
8038	FIO	Greater than 1000ns

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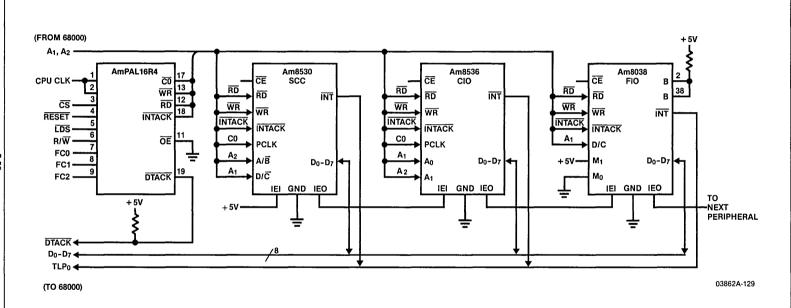


Figure 5. PAL Am8500 to MC68000 Hookup

PAL DESIGN SPECIFICATION PAL16R4 PAT050 MARK YOUNG 1/21/83 FAST AM8500 TO MOTOROLA 68000 PAL ADVANCED MICRO DEVICES CLK DCLK /CS /RESET /LDS RW FCO FC1 FC2 GND /OE /RD /WR /C3 /C2 /C1 /CO /INTACK /DTACK VCC : STATE MACHINE COUNTER CO - C3 CO := /CO; 8500 CLK C1 := CO\*/C1\*CS\*LDS\*/RESET + /CO\*C1\*CS\*LDS\*/RESET C2 := C0\*C1\*/C2\*CS\*/RESET + /C1\*C2\*CS\*/RESET + /CO\*C1\*C2\*CS\*/RESET C3 := C0\*C1\*C2\*/C3\*CS\*/RESET + /C1\*/C2\*C3\*CS\*/RESET + /CO\*C1\*/C2\*C3\*CS\*/RESET RD = C1\*/C2\*/C3\*RW\*/INTACK\*CS\*/RESET ; NORMAL READ ; NORMA : INTERRUPT ACKNOWLEDGE + RD\*INTACK\*CS\*/RESET WR = C1\*/C2\*/C3\*/RW\*CS\*/INTACK\*/RESET ; WRITE OPERATION + /C1\*C2\*/C3\*/RW\*CS\*/INTACK\*/RESET ; WRITE OPERATION ; DATA ACKNOWLEDGE IF (CS) DTACK = /DCLK\*/CO\*/C1\*C2\*/C3\*/INTACK\*/RESET + DTACK\*RD\*/RESET + DTACK\*WR\*/RESET + /DCLK\*CO\*/C1\*/C2\*C3\*INTACK\*/RESET ; INTERRUPT ACKNOWLEDGE INTACK = FCO\*FC1\*FC2\*C1\*/C3\*LDS\*/RESET + C2\*FC0\*FC1\*FC2\*/RESET

> + /C1\*C3\*FC0\*FC1\*FC2\*/RESET + /C0\*C1\*C3\*FC0\*FC1\*FC2\*/RESET

### FUNCTION TABLE:

NOTE: FOR THE SIMULATION, ALL THE SIGNALS USED ARE AT THE PIN LEVEL (I.E. WHAT THE CHIP SEES AND PUTS OUT). THE ONE EXCEPTION ARE THE CO - C3 PINS. THESE ARE DEFINED AT THE REGISTER OUTPUT LEVEL (NON-INVERTED) BECAUSE THEY WERE DIRECTLY DERIVED FROM THE TIMING DIAGRAMS AND THIS MAKES IT EASIER TO RELATE TO THE TIMING DIAGRAM.

CLK DCLK /CS /RESET /LDS RW FCO FC1 FC2

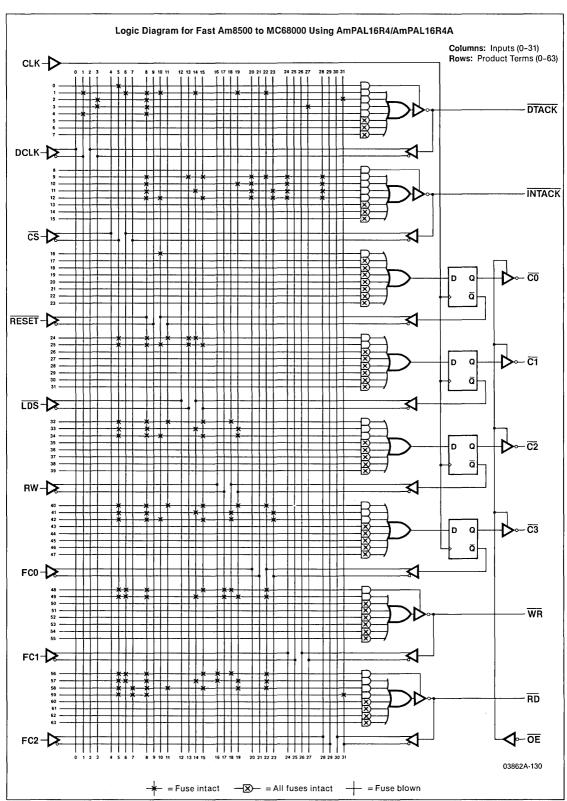
			CO (													,	
; ; ; ; ; ; ; ;	D C L K	/ C S	/ R E S E T	/ L D S	R W	F C O	F C 1	F C 2	/ O E	/ R D	/ W R	C 0	C 1	C 2	C 3	I N T A C K	D T A C K
;	ESET	SEO	UENCI	- <b>-</b>													
'n	H	Н	L	X	X	X	X	X	$\Gamma$	Н	Н	Н	L	L	L	Н	Z
L C	L H	H	L H	X X	X	X X	X	X	L	Н	H	H	L	L	L	Н	Z
L	n L	H H	н	X	X X	X	X X	X X	L L	H H	H H	L L	L L	L L	L L	H H	Z Z
C	H	Н	Н	Х	Х	X	X	X	L	Н	Н	Н	L	L	L	Н	Z
L :	L	Н	H	X	Х	X	X	X	L	Н	H	Н	L	L	L	Н	Z
;WR			ATIO		√=L)												
C L	H L	H H	H H	X X	X X	X X	X X	X X	L L	H H	H H	L L	L L	L L	L L	H H	Z Z
C	H	H	H	X	X	X	X	X	L	H	Н	H	L	L	L	Н	Z
L C	L	H	Н	X X	X	X	X	X	L	H	Н	H	L	L	L	H	Z
L	H L	H L	H H	л L	X L	X X	X X	X X	L L	H H	H H	L L	L L	L L	L L	H H	Z H
С	H	L	Н	L	L	X	X	X	L	Н	Н	Н	L	L	L	Н	Н
L C	L H	L L	H H	L L	L L	X X	X X	X X	L L	H H	H L	H L	L H	L L	L L	H H	H H
L	L	L	Н	L	L	X	X	X	L	H	Ĺ	L	Н	Ĺ	Ĺ	Н	Н
C L	H L	L L	H H	L L	L L	X X	X X	X X	L L	H H	L L	H H	H H	L L	L L	H H	H H
Ç	H	L	H	L	L	X	X	X	L	Н	L	L	L	H	L	Н	Н
L C	L H	L L	H	L L	L L	X X	X X	X X	L L	Н	L L	L	L L	H	L L	H H	L L
L	н L	L	H H	L	L	X	X	X	L	H H	L	H H	L	H H	L	н Н	L
С	Н	L	Н	L	H	X	X	X	L	Н	Н	L	Н	Н	L	Н	Н
L C	L H	H H	H H	X X	X X	X X	X X	X X	L L	H H	H H	L H	H L	H L	L L	H H	Z Z
Ĺ	L	Н	Н	X	X	X	X	X	Ĺ	H	H	Н	Ĺ	Ĺ	Ĺ	H	Z
; • TN'	TACK	CYC	a i														
C	H	H	Н	X	X	X	Х	X	L	Н	Н	L	L	L	L	Н	Z
L	L	Н	Н	X	X	X	X	X	L	Н	H	L	L	L	L	Н	Z
С	H	Н	Н	Х	X	Х	X	X	L	Н	Н	Н	L	L	L	Н	Z

C L C L C L C L C L C L	L L L L L L L L	H H H H H H H H	H H H H H H H H H H K H	H H H H H H H H H X	H H H H H H H H H K	H H H H H H H H H X	L L L L L L L L L L	H H H L L L L H H	H H H H H H H H H H	L H H L H H L H H L H	L L H H H L L H H H H	H H H H L L L L L		HHHHHHHHHHLLLHZ
L C									-					

#### DESCRIPTION:

THE FASTZTOM PAL PROVIDES INTERFACING BETWEEN THE SINGLE CHIP 8500 TO THE 68000. THE PAL USED IS A MEANS TO PROVIDE FOR THE FASTEST POSSIBLE INTERFACE. THE REQUIREMENTS FOR THIS MAXIMUM ACCESS UTILIZES IMPLEMENTED SOFTWARE FOR REPEATED ACCESSES. THE USER, HENCE, IS ABLE TO GET MAXIMUM ACCESS WITH MINIMAL WAIT STATE INSERTION. THE INTERFACE PROVIDES TOTAL SIGNAL COMPATIBILITY.

```
V0022 000100XXX00HLHLHLHL1 *
V0023 C10101XXX00HHHLLHHH1 *
V0024 0011XXXXX00HHHLLHHZ1 *
V0025 C111XXXXX00HHHHHLHZ1 *
VOO26 OO11XXXXXOOHHHHHLHZ1
VOO27 C111XXXXXXOOHHHHHHHZ1
V0028 0011XXXXX00HHHHHHZ1
VOO29 C111XXXXXXOOHHHHHLHZ1 *
V0030 0011XXXXX00HHHHHLHZ1 *
V0031 C1010111100HHHHLHLH1 *
V0032 00010111100HHHLHLH1 *
V0033 C1010111100HHHHLLLH1 *
V0034 00010111100HHHHLLLH1 *
V0035 C1010111100HHLLHHLH1 *
V0036 00010111100HHHLHHLH1 *
V0037 C1010111100HHHLHLLH1 *
V0038 00010111100HHLHLLH1 *
V0039 C1010111100HHLLHLH1 *
V0040 00010111100HHHLLHLH1
VOO41 C1010111100LHHLLLLH1 *
V0042 00010111100LHHLLLLH1 *
V0043 C1010111100LHLHHHLH1 *
VOO44 00010111100LHLHHHLH1 *
V0045 C1010111100LHLHHLLH1 *
V0046 00010111100LHLHHLLL1 *
V0047 C1010111100LHLHLHLL1 *
V0048 00010111100LHLHLHLL1 *
V0049 C1010111100HHLHLLHH1 *
V0050 00111XXXX00HHLHLLHZ1 *
V0051 C1111XXXX00HHHHHHHZ1 *
V0052 00111XXXX00HHHHHHHZ1 *
7BCF
```



```
PAL16R4
                                         PAL DESIGN SPECIFICATION
PATO51
                                         MARK YOUNG 1/21/83
SLOW AM8500/9500 TO MOTOROLA 68000 PAL
ADVANCED MICRO DEVICES
CLK DCLK /CS /RESET /LDS RW FCO FC1 FC2 GND
/OE /RD /WR /C3 /C2 /C1 /CO /INTACK /DTACK VCC
    : STATE MACHINE COUNTER CO - C3
CO := /CO
                                           ; 8500 CLK
C1 := C0*/C1*/C2*LDS*CS*/RESET
   + /C0*C1*/C2*LDS*CS*/RESET
   + CO*/C1*C2*LDS*CS*/RESET
   + /C0*C1*C2*C2*/C3*LDS*CS*/RESET
C2 := C0*C1*/C2*CS*/RESET
   + /C1*C2*CS*/RESET
   + /C0*C1*C2*/C3*CS*/RESET
C3 := C0*C1*C2*/C3*CS*/RESET
   + /C2*C3*CS*/RESET
   + /C1*C2*C3*CS*/RESET
RD = C1*/C2*C3*RW*CS*/INTACK*/RESET ; NORMAL READ
   + /C1*C2*C3*RW*CS*/INTACK*/RESET
                                      ; NORMAL READ
   + CO*C1*C2*/C3*INTACK*/RESET
                                      ; INTERRUPT ACKNOWLEDGE
                                       : INTERRUPT ACKNOWLEDGE
   + /C1*/C2*C3*INTACK*/RESET
   + /CO*C1*/C2*C3*INTACK*/RESET
                                       : INTERRUPT ACKNOWLEDGE
WR = C1*/C2*C3*/RW*CS*/INTACK*/RESET
                                      ; WRITE OPERATION
   + /C1*C2*C3*/RW*CS*/INTACK*/RESET ; WRITE OPERATION
      ; DATA ACKNOWLEDGE
IF (CS) DTACK = /DCLK*/CO*/C1*C2*C3*/INTACK*/DTACK*/RESET
     + DTACK*RD*/RESET
     + DTACK*WR*/RESET
     + /DCLK*CO*/C1*/C2*C3*INTACK*/RESET
      ; INTERRUPT ACKNOWLEDGE
INTACK = FCO*FC1*FC2*C1*/C3*LDS*CS*/RESET
      + C2*/C3*FC0*FC1*FC2*CS*/RESET
```

+ /C2\*C3\*FC0\*FC1\*FC2\*CS\*/RESET

## FUNCTION TABLE:

; NOTE: FOR THE SIMULATION, ALL THE SIGNALS USED ARE AT THE
PIN LEVEL (I.E. WHAT THE CHIP SEES AND PUTS OUT). THE
ONE EXCEPTION ARE THE CO - C3 PINS. THESE ARE DEFINED
AT THE REGISTER OUTPUT LEVEL (NON-INVERTED) BECAUSE
THEY WERE DIRECTLY DERIVED FROM THE TIMING DIAGRAMS
AND THIS MAKES IT EASIER TO RELATE TO THE TIMING
DIAGRAM.

CLK DCLK /CS /RESET /LDS RW FCO FC1 FC2 /OE /RD /WR CO C1 C2 C3 /INTACK /DTACK

;	C L K	D C L K	/ C S	/ R E S E T	/ L D S	R W	F C O	F C 1	F C 2	/ O E	/ R D	/ W R	C 0	C 1	C 2	C 3	/ I N T A C	/ D T A C
;	FSF	т ст	QUEN	CF														
,.	С	Н	Н	L	X	X	X	X	X	L	H	Н	H	L	L	L	Н	Z
	L C	L H	H H	L H	X X	X X	X X	X X	X X	L L	H H	H H	H L	L L	L L	L L	H H	Z Z
	L	L	H	Н	X	X	X	X	X	Ĺ	H	Н	Ĺ	Ĺ	Ĺ	L	H	Z
	С	H	H	Н	X	X	X	X	X	L	H	H	H	L	L	L	H	Z
	L	L	H	H	X	Х	X	X	X	L	Н	Н	H	L	L	L	H	Z
; :V	RIT	E OP	ERAT	ION	(RW=	:L)												
•	С	Н	Н	Н	X	X	X	X	X	L	H	H	L	L	L	L	Н	Z
	L	L	Н	Н	X	X	X	X	X	L	H	H	L	L	L	L	H	Z
	C	H	H	H	X	Х	X	X	X	L	H	H	H	Ļ	Ļ	Ļ	H	Z
	L C	L H	H H	Н	X	X	X	X	X	L	H	H	H	L	L	L	H	Z
	L	n L	н L	H H	X L	X L	X X	X X	X X	L L	H H	H H	L L	L L	L L	L L	H H	Z H
	C	H	Ĺ	H	Ĺ	Ĺ	X	X	X	Ĺ	H	H	H	Ĺ	Ĺ	Ĺ	H	H
	L	L	L	H	L	L	X	X	X	L	Н	Н	H	L	L	L	H	H
	С	H	L	Н	L	L	X	X	Х	L	H	H	L	H	L	L	H	H
	L	L	L	H	Ļ	L	X	X	Х	L	H	Н	L	H	L	L	Н	Н
	С	H	L	H	L	L	X	X	X X	L	H	H H	H	H H	L	L L	H H	H H
	L C	L H	L L	H H	L L	L L	X X	X X	X	L L	H H	H	H	L	L H	Ĺ	H	H
	Ĺ	L	Ĺ	H	Ĺ	L	X	X	X	Ĺ	H	H	Ĺ	Ĺ	H	Ĺ	H	H
	С	Н	L	Н	L	L	X	X	X	L	H	Н	Н	L	Н	L	H	H
	L C	L	L	H	L	L	X	Х	Х	L	H	Н	Н	L	Н	L	H	H
		H	L	H	L	H	X	X	X	L	H	H	L	H H	H H	L L	H H	H H
	L C	L H	L L	H H	L L	L L	X X	X X	X X	L L	H H	H H	L H	н Н	н Н	L	н Н	н
	Ĺ	L	Ĺ	Н	Ĺ	Ĺ	X	X	X	Ĺ	H	H	H	H	H	Ĺ	H	Н
	C	H	L	Н	L	L	X	X	X	L	Н	H	L	L	L	H	H	H

C I I I I I I I I I I I I I I I I I I I	H L H L H L H L H L H L H		H H H H H H H H H H H H H H H H H H H	L L L L L L L L X X X	L L L L L L L L X X	X X X X X X X X X X X X X X X X X X X	X X X X X X X X X X X X X X X X X X X	X X X X X X X X X X X X X X X X X X X		H H H H H H H H H H H H H H H H H H H	H H L L L L L H H H H H	L H H L H H L L H H L L			H H H H H H H H H L L L	H H H H H H H H H H H H H H H H H H H	H H H H H H L L H H Z Z Z Z
; :INTAC	к су	CLE															
C	H :	H	Н	X	X	X	X	X	L	Н	Н	Н	L	L	L	Н	Z
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		L L	H H	L L	H H	H H	H H	H H	L L	H H	H H	L L	H H	L L	L L	L L	H H
		Ĺ	H	Ĺ	Н	Н	H	H	L	Н	Н	Н	H	Ĺ	Ĺ	Ĺ	Н
		L	H	L	Н	Н	Н	Н	L	Н	Н	H	Н	L	L	L	Н
		L	H	L	Н	H.	Н	Н	L	Н	H	L	L	H	L	L	Н
		L L	H H	L L	H H	H H	H H	H H	L L	H H	H H	L H	L L	H H	L L	L L	H H
		L	Н	Ĺ	Н	H	Н	Н	L	H	Н	Н	Ĺ	Н	Ĺ	Ĺ	H
		Ĺ	H	Ĺ	H	H	H	H	L	Н	H	L	H	H	L	L	H
		L	Н	ŗ	H	H	Н	Н	Ţ	H	Н	L	H	H	Ţ	L	H
		L L	H H	L L	H H	H H	H H	H H	L L	L L	H H	H H	H H	H H	L L	L L	H H
		L L	H	Ĺ	H	H	H	H	Ĺ	Ĺ	Н	L	L	L	H	Ĺ	Н
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		L	H	L	Н	Н	H	H	L	L	H	H	L	L L	H H	L L	H
		L L	H H	L L	H H	H H	H H	H H	L L	L L	H H	H L	L H	L	п Н	L	L L
L I		L	Н	Ĺ	H	Н	H	H	L	L	Н	Ĺ	Н	Ĺ	H	Ĺ	Ĺ
		L	H	L	Н	Н	Н	H	L	Н	Н	Н	H	L	H	L	H
		H	H	H	X	X	X	X	L	H	Н	H	H	L	H L	Н	Z
		H H	H H	X X	X X	X X	X X	X X	L L	H H	H H	L L	L L	L L	L	H H	Z Z

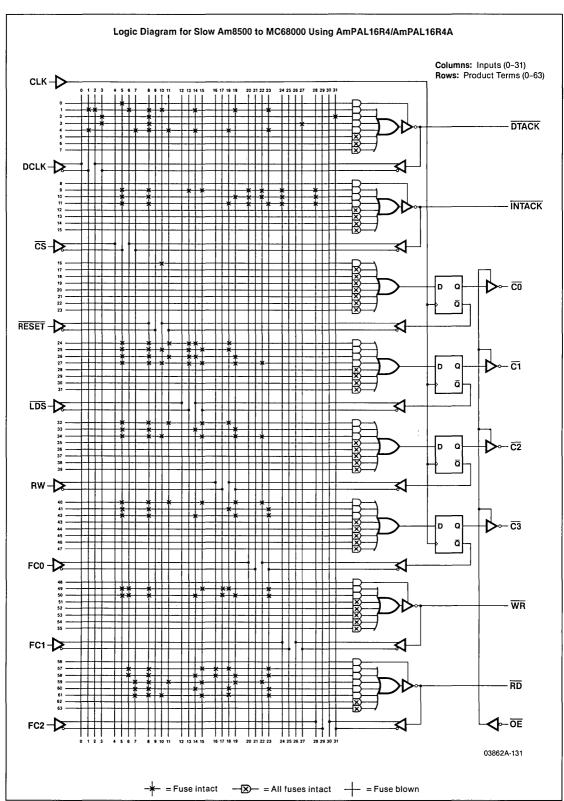
## DESCRIPTION:

THE SLOWZTOM PAL IS A SELF-CONTAINED 8500 TO 68000 INTERFACE. THERE IS NO USER SOFTWARE REQUIRED FOR THIS INTERFACE, BUT THERE IS A TRADE-OFF OF SLOWER ACCESS TIME. AGAIN, THE INTERFACE PROVIDES TOTAL SIGNAL COMPATIBILITY.

1/21/83

V0019 C10100XXX00HHHLHHHH1 \*

```
V0020 000100XXX00HHLHHHH1 *
V0021 C10100XXX00HHHLHLHH1 *
V0022 000100XXX00HHHLHLHH1
V0023 C10101XXX00HHHLLHHH1 *
VOO24 000100XXX00HHHLLHHH1 *
VOO25 C10100XXX00HHHLLLHH1 *
V0026 000100XXX00HHLLLHH1 *
V0027 C10100XXX00HHLHHHHH1 *
V0028 000100XXX00HHLHHHHH1 *
V0029 C10100XXX00HHLHHLHH1 *
V0030 000100XXX00HHLHHLHH1
V0031 C10100XXX00HLLHLHHH1 *
V0032 000100XXX00HLLHLHHH1 *
VOO33 C10100XXXOOHLLHLLHH1
V0034 000100XXX00HLLHLLHH1
V0035 C10100XXX00HLLLHHHH1
VOO36 OOO1OOXXXOOHLLLHHHL1
V0037 C10100XXX00HLLLHLHL1 *
V0038 000100XXX00HLLLHLHL1 *
V0039 C10100XXX00HHLLLHHH1 *
V0040 000100XXX00HLLLHHH1 *
V0041 C11111XXX00HHHHHLHZ1 *
V0042 0011XXXXX00HHHHHLHZ1 *
VOO43 C111XXXXXXOOHHHHHHHZ1 *
V0044 0011XXXXX00HHHHHHHZ1 *
V0045 C111XXXXXXOOHHHHHLHZ1 *
VOO46 OO11XXXXXOOHHHHHLHZ1
V0047 C1010111100HHHHLHLH1 *
V0048 00010111100HHHLHLH1
V0049 C1010111100HHHHLLLH1
V0050 00010111100HHHHLLLH1 *
V0051 C1010111100HHLHHLH1 *
V0052 00010111100HHHLHHLH1 *
V0053 C1010111100HHHLHLLH1 *
V0054 00010111100HHLHLLH1 *
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V0056 00010111100HHHLLHLH1 *
V0057 C1010111100LHHLLLLH1 *
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V0059 C1010111100LHLHHHLH1 *
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V0061 C1010111100LHLHHLLH1 *
V0062 00010111100LHLHHLLL1 *
V0063 C1010111100LHLHLHLL1 *
V0064 00010111100LHLHLHLL1 *
V0065 C1010111100HHLHLLLH1 *
V0066 00111XXXX00HHLHLLHZ1 *
V0067 C111XXXXX00HHHHHHHZ1 *
V0068 0011XXXXX00HHHHHHHZ1 *
F7FD
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# The Berkeley-1 Plus— A High Performance CPU Utilizing PALs

# by Jeff Kitson and Kevin Ow-Wing Advanced Micro Devices



## INTRODUCTION

This paper illustrates the design of a high performance 16-bit CPU, called the Berkeley-1 Plus, utilizing PALs. It is intended to show where PALs fit into an overall system design, what kind of complex functions PALs can implement, and how a designer can realize the full advantages of PALs. To oversimplify, PALs fit everywhere in a design. Of the 56 chips used in this design, 34 are PALs. In the data path, they are used for data steering and data manipulation. Using PALs for data steering functions simplified the implementation of a multiple bus architecture. The data manipulation functions include a 16-bit arithmetic barrel shifter, constant generation logic and sign extension logic. PALs are also used extensively to optimize the control path. For example, control functions include instruction predecoding, double pipelining control, microprogram branch control, register file control and special instruction control.

## THE BERKELEY-1 PLUS

The Berkeley-1 Plus was originally conceived of at the University of California, Berkeley as a design project for computer architecture students. The Berkeley-1 Plus is essentially a PDP-11 16-bit general purpose computer with a streamlined instruction set. The Berkeley-1 Plus was chosen as a test vehicle for PAL system design for three reasons. First, the authors had already designed the computer (in the class at Berkeley) using a limited parts list consisting mainly of fixedfunction TTL SSI/MSI devices. This provided a benchmark for the new design. Second, the original computer design by the authors was done separately and the new design was a joint effort. This proved to be a true test of the flexibility of PALs because of the effect of one designer's changes on the other. Finally, the architecture was not conceived with any particular device limitations in mind. This allowed the authors to optimize the PALs to implement the architecture, instead of optimizing the PALs to fit a constrained architecture limited by available devices.

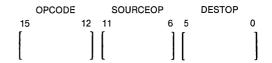
## **ARCHITECTURE**

The architecture of the Berkeley-1 Plus, like any other computer, is defined by the instruction set and the functional blocks required to implement the instruction set. The Berkeley-1 Plus architecture is organized as a two address, register based processor to implement its simple, yet powerful instruction set. The processor interfaces to a 16-bit address bus and a 16-bit data bus. This allows the processor to address up to 64K of memory and to operate on 16-bit data and instruction words. Instruction words are orthogonal in ature allowing selection of the instruction opcode to be independent of the selection of both operand addressing

modes (for instructions with operands). The instruction set and addressing modes are shown in Appendix A. To implement the instruction set, the architecture is defined to contain an arithmetic and logic unit (ALU), an eight location register file (RF), a 16-bit program counter (PC), a 16-bit instruction register (IR), and a 4-bit processor status word (PSW). In addition, the processor also supports interrupts and illegal instruction traps.

## **INSTRUCTION SET**

Berkeley-1 instructions have a general format that divides the instruction word into a separate 4-bit instruction opcode field (OPCODE), 6-bit source operand field (SOURCEOP) and 6-bit destination operand field (DESTOP). The general format is as follows:



The OPCODE field encodes which of the sixteen instructions is to be executed. This is true for all Berkeley-1 instructions, even those that do not follow the general format. The SOURCEOP field encodes which of the seven addressing modes is to be used to find the source operand. The DESTOP field is the same as the SOURCEOP field except that it also defines where the resit of an instruction is placed. For example, if the instruction is an addition, the SOURCEOP is register 1 and the DESTOP is register 2, the values inside of registers 1 and 2 would be added together and placed in register 2.

The instructions adhering to the general format include move (MOV), addition (ADD), subtraction (SUB), compare (CMP), logical and (AND), logical or (OR), exclusive-or (XOR), shift level (SHL), shift right (SHR), load multiple registers with memory (LDM), and store multiple registers to memory (STM). The unconditional jump (JMP) and unconditional jump to subroutine (CALL) instructions have the same general format except the SOURCEOP field is unused because the jump address is derived from the DESTOP field only. The unconditional return from subroutine (RET) and interrupt enable/disable (INTENB) instructions differ from the general format because they do not need any operands. The only instruction which differs from the general format significantly is the conditional branch (CBR) instruction.

The format of the CBR instruction is as follows:

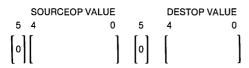


The 4-bit BRCOND field is used to select which of sixteen branch conditions are to be tested. The branch conditions are derived from the PSW. The BROFFSET field is an 8-bit signed offset that is added to the program counter, when the tested condition is true, to provide a new address. This allows position independent code, but limits the range of the CBR instruction to  $\pm$  127 or  $\pm$  128 locations relative to the program counter.

Each instruction is defined in more detail in Appendix A.

## **ADDRESSING MODES**

As previously mentioned there are seven different addressing modes that can be used to address operands. These addressing modes are: short immediate, register, register indirect, register indexed, absolute, stack pointer auto-increment, and stack pointer auto-decrement. The short immediate addressing mode is selected when the uppermost bit of the operand field (SOURCEOP or DESTOP) is zero, leaving the lower five bits of the field as the operand. The format for short immediate is as follows:



To encode the addressing modes that specify registers into the SOURCEOP and DESTOP fields, these two fields are each further divided into two smaller 3-bit fields as follows:



The SOURCEMODE and DESTMODE fields encode the addressing mode and the SOURCEREG and DESTREG fields select one of the eight registers. These modes are: register, register indirect, and register indexed. The remaining addressing modes, absolute, stack pointer auto-increment, and stack pointer auto-decrement, that do not use registers are selected by the register field when the mode field is equal to seven. Seven was chosen because the stack pointer is register seven in the register file. The format for these modes is shown below:

The addressing modes are shown in more detail in Appendix A.

## **IMPLEMENTATION**

The implementation of the Berkeley-1 is obviously controlled by the architecture, but the architecture definition does not

control the method of implementation. For example, the 16-bit arithmetic operations specified in the instruction set could be done serially four bits at a time in four repeatable cycles. This could result in a minimum parts count, but also in a very slow ALU. Conversely, an instruction can be executed at the same time as the next instruction is being decoded and the next one after that is being fetched. This results in a very fast machine, but parts count and the complexity of doing many things in parallel can be costly. The objective of this implementation of the Berkeley-1 Plus was to build a very high performance CPU that could fit on a single board with a very fast synchronous memory. This required a minimum parts count while implementing a complex machine operating in parallel. Thus PALs were brought to the rescue. Their ability to implement complex, custom functions at high speeds made them the ideal choice.

A block diagram of the CPU appears in Figure 1. It is characterized by multiple buses and functional blocks that have multiple input sources and multiple output destinations. The multiple buses and multiple input/output functional blocks facilitate parallel operation. The five major buses are the memory data bus (DBUS), the memory address bus (ABUS), the source operand bus (RBUS), the destination operand bus (SBUS), and the result bus (YBUS). The DBUS and ABUS are used for interface to the external world and the RBUS, SBUS and YBUS are used for internal CPU operations. The ten functional blocks are the ALU and register file, PC, IR, memory data register 1 (MDR<sub>1</sub>), memory data register 2 (MDR<sub>2</sub>), memory address register (MAR), barrel shifter, value register, RBUS control and SBUS control. The only other major functional block is the control sequencer.

The control sequencer block diagram appears in Figure 2. The control sequencer consists of two instruction mapping PROMs, a horizontal pipelined microprogram memory and a PAL conditional microbranch controller.

Significant performance enhancement resulted from the parallel, double-pipelined design implementation. For example, in a single cycle the Berkeley-1 can perform a barrel shift of up to 16 places while decoding the next instruction, incrementing the PC, fetching the next instruction plus one, and testing for interrupts and traps. All of this takes place in a worst case cycle time of 131ns. Effectively, due to all of these operations happening at the same time instructions are performed in a single cycle (short immediate and register mode only). This results in the Berkeley-1 Plus performing approximately 7.5 million instructions per second (7.5 MIPs). The timing and critical path analysis appears in Appendix B.

The actual design was divided up by the authors so that one was responsible for the data path and the other was responsible for the control path. The CPU portion shown in Figure 1 was designed by Jeff and the control sequencer of Figure 2 was designed by Kevin. This resulted in a more or less clean interface for interaction between the designers. Every time an optimization was contemplated in the CPU, an analysis had to take place to see if the control sequencer could support it or if the change was worth changing the sequencer, too. Likewise, every time the control sequencer needed to be changed the effects on the CPU had to be analyzed. With PALs, most of these changes were easily implemented by reprogramming a device by one designer or the other. For example, the original designs were not double-pipelined, but Jeff made changes in the data path and Kevin changed the control path to support it. Thus most of the design effort was in deciding the method of an optimized implementation (and working relationship) because of the flexibility of PALs to implement a design change easily.

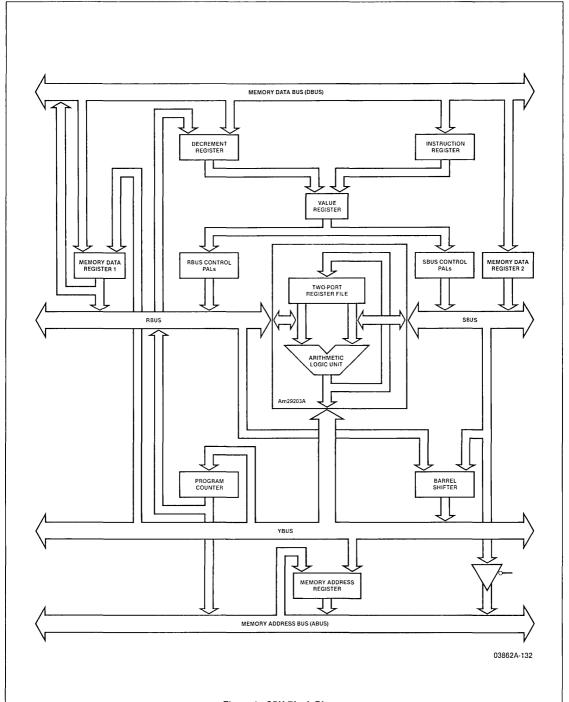
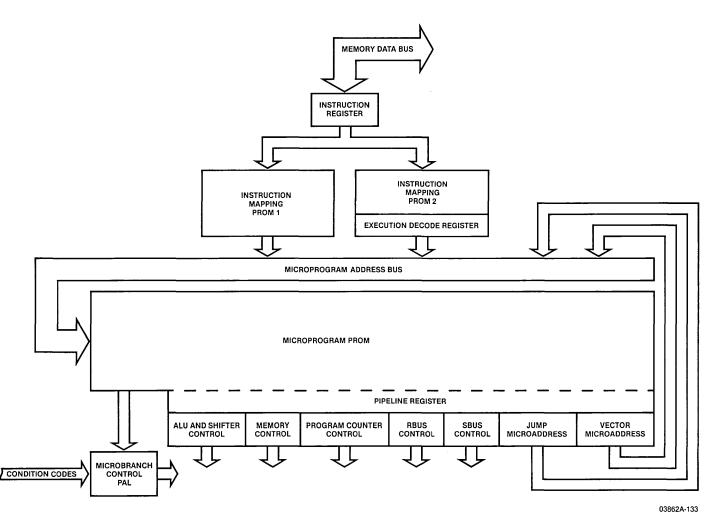


Figure 1. CPU Block Diagram





03002A-

Figure 2. Control Sequencer Block Diagram

A simplified state diagram of the Berkeley-1 Plus appears in Figure 3. The state diagram should allow the reader to easily understand the complexity of a double-pipelined CPU and to get a feel for how this implementation of the Berkeley-1 Plus actually performs instructions.

The various functional blocks are described in detail in the following sections. A logic diagram and PAL DESIGN SPECIFICATION for each PAL used in this design appear in Appendix C.

#### **ALU AND REGISTER FILE**

The logic diagram of the ALU and register file is shown in Figure 4. It is implemented with four 4-bit slice Am29203 bipolar microprocessors and one Am2902A high speed lookahead carry generator. A block diagram of the Am29203 appears in Figure 5. The Am29203s were chosen because their internal three bus architecture, two-port register file, ALU, ease of control from microcode, and high speed fit ideally into the design.

The three internal buses of the Am29203 interface directly to the three internal buses of the system (see Figure 1) via I/O pins on the device. The A port of the Am29203's register file is gated onto the RBUS by the signal  $\overline{\text{OEA}}$ , the B port of the register file is gated onto the SBUS by  $\overline{\text{OEB}}$ , and the ALU output is gated onto the YBUS by  $\overline{\text{OEY}}$ . Each of the control signals comes directly from microcode.

The two-port register file of the Am29203 allows reading both source and destination operands from the register file and writing an operation result into the destination in a single cycle. This capability is a necessity for performing the execution cycle of an instruction in a single CPU cycle. The source and destination registers are addressed on the A and B address inputs by the value register (explained later). Writing an operation result to the destination register is controlled by the microcode signal  $\overline{\text{WR REG}}$ .

The ALU in the Am29203 is controlled directly from microcode on the instruction inputs (INST(8:0)) and by the INSTEN input. The ALU performs all arithmetic and logical operations specified in the Berkeley-1 Plus architecture except the single state barrel shift. The single state barrel shift is performed in PALs (explained later). In addition, the Am29203 has capabilities such as BCD arithmetic, multiply and divide not specified by the Berkeley-1, but which could be added to the system by simply rewriting some of the microcode.

## **BARREL SHIFTER**

The barrel shifter is an excellent example of the trade-off between minimal implementation and performance. One easy implementation is to use the single bit shifter already present inside the Am29203. Unfortunately, a shift of fifteen bits would take fifteen CPU cycles. This is an acceptable level of performance only in machines that require a minimum amount of shift capability. Another alternative is to implement a barrel shifter which can perform a shift of any arbitrary number of bits in a single cycle. This alternative, although high in performance, can be complex to implement. An MSI solution would require the use of sixteen Am25S10 shifters. Another question is where to put the shifter; following the ALU or in parallel with the ALU. If the barrel shifter is implemented following the ALU, every operation must pass

through the ALU and the shifter resulting in a long delay. This is clearly unacceptable in a system where speed is the critical factor. In parallel, the delay is small but extra hardware is necessary to calculate the zero condition code which can no longer be calculated in the ALU. This is not a trivial task because condition codes must be calculated in parallel with the shift to maintain speed and therefore it is conditional which data bits affect the condition codes! (In MSI, this would require an additional barrel shifter for zero calculation.) In addition, hardware (two Am25LS244s) is required to gate the proper source, ALU or barrel shifter, onto the YBUS.

The Berkeley-1 uses eight AmPAL16H8As to implement the barrel shifter in parallel with the ALU for the highest performance while maintaining a reasonable parts count. In addition, the barrel shifter PALs perform condition code calculation on the data and can be gated onto the YBUS. The barrel shifter is shown in Figure 6. The implementation is in two levels; the first is the nibble shifter and the second is the bit shifter. The nibble shifter performs a shift of 0, 4, 8, or 12 bits based on the upper two bits of the four-bit shift distance (RBUS(3:2)). The nibble shifter also performs the zero condition code calculation based upon all four shift distance bits (RBUS(3:0)), the data (SBUS(15:0)), and the microcode control inputs INST(0) and SHIFTER/ALU. The second level is the bit shifter which performs a right or left bit shift of 0, 1, 2, or 3 places controlled by the lower two bits of the shift distance (RBUS(1:0)) and the microcode input SHR/SHL. In addition, the SHIFTER/ALU input controls the gating of the bit shifter onto the YBUS.

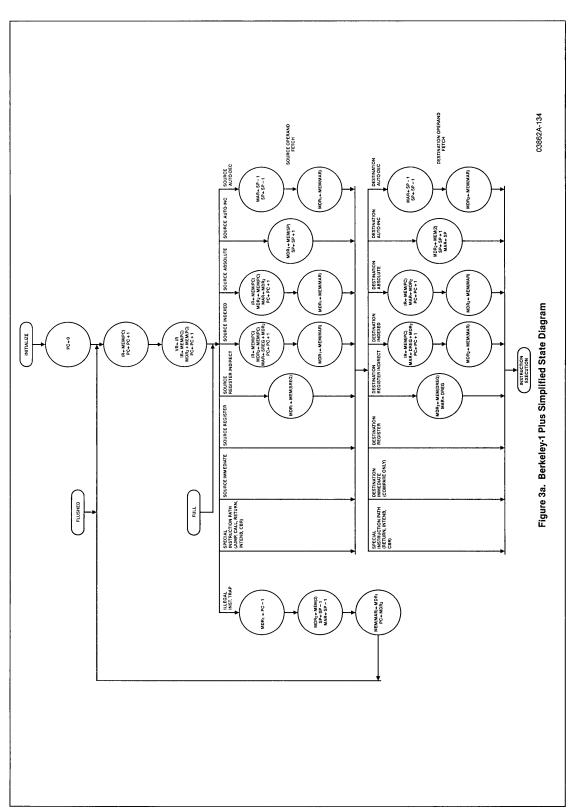
#### INSTRUCTION REGISTER

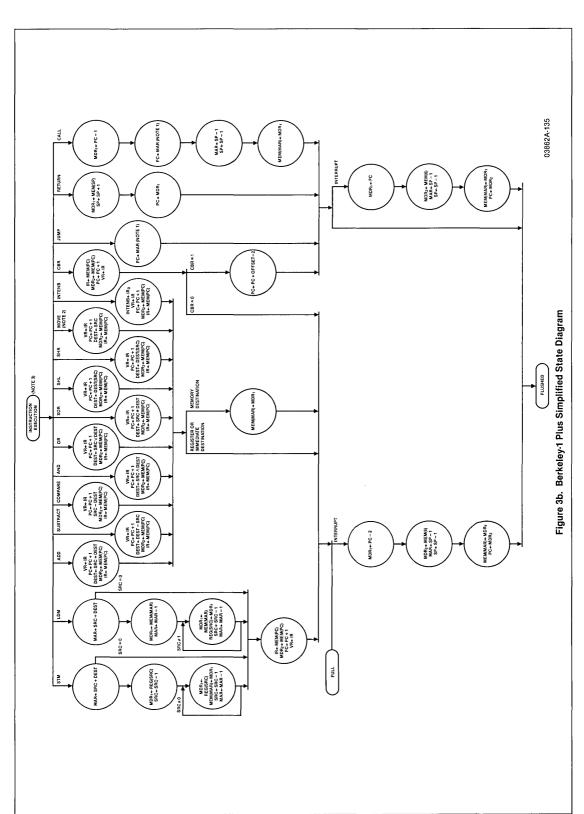
The instruction register (IR) is a good example of how PALs can be used to optimize a common function. An instruction register is generally used to receive instructions off of the data bus during memory fetch operations. The instruction is then decoded by the control sequencer and the instruction is executed. Any data in the instruction word, such as an immediate value or branch address, is operated on during the execution cycle. The Berkeley-1 instruction register performs the same function as well but in a special manner. Instruction information used during the decoding cycle is separated from information used during execution cycle. This allows the IR to predecode instructions on-the-fly from sixteen bits down to ten bits as they are received off of the data bus without losing data in the instruction word. The result is a significant increase in control sequencer speed.

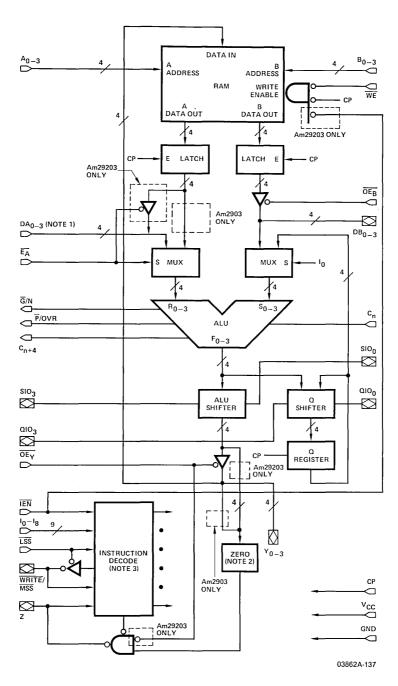
The instruction register can be seen in Figure 7. The IR is implemented with two AmPAL16R8As and one Am29825 8-bit register. The microcode input CEIR when low enables instructions to be clocked into the IR. The full instruction register is 22 bits wide. This includes the 10-bit field (MAP ADR(9:0)) of predecoded instruction information and a 12-bit field (IR(11:0)) of data information.

Predecoding of the instruction from sixteen bits down to ten is accomplished by encoding the SOURCEOP and DESTOP fields down from six bits each to three bits each.

		MAF	P ADR(9:0)	)	
OPC	ODE	SOUR	CEOP	DES	TOP
9	6	5	3	2	0
	]				







Notes: 1. DA<sub>0-3</sub> is input only on Am2903, but is I/O port on Am29203.
2. On Am2903, zero logic is connected to Y, after the OE<sub>Y</sub> buffer.
3. On Am2903, IEN controls WRITE. On Am29203 WRITE is not affected by IEN.

Figure 5. Block Diagram

DBUS1

D<sub>2</sub> D<sub>1</sub>

13 12

MAP ADR1

5 RFAR SEL<sub>3</sub>

6 RFAR SEL2

7 RFAR SEL1

8 RFAR SELn

9 CE VR

CLOCK

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MAP ADRo

MAP ADR<sub>2</sub>

Each three-bit field contains a value for one of the seven addressing modes or a value stating an illegal mode was chosen.

MODE	VALUE
Absolute	000
SP Auto-increment	001
SP Auto-decrement	010
Short Immediate	011
Register	100
Register Indirect	101
Register Indexed	110
Illegal	111

The MAP ADR(9:0) outputs are sent directly to the address inputs of the 1K mapping PROMs in the control sequencer.

The data field (IR(11:0)) is simply the lower twelve bits of the instruction word (i.e., everything but the opcode). IR(11:0) are sent directly to the value register. Notice that all 22 bits of the IR are always on and no three-state control is necessary.

#### **VALUE REGISTER AND DECREMENT REGISTER**

The value register is used to contain the instruction information, such as a conditional branch address, immediate data values, and/or register file addresses, necessary for the execution cycle. The value register is required to support the double-pipelined architecture implemented. For example, during a typical double-pipelined cycle where instruction n is being fetched from memory and instruction n-1 is in the IR and being decoded, instruction n-2 is being executed. Without the value register the information necessary to execute instruction n-2 would be lost. This register is the principal additional hardware required to implement double-pipelining. The value register, along with the decrement register, also controls all of the addressing required for the register file

The value register is implemented using three identically programmed AmPAL16R6As and the decrement register is implemented using a single AmPAL16R4A. Both can be seen in Figure 7. The microcode input  $\overline{\text{CEVR}}$  when low enables data to be clocked into the value register. The value register provides data information on the VR(11:0) outputs, the A address for the register file on the A ADR(2:0) outputs, and the B address on the B ADR(2:0) outputs. VR(11:0) is simply IR(11:0) delayed by one clock cycle.

Register A and B address selection is controlled by the RFAR SEL(3:0) inputs from microcode. The address selection combinations on the A address include the SOURCEREG(2:0) field (obtained from the IR or VR) and a HOLD mode. The address selection combinations on the B address include the DESTREG(2:0) field, SOURCEREG(2:0) field, decrement register, and a HOLD mode. Address selection is obtained from the IR on instructions that are to be executed in the following cycle and from the VR on instructions where multiple operand fetch and instruction execute cycles are necessary. The decrement register is used as an address source for the special LDM and STM instructions (see Appendix A) which require the loading and storing of multiple registers in sequence.

The decrement register is loaded with the address of the first register to be operated on and simply provides sequential addresses of the next registers to be operated on. The decrement register is loaded from the RBUS(2:0) when the register is selected via an immediate or register addressing mode or from the DBUS(2:0) when a memory addressing mode is selected. Loading and decrementing are controlled by the microcode inputs DR SEL(1:0). Additionally, the decrement

register is gated onto the RBUS(2:0) when the microcode input OERBUS is low to provide the lower three bits so that they can be added as an offset to the memory address where data is to be stored or loaded.

#### **RBUS CONTROL PALS**

The RBUS control PAL logic consists of two AmPAL16H8As and is shown in Figure 8. Their primary function is to perform sign extension for short immediate source operands and to put constant values onto the RBUS. SOURCEOP(4) selects the sign of the short immediate operand. The function is controlled by the microcode signal RBUS SEL. Additionally, they are used to gate zeroes onto the upper thirteen bits of the RBUS when the decrement register is on the lower three bits. This is controlled by the microcode signal OERBUS(15:3). The signal OERBUS(2:0) gates the lower three bits of the PALs onto the RBUS during all other functions.

## **CBR AND SBUS CONTROL PALS**

The CBR and SBUS control PAL logic is also shown in Figure 8. The primary function of these PALs is to perform all control necessary for execution of the conditional branch instruction (CBR), sign extension for short immediate destination operands (allowed for compare instruction (CMP) only), and constant generation. The CBR control logic is implemented in one AmPAL16R6A. The CBR logic derives a CBR flag dependent upon the true version of all eight branch conditions and which test is being selected. The branch conditions are generated from the four condition codes: zero (Z), minus (N), overflow (V), and carry (C). The condition being tested is selected by VR(10:8), The Z and N condition codes are loaded in the CBR PAL by the LOADZN microcode signal and the C and V condition codes are loaded by the LOADCV signal. The CBR flag is sent directly to the SBUS control PALs.

The SBUS control PALs are implemented using two AmPAL16H8As. The function performed by these PALs is controlled by microcode inputs SBUS SEL(1:0) and gating of data onto the SBUS is controlled by the OESBUS input. When a CBR instruction is selected, a sign extended branch offset relative to the PC is derived from VR(9:0) and gated onto the SBUS dependent upon the CBR flag and the true/false test polarity select (VR(11)). When high, the test polarity select initiates a branch when the CBR flag is also high (true), and when low it initiates a branch when the CBR flag is also low (false). Should the branch condition not be met the value -1 is added to the PC preventing a branch.

#### PROGRAM COUNTER

The program counter is an excellent example of how PALs are used in this design to implement data steering. The PC is shown in Figure 9. It is implemented using four identically programmed AmPAL16R4As and one AmPAL16H8A. The PC is basically implemented as an incrementing register that can be parallel loaded from the YBUS. The inherent problem with the PC is that it must source both the ABUS for memory fetch operations and the RBUS for relative branch calculations. Unfortunately, a typical MSI device cannot drive two separate buses because they are not designed with multiple three-state outputs. This can lead to the need to add separate three-state controls for each bus (four AM25LS244s) and unnecessary added delay in the memory path. The PC PALs are designed to provide multiple outputs thus saving ICs and delay time in the critical memory path.



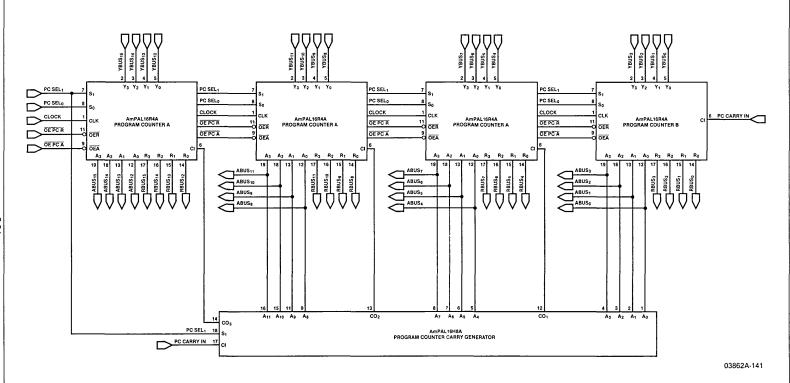


Figure 9. Program Counter

Microcode inputs PC SEL(1:0) select the function to be performed by the PC. The OEPCR and OEPCA inputs control whether the PC is to drive the RBUS or the ABUS, respectively. The PC CARRY IN signal is used to force incremention of the PC. Additionally, the PC internally generates the vector addresses necessary for initialization, illegal instruction traps and interrupts.

## **MEMORY ADDRESS REGISTER**

The memory address register (MAR) is primarily used for fetching of memory source and destination operands, and storing operation results in the memory destination. The MAR is implemented with four AmPAL16R4As and is shown in Figure 10. Memory address register functions are controlled by the MAR SEL(1:0) inputs. The MAR is gated onto the ABUS when the microcode input OEMAR is low. Note that the MAR also has the capability to decrement, which is necessary to support the special LDM and STM instructions.

#### **MEMORY DATA REGISTER 1**

Memory data register 1 (MDR $_1$ ) is another excellent example of PALs facilitating data steering functions in the Berkeley-1. MDR $_1$  is used for I/O operations between the CPU and memory requiring multiple input and output paths. It is implemented with four AmPAL16R4As and can also be seen in Figure 10. MDR $_1$  is loaded from the DBUS when the LOAD SEL input is high and the  $\overline{\text{CE}}$  MDR $_1$  input is low (enabled), and is loaded from the YBUS when LOAD SEL is low and  $\overline{\text{CE}}$  MDR $_1$  is enabled. Additionally, MDR $_1$  is gated onto the RBUS by  $\overline{\text{OE}}$  MDR $_1$   $\overline{\text{R}}$  and onto the DBUS by  $\overline{\text{OE}}$  MDR $_1$   $\overline{\text{D}}$ .

#### **MEMORY DATA REGISTER 2**

Memory data register 2 (MDR<sub>2</sub>) provides an additional data path from memory into the CPU. It is implemented wth two Am29823 high speed 8-bit registers. It is loaded by the  $\overline{\text{CE}}$  MDR<sub>2</sub> input and gated onto the SBUS by the  $\overline{\text{OE}}$  MDR<sub>2</sub> is primarily used to fetch memory destination operands.

#### THE CONTROL SEQUENCER

The control of the CPU is performed by an exceptionally fast (105ns worst case cycle time), pipelined, microprogrammed sequencer that is comprised of only 17 chips. The operation of the sequencer is very straightforward. After initialization (PC-0), the first instruction is fetched. The instruction is decoded and the microprogram branches to a specific sequence of states to fetch the operands or begin execution (for instructions that don't require operands). The starting microprogram PROM address of this sequence of states is given by the Instruction Mapping PROMs. The pipeline register is then successively loaded with the microinstruction corresponding to each state in the sequence and the instruction is "executed." When the execution of the current instruction is complete, the next instruction is fetched (if not already done during the execution of the previous instruction), decoded, and executed. This cycle repeats for every instruction.

The sequencer and its operation will now be separated into three sections and examined in greater detail.

#### INSTRUCTION DECODE

The Instruction Register (IR) is composed of three chips; two AmPAL16R8As and one Am29825. The PALs are used to decode the source and destination addressing modes of the instruction prior to actually being loaded into the IR. The main advantages of this "predecode" are:

- the number of address bits needed for the Instruction Mapping PROMs is reduced, thus reducing PROM space required.
- 2) sequencer cycle time is improved.

The 6-bit source and destination fields are both reduced to 3-bit fields, which is all that is necessary since there are only seven different addressing modes. These two 3-bit fields, along with the four opcode bits, form the 10-bit address to the Instruction Mapping PROMs, IMAP<sub>1</sub> and IMAP<sub>2</sub>. Both IMAP<sub>1</sub> and IMAP<sub>2</sub> use these ten bits to determine the microprogram PROM address needed to begin operand fetches and instruction executions. IMAP1 is used to generate the initial microprogram PROM addresses for all operand fetches and for the execution of instructions that don't require operands (e.g., CALL). IMAP2 generates the initial microprogram PROM addresses for the execution of instructions that require operand fetches. Addresses generated by IMAP2 are loaded into an Am29825, which is an 8-bit register with a clock enable and three-statable outputs. This step is necessary because the IR is often overwritten with the next instruction (instruction prefetching) and the address from IMAP<sub>2</sub> is not used until the operands have been fetched and execution is to begin. This is not required of IMAP<sub>1</sub> because the addresses it generates are always used immediately.

#### NEXT MICROPROGRAM ADDRESS SELECTION

There are four sources from which the next address for the microprogram PROM can come. These are IMAP1, IMAP2 and two microprogram PROMs. As previously mentioned, IMAP1 contains the addresses needed to begin operand fetch cycles or instruction execution cycles, and IMAP2 contains initial microprogram addresses for instruction execution cycles only. Both of the microprogram PROMs contain next state addresses for these cycles to complete.

One AmPAL16R6A is used to select which one of the four sources will provide the next microprogram PROM address. Inputs to this microbranch control PAL consist of three bits from microcode, the outputs of the decrement counter (3 bits), and two bits for interrupt control. There are four outputs, which control the three-state drivers of the four address sources.

The three bits from microcode are used to select the conditions which must be considered for microbranching (e.g., unconditional, DECREMENT COUNTER = 0?, INTERRUPT? and INTERRUPTS ENABLED?). The PAL decodes these conditions and selects the proper source for the next state address. The PAL's function table is shown in Appendix C along with the other PAL DESIGN SPECIFICATIONS.

#### MICROPROGRAM MEMORY

The microcode for the Berkeley-1 Plus resides in eight Am27S25512 x 8 registered PROMs and one Am27S29512 x 8 PROM. The latter PROM is used in conjunction with a AmPAL16R6A to generate the next microprogram address as explained above. The entire sequencer is shown in Figure 11.

## CONCLUSION

The PAL implementation of the Berkeley-1 Plus results in a truly high performance 16-bit CPU. Functions such as the barrel shifter and double-pipelining control are not feasibly implemented in standard SSI/MSI devices. Specialized functions such as LDM and STM are application dependent and therefore not easily optimized in LSI implementations either. The flexibility of PALs makes these functions easy to optimize, resulting in the high performance design shown.

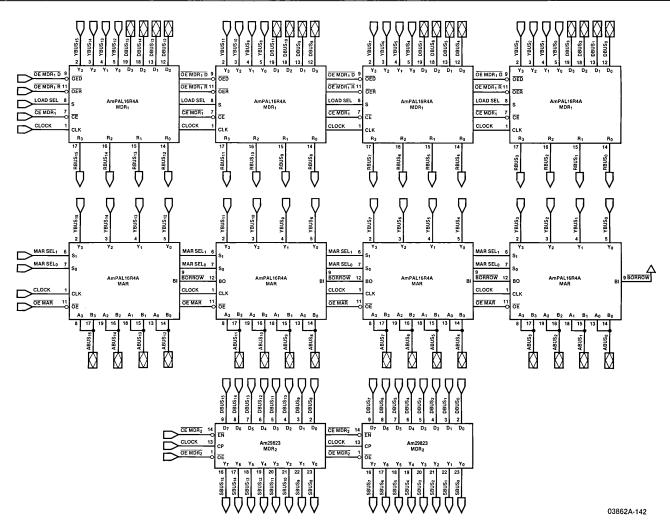


Figure 10. Memory Data Registers 1 and 2 and Memory Address Register

APPENDIX A Instruction Set and Addressing Modes	

INSTRUCTION	N SET		
Mnemonic/ Instruction	OPCODE	Operation	Condition Codes
ADD Add	00SSDD <sub>8</sub>	(dst ← (src) + (dst)	N: set if result < 0 Z: set if result = 0 V: set if there is arithmetic overfresult of the operation; that is operands were of the same siresult is of the opposite sign C: set if there is a carry from the significant bit of the result
SUB Subtract	01SSDD <sub>8</sub>	(dst) (dst) (src)	N: set if result < 0 Z: set if result = 0 V: set if there is arithmetic overl result of the operation, i.e., if operands were of opposite sing of the source is the sam of the result C: set if there is a borrow into the

Add			V:	set if there is arithmetic overflow as a result of the operation; that is, both operands were of the same sign and the result is of the opposite sign set if there is a carry from the most significant bit of the result
SUB Subtract	01SSDD <sub>8</sub>	(dst) (dst) (src)	Z: V:	set if result < 0 set if result = 0 set if there is arithmetic overflow as a result of the operation, i.e., if the operands were of opposite signs and the sign of the source is the same as the sign of the result set if there is a borrow into the most significant bit of the result
CMP Compare	02SSDD <sub>8</sub>	(src) – (dst)	Z: V:	set if result < 0 set if result = 0 set if there is arithmetic overflow; i.e., operands of opposite signs and the sign of the destination is the same as the sign of the result set if there is a borrow into the most significant bit of the result
AND And	03SSDD <sub>8</sub>	$(dst)$ — $(src) \land (dst)$	Z: V:	set if result < 0 set if result = 0 unaffected unaffected
OR Or	04SSDD <sub>8</sub>	(dst) (src) ∨ (dst)	Z: V:	set if result < 0 set if result = 0 unaffected unaffected
XOR Exclusive OR	05SSDD <sub>8</sub>	(dst) — [( ~ src) ∧ (dst)] ∨ [(src) ∧ ( ~ dst)] = src ∀dst	Z: V:	set if the result < 0 set if result = 0 unaffected unaffected
SHL Shift Left	06SSDD <sub>8</sub>	$(dst_i) \leftarrow (dst_{i-src}) : i \ge src$ $(dst_i) \leftarrow 0 : i < src$	Z: V:	set if result < 0 set if result = 0 unaffected unaffected
SHR Shift Right	07SSDD <sub>8</sub>	$(dst_i) \leftarrow (dst_{i+src}) : i \le 15 - src$ $(dst_i) \leftarrow (dst_{15}) : i > 15 - src$	Z: V:	set if result < 0 set if result = 0 unaffected unaffected
CONDITIONAL BRA	NCH INSTRUCTION	ONS:		
BA Branch	080000 <sub>8</sub> plus 8-bit	PC←PC+OFFSET	Z:	unaffected unaffected
(Unconditional)	OFFSET			unaffected unaffected
BEQ Branch if	080400 <sub>8</sub> plus 8-bit	$PC \leftarrow PC + OFFSET$ if $Z = 1$		unaffected unaffected
equal (to zero)	OFFSET			unaffected unaffected
BMI Branch if	081000 plus 8-bit	$PC \leftarrow PC + OFFSET$ if $N = 1$		unaffected unaffected
minus	OFFSET			unaffected unaffected

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# **INSTRUCTION SET (Continued)**

Mnemonic/ Instruction	OPCode	Operation	Condition Codes
BCS Branch if carry set	081400 <sub>8</sub> plus 8-bit OFFSET	PC — PC + OFFSET if C = 1	N: unaffected Z: unaffected V: unaffected C: unaffected
BVS Branch if V bit set	082000 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if V = 1	N: unaffected Z: unaffected V: unaffected C: unaffected
BLT Branch if less than	082400 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if N ∜ V = 1	N: unaffected Z: unaffected V: unaffected C: unaffected
BLE Branch if less than or equal to	083000 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if (Z) $\lor$ (N $\checkmark$ $\lor$ ) = 1	N: unaffected Z: unaffected V: unaffected C: unaffected
BLOS Branch if lower or same	083400 <sub>8</sub> plus 8-bit OFFSET	PC — PC + OFFSET if N V Z = 1	N: unaffected Z: unaffected V: unaffected C: unaffected
NOP No Operation	084000 <sub>8</sub> plus 8-bits of Don't Care	PCPC+1	N: unaffected Z: unaffected V: unaffected C: unaffected
BNE Branch if not equal	084400 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if Z = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
BHIS Branch if higher than or same	085000 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if N = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
BCC Branch if carry clear	085400 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if C = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
BVC Branch if V bit clear	086000 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if V = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
BGE Branch if greater than or equal	086400 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if N ☆ V = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
BGT Branch if greater than	087000 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if (Z) $\lor$ (N $\checkmark$ $\lor$ ) = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
BHI Branch if higher	087400 <sub>8</sub> plus 8-bit OFFSET	PC ← PC + OFFSET if N ∨ Z = 0	N: unaffected Z: unaffected V: unaffected C: unaffected
MOV Move	11SSDD <sub>8</sub>	(dst) ← (src)	N: unaffected Z: unaffected V: unaffected C: unaffected

INSTRUCTION SET (Continu	(baı

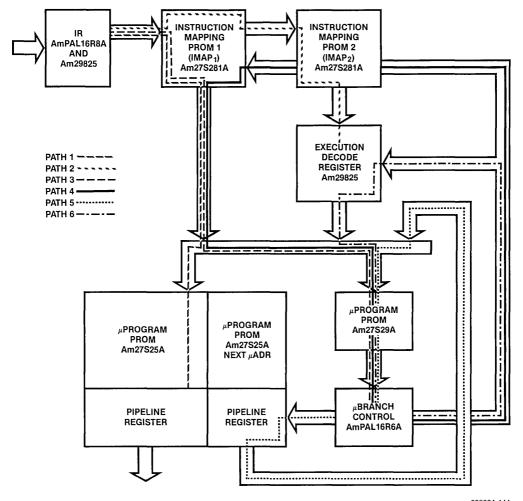
Mnemonic/ Instruction	OPCode	Operation	Condition Codes
CALL Jump to Subroutine	12XXDD <sub>8</sub>	MEM[SP – 1] – PC PC – dst	N: unaffected Z: unaffected V: unaffected C: unaffected
RET Return from Subroutine	13XXXX <sub>8</sub>	PC ← MEM[SP] SP ← SP + 1	N: unaffected Z: unaffected V: unaffected C: unaffected
LDM Load from Memory	14SSDD <sub>8</sub>	FOR i: = 0 to i = src BEGIN REG(src – i) ← MEM[dst + src – i] END	N: unaffected Z: unaffected V: unaffected C: unaffected
STM Store into Memory	15SSDD <sub>8</sub>	FOR i: = 0 to i = src BEGIN MEM[dst + src – i] — REG(src – i) END	N: unaffected Z: unaffected V: unaffected C: unaffected
INTENB Enable or Disable Interrupts	15XXX0 <sub>8</sub> to disable 16XXX1 <sub>8</sub> to enable	INT ENB FLAG ← IR <sub>0</sub>	N: unaffected Z: unaffected V: unaffected C: unaffected
JUMP Jump	17XXDD <sub>8</sub>	PC ← dst	N: unaffected Z: unaffected V: unaffected C: unaffected

# **ADDRESSING MODES**

Binary Code (SOURCEOP or DESTOP)	Name	Function	Binary Code (SOURCEOP or DESTOP)	Name	Function
011111	Short Immediate	Operand is contained in the instruction. It is the lower five bits of the SOURCEOP or DESTOP field, sign extended.	111000	Absolute	The contents of the memory location pointed to by the PC is the memory address of the operand. PC-PC+1.
100RRR	Register	The register specified by the REG field bits RRR, contains the operand.	111001	Stack Pointer Auto- Increment	The contents of the SP (register 7) is the memory ad- dress of the operand. The SP i
101RRR	Register Indirect	The register specified by the REG field bits RRR contains the memory address of the operand.	111010	Stack Pointer Auto- Decrement	then automaticall incremented. The contents of the SP is decremented and is now the
110RRR	Register Indexed	The contents of the memory location pointed to by the PC is added to the contents of the register specified by the REG field bits RRR. This forms the memory address of the operand PC-PC+1.	111011 1111XX	Reserved	memory address of the operand. Are currently flagged as illegal.

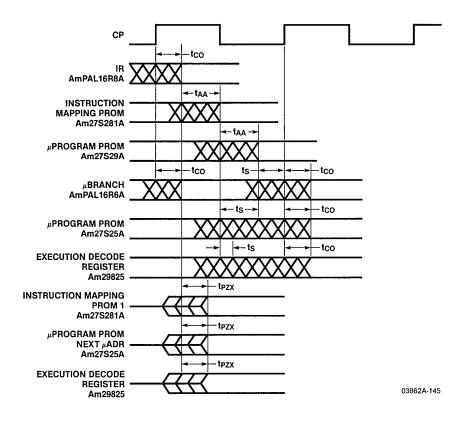
APPENDIX B	
Critical Path Analysis	

## **CRITICAL PATH ANALYSIS SEQUENCER**



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## **CRITICAL PATH TIMING ANALYSIS**



# **CRITICAL PATH ANALYSIS FOR BERKELEY-1 PLUS SEQUENCER**

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D	2	ŧ١	•	1	

Am27S	00110
t <sub>AA</sub> IMAP <sub>1</sub>	35ns

# Path 2:

tco	IR AmPAL16R8A	15ns
taa	IMAP <sub>2</sub> Am27S281A	35ns
ts	Execution Decode REG Am29825	4ns
		54ns

## Path 3:

tco	IR AmPAL16R8A	15ns
taa	IMAP₁ Am27S281A	35ns
tAA	μProgram PROM Am27S29A	35ns
ts	μBranch PAL AmPAL16R6A	20ns
		105ns

## Path 4:

AmPAL16R6A  tpzx IMAP1	95ns
AmPAL16R6A tpzx IMAP <sub>1</sub> Am27S281A t <sub>AA</sub> μProgram PROM	20ns
AmPAL16R6A t <sub>PZX</sub> IMAP <sub>1</sub>	35ns
	25ns
tco μBranch PAL	15ns

## Path 5:

tco	μBranch PAL AmPAL16R6A	15ns
tpzx	μProgram PROM next μADDRESS Am27S25A	25ns
t <sub>AA</sub>	μProgram PROM Am27S29A	35ns
ts	μBranch PAL AmPAL16R6A	20ns
		95ns

# Path 6:

		9500
ts	μBranch PAL AmPAL16R6A	20ns
tAA	μProgram PROM Am27S29A	35ns
t <sub>PZX</sub>	Execution Decode Register Am29825	15ns
tco	μBranch PAL AmPAL16R6A	15ns

Note:  $t_{CO}$  = Clock to Output Delay  $t_{AA}$  = Access Time delay  $t_{S}$  = Set-Up time  $t_{PZX}$  = Output Enable delay

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# CRITICAL PATH ANALYSIS FOR BERKELEY-1 PLUS CPU

## **INSTRUCTION ADD**

# Path 1:

t <sub>CO</sub> ADR to	VR AmPAL16R6A Pi, Gi of Am29203	15ns 52ns
Pi, Gi to	C <sub>n+z</sub> of Am2902A	9ns
C <sub>n</sub> to C	n + 4 of Am29203	18ns
ts	CBR Control PAL AmPAL16R6A	20ns
		114ns

## Path 2:

tco	μProgram PROM	25ns
	Am27S25A	
I to $\overline{P_i}$ , $\overline{C}$	Gi of Am29203	50ns
$\overline{P_i}, \overline{G_i}$ to	Cn+zof Am2902A	9ns
C <sub>n</sub> to C	<sub>n + 4</sub> of Am29203	18ns
ts	CBR Control PAL	20ns
	AmPAL16R6A	
		122ns

## Path 3:

tco	VR AmPAL16R6A	15ns
ADR to	Y of Am29203	68ns
ts	Destination (PALs)	20ns
		103ns

# Path 4:

tco	μProgram PROM Am27S25A	25ns
I to Y of A	m29203	64ns
ts	Destination (PALs)	20ns
		109ns

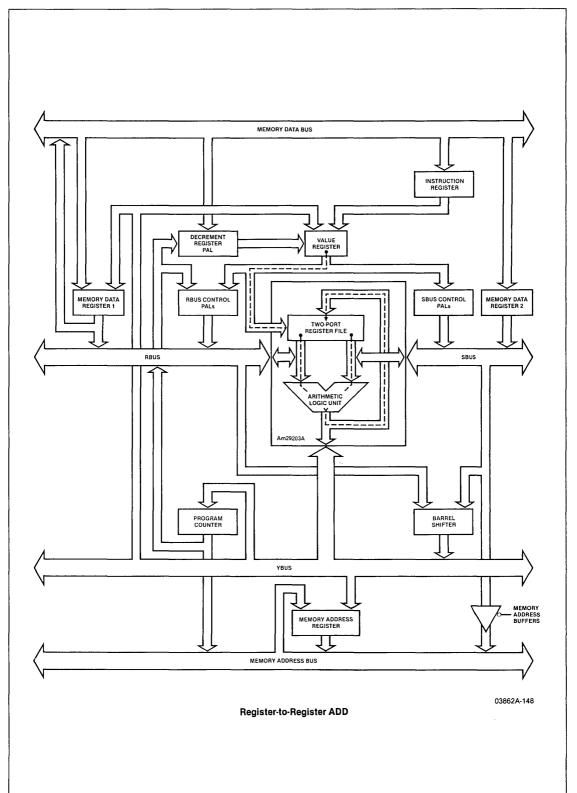
# Path 5:

tco	VR AmPAL16R6A RBUS Control PALs	15ns 25ns
t <sub>pd</sub>	AmPAL16H8A	20118
DA or D	B to P <sub>i</sub> , G <sub>i</sub> of Am29203	44ns
$\overline{P_i}, \overline{G_i}$ to	C <sub>n+z</sub> of Am2902A	9ns
C <sub>n</sub> to C	n + 4 of Am29203	18ns
ts	CBR Control PAL AmPAL16R6A	20ns
		131ns

## Path 6:

tco	VR AmPAL16R6A	15ns
t <sub>pd</sub>	RBUS Control PALs AmPAL16H8A	25ns
DA or DB to Y of Am29203		59ns
ts	Destination (PALs)	20ns
		119ns

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# **CRITICAL PATH ANALYSIS FOR BERKELEY-1 PLUS CPU (Continued)**

# **INSTRUCTION SHIFT:**

# Path 1:

tco A or B A	VR AmPAL16R6A DR to DA or DB of Am29203	15ns 24ns
t <sub>pd</sub>	Barrel Shifter	50ns
ts	Y to RAM of Am29203	16ns
		105ns

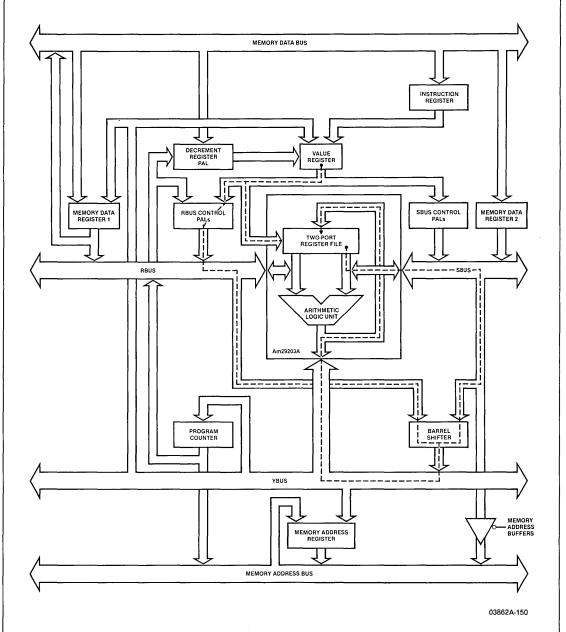
# Path 2:

tco	VR AmPAL16R6A	15ns
tpd	RBUS PALs	25ns
tpd	Barrel Shifter	50ns
ts	Y to RAM of Am29203	16ns
		106ns

# Path 3:

tco	VR AmPAL16R6A	15ns
tpd	RBUS PALs	25ns
tpd	Barrel Shifter	50ns
ts	MDR <sub>1</sub>	20ns
	AmPAL16R4A	
		110ns

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Immediate Source, Register Destination Shift

# CRITICAL PATH ANALYSIS FOR BERKELEY-1 PLUS CPU (Continued)

# **MEMORY ACCESS:**

# Indexed:

tco	VR AmPAL16R6A	15ns
<b>ADR</b> to	68ns	
ts	MAR	20ns
-	AmPAL16R4A	
		103ns

tco	μProgram PROM Am27S25A	25ns
t <sub>PZX</sub>	MDR <sub>2</sub> Am29823	15ns
DB to Y	of Am29203	59ns
ts	MAR AmPAL16R4A	20ns
		110nc

# Indirect:

tco	VR AmPAL16	R6A 15ns
BADR	to DB of Am29203	24ns
tpD	74S244	10.5ns
		49.5ns
		+ Memory Access
		Time
		+ Set-Up Time
		to DEST of Data

03862A-151

APPENDIX C PAL Design Specifications

# PAL DESIGN SPECIFICATION JEFF KITSON 10/4/82

PAL16H8
PAT023
BIT SHIFTER
ADVANCED MICRO DEVICES
IO I1 I2 I3 I4 I5 I6 I7 I8 GND
I9 YO Y1 OE SRNSL RO R1 Y2 Y3 VCC

# ;BIT SHIFTER OUTPUT SIGNALS

```
IF (OE) Y3
               = /R1*/R0*I6
                 /R1* RO* SRNSL*I7
                  R1*/RO* SRNSL*18
                  R1* RO* SRNSL*I9
                                     +
                 /R1* RO*/SRNSL*I5
                  R1*/RO*/SRNSL*I4
                  R1* RO*/SRNSL*I3
              = /R1*/R0*I5
IF (OE) Y2
                 /R1* RO* SRNSL*I6
                  R1*/RO* SRNSL*I7
                  R1* RO* SRNSL*18
                 /R1* RO*/SRNSL*I4
                  R1*/RO*/SRNSL*I3
                  R1* RO*/SRNSL*I2
IF (OE) Y1
               = /R1*/R0*I4
                 /R1* RO* SRNSL*I5
                  R1*/RO* SRNSL*16
                  R1* RO* SRNSL*I7
                 /R1* RO*/SRNSL*I3
                                     +
                  R1*/RO*/SRNSL*I2
                                     +
                  R1* RO*/SRNSL*I1
IF (OE)
             = /R1*/R0*I3
          YO
                 /R1* RO* SRNSL*I4
                  R1*/RO* SRNSL*I5
                  R1* RO* SRNSL*16
                 /R1* RO*/SRNSL*I2
                  R1*/RO*/SRNSL*I1
                  R1* RO*/SRNSL*IO
```

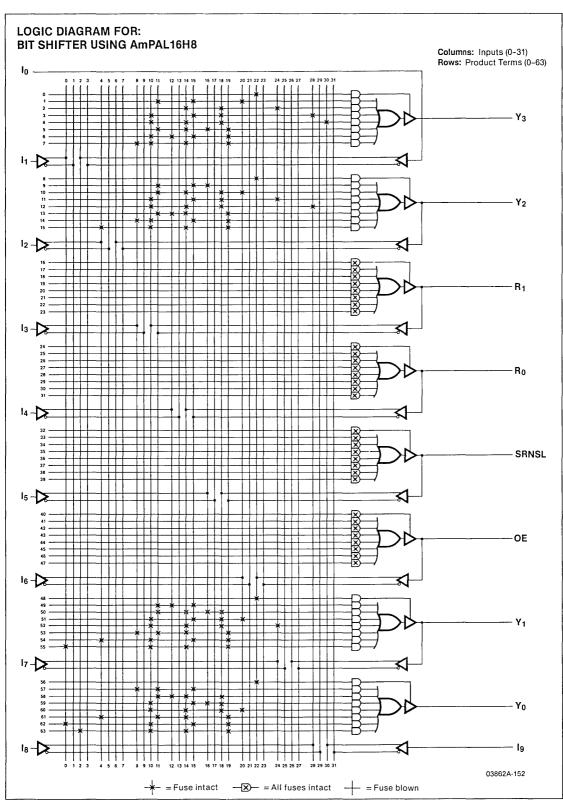
	NCT: I1				15	16	17	18	19	OE	SRNSL	R1	RO	YO Y1 Y2	Y3
;S	HIF	ΓZΙ	ERO												
Н	Н	H	L	L	L	Н	Н	H	L	H	H	L	L	LLL	H
H	H	Н	L	L	L	Н	Н	H	L	Н	L	L	L	$L \;\; L \;\; L$	Н
;S	HIF'	T O	ŀΕ												
Η	Η	Н	L	L	L	Η	Н	Η	L	Η	Н	L	Н	LLH	Н
Н	Н	Н	L	L	L	Η	Η	Н	L	Η	L	L	Н	H $L$ $L$	L
;S	HIF	TTW(	)												
Η	Н	H	L	L	L	Η	Η	Н	L	Η	Н	Н	L	L H H	Η
Η	Н	Н	L	L	L	Н	Н	Η	L	Н	L	Η	L	H $H$ $L$	L
;S	HIF	ГТ	IREI	Ξ											
Н	Н	Н	L	L	L	Н	Н	H	L	Η	Н	Н	Η	н н н	L
Н	Н	H	L	L	L	Н	Н	H	L	Н	L	Н	Н	н н н	L

# DESCRIPTION

THE SECOND LEVEL OF THE BARREL SHIFTER IS THE BIT SHIFTER PERFORMS A RIGHT OR LEFT SHIFT OF 0,1,2 OR 3 PLACES, WHICH IS CONTROLLED BY THE LOWER TWO BITS OF THE RBUS, I.E. RBUS<1:0>. THE SHR/SHL SIGNAL CONTROLS THE DIRECTION OF THE SHIFT. THE SHIFTER/ALU SIGNAL CONTROLS THE GATING OF THE SHIFTER ONTO THE YBUS. THIS FOUR INPUT AND FOUR OUTPUT PAL SLICE IS CASCADED TO IMPLEMENT A 16-BIT SHIFTER.

79AF

10/4/82



# PAL DESIGN SPECIFICATION JENNY YEE 10/4/82

PAL16H8
PAT024
NIBBLE SHIFTER A
ADVANCED MICRO DEVICES
S4 S3 S2 S1 S0 R3 R2 R1 R0 GND
OE NC SRNSL IO I1 I2 I3 ZOE Z VCC

#### ; NIBBLE SHIFTER A OUTPUTS

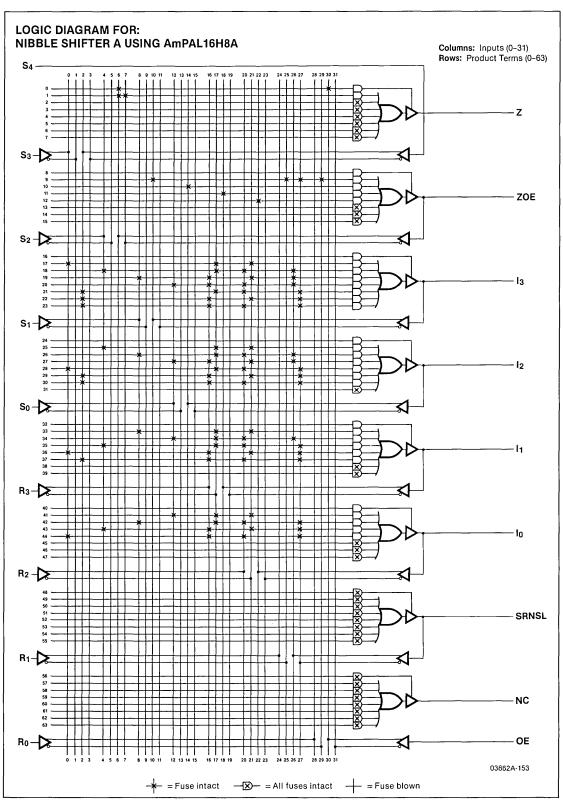
```
IF (OE*ZOE) Z
              = ZOE*/ZOE
              = /SRNSL*/R1* R0* I3
          ZOE
                                     12
                                     T 1
                                     TO
                  = SRNSL* S2*/R3* R2
         13
                     SRNSL* S1* R3* R2
                     SRNSL* SO* R3* R2
                    /SRNSL* S4*/R3* R2
                    /SRNSL* S4* R3*/R2
                    /SRNSL* S4* R3* R2
                            S3*/R3*/R2
          12
                   = SRNSL* S1*/R3* R2
                     SRNSL* SO* R3*/R2
                    /SRNSL* S3*/R3* R2
                    /SRNSL* S4* R3*/R2
                    /SRNSL* S4* R3* R2
                            S2*/R3*/R2
          11
                  = SRNSL* SO*/R3* R2
                    /SRNSL* S2*/R3* R2
                    /SRNSL* S3* R3*/R2
                    /SRNSL* S4* R3* R2
                            S1*/R3*/R2
                   = /SRNSL* S1*/R3* R2
          10
                     /SRNSL* S2* R3*/R2
                     /SRNSL* S3* R3* R2
                             SO*/R3*/R2
```

# FUNCTION TABLE

S4 S3 S2 S1 S0	R3	R2	R1	RO	SRNSL	OE	13	12	11	10	ZOE	Z
;SHIFT ZERO												
LHHHL	L	L	L	L	Н	H	H	H	Н	L	H	L
LHHHL	L	L	L	L	L	H	Н	Н	H	L	H	L
;SHIFT ONE												
LHLHH	L	Н	L	H	H	Н	L	Н	Н	L	H	L
LHLHH	L	Н	L	H	L	H	L	Н	L	H	H	L
;SHIFT TWO												
LHHLL	Н	L	H	L	H	H	L	L	L	L	L	Z
LHHLL	Н	L	Н	L	L	Н	L	L	Н	Н	Н	L
;SHIFT THREE												
LHLHH	Н	H	Н	H	H	H	H	L	L	L	L	Z
LHLHH	H	H	H	Н	L	H	L	L	L	H	Н	L

#### DESCRIPTION

THE NIBBLE SHIFTER IS IMPLEMENTED USING FOUR AMPAL16H8AS. IT PERFORMS A SHIFT OF 0,4,8 OR 12 BITS. THE NUMBER OF SHIFTS IS DEPENDENT UPON THE UPPER TWO BITS OF THE FOUR BIT SHIFT DISTANCE, RBUS<3:2>. ZERO CONDITION CODE CALCULATION IS PERFORMED USING ALL FOUR SHIFT DISTANCE BITS, RBUS<3:0>. SHIFT DIRECTION IS DETERMINED BY SHR/SHL. DATA INPUTS ARE SBUS<15:0>. NIBBLE SHIFTER A USES INPUTS SBUS<15,11,7,3>.



# PAL16H8 PATO24 NIBBLE SHIFTER B ADVANCED MICRO DEVICES S4 S3 S2 S1 S0 R3 R2 R1 R0 GND OE NC SRNSL IO I1 I2 I3 ZOE Z VCC

#### PAL DESIGN SPECIFICATION JEFF KITSON 10/4/82

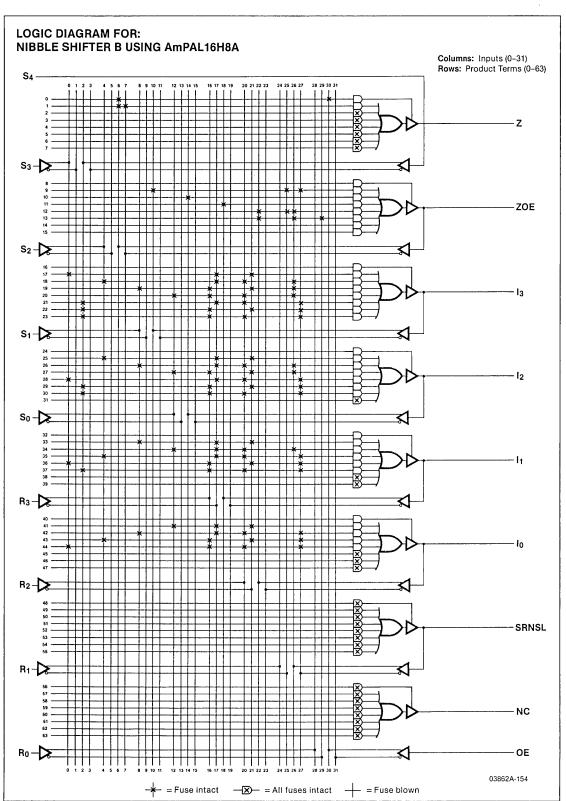
#### ; NIBBLE SHIFTER B OUTPUTS

```
= ZOE*/ZOE
IF (OE*ZOE) Z
          ZOE
                  = SRNSL*/R1* I3
                    SRNSL*/R1* IO
                    SRNSL*/RO* IO
                               12
                               11
                  = SRNSL* S2*/R3* R2
           13
                    SRNSL* S1* R3*/R2
                    SRNSL* SO* R3* R2
                   /SRNSL* S4*/R3* R2
                   /SRNSL* S4* R3*/R2
                   /SRNSL* S4* R3* R2
                           S3*/R3*/R2
                  = SRNSL* S1*/R3* R2
           12
                    SRNSL* SO* R3*/R2
                   /SRNSL* S3*/R3* R2
                                         +
                   /SRNSL* S4* R3*/R2
                                         +
                   /SRNSL* S4* R3* R2
                           S2*/R3*/R2
           I1
                  = SRNSL* SO*/R3* R2
                   /SRNSL* S2*/R3* R2
                   /SRNSL* S3* R3*/R2
                                         +
                   /SRNSL* S4* R3* R2
                           S1*/R3*/R2
                  =/SRNSL* S1*/R3* R2
           10
                   /SRNSL* S2* R3*/R2
                   /SRNSL* S3* R3* R2
                           SO*/R3*/R2
```

			TAI S1		R3	R2	R1	RO	SRNSL	OE	13	12	11	10	ZOE	Z
;S	HIF	т z	ERO													
L	H	H	Н	L	L	L	X	Х	H	L	Н	Н	Н	L		Z
L	H	Η	Η	L	L	L	X	X	L	L	Н	Н	Н	L	Н	Z
;S	HIF	T 0	NE													
L	Η	L	Н	H			X	X	H	L	L	Н	Н	L	Н	Z
L	Η	L	Н	H	L	Н	X	X	L	L	L	Η	L	Н	Н	Z
;S	HIF	T T	WO													
L	Η	Η	L	L	Н		Х	X	H	L	L	L	L	L	L	Z
L	Η	Η	L	L	Н	L	X	X	L	L	L	L	Н	Н	Н	Z
;S	HIF	T T	HRE	Ξ												
L	Н	L	Н	H	Η	Н	X	X	H	L	Н	L	L	L	Н	Z
L	Н	L	Н	H	Η	Н	X	X	L	L	L	L	L	Н	L	Z

# DESCRIPTION

NIBBLE SHIFTER B IS THE SECOND SLICE OF THE SERIES OF FOUR CASCADED NIBBLE SHIFTER PALS. THE FUNCTIONS ARE THE SAME, WITH NIBBLE SHIFTER B USING SBUS<14,10,6,2> AS DATA INPUTS.



```
PAL16H8
PATO25
NIBBLE SHIFTER C
ADVANCED MICRO DEVICES
S4 S3 S2 S1 S0 R3 R2 R1 R0 GND
OE NC SRNSL IO I1 I2 I3 ZOE Z VCC
;NIBBLE SHIFTER C OUTPUTS
IF (OE*ZOE) Z = ZOE*/ZOE
          ZOE = /SRNSL*/R1* I3
                 /SRNSL*/RO* 13
                 SRNSL*/R1* IO
                             T2
                             11
           I3 = SRNSL* S2*/R3* R2
                 SRNSL* S1* R3*/R2
                SRNSL* SO* R3* R2
                /SRNSL* S4*/R3* R2
                /SRNSL* S4* R3*/R2
                /SRNSL* S4* R3* R2
                        S3*/R3*/R2
           I2 = SRNSL* S1*/R3* R2
                SRNSL* SO* R3*/R2
                /SRNSL* S3*/R3* R2
                /SRNSL* S4* R3*/R2
                /SRNSL* S4* R3* R2
                       S2*/R3*/R2
           I1 = SRNSL* SO*/R3* R2
                /SRNSL* S2*/R3*/R2
                /SRNSL* S3* R3*/R2
                /SRNSL* S4* R3* R2
                       S1*/R3*/R2
           IO =/SRNSL* S1*/R3* R2
               /SRNSL* S2* R3*/R2
               /SRNSL* S3* R3* R2
                       SO*/R3*/R2
```

PAL DESIGN SPECIFICATION

10/4/82

JENNY YEE

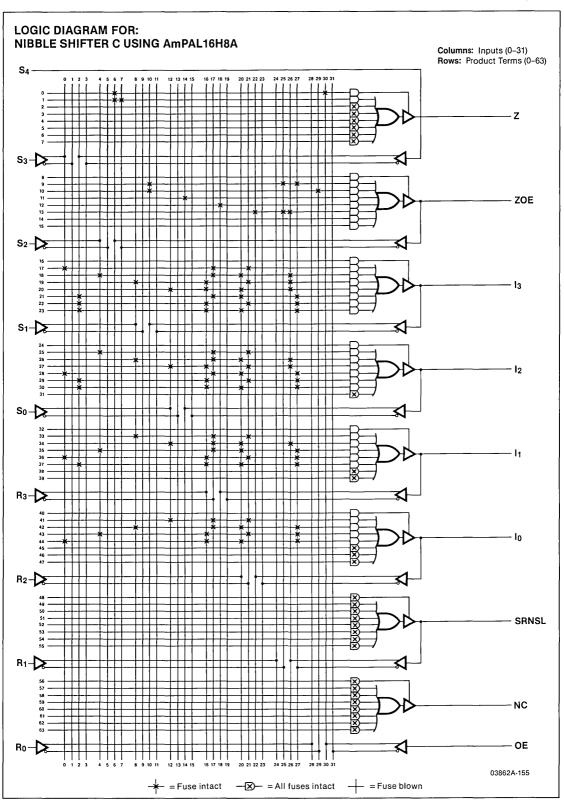
FUNCTION TABLE S4 S3 S2 S1 S0	R3 R2 R1 RO	SRNSL OE	13 12 11 10 ZOE Z
;SHIFT ZERO			
LHHHL	LLLL	н н	ннньнь
LHHHL	L $L$ $L$ $L$	L H	ннньнь
;SHIFT ONE			
LHLHH	LHLH	H H	LHHLHL
LHLHH	LHLH	L H	LHLHHL
;SHIFT TWO			
LHHLL	H $L$ $H$ $L$	H H	LLLLLZ
LHHLL	H $L$ $H$ $L$	L H	LLHHHL
;SHIFT THREE			
LHLHH	н н н н	н н	HLLLLZ
LHLHH	н н н н	L H	L L L H L Z

# DESCRIPTION

NIBBLE SHIFTER C IS THE THIRD SLICE OF THE FOUR CASCADED NIBBLE SHIFTER PALS. AGAIN, THE FUCNTIONS ARE THE SAME, WITH THIS SLICE HAVING DATA INPUTS FROM SBUS <13,9,5,1>.

```
PAL16H8
                                 PAL DESIGN SPECIFICATION
PATO25
                                 JENNY YEE
                                              10/4/82
NIBBLE SHIFTER C
ADVANCED MICRO DEVICES
*D9725
*F0*
LO256 1111 1111 1111 1111 1111 1111 1111 *
LO288 1111 1111 1101 1111 1111 1111 1010 1111 *
L0320 1111 1111 1101 1111 1111 1111 1110 1011 *
LO352 1111 1111 1111 1111 1111 1101 1001 1111 *
L0544 1111 0111 1111 1111 1011 0111 1101 1111 *
L0576 1111 1111 0111 1111 0111 1011 1101 1111 *
L0608 1111 1111 1111 0111 0111 0111 1101 1111 *
L0640 1101 1111 1111 1111 1011 0111 1110 1111 *
L0672 1101 1111 1111 1111 0111 1011 1110 1111 *
LO704 1101 1111 1111 1111 0111 0111 1110 1111 *
L0768 1111 1111 1111 1111 1111 1111 1111 *
L0800 1111 1111 0111 1111 1011 0111 1101 1111 *
L0832 1111 1111 1111 0111 0111 1011 1101 1111 *
L0864 0111 1111 1111 1111 1011 0111 1110 1111 *
L0896 1101 1111 1111 1111 0111 1011 1110 1111 *
L0928 1101 1111 1111 1111 0111 0111 1110 1111 *
L0960 1111 0111 1111 1111 1011 1011 1111 1111 *
L1056 1111 1111 1111 0111 1011 0111 1101 1111 *
L1088 1111 0111 1111 1111 1011 1011 1110 1111 *
L1120 0111 1111 1111 1111 0111 1011 1110 1111 *
L1152 1101 1111 1111 1111 0111 0111 1110 1111 *
L1312 1111 1111 0111 1111 1011 0111 1110 1111 *
L1344 1111 0111 1111 1111 0111 1011 1110 1111 *
L1376 0111 1111 1111 1111 0111 0111 1110 1111 *
L1408 1111 1111 1111 0111 1011 1011 1111 1111 *
C82EB*
V0001 01110000001X1LHHHHHH1 *
V0002 01110000001X0LHHHHHH1 *
V0003 01011010101X1LHHLHH1 *
V0004 01011010101X0HLHLHH1 *
V0005 01100101001X1LLLLLL1 *
V0006 01100101001X0HHLLHH1 *
V0007 01011111101X1LLLHLL1 *
V0008 010111111101X0HLLLLL1 *
```

8DF2



```
PAL16H8
PATO26
NIBBLE SHIFTER D
ADVANCED MICRO DEVICES
S4 S3 S2 S1 S0 R3 R2 R1 R0 GND
OE NC SRNSL IO I1 I2 I3 ZOE Z VCC
; NIBBLE SHIFTER D OUTPUTS
IF (OE*ZOE) Z = ZOE*/ZOE
       ZOE = I3
               12
               11
               SRNSL* IO*/R1*/RO
        I3 =
                      S3*/R3*/R2
               SRNSL* S2*/R3* R2
               SRNSL* S1* R3* R2
               SRNSL* SO* R3* R2
              /SRNSL* S4*/R3* R2
              /SRNSL* S4* R3*/R2
              /SRNSL* S4* R3* R2
       I2 = S2*/R3*/R2
               SRNSL* S1*/R3* R2
               SRNSL* SO* R3*/R2
              /SRNSL* S3*/R3* R2
              /SRNSL* S4* R3*/R2
              /SRNSL* S4* R3* R2
                     S1*/R3*/R2
               SRNSL* SO*/R3* R2
              /SRNSL* S2*/R3* R2
              /SRNSL* S3* R3*/R2
              /SRNSL* S4* R3* R2
         I0 =
                     SO*/R3*/R2
              /SRNSL* S1*/R3* R2
              /SRNSL* S2* R3*/R2
```

/SRNSL\* S3\* R3\* R2

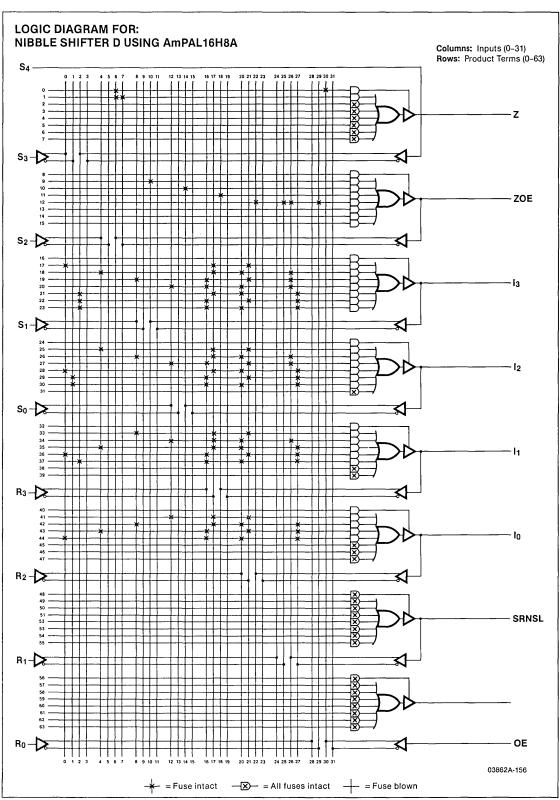
PAL DESIGN SPECIFICATION JEFF KITSON 10/4/82

FUNCTION TABLE S4 S3 S2 S1 S0	R3 R	2 R1	RO	SRNSL OE	I3 I2 I1 I0 ZOE Z
;SHIFT ZERO					
LHHHL	L L	L	L	H L	ннньк
LHHHL	LL	. L	L	$\mathbf{L}$ $\mathbf{L}$	ннньнг
;SHIFT ONE					
LHLHH	L H		Н	H L	LHHLHZ
LHLHH	L H	L	H	L L	LHLHHZ
;SHIFT TWO					
LHHLL	H L	Н	L	H L	LLLLZ
LHHLL	H L	H	L	$\mathbf{L}$ $\mathbf{L}$	L L Н Н Н Z
;SHIFT THREE					
LHLHH	H H	Н	Н	H L	HLLLHZ
LHLHH	H H	H	H	L L	LLLHLZ

# DESCRIPTION

NIBBLE SHIFTER D IS THE LAST OF THE FOUR NIBBLE SHIFTER SLICES. IT USES DATA INPUTS SBUS <12,8,4,0>.

```
PAL16H8
                                 PAL DESIGN SPECIFICATION
PAT026
                                 JEFF KITSON
                                              10/4/82
NIBBLE SHIFTER D
ADVANCED MICRO DEVICES
*D9725
*F0*
L0256 1111 1111 1111 1111 1111 1111 1111 *
LO288 1111 1111 1101 1111 1111 1111 1111 *
L0544 0111 1111 1111 1111 1011 1011 1111 1111 *
L0576 1111 0111 1111 1111 1011 0111 1101 1111 *
L0608 1111 1111 0111 1111 0111 0111 1101 1111 *
L0640 1111 1111 1111 0111 0111 0111 1101 1111 *
L0672 1101 1111 1111 1111 1011 0111 1110 1111 *
L0704 1101 1111 1111 1111 0111 1011 1110 1111 *
L0736 1101 1111 1111 1111 0111 0111 1110 1111 *
L0768 1111 1111 1111 1111 1111 1111 1111 *
L0800 1111 0111 1111 1111 1011 1011 1111 1111 *
L0832 1111 1111 0111 1111 1011 0111 1101 1111 *
L0864 1111 1111 1111 0111 0111 1011 1101 1111 *
L0896 0111 1111 1111 1111 1011 0111 1110 1111 *
L0928 1101 1111 1111 1111 0111 1011 1110 1111 *
L0960 1101 1111 1111 1111 0111 0111 1110 1111 *
L1088 1111 1111 1111 0111 1011 0111 1101 1111 *
L1120 1111 0111 1111 1111 1011 0111 1110 1111 *
L1152 0111 1111 1111 1111 0111 1011 1110 1111 *
L1184 1101 1111 1111 1111 0111 0111 1110 1111 *
L1312 1111 1111 1111 0111 1011 1011 1111 1111 *
L1344 1111 1111 0111 1111 1011 0111 1110 1111 *
L1376 1111 0111 1111 1111 0111 1011 1110 1111 *
L1408 0111 1111 1111 1111 0111 0111 1110 1111 *
C7F25*
V0001 011100000000X1LHHHHZ1 *
V0002 01110000000X0LHHHHZ1 *
V0003 01011010100X1LHHLHZ1 *
V0004 01011010100X0HLHLHZ1 *
V0005 01100101000X1LLLLZ1 *
V0006 01100101000X0HHLLHZ1 *
V0007 010111111100X1LLLHHZ1 *
V0008 010111111100X0HLLLLZ1 *
8617
```



# PAL16R8 PAL DESIGN SPECIFICATION PAT017 JENNY YEE 10/4/82 INSTRUCTION REGISTER ADVANCED MICRO DEVICES

# :INSTRUCTION REGISTER OUTPUT SIGNALS

CLK D5 D4 D3 D2 D1 D0 NC /CE GND /OE MO M1 M2 IRO IR1 IR2 IR3 IR4 VCC

; INSIKUCIIC	N REGISTER OUTPUT SIGNALS	
/IR4	:= CE*/D4 /CE*/IR4	-
/IR3	:= CE*/D3 /CE*/IR3	+
/IR2	:= CE*/D2 /CE*/IR2	÷
/IR1	:= CE*/D1	F
/IRO	:= CE*/DO	-
/M2	:= /CE*/M2 CE*/D5 CE* D5* D4* D3*/D2*/D1*/D0 CE* D5* D4* D3*/D2*/D1* D0 CE* D5* D4* D3*/D2* D1*/D0	++++
/M1	:= /CE*/M1 CE* D5*/D4*/D3 CE* D5*/D4* D3 CE* D5* D4* D3*/D2*/D1*/D0 CE* D5* D4* D3*/D2*/D1* D0	+ + +
/MO	:= /CE*/MO CE* D5*/D4*/D3 CE* D5* D4*/D3 CE* D5* D4* D3*/D2*/D1*/D0 CE* D5* D4* D3*/D2* D1*/D0	+ + +

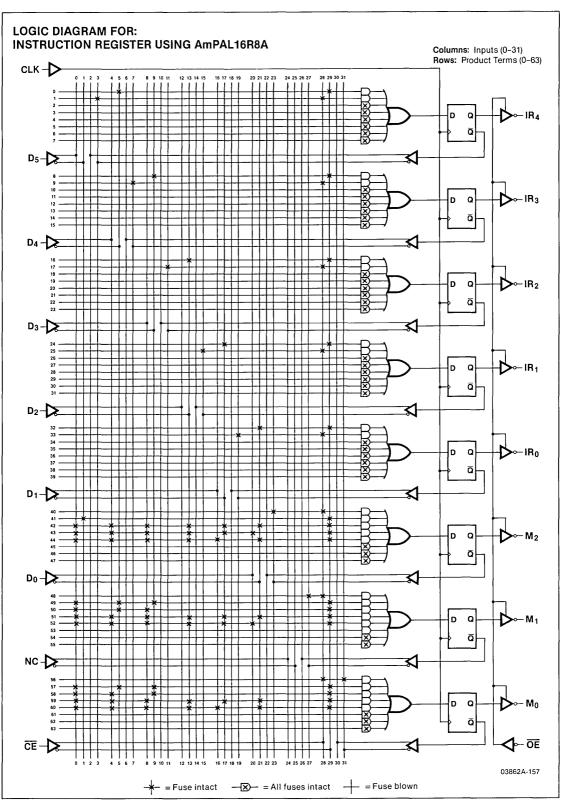
# FUNCTION TABLE

CLK	/OE	/CE	D5	D4	D3	D2	D1 :	DO		IR4	IR3	IR2	IR1	IRO	M2	M1	MO
•10			TEDC			THE	Oumpum	ONITIO									
, 10	אט עו	CTO	TEVO	r r	UN	THE	שמ	US.	AND	OUTPUT	ONTO	υŲ					
С	L	L	L	Н	L	Н	L	Н		H	L	Н	L	H	L	Н	H
С	L	L	Η	L	L	L	Η	L		L	L	L	H	L	Н	L	L
С	L	L	H	L	Η	Н	L	H		L	Н	Н	L	Н	Н	L	Н
С	L	L	Н	Н	L	L	H	L		H	L	L	Н	L	Н	Н	L
C	L	L	Н	Η	Н	L	L	L		Н	Н	L	L	L	L	L	L
С	L	L	H	Н	Н	L	L	Н		H	Н	L	L	H	L	L	Н
С	L	L	Н	Н	Н	L	Н	L		H	H	L	Н	L	L	Н	L
С	L	L	Н	Н	Н	L	Н	Н		H	Н	L	Н	Н	Н	Н	Н
С	L	L	H	Н	Н	Н	L	Н		Н	Н	Н	L	Н	Н	Н	Н
; HO	LD TH	IIS '	VALU	ΕA	ND	OUT	PUT	ON'	TO (	)							
С	L	H	X	X	X	X	X	X		` Н	Н	H	L	H	Н	Н	H

# DESCRIPTION

THE INSTRUCTION REGISTER (IR) IS IMPLEMENTED USING TWO AMPAL16R8AS AND ONE AM29825. THE INSTRUCTION REGISTER TAKES 16-BITS OF INPUT DATA FROM THE DBUS, PREDECODES THE OPCODE AND ADDRESSING MODES, GENERATING A 10-BIT FIELD FOR THE MAPPING PROM. IN ADDITION TO THIS, IR<11:0> IS PASSED THROUGH TO THE VALUE REGISTER, WHICH USES THIS DATA TO GENERATE CONDITIONAL BRANCH ADDRESSES, IMMEDIATE DATA VALUES, AND REGISTER FILE ADDRESSES.

```
PAL16R8
                             PAL DESIGN SPECIFICATION
PATO17
                             JENNY YEE
                                       10/4/82
INSTRUCTION REGISTER
ADVANCED MICRO DEVICES
*D9724
*F0*
L0256 1111 1111 1011 1111 1111 1111 1111 1011 *
L0768 1111 1111 1111 1111 1011 1111 1111 1011 *
L1024 1111 1111 1111 1111 1111 1011 1111 1011 *
L1280 1111 1111 1111 1111 1111 1110 1111 0111 *
L1344 0111 0111 0111 1011 1011 1011 1111 1011 *
L1376 0111 0111 0111 1011 1011 0111 1111 1011 *
L1408 0111 0111 0111 1011 0111 1011 1111 1011 *
L1536 1111 1111 1111 1111 1111 1111 1110 0111 *
L1568 0111 1011 1011 1111 1111 1111 1111 1011 *
L1632 0111 0111 0111 1011 1011 1011 1111 1011 *
L1824 0111 1011 1011 1111 1111 1111 1111 1011 *
L1856 0111 0111 1011 1111 1111 1111 1111 1011 *
L1888 0111 0111 0111 1011 1011 1011 1111 1011 *
L1920 0111 0111 0111 1011 0111 1011 1111 1011 *
C5BD1*
V0001 C010101X000HHLHLHLH1 *
V0002 C100010X000LLHLHLLL1 *
V0003 C101101X000HLHHLHHL1 *
V0004 C110010X000LHHLHLLH1 *
V0005 C111000X000LLLLLLHH1 *
V0006 C111001X000HLLHLLHH1 *
V0007 C111010X000LHLLHLHH1 *
V0008 C111011X000HHHHHLHH1 *
V0009 C111101X000HHHHLHHH1 *
VOO10 CXXXXXXX100HHHHLHHH1 *
5196
```



PAL16R6 PAT022

/VR4

PAL DESIGN SPECIFICATION JENNY YEE 10/4/82

VALUE REGISTER AND REGISTER FILE

ADVANCED MICRO DEVICES

CLK IR1 IR2 IR3 SL3 SL2 SL1 SL0 /CE GND /OE IR4 VR4 VR3 VR2 VR1 B A DR VCC

# ; VALUE REGISTER AND REGISTER FILE OUTPUTS

:= /CE\*/VR4 CE\*/IR4

#### FUNCTION TABLE

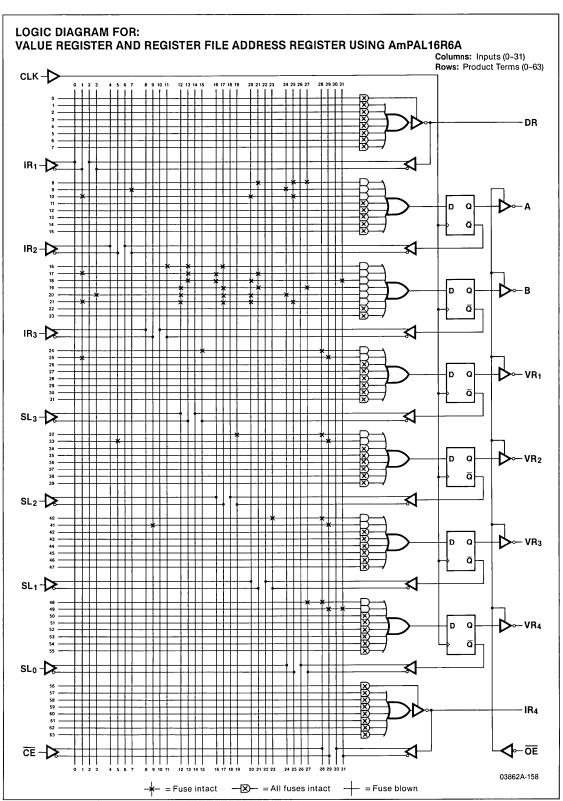
CLK /OE	/CE SL3	SL2	SL1	SLO	IR4	IR3	IR2	IR1	DR	A	В	VR4	VR3	VR2	VR1
;LOAD VI	R REGIST	ERS													
C L	L X	X	X	X	L	L	H	L	X	X	Х	L	L	Н	L
;		***													
C L	HIS VALU H X	JE X	Х	Y	Х	X	Х	Х	Х	Y	Y	L	L	Н	L
	G ALL VA					Λ	Λ	Λ	Λ	Λ	Λ	ъ	ь	11	ь
;A= IR1	B=IR4		. 01.												
C L	H L	Н	H	L	L	Н	L	Н	L	Н	L	L	L	Н	L
;A=VR4	B=B														
C L	H L	L	L	L	L	Н	L	Н	L	L	L	L	L	Н	L
;A=A C L	B=B H L	L	Х	Н	L	Н	L	Н	L	L	т	L	L	Н	L
;A=IR1	B=B	1.1	Λ	11	1.5	11	1.1	11	п	ב	ш	ь	ь	11	ъ
C L	H L	L	Н	L	L	Н	L	Н	L	Н	L	L	L	Н	L
;A=VR4	B=IR1														
C L	H L	H	L	L	L	Н	L	Η	L	L	Н	L	L	Н	L
;A=A C L	B=IR1	Н	L	11	11	т	11	т	L	т	τ.	7	т	7.7	T
;A=A	H L B=IR4		ь	Н	Н	L	Н	L	Ь	L	L	L	L	Н	L
C L	H L	Н	Н	Н	Н	L	H	L	L	L	Н	L	L	Н	L
	B=VR4					_			_	_		_	_		_
C L	н н	L	L	L	Н	L	Η	L	L	L	L	L	L	Н	L
;A=A	B=VR4				**		.,,							**	
C L :A=IR1	H H B=IR1	L	L	H	Н	L	H	L	L	L	L	L	L	H	L
C L	H H	L	Н	L	L	Н	L	Н	L	Н	н	L	L	Н	L
; A=A	B=DR	_	••	_	-	••	_	••	_		••		_	••	
Ć L	н н	L	Н	Н	L	Н	L	H	L	Н	L	L	L	Н	L
;A=VR4	B=1														
C L	н н	H	L	L	L	Н	L	Н	L	L	Н	L	L	Н	L
;A=A C L	B=1 H H	Н	Х	Н	L	Н	L	Н	L	L	ш	L	L	Н	L
;A=IR1	п п В=1	11	Λ	11	ь	п	ь	п	ь	L	п	ь	П	п	ь
C L	Н Н	Н	Н	L	L	Н	L	Н	L	Н	Н	L	L	Н	L

#### DESCRIPTION

THE VALUE REGISTER IS NECESSARY FOR DOUBLE-PIPELINING. THIS REGISTER, ALONG WITH THE DECREMENT REGISTER, CONTROL ALL OF THE ADDRESSING REQUIRED FOR THE REGISTER FILE. THE VALUE REGISTER IS IMPLEMENTED USING 3 IDENTICALLY PROGRAMMED AMPALIGROAS. THE VALUE REGISTER GENERATES DATA INFORMATION ON VR<11:0> (WHICH IS SIMPLY IR<11:0> DELAYED BY ONE CLOCK CYCLE), AND THE A AND B ADDRESSES FOR THE REGISTER FILE ON A ADR<2:0> AND B ADR<2:0>, RESPECTIVELY. THE A AND B ADDRESS SELECTION IS CONTROLLED BY THE RFAR SEL<3:0> FROM MICROCCODE.

```
PAL16R6
                               PAL DESIGN SPECIFICATION
                               JENNY YEE
                                           10/4/82
PATO22
VALUE REGISTER AND REGISTER FILE
ADVANCED MICRO DEVICES
*D9724
*F0*
L0256 1111 1111 1111 1111 1111 1011 1010 1111 *
LO288 1111 1110 1111 1111 1111 1111 0111 1111 *
L0320 1011 1111 1111 1111 1111 0111 1011 1111 *
LO544 1011 1111 1111 1011 0111 1011 1111 1111 *
L0608 1111 1111 1111 0111 1011 1011 1110 1111 *
L0672 1011 1111 1111 0111 1011 0111 1011 1111 *
L0768 1111 1111 1111 1110 1111 1111 1111 0111 *
L1280 1111 1111 1111 1111 1111 1110 1111 0111 *
L1536 1111 1111 1111 1111 1111 1111 1110 0111 *
C3EEO*
V0001 C010XXXX0000LLHLXXX1 *
VOOO2 CXXXXXXX100XLLHLXXX1 *
V0003 C10101101000LLHLLH01 *
V0004 C10100001000LLHLLL01 *
V0005 C10100X11000LLHLLL01 *
V0006 C10100101000LLHLLH01 *
V0007 C10101001000LLHLHL01 *
V0008 C01001011001LLHLLL01 *
V0009 C01001111001LLHLHL01 *
V0010 C01010001001LLHLLL01
V0011 C01010011001LLHLLL01 *
V0012 C10110101000LLHLHH01
V0013 C10110111000LLHLLH01 *
V0014 C10111001000LLHLHL01
V0015 C10111X11000LLHLHL01 *
V0016 C10111101000LLHLHH01 *
```

3139



```
PAL DESIGN SPECIFICATION
PAL16R4
                                          JEFF KITSON
PAT016
DECREMENT REGISTER
ADVANCED MICRO DEVICES
CLK D2 D1 DO CBR VR11 S1 SO /OER GND
/OE RO R1 QO Q1 Q2 NC R2 CXV VCC
; DECREMENT REGISTER OUTPUT SIGNALS
IF (OER) /R2
                          /Q2
                =
        /Q2
             := /S1*/S0*/Q2
                  /S1* S0*/R2
                   S1*/S0*/D2
                   S1* S0* Q2*/Q1*/Q0
                   S1* S0*/Q2* Q0
                   S1* S0*/Q2* Q1
                := /S1*/S0*/Q1
         /Q1
                  /S1* S0*/R1
                   S1*/S0*/D1
                   S1* S0* Q1*/Q0
                   S1* S0*/Q1* Q0
         /Q0
                := /S1*/S0*/Q0
                                          +
                  /S1* S0*/R0
                   S1*/S0*/D0
                   S1* S0* Q0
IF (OER) /R1
                          /Q1
```

/Q0

= CBR\* VR11 /CBR\*/VR11

IF (OER) /RO

/CXV

10/4/82

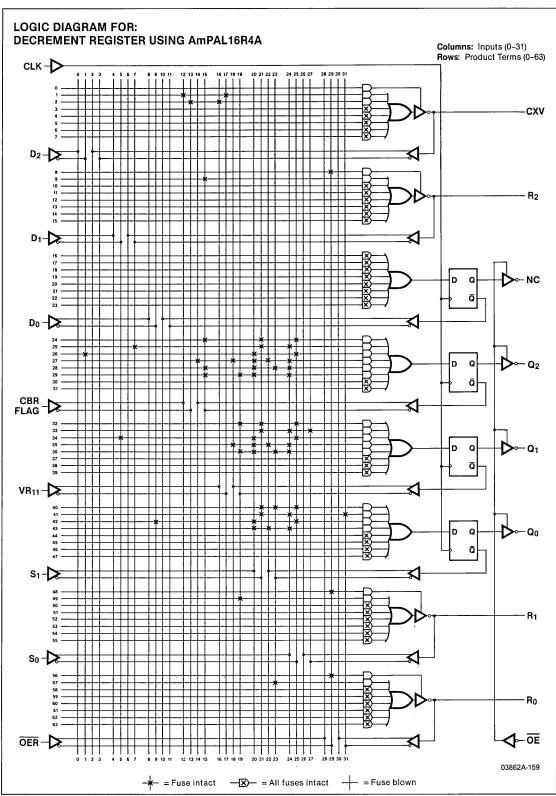
#### FUNCTION TABLE

CLK /	OER	/OF	E S1	S0	D2	D1	DO	CBR	VR	11 R	2 R1	RO	CXV	Q2	Q1	Q0	
;LOAD	REG	IST	ERS	FRC	M R	BUS	S AN	D OI	JTPI	JT ON	TO 0					_	
	Н		L		X		X		X	X	Ĺ	Н	L	X	L	Н	L
;LOAD	REG	IST	'ERS	FRC	M D	BUS	S AN	D OI	JTPl	JT ON	TO Q						
С	Н		Η	L		L	Η		X	X	Z	Z	Z	Х	H	L	Н
; HOLD					_	-	JT C	OTN	•								
С	Н		L	_	X		Х		X	X	Z	Z	Z	X	Н	L	Н
;DECR								ONTO	•								
C	H	L	H	Н	Х	X	Х		Х	X	Z	Z	Z	Х	Н	L	L
C	Н	L	Н	H	X	X	Х		X	X	Z	Z	Z	X	L	H	Η
C	Н	L	Н	Н	X	X	X		X	X	Z	Z	Z	Х	L	Н	L
C	Н	L	Н	H	X	X	X		X	Х	Z	Z	Z	X	L	L	H
С	H	L	Н	Н	X	X	X		X	X	Z	Z	Z	Х	L	L	L
C	H	L	H	Н	X	X	X		X	Х	Z	Z	Z	Х	Н	Η	Η
С	H	L	Н	Н	Х	Х	X		X	X	Z	Z	Z	X	Н	Н	L
С	H	L	H	H	Х	Х	Х		X	Х	Z	Z	Z	X	Н	L	Η
;OUTP	UT T	HE '	VALU.	E O	ОТИ	ΤH	E R	BUS	AND	TON	ONTO	Q					
X	L	Н	X	Х		X	X		X	Х	Н	L	H	X	Z	Z	Z
;TEST	CON	DIT	IONA.	L B	RANG	CH	POL.	ARIT	Y X	OR							
L	X	Х	X	X	X	X	X		L	L	Х	X	X	L	X	Х	X
L	X	X	X	Х	X	X	X		L	H	Х	X	X	Н	X	Х	X
L	X	X	X	X	X	X	X		H	L	X	X	X	Н	X	X	X
L	X	X	X.	X	X	X	Х		H	Н	X	X	X	L	X	X	X

#### DESCRIPTION

THE DECREMENT REGISTER IS IMPLEMENTED USING A SINGLE AMPAL16R4A. IT IS LOADED FROM RBUS<2:0> WHEN THE REGISTER IS SELECTED BY IMMEDIATE OR REGISTER ADDRESSING MODES, OR FROM DBUS<2:0> WHEN A MEMORY ADDRESSING MODE IS USED. LOADING OR DECREMENTING IS CONTROLLED BY DR SEL<1:0> VIA MICROCODE. THE DECREMENT REGISTER, IN CONJUNCTION WITH THE VALUE REGISTER, PROVIDE ALL OF THE ADDRESSING REQUIRED FOR THE REGISTER FILE. SEQUENTIAL ADDRESSING OF THE REGITER FILE (FOR LDM AND STM INSTRUCTIONS) IS QUICK AND EASY WITH THE DECREMENT REGISTER. IT IS ALSO USED TO PROVIDE AN OFFSET TO THE MEMORY ADDRESS WHERE THE DATA IS TO BE STORED INTO OR LOADED FROM.

7DD3



```
PAL16H8
PAT012
RBUS CONSTANT CONTROL A
ADVANCED MICRO DEVICES
VR6 VR7 VR10 NC NC NC /OEH /OEL S GND
NC R9 R8 R7 R6 R5 R4 R1 R0 VCC
;RBUS A OUTPUT SIGNAL

LF (OEL) R0 = VR6*S
```

#### FUNCTION TABLE

VR6	VR7	VR1	0 /OEH	/OEL	S	RO	0 1	R1	R4	R5	R6	R7	R8	R9
;SI	ELECT	RO	AND R1											
X	X	X	H	L	L	L	]	Ĺ	Z	Z	Z	Z	Z	Z
L	L	X	H	L	Н	L	]	L	Z	Z	Z	Z	Z	Z
L	Н	X	H	L	Н	L	I	H	Z	Z	Z	Z	Z	Z
Η	L	Х	H	L	Н	H	]	Ĺ	Z	Z	Z	Z	Z	Z
H	Н	X	H	L	Н	H	I	H	Z	Z	Z	Z	Z	Z
;SEI	LECT	R4 '	TO R9											
Х	X	L	L	H	Н	Z	2	Z	L	L	L	L	L	L
X	Х	H	L	H	Н	Z	2	Z	Н	Н	Н	Н	Н	Н
X	X	X	L	Н	L	Z	- 2	Z	L	L	L	L	L	L
;SEI	LECT	RO '	ΓO R9											
Η	H	H	L	L	Н	H	ŀ	ŀ	Н	Н	Н	Н	Н	H
X	X	Х	L	L	L	L	I	_1	Ļ	L	L	L	L	L

PAL DESIGN SPECIFICATION

10/4/82

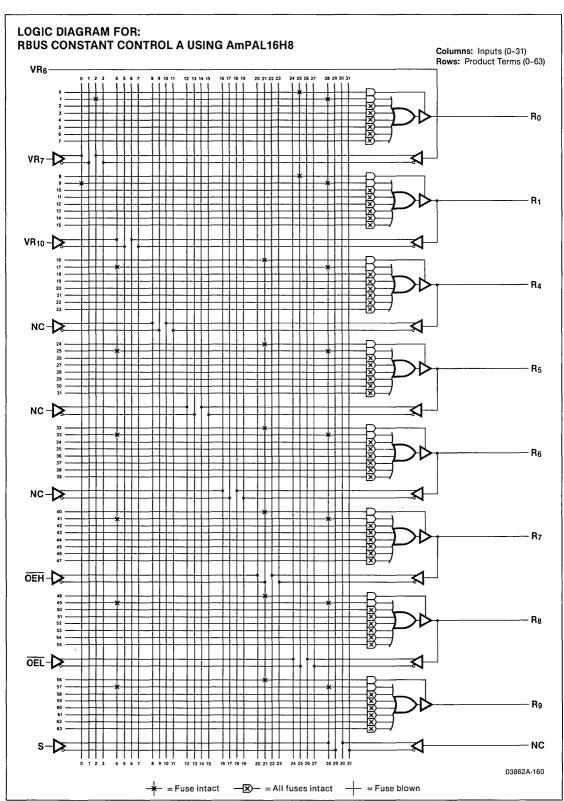
JENNY YEE

# DESCRIPTION

THE RBUS CONTROL PERFORMS SIGN EXTENSION FOR SHORT IMMEDIATE SOURCE OPERANDS AND PUTS CONSTANT VALUES ON THE RBUS. THE FUNCTION IS CONTROLLED BY THE RBUS SELECT SIGNAL FROM MICROCODE. ITS IMPLEMENTATION REQUIRES TWO AMPAL16H8AS. RBUS CONTROL A MANIPULATES RBUS<9:4,1:0> USING INPUTS FROM THE VALUE REGISTER, VR<10,7,6>.

VOO10 XXXXXXOOOOXLLLLLLLL1 \*

0C71



```
PAL16H8
```

PAL DESIGN SPECIFICATION JENNY YEE 10/4/82

PATO13 RBUS CONSTANT CONTROL B

ADVANCED MICRO DEVICES

VR8 VR9 VR10 NC NC NC /OEH /OEL S GND

NC R15 R14 R13 R12 R11 R10 R3 R2 VCC

## ; RBUS B OUTPUT SIGNALS

IF (OEL) R2 = VR8\*S

IF (OEH) R3 = VR9\*S

IF (OEH) R10 = VR10\*S

IF (OEH) R11 = VR10\*S

IF (OEH) R12 = VR10\*S
IF (OEH) R13 = VR10\*S
IF (OEH) R14 = VR10\*S

IF (OEH) R15 = VR10 %S

## FUNCTION TABLE

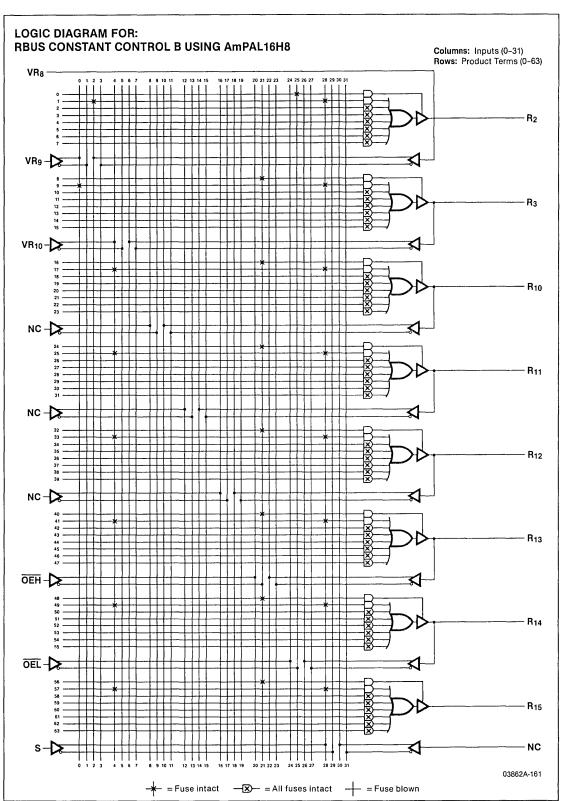
VR8	VR9	VR10	/OEH	/OEL	S	R2	R3	R10	R11	R12	R13	R14	R15
;SEL	ECT	R2 ON	ILY										
X	X	X	H	L	L	L	Z	Z	Z	Z	Z	Z	Z
H	X	X	H	L	H	H	Z	Z	Z	Z	Z	Z	Z
L	X	X	H	L	H	L	Z	Z	Z	Z	Z	Z	Z
;SEL	ECT	R3 T0	R15										
X	X	X	L	H	L	Z	L	L	L	L	L	L	L
X	L	L	L	H	H	Z	L	L	L	L	L	L	L
X	Η	Н	L	Н	H	Z	Η	Н	H	H	Н	Η	Η
X	Η	L	L	Н	Н	Z	Н	L	L	L	L	L	L
X	L	H	L	H	H	Z	L	H	H	Н	Н	Н	Н
;SEL	ECT	R2 TC	R15										
X	X	X	L	L	L	L	L	L	L	L	L	L	L

### DESCRIPTION

THE RBUS CONTROL B HANDLES RBUS<15:10,3:2>. ITS INPUTS ARE PROVIDED BY VR<10:8>.

```
PAL16H8
                           PAL DESIGN SPECIFICATION
                           JENNY YEE
                                   10/4/82
PAT013
RBUS CONSTANT CONTROL B
ADVANCED MICRO DEVICES
*D9725
*F0*
L0000 1111 1111 1111 1111 1111 1111 1011 1111 *
LO288 0111 1111 1111 1111 1111 1111 1111 0111 *
L0512 1111 1111 1111 1111 1111 1011 1111 1111 *
L1280 1111 1111 1111 1111 1111 1011 1111 1111 *
L1536 1111 1111 1111 1111 1011 1111 1111 *
L1568 1111 0111 1111 1111 1111 1111 1111 0111 *
L1824 1111 0111 1111 1111 1111 1111 1111 0111 *
C3DF9*
V0001 XXXXXX1000XZZZZZZZL1 *
VOOO2 1XXXXX1010XZZZZZZZH1 *
V0003 OXXXXX1010XZZZZZZZL1 *
VOOO4 XXXXXXO1OOXLLLLLLLZ1 *
V0005 X00XXX0110XLLLLLLZ1 *
V0006 X11XXX0110XHHHHHHHZ1 *
VOOO7 X10XXX0110XLLLLLLHZ1 *
V0008 X01XXX0110XHHHHHHLZ1 *
VOOO9 XXXXXXOOOOXLLLLLLLL1 *
```

052C



PAL16R6

PAT014

CBR CONTROL

ADVANCED MICRO DEVICES

CLK Z N C V VR10 VR9 VR8 ZN GND

/OE CV CBR NXORV VF CF NF ZF NC

PAL DESIGN SPECIFICATION

10/4/82

JENNY YEE

VCC

## ;CBR CONTROL OUTPUT SIGNALS

/ZF := ZN\*/Z/ZN\*/ZF /NF := ZN\*/N/ZN\*/NF := CV\*/C /CF /CV\*/CF := CV\*/V /VF /CV\*/VF := /ZN\*/CV\*/NXORV /NXORV /ZN\* CV\* NF\*V /ZN\* CV\*/NF\*/V ZN\*/CV\*/N\*/VF ZN\*/CV\* N\* VF ZN\* CV\*/N\*/V ZN\* CV\* N\* V

/CBR := /VR10\*/VR9\*/VR8\*/NF + /VR10\*/VR9\* VR8\*/ZF + /VR10\* VR9\* VR8\*/CF + VR10\*/VR9\*/VR8\*/VF + VR10\*/VR9\* VR8\*/NXORV + VR10\* VR9\*/VR8\*/NXORV\*/ZF + VR10\* VR9\* VR8\*/ZF\*/NF

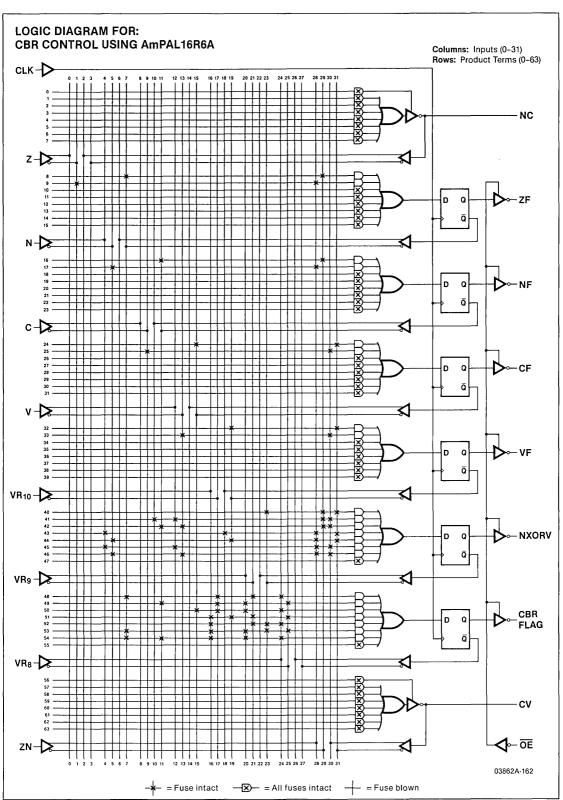
CLK	/OE	ZI	V CV	VR1	O VR	9 VR8	Z	N	С	V	ZF	NF	CF	۷F	NXORV	CBR
:LOA	D Z	. N . (	C.AND	V R	EGTS'	TERS	 (TE	ST I	NXO.	 RV)						
			Н	X	X	X	H		Н	,	Н	L	Н	L	L	X
; HOL	D Z	, N ,(	C,AND	V R	EGIST	ΓERS	(TI	EST	NXO	ORV)						
_	_		L		X	X	X	X	X	X	H	L	Н	L	L	X
•						COND	-									
	L		L	X	X	X	L	Н	X	X	L	H	H	L	Н	X
C	L		Н	X	X	X	X		L	H	L	Н	L	Н	L	X
•						ATIONS		F VI	R							
•						YS ONI										
С			_	L	L	L	X	X	X	X	L	Н	L	H	L	H
;BRAI			ZF													
	L		L	L	L	H	Х	X	Х	X	L	Н	L	H	L	L
;BRAI			NF													
С				L	H	L	X	X	Х	X	L	H	L	Н	L	Η
;BRAI																
	L			L	Н	H	X	X	X	X	L	Н	L	H	L	L
;BRAI	NCH	ON	VF													
С	L	L	L	Н	L	L	X	X	X	X	L	H	L	Н	L	H
;BRA1	NCH	ON	NXORV	7												
С	L	L	L	H	L	H	X	X	X	X	L	Н	L	Н	L	L
;BRAI	NCH	ON	NXORV	OR	ZF											
C	L	L	L	H	H	L	X	Х	X	Х	L	Н	L	Н	L	L
:BRAN	NCH	ON	NF OF	R ZF												_
C		L	L	Н	Н	Н	Х	X	X	X	L	Н	L	Н	L	H
											_		_		_	

## DESCRIPTION

THE CBR CONTROL PAL GENERATES ALL THE CONTROL NECESSARY FOR THE EXECUTION OF CONDITIONAL BRANCH INSTRUCTIONS, SIGN EXTENSION FOR SHORT IMMEDIATE DESTINATION OPERANDS, AND CONSTANT GENERATION. THE IMPLEMENTATION REQUIRES ONE AMPAL16R6A. BRANCH CONDITIONS ARE GENERATED FROM THE FOUR CONDITIONS CODES: ZERO(Z), MINUS(N), OVERFLOW(V), AND CARRY(C). THE CONDITION BEING TESTED IS SELECTED BY VR<10:8>.

```
PAL16R6
                           PAL DESIGN SPECIFICATION
PATO14
                           JENNY YEE
                                    10/4/82
CBR CONTROL
ADVANCED MICRO DEVICES
*D9724
*F0*
L0256 1011 1111 1111 1111 1111 1111 1111 0111 *
L1280 1111 1111 1111 1111 1111 1110 1111 1010 *
L1376 1111 1011 1111 1111 1110 1111 1111 0110 *
L1472 1111 0111 1111 0111 1111 1111 1111 0101 *
L1536 1111 1111 1110 1111 1011 1011 1011 1111 *
L1568 1111 1110 1111 1111 1011 1011 0111 1111 *
L1632 1111 1111 1111 1111 0110 1011 1011 1111 *
L1664 1111 1111 1111 1111 0111 1010 0111 1111 *
L1696 1111 1110 1111 1111 0111 0110 1011 1111 *
L1728 1111 1110 1110 1111 0111 0111 0111 1111 *
C4C20*
V0001 C1010XXX1001XLLHLHX1 *
VOOO2 CXXXXXXXXOOOOXLLHLHX1 *
V0003 C01XXXXX1000XHLHHLX1 *
VOOO4 CXXO1XXXOOO1XLHLHLX1 *
V0005 CXXXX0000000HLHLHLX1 *
V0006 CXXXX0010000LLHLHLX1 *
V0007 CXXXX0100000HLHLHLX1 *
V0008 CXXXX0110000LLHLHLX1 *
V0009 CXXXX1000000HLHLHLX1 *
V0010 CXXXX1010000LLHLHLX1 *
V0011 CXXXX1100000LLHLHLX1 *
V0012 CXXXX1110000HLHLHLX1 *
```

4800



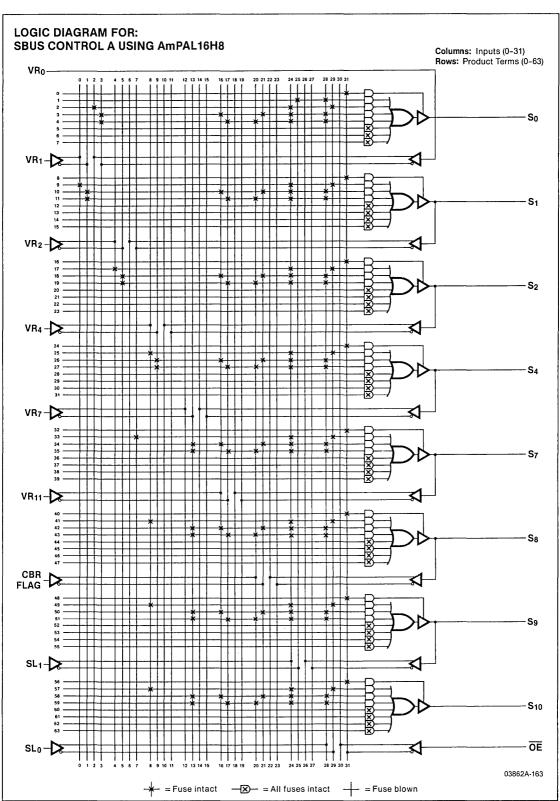
## PAL16H8 PAL DESIGN SPECIFICATION JEFF KITSON 10/4/82 PATO14 SBUS CONTROL A ADVANCED MICRO DEVICES VRO VR1 VR2 VR4 VR7 VR11 CBR SL1 SLO GND S8 S7 S4 S2 S1 S0 VCC /OE S10 S9 ;SBUS A OUTPUT SIGNAL IF (OE) /SL1\* SL0 S0 SL1\*/SLO\* VRO SL1\* SL0\*/VRO\* VR11\*/CBR SL1\* SL0\*/VR0\*/VR11\* CBR IF (OE) SL1\*/SLO\* VR1 S1 SL1\* SLO\*/VR1\* VR11\*/CBR SL1\* SLO\*/VR1\*/VR11\* CBR SL1\*/SL0\* VR2 IF (OE) S2 SL1\* SLO\*/VR2\* VR11\*/CBR

SL1\* SL0\*/VR7\*/VR11\* CBR

VRO	VR1	VR2	VR4	VR	7 VR11	CBR	SL1	SLO	/OE	S0	S1	S2	S4	S7	S8	S9	S10
;SEI	LECT	ZER	)S														
X	X	X	X	X	X	X	L	L	L	L	L	L	L	L	L	L	L
;SEI	LECT	ONES	3														
Х	X	X	X	X	X	X	L	Н	L	H	L	L	L	L	L	L	L
;SEI	LECT	VRO	TO	VR4													
L	Н	L	Н	X	X	X	H	L	L	L	Н	L	Н	Н	Н	Н	Н
H	L	Н	L	X	X	X	H	L	L	H	L	H	L	L	L	L	L
; SEI	LECT	CBR	OFF	SET	VR(0-	7) OF	R ZEI	ROS									
Н	Н	Н	Н	Н	L	H	H	Н	L	L	L	L	L	L	L	L	L
L	Н	L	Н	L	L	H	Η	Н	L	Н	L	Н	L	Н	Η	Н	Н
Н	L	Η	L	Н	Н	L	Н	Н	L	L	Η	L	H	L	L	L	L
L	L	L	L	L	H	L	Н	Н	L	H	Н	H	Н	Н	Н	Н	Н

## DESCRIPTION

THE IMPLEMENTATION OF THE SBUS CONTROL REQUIRES TWO AMPAL16H8AS. THE FUNCTIONS PERFORMED BY THE PALS ARE CONTROLLED BY MICROCODE INPUTS SBUS SEL<1:0>. FOR IMMEDIATE DESTINATION OPERANDS, THESE PALS PERFORM SIGN EXTENSION. IF A CBR INSTRUCTION IS SELECTED, A SIGN EXTENDED BRANCH OFFSET IS DERIVED FROM VR<9:0>. VR<11> AND THE CBR FLAG INITIATE A BRANCH WHEN THEY ARE THE SAME POLARITY, AT WHICH TIME THE OFFSET IS ADDED TO THE PC. IF THE BRANCH CONDITION IS NOT MET, -1 IS ADDED TO THE PC TO RESUME PROPER INSTRUCTION EXECUTION. THE SBUS CONTROL A PAL CONTROLS SBUS<10:7,4,2:0>.



### PAL16H8 PAL DESIGN SPECIFICATION PATO19 JEFF KITSON SBUS CONTROL B ADVANCED MICRO DEVICES VR3 VR4 VR5 VR6 VR7 VR11 CBR S1 SO GND /OE S15 S14 S13 S12 S11 S6 S5 S3 VCC ;SBUS CONTROL OUTPUT SIGNAL = S1\*/S0\* VR3 IF (OE) S3 S1\* S0\*/VR3\* VR11\*/CBR S1\* S0\*/VR3\*/VR11\* CBR IF (OE) = S1\*/S0\* VR4S5 S1\* S0\*/VR5\* VR11\*/CBR S1\* S0\*/VR5\*/VR11\* CBR IF (OE) S6 = S1\*/S0\* VR4S1\* S0\*/VR6\* VR11\*/CBR S1\* S0\*/VR6\*/VR11\* CBR IF (OE) S11 = S1\*/S0\* VR4S1\* S0\*/VR7\* VR11\*/CBR S1\* S0\*/VR7\*/VR11\* CBR S12 = S1\*/S0\* VR4IF (OE) S1\* S0\*/VR7\* VR11\*/CBR S1\* S0\*/VR7\*/VR11\* CBR IF (OE) S13 = S1\*/S0\* VR4S1\* S0\*/VR7\* VR11\*/CBR S1\* S0\*/VR7\*/VR11\* CBR IF (OE) S14 = S1\*/S0\* VR4S1\* S0\*/VR7\* VR11\*/CBR S1\* S0\*/VR7\*/VR11\* CBR

S15 = S1\*/S0\* VR4

S1\* S0\*/VR7\* VR11\*/CBR S1\* S0\*/VR7\*/VR11\* CBR

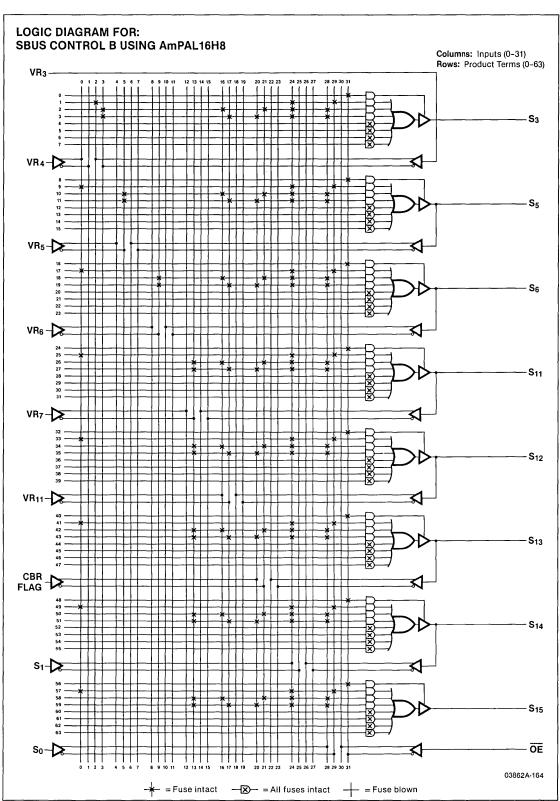
IF (OE)

VR3 VR4 VR5 VR6 VR	' VR11 CBR S1 S	/OE S3 S5 S	36 S11 S12 S13 S14 S15
--------------------	-----------------	-------------	------------------------

;SEL	LECT	ZER	JS															
X	Х	X	X	Х	Х	Х	L	L	L	L	L	L	L	L	L	L	L	
;SEI	LECT	ONE	S															
Х	X	X	X	X	X	X	L	Η	L	L	L	L	L	L	L	L	L	
;SEI	LECT	VRO	TO	VR4														
L	Н	L	Н	X	Х	X	Н	L	L	L	H	Н	H	Н	Н	Н	H	
H	L	Н	L	Х	X	X	Н	L	L	H	L	L	L	L	L	L	L	
;SEI	LECT	CBR	OFF	SET	OR ZE	ROS												
Н	Х	H	Н	Н	Н	L	Н	Н	L	L	L	L	L	L	L	L	L	
L	Х	Η	L	H	Н	$\mathbf{L}$	Н	Н	L	Н	L	H	L	L	L	L	L	
H	X	L	Н	L	L	Н	Н	Η	L	L	H	L	Н	Н	H	Н	H	
L	Х	L	L	L	L	H	Н	Н	L	H	H	H	Н	Н	Η	Н	H	
H L			H L		Ľ L		H	H	Ľ L	Ĺ		L						

#### DESCRIPTION

THE IMPLEMENTATION OF THE SBUS CONTROL REQUIRES TWO AMPAL16H8AS. THE FUNCTIONS PERFORMED BY THE PALS ARE CONTROLLED BY MICROCODE INPUTS SBUS SEL<1:0>. FOR IMMEDIATE DESTINATION OPERANDS, THESE PALS PERFORM SIGN EXTENSION. IF A CBR INSTRUCTION IS SELECTED, A SIGN EXTENDED BRANCH OFFSET IS DERIVED FROM VR<9:0>. VR<11> AND THE CBR FLAG INITIATE A BRANCH WHEN THEY ARE THE SAME POLARITY, AT WHICH TIME THE OFFSET IS ADDED TO THE PC. IF THE BRANCH CONDITION IS NOT MET, -1 IS ADDED TO THE PC TO RESUME PROPER INSTRUCTION EXECUTION. THE SBUS CONTROL B PAL CONTROLS SBUS<15:11,6:5,3>.



```
PAL DESIGN SPECIFICATION
PAL16R4
                                          JENNY YEE
PATO20
PROGRAM COUNTER A
ADVANCED MICRO DEVICES
CLK Y3 Y2 Y1 YO CI S1 SO /OEA GND
             RO R1
                    R2 R3 A2 A3 VCC
OER AO A1
; PROGRAM COUNTER A OUTPUT
IF (OEA) /A3
                  = /S1*/R3
                     S1
IF (OEA) /A2
                  = /S1*/R2
                     S1
          /R3
                 := /S0*/S1*/Y3
                      S0*/S1* R3* R2* R1* R0* CI
                      SO*/S1*/R3*/CI
                      S0*/S1*/R3*/R2
                                                  +
                      SO*/S1*/R3*/R1
                                                  +
                      S0*/S1*/R3*/R0
                          S1*/R3
          /R2
                 := /S0*/S1*/Y2
                     SO*/S1* R2* R1* RO* CI
                     S0*/S1*/R2*/CI
                                                 +
                     S0*/S1*/R2*/R1
                                                 +
                     SO*/S1*/R2*/RO
                         S1*/R2
          /R1
                 := /S0*/S1*/Y1
                     SO*/S1* R1* RO* CI
                     SO*/S1*/R1*/CI
                     SO*/S1*/R1*/RO
                         S1*/R1
          /RO
                 := /S0*/S1*/Y0
                     SO*/S1* RO* CI
                     S0*/S1*/R0*/CI
                         S1*/R0
                  = /S1*/R1
IF (OEA) /A1
```

S1 = /S1\*/R0

S1

IF (OEA) /AO

•10	ΔD P	EGISTI	DC DI		VDI		MD		יייי	ONTO	DDUC							
C	H H	LGISII	I.	L	LDU	ъ Н	L	H	X	ONTO	KBUS Z	Z	7.	Z	L	Н	L	Н
-	CREM	ENT RI	EGISTE		_		_	 ⊬CI	71			_		_	ы		ъ	•••
C	Н	L	L	Н	X	X	X	X	L		Z	Z	Z	Z	L	Н	T.	Н
С	H	L	L	Н	X	X	X	X	Н		Ž	Z		Z	Ĺ	H	H	Ĺ
С	H	L	L	Н	X	X	Х	X	Н		Z	Z	Z	Z	L	Н	Н	Н
С	H	L	L	H	X	X	Х	X	Н		Z	Z	Z	Z	Н	L	L	L
С	Н	L	L	H	X	X	X	X	Н		Z	Z	Z	Z	Н	L	L	Н
С	Н	L	$_{ m L}$	Н	X	X	X	X	Н		Z	Z	Z	Z	Н	L	Н	L
C	Η	L	L	Η	Х	X	X	X	Н		Z	Z	Z	Z	Η	L	H	Н
C	H	L	L	H	Х	X	X	X	Н		Z	Z	Z	Z	Η	Η	L	L
С	H	L	L	H	Х	X	X	X	Η		Z	Z	Z	Z	Н	Н	L	Н
C	H	L	L	Н	Х	X	Х	Х	H		Z	Z	Z	Z	H	Н	Н	L
С	Н	L	L	Η	X	X	X	X	Н		Z	Z	Z	Z	H	Η	Н	H
C	Н	L	L	Н	Х	X	X	Х	H		Z	Z	Z	Z	L	L	L	L
С	Н	L	L	Н	Х	X	X	X	Н		Z	Z	Z	Z	L	L	L	Н
C	H	L	L	H	X	X	X	Х	Η		Z	Z	Z	Z	L	L	H	L
C	H	L	L	H	X	X	Х	X	Н		Z	Z	Z	Z	L	L	Η	Н
C	H	L	L	Н	X	X	X	Х	Н		Z	Z	Z	Z	L	H	L	L
С	Н	L	L	H	X	X	X	X	Н		Z	Z	Z	Z	L	Н	L	Η
	LD V	ALUE 1			'ERS			UTP		ONTO	RBUS							
С	Н	_ L	H	Х	Х	X	X	X	Х		Z	Z	Z	$\mathbf{Z}_{\cdot}$		H	L	Н
	TPUT		URREN							ABUS A			ONT			RBU	S	
X	L	Н	L	X	_X	Х	X	X	X		L	Н	L	H	Z	Z	Z	Z
	TPUT	ZEROS			E A						_	_						
Х	L	Н	Н	X	X	X	X	X	X		L	L	L	L	Z	Z	Z	Z

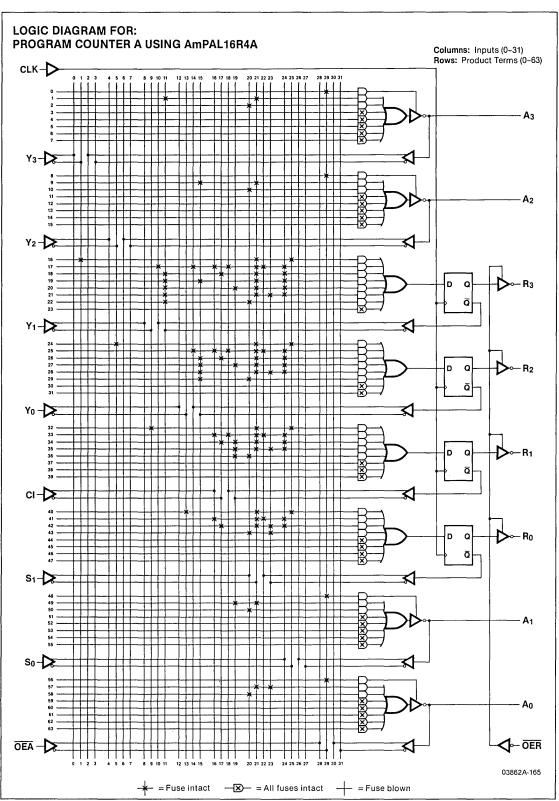
### DESCRIPTION

THE PROGRAM COUNTER EXAMPLE USED HERE SHOWS HOW PALS CAN BE USED IN THE DESIGN TO IMPLEMENT DATA STEERING. THE PC IS IMPLEMENTED AS AN INCREMENTING REGISTER THAT CAN BE PARALLEL LOADED FROM THE YBUS. THE PC IS USED TO SOURCE THE ABUS WITH MEMORY ADDRESSES FOR INSTRUCTIONS, AND ALSO SOURCES THE RBUS FOR RELATIVE BRANCH CALCULATIONS. PROGRAM COUNTER A GENERATES ZEROS IN THE 12 MOST SIGNIFICANT BITS FOR TRAPS AND INTERRUPTS AS WELL. THESE 3 IDENTICALLY PROGRAMMED AMPAL16R4AS, CALLED PROGRAM COUNTER A, ARE THE 3 MOST SIGNIFICANT SLICES OF THE 4-SLICE PROGRAM COUNTER.

```
PAL16R4
                             PAL DESIGN SPECIFICATION
PATO20
                              JENNY YEE
PROGRAM COUNTER A
ADVANCED MICRO DEVICES
*D9724
*F0*
LO288 1111 1111 1111 1110 1111 1011 1111 1111 *
LO544 1111 1111 1101 1101 0101 1001 0111 1111 *
L0576 1111 1111 1110 1111 1011 1011 0111 1111 *
L0608 1111 1111 1110 1110 1111 1011 0111 1111 *
L0640 1111 1111 1110 1111 1110 1011 0111 1111 *
L0672 1111 1111 1110 1111 1111 1010 0111 1111 *
L0768 1111 1011 1111 1111 1111 1011 1011 1111 *
L0800 1111 1111 1111 1101 0101 1001 0111 1111 *
L0832 1111 1111 1111 1110 1011 1011 0111 1111 *
L0864 1111 1111 1111 1110 1110 1011 0111 1111 *
L0896 1111 1111 1111 1110 1111 1010 0111 1111 *
L1056 1111 1111 1111 1111 0101 1001 0111 1111 *
L1088 1111 1111 1111 1111 1010 1011 0111 1111 *
L1120 1111 1111 1111 1111 1110 1010 0111 1111 *
L1312 1111 1111 1111 1111 0111 1001 0111 1111 *
L1344 1111 1111 1111 1111 1011 1010 0111 1111 *
L1376 1111 1111 1111 1111 1111 0110 1111 1111 *
L1600 1111 1111 1111 1111 1111 0111 1111 *
L1824 1111 1111 1111 1111 1010 1111 1111 *
C7B62*
V0001 C0101X00100ZZHLHLZZ1 *
VOOO2 CXXXXOO1100ZZHLHLZZ1 *
V0003 CXXXX101100ZZLHHLZZ1 *
V0004 CXXXX101100ZZHHHLZZ1 *
V0005 CXXXX101100ZZLLLHZZ1 *
V0006 CXXXX101100ZZHLLHZZ1 *
V0007 CXXXX101100ZZLHLHZZ1 *
V0008 CXXXX101100ZZHHLHZZ1 *
V0009 CXXXX101100ZZLLHHZZ1 *
V0010 CXXXX101100ZZHLHHZZ1 *
V0011 CXXXX101100ZZLHHHZZ1 *
V0012 CXXXX101100ZZHHHHZZ1 *
V0013 CXXXX101100ZZLLLLZZ1 *
V0014 CXXXX101100ZZHLLLZZ1 *
V0015 CXXXX101100ZZLHLLZZ1 *
V0016 CXXXX101100ZZHHLLZZ1 *
V0017 CXXXX101100ZZLLHLZZ1 *
V0018 CXXXX101100ZZHLHLZZ1 *
VOO19 CXXXXX1X100ZZHLHLZZ1 *
VOO20 XXXXXXOXOO1HLZZZZHL1 *
```

V0021 XXXXXX1X001LLZZZZLL1 \*

F390



```
PAL DESIGN SPECIFICATION
PAL16R4
PATO21
                                          JEFF KITSON
PROGRAM COUNTER B
ADVANCED MICRO DEVICES
CLK Y3 Y2 Y1 YO CI S1 SO /OEA GND
/OER AO A1 RO R1 R2 R3 A2
                                A3 VCC
; PROGRAM COUNTER B OUTPUT SIGNALS
IF (OEA)
          /A3
                  = /S1*/R3
                     S1
IF (OEA)
          /A2
                  = /S1*/R2
                     S1*/S0
                 := /S0*/S1*/Y3
           /R3
                     S0*/S1* R3* R2* R1* R0* CI +
                     SO*/S1*/R3*/CI
                                                 +
                     SO*/S1*/R3*/R2
                     SO*/S1*/R3*/R1
                     SO*/S1*/R3*/R0
                         S1*/R3
                 := /S0*/S1*/Y2
         /R2
                     SO*/S1* R2* R1* RO* CI
                     SO*/S1*/R2*/CI
                     SO*/S1*/R2*/R1
                     SO*/S1*/R2*/R0
                         S1*/R2
                 := /S0*/S1*/Y1
         /R1
                     SO*/S1* R1* R0* CI
                     SO*/S1*/R1*/CI
                     SO*/S1*/R1*/R0
                         S1*/R1
         /RO
                 := /S0*/S1*/Y0
                     SO*/S1* RO* CI
                     SO*/S1*/RO*/CI
```

S1\*/R0

= /R1\*/S1

= /S1\*/R0S1

IF (OEA) /A1

IF (OEA) /AO

CLK	/OEA	/OE	R S1	S0	Y3	Y2	Y1	YO	CI	4	<b>A</b> 3	A2	A1	AO	R3	R2	R1	RO
:LOA	AD RE	GTST	ERS 1	FROM	YF	us	ANI	011	TPI	JT ON	ro R	BUS						
C	Н	L	L	L	L	Н	L	H	X	011	Z	Z	Z	Z	L	Н	L	Н
; INC	CREME	NT R	EGIS'	ΓERS		RE	G=R1	EG +	C	[								
C	H	L	L	Н	Х	X	X	X	L		Z	Z	Z	Z	L	Н	L	H
С	H	L	L	Н	X	Х	X	X	Н		Z	Z	Z	Z	L	H	Н	L
С	H	L	L	Н	Х	X	X	X	Н		Z	Z	Z	Z	L	Н	H	H
C	H	L	L	H	X	Х	X	X	Н		Z	Z	Z	Z	Н	L	L	L
С	Н	L	L	Н	X	X	X	X	Н		Z	Z	Z	Z	Н	L	L	H
С	H	L	L	Η	X	X	X	X	Н		Z	Z	Z	Z	Н	L	Н	L
С	Н	L	L	Н	Χ	X	X	X	H		Z	Z	Z	$\mathbf{Z}$	Н	L	Н	H
С	Н	L	L	Η	Х	X	X	X	Н		Z	Z	Z	Z	Н	Н	L	L
С	Н	L	L	Н	Χ	X	X	X	Н		Z	Z	Z	Z	Н	Н	L	Н
С	Н	L	L	Н	X	X	X	X	Н		Z	Z	Z	Z	Н	Η	Н	L
С	H	L	L	Η	X	Х	X	X	Н		Z	Z	Z	Z	H	Н	Н	H
С	Η	L	L	Η	X	Х	X	X	Н		Z	Z	Z	Z	L	L	L	L
С	Η	L	L	H	Χ	X	X	X	H		Z	Z	Z	Z	L	L	L	Н
С	Η	L	L	Н	X	X	X	X	Н		Z	Z	Z	Z	L	L	Н	L
С	Η	L	L	Н	X	X	X	Х	Н		Z	Z	Z	Z	L	L	Н	Η
С	Н	L	L	Η.	X	X	X	X	Η		Z	Z	Z	Z	L	H	L	L
С	Н	L	L	Η	X	Х	X	X	Н		Z	Z	Z	Z	L	Н	L	Н
;HOL	LD VA	LUE :	IN RI	EGIS	TER	S	AND	OTP	UT	ONTO	RBU	IS						
С	H	L	Н	X	X	X	X	Х	X		Z	Z	Z	Z	L	H	L	Н
;OUT	ΓPUT	THE (	CURRI	ENT	VAL		ONT	T O		ABUS	AND	NOT	ON	то т	HE R	BUS		
X	L	Н	L	X	X	Х	X	X	X		L	Н	L	Н	Z	Z	Z	Z
;OUT		TWO (	OTNC	THE	AB	US												
X	L	H	Н	L	X	X	X	X	X		L	L	Н	L	Z	Z	Z	Z
,	-		OTNC	THE		US												
X	L	Н	H	Н	X 	X 	X	X	X		L	Н	H	L	Z	Z	_ Z	_ Z _

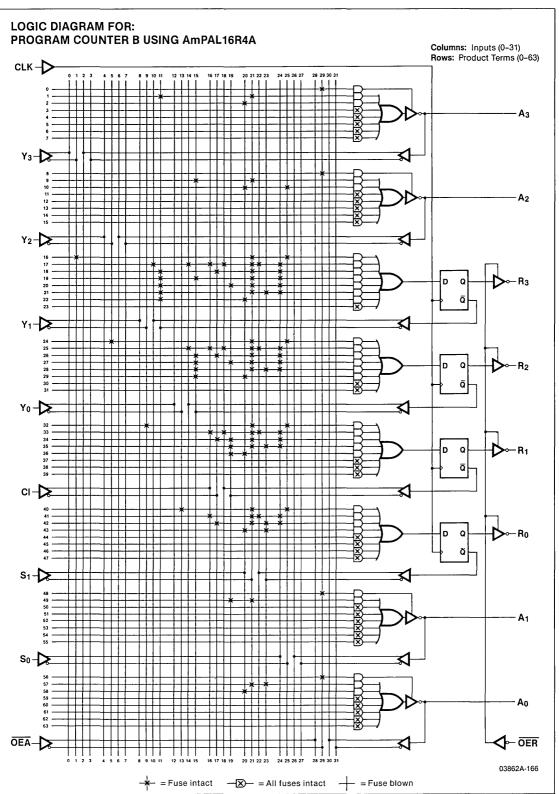
# DESCRIPTION

PROGRAM COUNTER B IS THE LEAST SIGNIFICANT SLICE OF THE PROGRAM COUNTER. THIS SLICE OF THE PROGRAM COUNTER IS FUNCTIONALLY THE SAME AS PROGRAM COUNTER A. THE CONSTANTS TWO AND SIX ARE GENERATED FOR TRAPS AND INTERRUPTS.

```
PAL16R4
                               PAL DESIGN SPECIFICATION
PATO21
                               JEFF KITSON
PROGRAM COUNTER B
ADVANCED MICRO DEVICES
*D9724
*F0*
L0288 1111 1111 1111 1110 1111 1011 1111 1111 *
L0320 1111 1111 1111 1111 1111 0111 1011 1111 *
L0544 1111 1111 1101 1101 0101 1001 0111 1111 *
L0576 1111 1111 1110 1111 1011 1011 0111 1111 *
L0608 1111 1111 1110 1110 1111 1011 0111 1111 *
L0640 1111 1111 1110 1111 1110 1011 0111 1111 *
L0672 1111 1111 1110 1111 1111 1010 0111 1111 *
L0768 1111 1011 1111 1111 1111 1011 1011 1111 *
L0800 1111 1111 1111 1101 0101 1001 0111 1111 *
L0832 1111 1111 1111 1110 1011 1011 0111 1111 *
L0864 1111 1111 1111 1110 1110 1011 0111 1111 *
L0896 1111 1111 1111 1110 1111 1010 0111 1111 *
L1056 1111 1111 1111 1111 0101 1001 0111 1111 *
L1088 1111 1111 1111 1111 1010 1011 0111 1111
L1120 1111 1111 1111 1111 1110 1010 0111 1111 *
L1312 1111 1111 1111 1111 0111 1001 0111 1111 *
L1344 1111 1111 1111 1111 1011 1010 0111 1111 *
L1376 1111 1111 1111 1111 1111 0110 1111 1111 *
L1824 1111 1111 1111 1111 1010 1111 1111 *
C7774*
V0001 C0101X00100ZZHLHLZZ1 *
VOOO2 CXXXXOO1100ZZHLHLZZ1 *
V0003 CXXXX101100ZZLHHLZZ1 *
V0004 CXXXX101100ZZHHHLZZ1 *
V0005 CXXXX101100ZZLLLHZZ1 *
V0006 CXXXX101100ZZHLLHZZ1 *
V0007 CXXXX101100ZZLHLHZZ1 *
V0008 CXXXX101100ZZHHLHZZ1 *
V0009 CXXXX101100ZZLLHHZZ1 *
V0010 CXXXX101100ZZHLHHZZ1 *
V0011 CXXXX101100ZZLHHHZZ1 *
V0012 CXXXX101100ZZHHHHZZ1 *
V0013 CXXXX101100ZZLLLLZZ1 *
V0014 CXXXX101100ZZHLLLZZ1 *
V0015 CXXXX101100ZZLHLLZZ1 *
V0016 CXXXX101100ZZHHLLZZ1 *
V0017 CXXXX101100ZZLLHLZZ1 *
V0018 CXXXX101100ZZHLHLZZ1 *
V0019 CXXXXX1X100ZZHLHLZZ1 *
V0020 XXXXXXOX001HLZZZZHL1 *
V0021 XXXXXX10001LHZZZZLL1 *
V0022 XXXXXX11001LHZZZZHL1 *
```

10/4/82

F275



PAL16H8
PAT015
PC CARRY GENERATOR
ADVANCED MICRO DEVICES
AO A1 A2 A3 A4 A5 A6 A7 A8 GND
A9 C01 C02 C03 A10 A11 SL1 CI NC VCC

PAL DESIGN SPECIFICATION JEFF KITSON 10/4/82

## ; PC CARRY GENERATOR OUTPUT SIGNALS

CO3	= SL1*CI /SL1*CI*AO*A1*A2*A3*A4*A5*A6*A7*A8*A9*A10*A11	+
CO2	= SL1*CI /SL1*CI*AO*A1*A2*A3*A4*A5*A6*A7	+
CO1	= SL1*CI /SL1*CI*AO*A1*A2*A3	+

#### FUNCTION TABLE

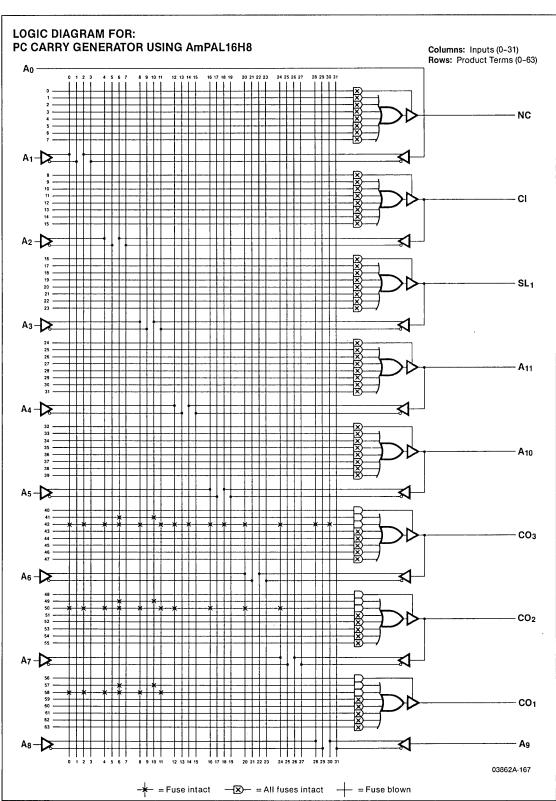
AO AI	. A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	CI	SL1	CO1	CO2	C03
X X H H H H H H L L	H H H	H H H	H H L	H H L	H H L	H H L	H L H	H L H	H L H	H L H	H H H	L	H H H	H H H L L	H

## DESCRIPTION

THE 4-BIT OUTPUTS FROM THE 3 LEAST SIGNIFICANT SLICES OF THE 4-SLICE PC ARE USED TO CREATE A 12-BIT INPUT TO THE PC CARRY GENERATOR. THE PC CARRY GENERATOR TAKES THESE INPUTS AND GENERATES THE CARRY-IN FOR THE 3 MOST SIGNIFICANT SLICES OF THE PROGRAM COUNTER. THE PC CARRY GENERATOR IS CONTROLLED BY THE PC SELECT INPUT FROM MICROCODE.

```
PAL16H8
                      PAL DESIGN SPECIFICATION
                      JEFF KITSON 10/4/82
PAT015
PC CARRY GENERATOR
ADVANCED MICRO DEVICES
*D9725
*F0*
L1824 1111 1101 1101 1111 1111 1111 1111 *
L1856 0101 0101 0110 1111 1111 1111 1111 *
C211E*
VOOO1 XXXXXXXXXXXXXHHHXX11X1 *
VOO02 111111111101HHH1101X1 *
VOOO3 111111111000HHL0001X1 *
V0004 11110000101HLL1101X1 *
V0005 00001111101LLL1101X1 *
```

A5CF



```
PAL DESIGN SPECIFICATION
PAL16R4
                                                           10/4/82
                                            JENNY YEE
PATO10
MEMORY ADDRESS REGISTER
ADVANCED MICRO DEVICES
CLK Y3 Y2 Y1 YO S1 SO A3 /BI GND
/OE /BO AO BO B1 B2 B3 A1 A2 VCC
;MAR OUTPUT SIGNALS
                                           + ; HOLD
/B3
            := /S1*/S0*/B3
                                               :LOAD YBUS INTO MAR
               /S1* S0*/Y3
                                               ; LOAD ABUS INTO MAR
                S1*/S0*/A3
                                               ; DECREMENT
                S1* S0* B3*/B2*/B1*/B0*BI +
                S1* S0*/B3* B2
                                           +
                S1* S0*/B3* B1
                                           +
                S1* S0*/B3* B0
                                           +
                S1* S0*/B3*/BI
            := /S1*/S0*/B2
/B2
               /S1* S0*/Y2
                S1*/S0*/A2
                S1* S0* B2*/B1*/B0*BI
                S1* S0*/B2* B1
                S1* S0*/B2* B0
                S1* S0*/B2*/BI
            := /S1*/S0*/B1
/B1
                /S1* S0*/Y1
                S1*/S0*/A1
                S1* S0* B1*/B0*BI
                                           +
                S1* S0*/B1* B0
                S1* S0*/B1*/BI
             := /S1*/S0*/B0
/B0
                /S1* S0*/Y0
                 S1*/S0*/A0
                 S1* S0* B0* BI
                 S1* S0*/B0*/BI
             = /B3*/B2*/B1*/B0*BI
  BO
```

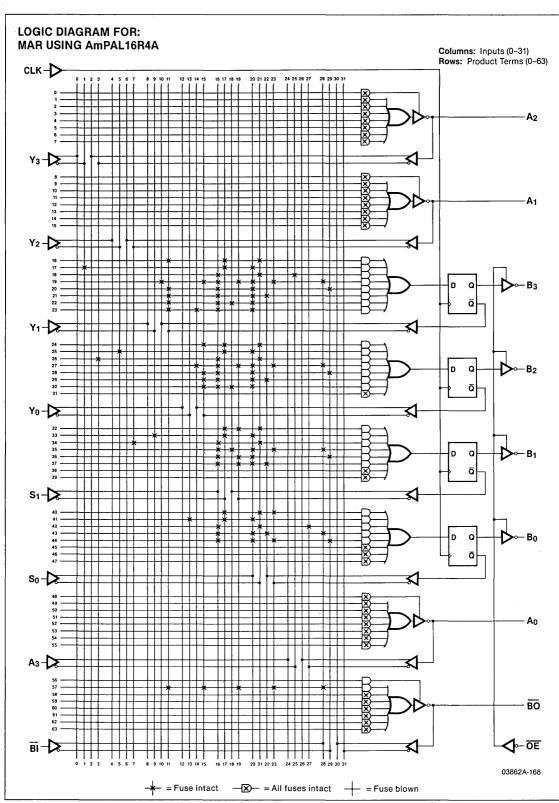
CLK	/OE	S1	S0	Y3	Y2	Y1	YO	АЗ	A2	A1	AO	/BI						1 P	0
;LO	AD R	EGI	STER	RS F	ROM	YE	SUS	ANI	OU	TPU	JT C	NTO	В						
С	L	L	H	L	Н	L	Η	Х	Х	X	X	X			X	L	Н	L	H
;LO	AD R	EGI	STER	S F	ROM	AE	SUS	AND	) OU	TPU	T C	NTO	В						
С	L	Н	L	Х	Х	Х	Х	Н	L	H	L	X			X	Η	L	Н	L
		HIS	VAL	UΕ	AND	OU	TPU	T C	NTC	) B									
С	L	L	L	Х	Х	Х	Х	Х	Х	Х	X	Х			X	Н	L	H	L
;DEC			REG	ISI	ERS	W	HER	E	R=	R -	BI								
С	L	Н	Н	X	Х	Х	X	Х	Х	Х	X	H			H	H	L	H	L
С	L	Н	Н	Х	X	X	Х	Х	Х	Х	X	L			Н	Η	L	L	H
С	L	H	Η	Х	Х	Х	X	Х	Х	X	X	L			H	H	L	L	L
С	L	H	Н	Х	Х	X	X	Х	X	Х	X	L			Н	L	Н	Н	H
С	L	Н	Н	X	X	X	Х	X	Х	Х	X	L			H	L	H	H	L
С	L	Н	Н	Х	Х	Х	Х	Х	X	X	X	L			Н	L	Н	L	Н
С	L	Н	Н	X	Х	X	X	X	Х	X	X	L			H	L	Н	L	L
С	L	Н	H	X	X	Х	Х	X	Х	Х	Х	L			H	L	L	Н	H
С	L	Н	Н	X	X	X	X	X	Х	Х	Х	L			Н	L	L	Н	Ĺ
С	L	Н	Н	X	X	X	Х	Х	Х	Х	X	L		i	H	L	L	ī.	Н
С	L	Н	Н	Х	X	Х	X	X	Х	Х	Х	L		-	L	L	Ĺ	Ĺ	Ĺ
С	L	H	Н	X	X	X	Х	Х	Х	Х	Х	L			H	Н	Н	H	H
C	L	Н	Н	X	X	Х	Х	Х	X	X	X	L			H	H	H	Ĥ	Ĺ
С	L	Н	Н	X	X	Х	Х	Х	X	X	X	L			H	Н	Н	L	H
С	L	Н	Н	Х	Х	X	X	X	X	X	X	Ĺ			H	Н	Н	L	Ĺ
С	L	Н	H	X	X	X	X	X	X	X	X	Ĺ			H	Н	L	H	H
С	L	Н	Н	X	X	X	X	X	X	X	X	Ĺ			H	Н	Ĺ	H	L
	_														• •			*1	

## DESCRIPTION

THE MEMORY ADDRESS REGISTER (MAR) IS USED FOR PLACING ADDRESSES ON THE MEMORY ADDRESS BUS WHEN FETCHING OPERANDS FROM MEMORY FOR SOURCE AND DESTINATION. IT IS ALSO USED TO HOLD THE MEMORY DESTINATION ADDRESS FOR STORING RESULTS FROM AN OPERATION. THE MAR HAS THE CAPABILITY TO DECREMENT TO SUPPORT THE SPECIAL LOAD MEMORY AND STORE MEMORY INSTRUCTIONS. THESE MAR OPERATIONS ARE CONTROLLED BY MAR SEL<1:0>. THE MAR IS IMPLEMENTED USING FOUR AMPAL16R4AS.

10/4/82

**B9E4** 



PAL DESIGN SPECIFICATION PAL16R4 PATO11 JENNY YEE 10/4/82

MEMORY DATA REGISTER (1) ADVANCED MICRO DEVICES

CLK Y3 Y2 Y1 YO NC /CE S /OED GND /OER /DO /D1 /RO /R1 /R2 /R3 /D2 /D3 VCC

## ;MDR OUTPUT SIGNALS

IF (OED) D3 IF (OED) D2 = R3 = R2

/CE\*R3 + ;HOLD

CE\* S\* D3 + ;LOAD FROM DBUS

CE\*/S\*/Y3 :10AD FROM R3 := /CE\*R3

R2 := /CE\*R2 CE\* S\* D2 CE\*/S\*/Y2

:= /CE\*R1 R1 CE\* S\* D1 CE\*/S\*/Y1

:= /CE\*RO RO CE\* S\* DO CE\*/S\*/YO

IF (OED) D1 = R1 IF (OED) DO = RO

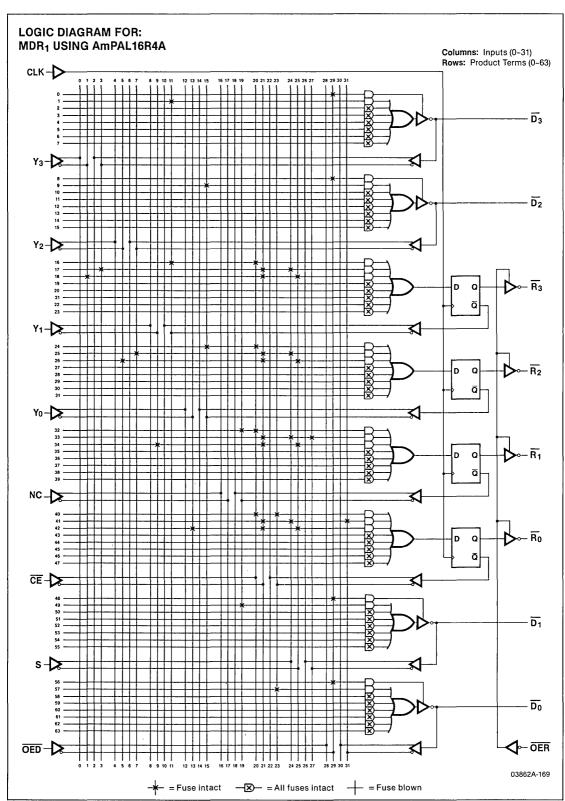
CLK	OED	OER	S	Y3	Y2	Y1	YO	/CE	/D3	/D2	/D1	/D0	/R3	/R2	/R1	/RO
;LO	AD RI	EGIS	TER	S F	ROM	I YI	BUS	AND	OUTPUT	ONTO	RBI	JS	 			
С	L	Н	L	L	H	L	Н	L	Z	Z	Z	Z	L	H	L	Н
;	_															
; LO	AD RI	EGIS	TER	S F	ROM	I DI	BUS	AND	OUTPUT	ONTO	RBU	JS				
С	L	H	Η	Х	X	Х	X	L	Н	L	Н	L	Н	L	Н	L
;																
;HOI	JD VA	LUE	ΑN	D O	UTP	UΤ	ONT	O RI	BUS							
С	L	Η	Х	X	X	X	X	Η	Z	Z	Z	Z	H	L	Н	L
;																
;007	PUT	VAL	UE	CNT	70 D	BUS	S AN	ID NO	OT ONTO	RBUS	,					
С	H	H	Х	X	X	X	X	Н	Н	L	H	L	H	L	Н	L

# DESCRIPTION

THE MEMORY DATA REGISTER 1 (MDR1) IS AN I/O REGISTER WITH MULTIPLE INPUT AND OUTPUT PATHS TO FACILITATE READING AND WRITING DATA FROM MEMORY. IT MAY BE LOADED FROM EITHER THE YBUS (WRITE) OR DBUS (READ) AND OUTPUT ON THE RBUS (READ) OR DBUS (WRITE). IT IS IMPLEMENTED USING FOUR AMPAL16R4AS AND CONTROLLED FROM MICROCODE.

```
PAL16R4
                  PAL DESIGN SPECIFICATION
                   JENNY YEE
PATO11
MEMORY DATA REGISTER (1)
ADVANCED MICRO DEVICES
*D9724
*F0*
LO544 1110 1111 1111 1111 1111 1011 0111 1111 *
L0576 1011 1111 1111 1111 1111 1011 1011 1111 *
L0832 1111 1011 1111 1111 1111 1011 1011 1111 *
L1056 1111 1111 1111 1111 1111 1011 0110 1111 *
L1280 1111 1111 1111 1111 1111 0110 1111 1111 *
L1312 1111 1111 1111 1111 1111 1011 0111 1110 *
L1824 1111 1111 1111 1111 1111 1110 1111 1111 *
C4A70*
V0001 C0101X00100ZZHLHLZZ1 *
V0002 CXXXXX0110001LHLH011 *
VOOO3 CXXXXX1X1OOZZLHLHZZ1 *
VOOO4 CXXXXX1XOOOLHLHLHLH1 *
```

015E



PAL16R6
PAT018
MICROBRANCH CONTROL
ADVANCED MICRO DEVICES

PAL DESIGN SPECIFICATION KEVIN OW-WING 1-18-83

CLK S2 S1 S0 DRO DR1 DR2 INT LDINT GND /OE VRO INTEND /OEVEC /OEJMP /OEMAP2 /OEMAP1 INTFLAG CXV VCC

# ;MICROBRANCH EQUATIONS

/INTFLAG	:=	/INT	
OEMAP1	:=	/S2*/S1*/S0 /S2* S1* S0*/INTENB /S2* S1* S0*/INTFLAG	+
OEMAP2	:=	/S2*/S1* S0	
OEJMP	:=	/S2* S1*/S0 S2*/S1*/S0* DR0 S2*/S1* DR1 S2*/S1* DR2 S2*/S1* S0*/DR0 S2* S1*/S0*/CXV	+ + + + +
OEVEC	:=	/S2* S1* S0* INTFLAG* INTENB S2*/S1*/S0*/DR0*/DR1*/DR2 S2*/S1* S0* DR0*/DR1*/DR2 S2* S1*/S0* CXV	+ + +
/INTENB	:=	- LDINT*/VRO /LDINT*/INTENB	+

# FUNCTION TABLE CLK /OE S2 S1 SO DR2 DR1 DR0 INT LDINT VRO CXV INTFLAG INTENB OFMAP1 OFMAP2 OF IMP OFVEC NIOO T. TNEEOO ь D F T M M E E L E A A J V A N P P M E ;C / D D D I I V C ;C / D D D I I V C ;L O S S S R R R N N R X ;K E 2 1 O 2 1 O T T O V G B 1 2 P C ;UNCONDTIONAL BRANCH :SET INTENB AND INTFLAG CLXXXXXXHHHX HHXXXX;TEST FOR INTERRUPTS C L L H H X X X L X X X C L L H H X X X X H H L X C L L H H X X X X X X X L H L L L H H L H L L L XXHLLL ;DECREMENT COUNTER = O C L H L L L L L X X X X C L H L L L L L H X X X X X X L L L H X X L L H L CLHLLXHXXXXX CLHLLHXXXXXX CLHLHLHXXXXX CLHLHXXLXXXX CLHLHXHHXXXXXX ;DECREMENT COUNTER = 1 XXLLLH XXFFHF XXLLHL XXLLHL ;TEST FOR CONDITIONAL BRANCH

# DESCRIPTION

CLHHLXXXXXXL

CLHHLXXXXXXX

THE MICROBRANCH PAL, AN AMPALIERGA, IS USED TO CONTROL BRANCHING IN THE MICROSEQUENCER. IT OPERATES BY SELECTING THE PROPER BRANCH CONDITION (UNCONDITIONAL, INTERRUPT, COUNTER=0, COUNTER=1, CBR FLAG), TESTING THE CONDITION, AND THEN ACTIVATING ONE OF FOUR POSSIBLE ADDRESS SOURCE OUTPUT ENABLES DEPENDENT UPON THE STATUS OF THE CONDITION TESTED. THE SELECT INPUTS ARE FROM MICROCODE PROM AND THE OUTPUT ENABLES GENERATED BY THE MICROBRANCH PAL ARE ACTUALLY PART OF THE MICROCODE PIPELINE REGISTER.

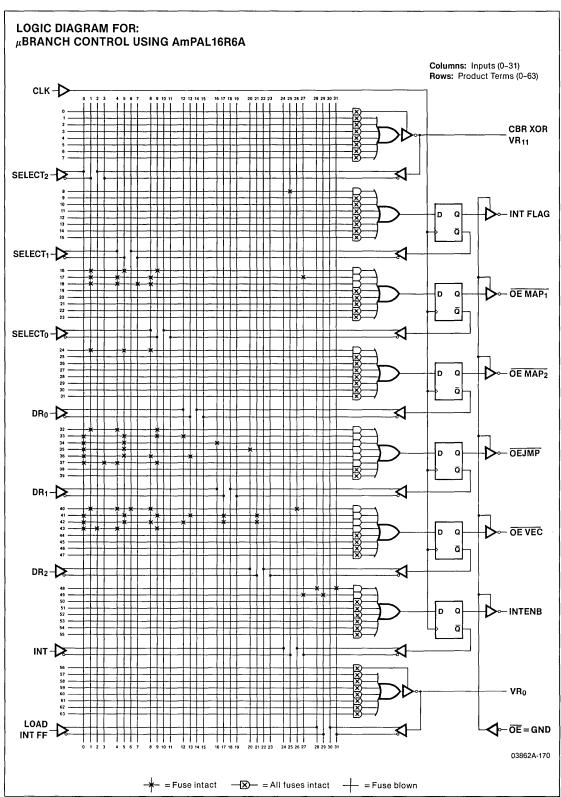
XXLLHL

XXLLLH

NOTE ALSO THAT INTERRUPT SYNCHRONIZATION AND CONTROL ARE ALSO INTEGRATED INTO THE MICROBRANCH PAL.

VOO17 C110XXXXXXOOXXLHHHX11 \*

43CA





# Testing, Programming, Reliability Information

Factory Testing of PALs Logic Verification for PALs PAL Programming AMD Programmable Array Logic Reliability



# Factory Testing of PALs



Advanced Micro Devices' PALs include special test circuitry designed to permit thorough AC and DC testing to be accomplished on an unprogrammed unit. This test circuitry is used to insure good programming yield and to verify that devices will meet all parametric and switching specifications after programming.

Programming circuitry testing includes tests to assure unique addressing of all fuses. To accomplish this, special test pads are provided which are accessible only during wafer probing. Using these, Advanced Micro Devices confirms that each driver is capable of sinking sufficient current to blow fuses and has appropriate saturation characteristics for AC performance. The ability of all circuitry in the programming path to handle the large currents and voltages necessary to blow fuses reliably is also thoroughly checked.

Each PAL has special test fuses. These test fuses are blown during factory testing and demonstrate beyond reasonable doubt that the device is capable of opening all fuses when programmed by the user. They also increase the confidence level in unique addressing.

The special probing pads and test fuses are all employed in programmability testing. This testing coupled with AMD's excellent process control gives industry leading programming yields (>98%) for all AMD PALs.

Special test circuitry, enabled by means of high voltage signals, checks functionality and DC parameters under conditions that simulate post programming operations. Most of the circuitry and levels that can be involved in operation after programming are checked under worst case conditions. For example, all input buffers are tested for functionality by switching them through a special path to a single output

and all product term AND-gates are switched and sensed for uniqueness and functionality.

The fuses blown during programmability testing also permit 100% AC testing of a critical path in every device prior to shipment from the factory. These provide correlatable measures of the propagation delay times that the user can expect from his devices after he has placed his own logic in the PAL.

Because of the large percentage of die area devoted to fixed logic circuitry, all programmable devices from all manufacturers exhibit some percentage of units which fail to function to the desired truth table, even though all fuses are correctly programmed. AMD's special test circuits and extensive factory testing procedures have virtually eliminated this problem. However, to eliminate the possibility of any potential failures reaching the assembly line, the user should exercise the PAL after programming to insure that it functions correctly. This can be performed on an I/C tester, or on some PAL programmers, using user defined test vectors or by comparison against a known good unit.

Test vectors are relatively easy to generate for combinatorial designs using PALs. Sequential function testing is more difficult. AMD PALs are designed to provide the capability of loading the output registers to any desired value during testing. This feature, known as PRELOAD, simplifies functional testing of sequential devices. The following section, Logic Verification for PALs, describes PRELOAD in more detail and provides some guidelines for developing test procedures.



# Logic Verification for PALs

by Brad Kitson Advanced Micro Devices

The purpose of logic verification is to prove that a device functions correctly before it is put in a system. A completely reliable logic verification procedure should test all logic transitions of a device, through its normal inputs and outputs, and at normal TTL operating levels. This guarantees all parts of a device are functionally tested in the same way that they will be used in a system.

# BENEFITS OF LOGIC VERIFICATION

The benefits of logic verification are to provide confidence that a device will function in a board. It also reduces production test time and cost because less board and system debug time is necessary. It is estimated that each succeeding level of testing during system production costs up to an order of magnitude more than the preceding level. So, should logic verification find a faulty device before it is put in a board and tested, significant test cost is saved. Should the faulty device be found before getting to system test or final on-site installation check-out, even more is saved. Programmable logic can implement functions on-chip that used to be done

in multiple devices on a board. Thus some board-level testing can be done on programmable logic by logic verification, saving even more testing time and cost. Logic verification can also be beneficial during the initial design phase with programmable logic. The system designer can program a new design into a device and perform logic verification to see if the device performs the function correctly.

# **FUSE VERIFY FOR PROMS**

With PROMs, logic verification is straightforward. A PROM is simply a read only memory with fuses as the information storage elements. Since the logic function of a PROM is to read out stored information at a given address, logic verification requires reading out and verifying correct status of the fuses at each address, after programming. Therefore, if a PROM verifies as correctly programmed, it is logically correct. Figure 1 shows the block diagram of a PROM. The fuse array is addressed by the input decode and is read from the outputs.

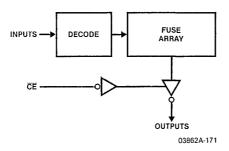


Figure 1. PROM

# **FUSE VERIFY FOR PROGRAMMABLE LOGIC**

Fuse verification, however, doesn't perform logic verification for programmable logic. Programmable logic devices are programmed and fuse verified like PROMs, but don't logically function like PROMs. Figure 2 shows the block diagram of a registered PAL. The input decode of Figure 1 is again present as an input to the fuse array, but is enabled for programming and fuse verifying only. Instead, additional direct inputs and registered feedback inputs of the PAL serve as the logical inputs to its fuse array. The logical inputs must be disabled during fuse verification thereby losing any logical information from the direct inputs and state information from the feedback inputs. Therefore, fuse verification only helps prove correct programming. Figure 3 shows the block diagram of a combinatorial PAL. The programmable output enable and feedback buffers of this device are also untested during fuse verification. Arrows in Figures 2 and 3 denote the untested hardware blocks.

# **INPUT DON'T CARES**

Figure 4 shows a simple design example utilizing two separate state machines. The microprogram for both machines is

shown in Table 1. If both machines are implemented individually in SSI/MSI, relatively few don't care conditions result.

Table 1

FSM A

Current State	Input X	Next State
0	X	1
1	X	2
2	X	3
3	1	2
3	0	3

FSM B

Current State	Input Ÿ	Next State
0	X	1
1	X	3
2	1	1
2	0	3
3	X	2

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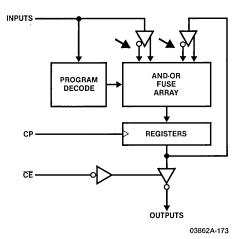


Figure 2. Registered PAL

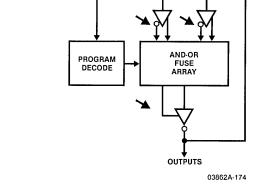
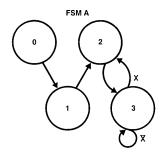
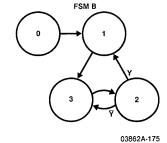


Figure 3. Combinatorial PAL





INPUTS

Figure 4

This is because the SSI/MSI used will only be enough to perform the function desired. In contrast, Table 2 shows the microprogram for the implementation of the design example in a single PAL. Since inputs are present for both machines and the PAL is a superset of either function, a large number of don't cares result. The point to be made here is that all don't care conditions must be tested to prove that both machines are still independent. In the example of Figure 4, to fully test FSM A, each state must be tested with every possible state of FSM B. Only in this way can one be sure that FSM A is independent of FSM B. Futhermore, every combination of states in FSM A and FSM B must be tested with all permutations of the input vectors. Table 3 shows the transitions necessary to fully test the first line in Table 2, i.e., the transition of FSM A state 0 to state 1. In general, the implementation of a logic function in a PAL, or other programmable device, will result in many don't cares since the device will be a superset of the function desired. So, one of the main requirements of logic verification is to prove that don't care conditions indeed don't care. To test all don't cares, an exhaustive list of input vectors is required. Also, in this case, a method is needed to repeatedly get into each state to test each don't care.

**PRELOAD** 

The capability of Advanced Micro Devices' PALs to PRE-LOAD internal feedback registers facilitates logical verification for sequential programmable logic. Two complications exist when PRELOAD is not available. First, getting into a given state to test transitions out of that state becomes much more difficult. For example, referring to Figure 4, getting into state 3 of FSM A could require sequencing through states 0, 1, and 2. Furthermore, this would have to be repeated for each test of state 3. Moreover, to test a state in FSM A with a state in FSM B might require a lengthy and sometimes impossible sequence until the desired combination is obtained, i.e., the only way to get into FSM A state 2 and FSM B state 2 (2, 2) from state (0, 0) would be to sequence through (1, 1), (2, 3), (3, 2), and (3, 3). This is a difficult task to test just one state transition. With PRELOAD, state (2, 2) can be entered directly and tested. Second, power-up initialization becomes very difficult to test. Typically, a state machine has additional don't care states that only affect power-up. Should any of these don't care states be entered on power-up the machine must be able to exit them to start normal operations. Without PRELOAD these states can't be entered and tested to see if they can be exited. PRELOAD allows for these

states to be entered directly and tested. States 0 and 1 of FSM A and state 0 of FSM B are examples of don't care states.

Table 2

Combined State				Next	
FSM A	FSM B	Inp	uts	FSM	FSM B
			1	<del>- ^-</del>	
0	×	Х	Х	1	Х
1	x	Х	Х	2	Х
2	Х	Х	Х	3	X
3	Х	1	X	2.	Х
3	х	0	X	3	Χ
X	0	Х	Х	×	1
X	1	Χ	X	×	3
X	2	X	1	×	1
X	2	Χ	0	x	3
×	3	X	Χ	x	2

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Table 3

Sta	ate			Next State
FSM	FSM	Inp	outs	FSM
Α	В	X	Υ	 Α
0	0	0	0	1
0	0	0	1	1
0	0	1	0	1
0	0	1	1	1
0	1	0	0	1
0	1	0	1	1
0	1	1	0	1
0	1	1	1	1
0	2	0	0	1
0	2	0	1	1
0	2	1	0	1
0	2	1	1	1
0	3	0	0	1
0	3	0	1	1
0	3	1	0	1
0	3	1	1	1

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# PAL Programming



AMD PALs are manufactured using the high performance IMOX oxide isolated process and high reliability platinum-silicide fuses. These technologies require the use of specific programming equipment which has been designed to ensure consistent programming yields in excess of 98%. To maintain these extremely high programming yields, AMD subjects all approved PAL programming equipment to a complete testing and qualification procedure which assures the user that the programmer will program AMD PALs reliably.

The fusing algorithm, which is described in detail in the reliability report, is designed to minimize tight tolerance requirements on the programming equipment. A chip enable input is used to gate the fusing current from a programming source voltage on the PAL output. The delivery of fusing current is therefore controlled by the switching speed of the internal PAL circuitry, not by the circuitry in the programmer. This should minimize the need for constant recalibration of a programmer. However, it is recommended that a user's log be maintained with each machine to collect a record of the hours of service use and programming yield of each lot. The programming equipment should be calibrated after every 50 hours of service or whenever programming yields fall below 98% with AMD PALs.

# PROGRAMMER APPROVAL CRITERIA

Full details of the required programming parameters, waveforms and addressing schemes are provided on each device data sheet. All AMD PALs, standard, high speed ('A' versions) and half power ('L' versions) use the same algorithm and can be programmed on identical modules and adapters. The minimum requirements for approval of a programmer by AMD are that it

- —Programs and fuse verifies AMD PALs with the appropriate conditions described on the device data sheet and provides consistent yields in excess of 98%
- -Programs the security fuse
- —Can program an AMD PAL after master loading from another manufacturer's device.

A desirable feature is the ability to perform logical verification following fuse verification. This will prevent the assembly of a PAL having a logical failure, which cannot be detected from the fuse array alone, into a system.

As noted in the section on testing, all AMD PALs have additional circuitry built into the device to aid detection of logical failures at this point.

Another important feature is the ability to generate output in the JEDEC industry standard Programmable Logic Data Transfer Format. This insures that the equipment will program PALs from all suppliers without special modification or awkward copying procedures.

# QUALIFIED PROGRAMMING EQUIPMENT

The list of AMD qualified PAL programmer models appears below. New programming equipment and vendors are constantly under evaluation. Contact your local AMD Field Applications Engineer or the factory to determine the approval status of any equipment not listed here.

AMD is committed to maintaining continued close working relationships with the major PAL programmer manufacturers so that new programmable logic devices will be properly supported in a timely manner.

Vendor	Programmer Model(s)	AMD PAL Personality Module	Socket Adapter
Data I/O 10525 Willows Rd. N.E. Redmond, WA 98052	Model-100, 29, 19, or 17	Logicpak 950-1942-001	715-1947-003
Digilec, Inc. 7335 E. Acoma Dr. Dept-103 Scottsdale, AZ 85260	Under Development		
Kontron Electronics, Inc. 630 Price Avenue Redwood City, CA 94063	Model-MPP-80S or EPP80	MOD-33	SA37
Stag Microsystems	Model-PPX (or)	PPM2200	Am202S
528-5 Weddel Drive Sunnyvale, CA 94086	ZL30	On-Board	On-Board
Structured Design, Inc. 1700 Wyatt Drive Suite 3 Santa Clara, CA 95084	SD-1000	On-Board	On-Board



# AMD Programmable Array Logic Reliability

# by W. Sievers Advanced Micro Devices



Advanced Micro Devices' Programmable Array Logic (PAL) devices are based on two key technologies with many years of high volume production experience behind them.

- IMOX—the basic process technology employed is IMOX, an advanced ion-implanted, oxide isolated structure. IMOX provides very high performance devices with predictable manufacturing yields. It has accumulated many millions of hours of life test history through its application to the Am27S series of PROMs and the Am2900 family of bipolar microprocessors.
  - A comprehensive report on IMOX reliability titled IMOX RELIABILITY REPORT (AMD publication #03687A-MPR) is available for those interested in a detailed presentation of this subject.
- 2) Platinum-silicide fuses—this fuse structure was originally developed for use on Advanced Micro Devices' families of junction isolated PROMs. It quickly established a new standard of excellence for high programming yields and long term reliability. Several years ago it was applied to a new generation of ultra high performance PROMs based on the IMOX process.

This combination of IMOX and platinum-silicide fuses has an outstanding record of reliability which has been verified repeatedly through in-house life testing and by high reliability customer qualification testing and system use.

Advanced Micro Devices' PALs are fabricated with this same combined process technology. Not only is the technology for building PALs and PROMs the same, but also the programming algorithm and programming circuitry used to program the platinum-silicide fuses are the same in all characteristics of importance. The result is that the fusing conditions seen by an AMD PAL fuse are the same as those seen by an AMD PROM fuse.

Due to the common process technology, fuse design and fuse programming circuitry design, reliability and programming yield results are expected to be the same for PALs and PROMs. Data accumulated to date on PALs appears to confirm this expectation.

This report describes:

- The characteristics of the platinum-silicide fuse and programming conditions for the fuse.
- The dynamic and static burn-in circuits used for HTRB reliability testing.
- Reliability results accumulated to date on IMOX PROMs and PALs.

# PLATINUM-SILICIDE FUSE

# **Fusing Technique**

Advanced Micro Devices' PAL circuits are designed to use a programming algorithm which minimizes the requirements on the programmer yet allows the circuit to fuse the platinum-silicide links quickly and reliably.

The sequence of events to program a fuse are:

- 1) V<sub>CC</sub> power is applied to the chip.
- The address of the fuse to be programmed is selected by TTL levels on the appropriate address pins.
- The outputs are disabled (Pin 1 serves this purpose on PALs).
- 4) The programming voltage is then applied to one output.
- 5) A fuse enable is accomplished by raising an input to a level above normal TTL operating voltage. (Pin 11 is used for this on PALs.) This action gates the current flow through the proper fuse, resulting in an open fuse in a few microseconds.
- The output programming voltage is lowered and then removed.
- 7) The device is enabled and clocked if required. The output state then indicates whether successful programming has occurred. If programming has not occurred a sequence of much longer pulses is applied until programming occurs.
- 8) The sequence of 2 through 7 is repeated for each bit which must be programmed.

There are several advantages to this technique relative to that used by other PAL manufacturers. First, the two high current power sources,  $V_{\rm CC}$  and the voltage applied to the output, do not have critical timing requirements. As the fusing current is gated through the fuse actively, there is no dependence on the rise rate of the programming voltage. A fast application of fusing current is desirable for optimum fusing. Since the output programming voltage does not have to be applied rapidly, breakdown and latchback problems attributed to fast voltage rise times on the output are avoided.

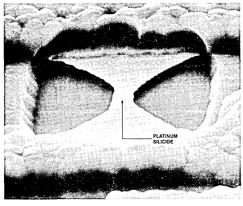
This programming procedure has a second major advantage. If the fuse does not open during the first attempt to blow it, longer programming pulses are used. With the platinum-silicide fuse longer programming pulses may be safely applied with no danger of developing a reliability problem. The algorithm can therefore be designed to minimize the time required to program by using a fast first pulse to maximize the probability that any circuit will program. Then a longer pulse can be applied to the occasional fuse that does not open with the first short pulse. Most devices do fuse satisfactorily with all short pulses.

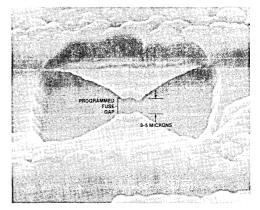
Circuit defects resistant to discovery with pre-programming testing and random marginally wide fuses make it important to have a material not adversely affected by application of near DC programming conditions. The platinum-silicide fuse is such an element.

# **Fuse Characteristics**

When a fast (less than 500ns rise time) current pulse is applied to a fuse, the fuse voltage rises abruptly to a value approaching the level expected from calculation of the room temperature resistance. However, it quickly falls to a value of

approximately 2V. This value is nearly independent of the applied curent. During the period of time the fuse is molten, the fuse current drops very abruptly to zero indicating the separation of the platinum-silicide into two distinct sections. Scanning Electron Microscope photographs of the resulting fuses (Figure 1) indicate that the typical case is a sharp clean separation in excess of a micron. This separation occurs in the center of the fuse because the "bow-tie" structure (Figure 2) concentrates the energy density in the center away from the aluminum interconnect lines. The energy density in the center of the fuse creates temperatures substantially greater than those required to melt the silicide. Melted material is then "wicked" from the center of the fuse to either side due to surface tension.





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**Unprogrammed Fuse** 

**Programmed Fuse** 

Figure 1

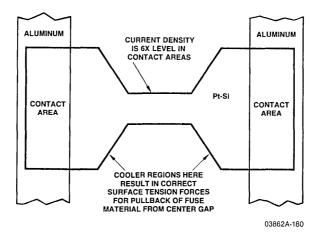


Figure 2. Bow-tie Fuse Design

# RELIABILITY OF FUSES PROGRAMMED UNDER NON-OPTIMAL CONDITIONS

The marginally opened fuse has been studied at AMD in detail even though it rarely occurs in practice. Under conditions where the fuse is purposely blown at much slower rates, it is possible for the fuse to assume a high impedance state which is sensed as an open fuse by the circuit. This occurs when the fuse cools before separation is achieved. Electrical and SEM studies of fuses blown under these conditions indicate that a small conductive path of silicon remains of sufficiently high resistance to prevent the power transfer required for complete opening on subsequent applications of power.

Under these slow-blow conditions, sufficient time exists for the heat flow to carry a significant amount of energy away from the fuse preventing the normal abrupt separation.

To investigate what might happen if a fuse were subjected to these under-blow conditions a large number of fuses were deliberately programmed this way at AMD. After over two thousand hours of life testing these devices with under-blown fuses, there have been no failures. It is clear from the study that partially blown platinum-silicide fuses are stable even though it will rarely occur in a circuit which has been programmed under normal conditions. Advanced Micro Devices believes that such fuses do not represent a reliability hazard based on this study and the results of other studies run on PROMs.

It should be noted that most manufacturers carefully specify the conditions under which their devices must be programmed

in order to avoid reliability problems. Reliability data available on these devices must be assumed to have been generated using optimally programmed devices.

Advanced Micro Devices believes that the study described here and over forty billion fuse hours of data from life testing many different production lots of PROMs and PALs demonstrates the outstanding reliability record of the platinum-silicide fuse under a wide variety of conditions.

# **Reliability Testing Data**

Data on the reliability of PAL and PROM devices with platinum-silicide fuses has been gathered over millions of device hours and more than 40 billion fuse hours of testing at 125°C. This data is shown in Table 1 to project a unit failure at 60% confidence of 0.0003% per 1000 hours at 70°C.

The life test circuits used in this work conform to MIL-STD-883 Method 1005 conditions C and D and are shown in Figure 3.

# SUMMARY

In high temperature operating life tests (HTOL) to date, PALs are exhibiting the same excellent reliability results shown by other IMOX and platinum-silicide fuse products. HTOL testing is an ongoing activity with all product lines at AMD. Updates of these results are generated periodically and can be obtained through inquiry to the AMD Programmable Logic Product directorate.

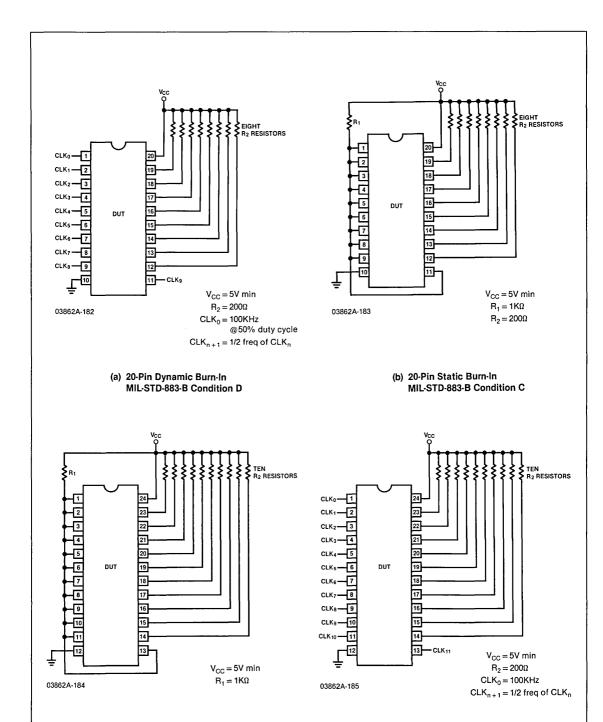
Table 1. Bipolar PROM and PAL Reliability Summary

Product	Production Lots	Units Tested	Total Unit Hours (thousands)	Total Fuse Hours (billions)	Unit Failures	Fuse Related Failures	Unit Failure Rate@60% Confidence %/1000 hrs at 125°C	Unit Failure Rate*@60% Confidence %/1000 hrs at 70°C
27S18/19 (256-bit PROM)	5	491	982	0.251B	0	0	0.10	0.0010
27S20/21 (1K bit PROM)	16	1321	2207	2.260B	2**	0	0.14	0.0013
27S12/13 (2K bit PROM)	11	571	1840	3.768B	0	0	0.05	0.0005
27S15 27S27 27S28/29 27S32/33 (4K bit PROM)	24	1870	1408	5.767B	0	0	0.07	0.0007
27S180/181 (8K bit PROM)	12	463	926	7.586B	0	0	0.11	0.0010
27S184/185 IMOX (8K bit PROM)	15	556	1112	9.109B	0	0	0.09	0.0008
27S190/191 IMOX (16K bit PROM)	2	69	795	13.025B	0	0	0.12	0.0011
20-pin IMOX PALs	10	976	700	1.434B	0	0	0.13	0.0012
Totals for PALs and PROMs	95	6317	9970	43.200B	2**	0	0.031	0.0003

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<sup>\*</sup>Assuming on activation energy of 1.0 eV.

<sup>\*\*</sup>Oxide failure.



(c) 24-Pin Static Burn-In MIL-STD-883-B Condition C

(d) 24-Pin Dynamic Burn-In MIL-STD-883-B Condition D

Figure 3. Life Test Circuits for AMD PALs

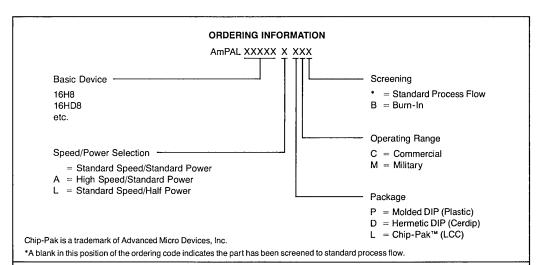
# Section 7

# **General**



Ordering Information AMD Sales Offices

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# **Device Listing**

Ordering Part #	Package/Operating Range Combinations Available
AmPAL16H8	DC, DM, LC, LM, PC
AmPAL16H8A	DC, DM, LC, LM, PC
AmPAL16H8L	DC, DM, LC, LM, PC
AmPAL16HD8	DC, DM, LC, LM, PC
AmPAL16HD8A	DC, DM, LC, LM, PC
AmPAL16HD8L	DC, DM, LC, LM, PC
AmPAL16L8	DC, DM, LC, LM, PC
AmPAL16L8A	DC, DM, LC, LM, PC
AmPAL16L8L	DC, DM, LC, LM, PC
AmPAL16LD8	DC, DM, LC, LM, PC
AmPAL16LD8A	DC, DM, LC, LM, PC

Ordering Part #	Package/Operating Range Combinations Available
AmPAL16LD8L	DC, DM, LC, LM, PC
AmPAL16R4	DC, DM, LC, LM, PC
AmPAL16R4A	DC, DM, LC, LM, PC
AmPAL16R4L	DC, DM, LC, LM, PC
AmPAL16R6	DC, DM, LC, LM, PC
AmPAL16R6A	DC, DM, LC, LM, PC
AmPAL16R6L	DC, DM, LC, LM, PC
AmPAL16R8	DC, DM, LC, LM, PC
AmPAL16R8A	DC, DM, LC, LM, PC
AmPAL16R8L	DC, DM, LC, LM, PC
AmPAL22V10	In Development
AmPAL22V10A	In Development

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